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Before you begin

Overview

This manual contains the reference material needed when working with special circuit analyses in PSpice A/D.

Included in this manual are detailed command descriptions, start-up option definitions, and a list of supported devices in the digital and analog device libraries.

Typographical conventions

Library names and filenames are shown using the following typographical convention:

Notation: monospace font

■ Example: Discrete.olb

Command syntax formats

The following table provides the command syntax formats.

| Notation | Examples | Description |
|----------------|-------------------------|---|
| monospace font | abcd | User input including keypad symbols, numerals, and alphabetic characters as shown; alphabetic characters are not case sensitive. |
| < > | <model name=""></model> | A required item in a command line. For example, <model name=""> in a command line means that the model name parameter is required.</model> |
| < >* | <value>*</value> | The asterisk indicates that the item shown in italics must occur one or more times in the command line. |
| [] | [AC] | Optional item. |
| []* | [value]* | The asterisk indicates that there is zero or more occurrences of the specified subject. |

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| Notation | Examples | Description |
|----------|------------------------|---|
| < > | <yes no="" =""></yes> | Specify one of the given choices. |
| [] | [ON OFF] | Specify zero or one of the given choices. |

Numeric value conventions

The numeric value and expression conventions in the following table not only apply to the PSpice A/D <u>Commands</u>, but also to the device declarations and interactive numeric entries described in subsequent chapters.

Literal numeric values are written in standard floating point notation. PSpice A/D applies the default units for the numbers describing the component values and electrical quantities. However, these values can be scaled by following the number using the appropriate scale suffix as shown in the following table.

| Scale | Symbol | Name |
|--|--------|--------------------------|
| 10 ⁻¹⁵ | F | femto- |
| 10 ⁻¹² | Р | pico- |
| 10 ⁻⁹ | N | nano- |
| 10 ⁻⁶ | U | micro- |
| 25.4*10 ⁻⁶ | MIL | |
| 10 ⁻³ | M | milli- |
| | С | clock cycle ¹ |
| 10 ⁺³ | K | kilo- |
| 10 ⁺³ 10 ⁺⁶ 10 ⁺⁹ 10 ⁺¹² | MEG | mega- |
| 10 ⁺⁹ | G | giga- |
| 10 ⁺¹² | Т | tera- |

^{1.} Clock cycle varies and must be set where applicable.

Note: The lowest value supported in PSpice A/D is 5E-37.

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Numeric expression conventions

Numeric values can also be indirectly represented by parameters; see the ".PARAM (parameter)" on page 87 command. Numeric values and parameters can be used together to form arithmetic expressions. PSpice A/D expressions can incorporate the intrinsic functions shown in the following table.

The Function column lists expressions that PSpice A/D recognizes. The Meaning column lists the mathematical definition of the function. There are also some differences between the intrinsic functions available for simulation and those available for waveform analysis. Refer to your *PSpice A/D User Guide* for more information about waveform analysis.

| Function ¹ | Meaning | Comments |
|-----------------------|--|-------------------------|
| ABS(x) | x | |
| ACOS(x) | arccosine of x | -1.0 <= x <= +1.0 |
| ACOSH(x) | inverse | result in radians |
| | hyperbolic cosine of x | x is an expression |
| ARCTAN(x) | tan ⁻¹ (x) | result in radians |
| ASIN(x) | arcsine of x | -1.0 <= x <= +1.0 |
| ASINH(x) | inverse | result in radians |
| | hyperbolic sine of x | x is an expression |
| ATAN(x) | tan ⁻¹ (x) | result in radians |
| ATAN2(y,x) | arctan of (y/x) | result in radians |
| ATANH(x) | inverse | result in radians |
| | hyperbolic tan of x | x is an expression |
| COS(x) | cos(x) | x in radians |
| COSH(x) | hyperbolic cosine of x | x in radians |
| DDT(x) | $\begin{array}{c} \text{time derivative of} \\ \mathbf{x} \end{array}$ | transient analysis only |
| EXP(x) | e ^X | |
| | | |

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| Function ¹ | Meaning | Comments |
|---|--|--|
| IF(t, x, y) | x if t=TRUE | t is a Boolean expression that evaluates to |
| | y if t=FALSE | TRUE or FALSE and can include logical and relational operators (see <u>Command line options</u> on page 18). X and Y are either numeric values or expressions. |
| | | For example, |
| | | {IF $(v(1) < THL, v(1), v(1) * v(1) / THL)}$ |
| | | Care should be taken in modeling the discontinuity between the IF and ELSE parts, or convergence problems can result. |
| IMG(x) | imaginary part of x | returns 0.0 for real numbers |
| <pre>LIMIT(x, min, max)</pre> | | result is min if $x < min$, max if $x > max$, and x otherwise |
| LOG(x) | ln(x) | log base e |
| LOG10(x) | log(x) | log base 10 |
| M(x) | magnitude of x | this produces the same result as ABS(x) |
| MAX(x,y) | maximum of x and y | |
| MIN(x,y) | minimum of x and y | |
| P(x) | phase of x | returns 0.0 for real numbers |
| PWR(x,y) | x y | the binary operator ** is interchangeable with |
| | or, {x**y} | PWR(x,y). |
| PWRS(x,y) | $+ x ^y$ (if $x>0$), | |
| | $- x ^y$ (if x<0) | |
| R(x) | real part of x | |
| SCHEDULE | piecewise constant function: from time x forward use y | Must include an entry for TIME=0. |
| (x ₁ , y ₁ , x ₂ , y 2, x _n , y _n) | | All y values must be legal for the associated parameter. |
| | | Time (x) values must be ≥ 0 . |
| SDT(x) | time integral of x | For transient analysis only. |
| SGN(x) | signum function | |

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| Function ¹ | Meaning | Comments |
|---|-------------------------|--|
| SIN(x) | sin(x) | x in radians |
| | | |
| SINH(x) | hyperbolic sine of x | |
| STP(x) | 1 if x>=0.0 | The unit step function can be used to suppress a value until a given amount of time has |
| | 0 if x<0.0 | passed. For instance, |
| | | {v(1)*STP(TIME-10ns)} |
| | | gives a value of 0.0 until 10ns has elapsed, then gives $v(1)$. |
| SQRT(x) | x ^{1/2} | |
| TAN(x) | tan(x) | x in radians |
| TANH(x) | hyperbolic tangent of x | x in radians |
| TABLE (x, x ₁ , y ₁ , x ₂ , y ₂ , x _n , y _n) | | Result is the y value corresponding to x, when all of the x_n , y_n points are plotted and connected by straight lines. If x is greater than the max x_n , then the value is the y_n associated with the largest x_n . If x is less than the smallest x_n , then the value is the y_n associated with the smallest x_n . |
| zero(expression) | | The expression is evaluated and the result is ignored. Function returns the value 0. |
| | | Example: |
| | | EE15 12 0 VALUE=+ |
| | | {ZERO(BREAK(time+10e-6))} |
| one(expression) | | The expression is evaluated and the result is ignored. Function returns the value 1. |

Before you begin

| Function ¹ | Meaning | Comments |
|-----------------------|------------|---|
| ceil(arg) | | Returns an integer value. |
| | | The argument for this function should be a numeric value or an expression that evaluates to a numeric value. If arg is an integer, the return value is equal to the argument value. If arg is a non-integer value, the return value is the nearest integer greater than the argument value. |
| | | Example: |
| | | ceil(PI)=4 |
| | | ceil(5)=5 |
| | | ceil(5.4)=6 |
| floor(arg) | | Returns an integer value. |
| | | The argument for this function should be a numeric value or an expression that evaluates to a numeric value. If arg is an integer, the return value is equal to the argument value. If arg is a non-integer value, the return value is the nearest integer smaller than the argument value. |
| | | Example: |
| | | floor(PI)=3 |
| | | floor(5)=5 |
| | | floor(5.4)=5 |
| intq(arg) | is integer | Returns 1 if argument is an integer. |
| | | Returns 0 if argument is not an integer. |
| | | The argument passed to this function can be a numeric value or an expression that evaluates to a numeric value |

^{1.} Most numeric specifications in PSpice A/D allow for arithmetic expressions. Some exceptions do exist and are summarized in your *PSpice A/D User Guide*. There are also some differences between the intrinsic functions available for simulation and those available for waveform analysis. Refer to your *PSpice A/D User Guide* for more information about waveform analysis.

Before you begin

Expressions can contain the standard operators as shown in the following table.

| Operators | Meaning |
|-------------------|------------------------------------|
| arithmetic | |
| + | addition (or string concatenation) |
| - | subtraction |
| * | multiplication |
| / | division |
| ** | exponentiation |
| PWR() | |
| PWRS() | |
| logical | |
| ~ | unary NOT |
| 1 | boolean OR |
| ٨ | boolean XOR |
| & | boolean AND |
| relational (withi | n IF() functions) |
| == | equality test |
| != | non-equality test |
| > | greater than test |
| >= | greater than or equal to test |
| < | less than test |
| <= | less than or equal to test |

Before you begin

Command line options

Command files

A command file is an ASCII text file which contains a list of commands to be executed. A command file can be specified in multiple ways:

- at the command line when starting PSpice A/D and Stimulus Editor
- by choosing *Run Commands* from the *File* menu and entering a command file name (for PSpice A/D and Stimulus Editor only)

The command file is read by the program and all of the commands contained within the file are performed. When the end of the command file is reached, commands are taken from the keyboard and the mouse. If no command file is specified, all of the commands are received from the keyboard and mouse.

The ability to record a set of commands can be useful when using PSpice A/D and Stimulus Editor. This is especially useful in PSpice A/D, if you are repeatedly doing the same simulation and looking at the same waveform with only slight changes to the circuit before each run. It can also be used to automatically create hard-copy output at the end of very long (such as overnight) simulation runs.

Creating and editing command files

You can create your own command file using a text editor (such as Notepad). In PSpice A/D and Stimulus Editor, you can choose Log Commands from the File menu (see Log files on page 19 for an example) to record a list of transactions in a log file, then choose *Run Commands* from the *File* menu to run the logged file.

Note: After you activate cursors (from the Tools menu, choose Cursor), any mouse or keyboard movements that you make for moving the cursor will not be recorded in the command file.

If you choose to create a command file using a text editor, note that the commands in the command file are the same as those available from the keyboard with these differences:

- The name of the command or its first capitalized letter can be used.
- Any line that begins with an * is a comment.
- Blank lines are ignored, therefore, they can be added to improve the readability of the command file.

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■ The command PAUSE causes PSpice A/D or Stimulus Editor to wait until ENTER key on the keyboard is pressed. In the case of PSpice A/D, this can be useful to examine a waveform before the command file draws the next one.

The commands are one to a line in the file, but comment and blank lines can be used to make the file easier to read.

Assuming that a waveform data file has been created by simulating the circuit <code>example.dsn</code>, you can manually create a command file (using a text editor) called <code>example.cmd</code> which contains the commands listed below. This set of commands draws a waveform, allows you to look at it, and then exits PSpice A/D.

```
* Display trace v(out2) and wait
Trace Add
v(out2)
Pause
* Exit Probe environment
File Exit
```

See <u>Simulation command line specification format</u> and <u>Specifying simulation command line options</u> for specifying command files on the simulation command line. See <u>Simulation command line specification format</u> and <u>Specifying simulation command line options</u> for details on specifying the /C or -c option for PSpice A/D.

Note: The Search Commands feature is a Cursor option for positioning the cursor at a particular point. To learn more about Search Commands, see *PSpice A/D Help*.

Log files

Instead of creating command files by hand, using a text editor, you can generate them automatically by creating a log file while running PSpice A/D or Stimulus Editor. While executing the particular package, all of the commands given are saved in the log file. The format of the log file is correct for use as a command file.

To create a file in PSpice A/D or Stimulus Editor, from the File menu, choose Log Commands and enter a log file name. This turns logging on. Any action taken after starting Log Commands is logged in the named file and can be run in another session by choosing Run Commands.

Note: Some commands might not be added to the log file.

You can also create a log file for PSpice A/D or Stimulus Editor by using the /I or -I option at the command line. For example:

```
PSPICE /L EXAMPLE.LOG
```

Before you begin

Of course, you can use a name for the log file that is more recognizable, such as acplots.cmd (to PSpice A/D and Stimulus Editor, the file name is any valid file name for your computer).

Note: You can use either (/) or (-) as separators, and file names can be in upper or lower case.

Editing log files

After PSpice A/D or Stimulus Editor is finished, the log file is available for editing to customize it for use as a command file. You can edit the following items:

Add blank lines and comments to improve readability (perhaps a title and short discussion of what the file does).

Note: Note: At some places, blank lines do not work in Stimulus Editor.

- Add the Pause command for viewing waveforms before proceeding.
- Remove the Exit command from the end of the file, so that PSpice A/D and Stimulus Editor do not automatically exit when the end of the command file is reached.

You can add or delete other commands from the file or even change the file name to be more recognizable. It is possible to build onto log files, either by using your text editor to combine files or by running PSpice A/D and Stimulus Editor with both a command and log file:

```
PSpice.exe /C IN.CMD /L OUT.LOG
```

The file in.cmd gives the command to PSpice A/D and PSpice A/D saves the (same) commands into the out.log file. When in.cmd runs out of commands, and PSpice A/D is taking commands from the keyboard, these commands also go into the out.log file.

To log commands in PSpice A/D

Use command logging in PSpice A/D to record and save frequently used actions to a command file. Command files are useful when you need to remember the steps taken in order to display a set of waveforms for any given data file.

- 1. From the File menu, choose Log Commands.
- 2. In the Log File Name text box, type 2traces, then click OK.

A check mark appears next to Log Command to indicate that logging is turned on.

- **3.** From the File menu, choose Open.
- **4.** Select example.dat (located in the examples directory), then click OK.

Before you begin

- **5.** From the *Trace* menu, choose Add.
- **6.** Select V(OUT1) and V(OUT2), then click OK.
- 7. From the File menu, choose Log Commands to turn command logging off.

The check mark next to the command disappears. Subsequent actions performed are not logged in the command file.

You can view the command file using an ASCII text editor, such as Notepad. Command files can be edited or appended, depending on the types of commands you want to store for future use. The file 2traces.cmd should look as shown below (with the exception of a different file path).

```
*Command file created by Probe - Wed Apr 17 10:33:55
File Open
/Cadence/probe/example.dat
OK
Trace Add
V(OUT1) V(OUT2)
OK
```

To run the command log

- **1.** From the *File* menu, choose *Run Commands*.
- **2.** Select 2traces.cmd, then click *OK*.

The two traces appear.

Before you begin

Simulation command line specification format

The format for specifying command line options for PSpice A/D are as follows:

pspice [options] [input file(s)]

Where:

options

One or more of the options listed in <u>Simulation command line options</u> on page 22. Options can be entered using the dash (-) or slash (/) separator.

input file

Specifies the name of a circuit file for PSpice A/D to simulate after it starts. The input file can be a simulation file (.sim, .cir, .net), data files (.dat), output files (.out), or any files (*.*). PSpice A/D opens any files whose extension PSpice A/D does not recognize as a text file.

You can specify multiple input files, but if the output file or data file options are specified, they apply only to the first specified input file.

The input file name can include wildcard characters (* and ?), in which case all file names matching the specification are simulated.

Table 1-1 Simulation command line options

| Option | Description |
|---------------------------------|---|
| -c <file name=""></file> | Specifies the command file, which runs the session until the command file ends or PSpice A/D stops. |
| -d <i><data file=""></data></i> | Specifies the name of the waveform data file to which PSpice A/D saves the waveform data from the simulation. By default, the name of the waveform data file is the name of the input file with a .dat extension. |
| -е | Exits PSpice A/D after all specified files have been simulated. |
| | This option replaces the -wONLY option. |
| | |

Before you begin

Table 1-1 Simulation command line options

| Option | Description |
|--------------------------------|--|
| -i <ini file="" name=""></ini> | Specifies the name of an alternate initialization file. If not specified, the simulator uses: |
| | <pre>%HOME%\cdssetup\OrCAD_PSpice\<pspice_ve rsion=""></pspice_ve></pre> |
| -1 <file name=""></file> | Creates a log file, which saves the commands from this session. This log file can later be used as an input command file for PSpice A/D. |
| -o <output file=""></output> | Specifies the output file to which PSpice A/D saves the simulation output. |
| -r | Runs simulation files. If this option is not specified, the specified files are opened but not simulated. |

Specifying simulation command line options

The command line options that use <file name> assume default extensions. These command line options can be used without specifying the extension to <file name>. For example:

```
-c makeplot -p newamp
-c makeplot.cmd -p newamp.prb
```

are equivalent.

However, PSpice A/D searches first for the exact < file name > specified for these command line options, and if that < file name > exists, PSpice A/D uses it. If the exact < file name > does not exist, PSpice A/D adds default extensions to < file name > and searches for those. The following default extensions are used:

```
<file name[.dat]> waveform data file
-c<file name[.cmd]> command file
-1<file name[.log]> log file
```

References

■ To learn more about PSpice A/D macros, see *PSpice A/D Help*.

Before you begin

■ To learn how to build and compile various PSpice Device Modeling Interface (DMI) compatible C and SystemC models, see the *PSpice Device and System Modeling in C/C++ and SystemC Tutorial*.

Commands

| Otanaland analyses | |
|---|--|
| Standard analyses | |
| .AC (AC analysis) on page 30 .DC (DC analysis) on page 35 .FOUR (Fourier analysis) on page 46 .NOISE (noise analysis) on page 67 | OP (bias point) on page 70 SENS (sensitivity analysis) on page 105 TF (transfer) on page 120 TRAN (transient analysis) on page 121 |
| Output control | |
| .PLOT (plot) on page 89 .PRINT (print) on page 91 .PROBE (Probe) on page 93 | .VECTOR (digital output) on page 124 .WATCH (watch analysis results) on page 127 |
| Simple multi-run analyses | |
| .STEP (parametric analysis) on page 106 | .TEMP (temperature) on page 117 |
| Circuit file processing | |
| .END (end of circuit) on page 43 .FUNC (function) on page 47 .INC (include file) on page 50 | .LIB (library file) on page 51 .PARAM (parameter) on page 87 .DMILIB (library file) on page 41 |
| Statistical analyses | |
| .MC (Monte Carlo analysis) on page 53 | .WCASE (sensitivity/worst-case analysis) on page 129 |
| Device modeling | |
| .SUBCKT (subcircuit) on page 112 .ENDS (end subcircuit) on page 44 .DISTRIBUTION (user-defined distribution) on page 39 | .MODEL (model definition) on page 57 .SUBCKT (subcircuit) on page 112 |
| Initial conditions | |

Commands

.IC (initial bias point condition) on page 49 .LOADBIAS (load bias point file) on page 52 .SAVEBIAS (save bias point to file) on

.NODESET (set approximate node voltage for bias point) on page 66 page 101

Miscellaneous

.ALIASES, .ENDALIASES (aliases and endaliases) on page 32 .AUTOCONVERGE (Autoconvergence of simulations) on page 33 .CHKPT (Generate CheckPoints) on page 34 .EXTERNAL (external port) on page 45 .OPTIONS (analysis options) on page 71 .STIMLIB (stimulus library file) on page 110

.RESTART (Restart simulation from a CheckPoint) on page 69 .STIMULUS (stimulus) on page 111 .TEXT (text parameter) on page 118 .TCLPOSTRUN(Runs TCL file post simulation) on page 116 * (comment) on page 133 ; (in-line comment) on page 134 + (line continuation) on page 135

PSpice A/D Reference Guide Commands

Command reference for PSpice and PSpice A/D

You can provide analysis specifications through the Analysis Setup dialog box (from the Analysis menu, select Setup).

| Function | PSpice command | Description |
|-------------------------------|---|--|
| Standard | .AC (AC analysis) | frequency response |
| Analyses | .DC (DC analysis) | DC sweep |
| | .FOUR (Fourier analysis) | Fourier components |
| | .NOISE (noise analysis) | noise |
| | .OP (bias point) | bias point |
| | .SENS (sensitivity analysis) | DC sensitivity |
| | .TF (transfer) | small-signal DC transfer function |
| | .TRAN (transient analysis) | transient |
| Simple Multi- Run Analyses | .STEP (parametric analysis) | parametric |
| | .TEMP (temperature) | temperature |
| Statistical Analyses | .MC (Monte Carlo analysis) | Monte Carlo |
| | .WCASE (sensitivity/worst-case analysis) | sensitivity/worst-case |
| Initial Conditions | .IC (initial bias point condition) | clamp node voltage for bias point calculation |
| | .LOADBIAS (load bias point file) .NODESET (set approximate node | to restore a .NODESET bias point |
| | voltage for bias point) .SAVEBIAS (save bias point to file) | to suggest a node voltage for bias calculation |
| | | to store .NODESET bias point information |

PSpice A/D Reference Guide Commands

| Function | PSpice command | Description |
|----------------------------|---|---|
| Device Modeling | .ENDS (end subcircuit) | end of subcircuit definition |
| | .DISTRIBUTION (user-defined distribution) | model parameter tolerance |
| | .MODEL (model definition) | distribution |
| | .SUBCKT (subcircuit) | modeled device definition |
| | | to start subcircuit definition |
| Output Control | .PLOT (plot) | to send an analysis plot to output file (line printer format) |
| | .PRINT (print) | to send an analysis table to output file |
| | .PROBE (Probe) | to send simulation results to Probe data file |
| | .VECTOR (digital output) | digital state output |
| | .WATCH (watch analysis results) | view numerical simulation results in progress |
| Circuit File Processing | .END (end of circuit) | end of circuit simulation description |
| | .FUNC (function) | expression function definition |
| | .INC (include file) | include specified file |
| | .LIB (library file) | reference specified library |
| | .PARAM (parameter) | parameter definition |
| | .DMILIB (library file) | reference DMI model library |

PSpice A/D Reference Guide Commands

| Function | PSpice command | Description |
|---------------|---|--|
| miscellaneous | .ALIASES, .ENDALIASES (aliases and endaliases) on page 32 | to begin and end an alias definition |
| | .AUTOCONVERGE (Autoconvergence of simulations) on page 33 | to identify nets representing the outermost (or peripheral) connections to the circuit being simulated |
| | .EXTERNAL (external port) on page 45 | to set miscellaneous simulation limits, analysis control parameters, and output characters |
| | | to specify a stimulus library name containing .STIMULUS information |
| | <u>.OPTIONS (analysis options)</u> on page 71 | stimulus device definition |
| | pago 7 i | text expression, parameter, or file name used by digital devices |
| | | to create a comment line |
| | <u>.STIMLIB (stimulus library file)</u> on page 110 | to add an in-line comment |
| | | to continue the text of the previous line |
| | .STIMULUS (stimulus) on page 111 | |
| | .TEXT (text parameter) on page 118 | |
| | | |
| | * (comment) on page 133 | |
| | ; (in-line comment) on page 134 | |
| | + (line continuation) on page 135 | |

Commands

.AC (AC analysis)

Purpose The .AC command calculates the frequency response of a circuit over

a range of frequencies.

General form .AC <sweep type> <points value>

+ <start frequency value> <end frequency value>

Examples .AC LIN 101 100Hz 200Hz

.AC OCT 10 1kHz 16kHz .AC DEC 20 1MEG 100MEG

Arguments and options

<sweep type>

Must be LIN, OCT, or DEC, as described below.

| Parameter | Description | Description |
|-----------|---------------------|--|
| LIN | linear sweep | The frequency is swept linearly from the starting to the ending frequency. The <pre><points value=""></points></pre> is the total number of points in the sweep. |
| OCT | sweep by octaves | The frequency is swept logarithmically by octaves. The <pre><pre> <points value=""> is the number of points per octave.</points></pre></pre> |
| DEC | sweep by decades | The frequency is swept logarithmically by decades. The $$ is the number of points per decade. |

<points value>

Specifies the number of points in the sweep, using an integer.

Commands

outputs and dividing by the frequency increment.

<start frequency value> <end frequency value>
The end frequency value must not be less than the start frequency value, and both must be greater than zero. The whole sweep must include at least one point. If a group delay (G suffix) is specified as an output, the frequency steps must be close enough together that the phase of that output changes smoothly from one frequency to the next. Calculate group delay by subtracting the phases of successive

Comments

A <u>.PRINT (print)</u> on page 91, <u>.PLOT (plot)</u> on page 89, or <u>.PROBE (Probe)</u> on page 93 command must be used to get the results of the AC sweep analysis.

AC analysis is a linear analysis. The simulator calculates the frequency response by linearizing the circuit around the bias point.

All independent voltage and current sources that have AC values are inputs to the circuit. During AC analysis, the only independent sources that have nonzero amplitudes are those using AC specifications. The SIN specification does not count, as it is used only during transient analysis.

To analyze nonlinear functions such as mixers, frequency doublers, and AGC, use .TRAN (transient analysis).

Commands

.ALIASES, .ENDALIASES (aliases and endaliases)

Purpose

The Alias commands set up equivalences between node names and pin names, so that traces in the Probe display can be identified by naming a device and pin instead of a node. They are also used to associate a net name with a node name.

General form

Examples

The first alias definition shown in the example allows the name RBIAS to be used as an alias for R_RBIAS, and it relates pin 1 of device R_RBIAS to node \$N_0001 and pin 2 to VDD.

The last alias definition equates net name OUT to node name \$N_0007.

.AUTOCONVERGE (Autoconvergence of simulations)

Purpose Users can suggest relaxed limits for various options that PSpice can

modify during a simulation to achieve convergence.

General form .AUTOCONVERGE coption 1>=<relaxed value> <option</pre>

2>=<relaxed value> ...<option n>=<relaxed value>

<restart=0>

Examples .autoconverge ITL1=1000 ITL2=1000 ITL4=1000 RELTOL=0.05

ABSTOL=1.0E-6 VNTOL=.001 PIVTOL=1.0E-10

Arguments and options

<option n>

can be any one or more of the options ITL1, ITL2, ITL4, RELTOL, ABSTOL, VNTOL, or PIVTOL. PSpice will modify the specified options to achieve convergence of simulations.

<relaxed value>

The relaxed limit for the option.

<restart=0>

Restarts simulation with relaxed value from T=0 when convergence is not achieved with relaxed value at the end of the current simulation run.

Comments The < relaxed value> must be more relaxed then the normal limit.

.CHKPT (Generate CheckPoints)

Purpose Save the state of a transient simulation at different moments as

CheckPoints. You can specify any of the CheckPoints as a restart point and rerun the simulation from that point using the .restart command.

General form .chkpt <CheckPoint_name> <time_interval_type>

<time_interval_value> [<time_interval_type>
<time_interval_value>][TSTEP <timestep>]

Examples .chkpt "D:/simdata/checkset1" SINT 1ms RINT 10min TP

2.5ms, 7.5ms

Arguments and options

<checkpoint_name>

Specifies the name of the CheckPoint.

time_interval_type

Can be any one of:

- SINT : Specifies simulation time interval
- RINT: Specifies real time interval
- TP: Specifies time points

time_interval_value

The time interval in seconds.

TSTEP < timestep>

Specifies the time step to be used, where:

 0 generates checkpoints closest to default time step of PSpice engine

and

1 generates checkpoints at user specified time points.

<RESTART=n>

where RESTART=0 means CheckPoint Restart is off and RESTART=1 means it is on. RESTART=1 is the default.

Commands

.DC (DC analysis)

Purpose The .DC command performs a linear, logarithmic, or nested

DC sweep analysis on the circuit. The DC sweep analysis calculates the circuit's bias point over a range of values for

<sweep variable name>.

Sweep type

The sweep can be linear, logarithmic, or a list of values.

| Parameter | Description | Meaning |
|-----------|---------------------|---|
| LIN | linear sweep | The sweep variable is swept linearly from the starting to the ending value. |
| OCT | sweep by octaves | Sweep by octaves. The sweep variable is swept logarithmically by octaves. |
| DEC | sweep by decades | Sweep by decades. The sweep variable is swept logarithmically by decades. |
| LIST | List of values | Use a list of values. |

Linear sweep

General form .DC [LIN] <sweep variable name>

+ <start value> <end value> <increment value>

+ [nested sweep specification]

Examples .DC VIN -.25 .25 .05

.DC LIN I2 5mA -2mA 0.1mA

.DC VCE 0V 10V .5V IB 0mA 1mA 50uA .DC RES RMOD(R) 0.9 1.1 .001

Arguments and options

<start value>

Can be greater or less than <end value>: that is, the sweep can go in either direction.

<increment value>

The step size. This value must be greater than zero.

Commands

Comments

The sweep variable is swept linearly from the starting to the ending value.

The keyword LIN is optional.

Logarithmic sweep

General form .DC <logarithmic sweep type> <sweep variable name>

+ <start value> <end value> <points value>

+ [nested sweep specification]

Examples

.DC DEC NPN QFAST(IS) 1E-18 1E-14 5

Arguments and options

<logarithmic sweep type>

Must be specified as either DEC (to sweep by decades) or OCT (to sweep by octaves).

<start value>

Must be positive and less than <end value>.

<points value>

The number of steps per octave or per decade in the sweep. This value must be an integer.

Comments

Either OCT or DEC must be specified for the <logarithmic sweep type>.

Commands

Nested sweep

General form .DC <sweep variable name> LIST <value>*

+[nested sweep specification]

Examples .DC TEMP LIST 0 20 27 50 80 100 PARAM Vsupply 7.5 15 .5

Arguments and options

<sweep variable name>

After the DC sweep is finished, the value associated with <sweep variable name> is set back to the value it had before the sweep started. The following items can be used as sweep variables in a DC sweep:

| Parameter | Description | Meaning |
|---------------------|---|--|
| Source | A name of an independent voltage or current source. | During the sweep, the source's voltage or current is set to the sweep value. |
| Model Parameter | A model type and model name followed by a model parameter name in parenthesis. | The parameter in the model is set to the sweep value. The following model parameters cannot be (usefully) swept: L and W for the MOSFET device (use LD and WD as a work around), and any temperature parameters, such as TC1 and TC2 for the resistor. |
| Temperature | Use the keyword TEMP for <sweep na<br="" variable="">me>.</sweep> | • |
| Global Parameter | Use the keyword PARAM, followed by the parameter name, for <sweep name="" variable="">.</sweep> | During the sweep, the global parameter's value is set to the sweep value and all expressions are reevaluated. |

Commands

Comments

For a nested sweep, a second sweep variable, sweep type, start, end, and increment values can be placed after the first sweep. In the nested sweep example, the first sweep is the inner loop: the entire first sweep is performed for each value of the second sweep.

When using a list of values, there are no start and end values. Instead, the numbers that follow the keyword LIST are the values that the sweep variable is set to.

The rules for the values in the second sweep are the same as for the first. The second sweep generates an entire <u>.PRINT (print)</u> on page 91 table or <u>.PLOT (plot)</u> on page 89 plot for each value of the sweep. Probe displays nested sweeps as a family of curves.

.DISTRIBUTION (user-defined distribution)

Purpose

The .DISTRIBUTION command defines a user distribution for tolerances, and is only used with Monte Carlo and sensitivity/worst-case analyses. The curve described by a .DISTRIBUTION command controls the relative probability distribution of random numbers generated by PSpice to calculate model parameter deviations.

General form

```
DISTRIBUTION <name> (<deviation> <probability>) *
```

Examples

```
.DISTRIBUTION bi_modal (-1,1) (-.5,1) (-.5,0) (.5,0) + (.5,1) (1,1)
```

.DISTRIBUTION triangular (-1,0) (0,1) (1,0)

Arguments and options

```
(<deviation> <probability>)
```

Defines the distribution curve by pairs, or corner points, in a piecewise linear fashion. You can specify up to 100 value pairs.

```
<deviation>
```

Must be in the range (-1,+1), which matches the range of the random number generator. No < deviation > can be less than the previous < deviation > in the list, although it can repeat the previous value.

```
obability>
```

Represents a relative probability, and must be positive or zero.

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Comments

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Commands

Deriving updated parameter values

The updated value of a parameter is derived from a combination of a random number, the distribution, and the tolerance specified. This method permits distributions which have different excursions in the positive and negative directions. It also allows the use of one distribution even if the tolerances of the components are different so long as the general shape of the distributions are the same.

- **1.** Generate a <temporary random number> in the range (0, 1).
- 2. Normalize the area under the specified distribution.
- **3.** Set the <final random number> to the point where the area under the normalized distribution equals the <temporary random number>.
- **4.** Multiply this <final random number> by the specified tolerance.

Usage example

To illustrate, assume there is a 1.0 μ fd capacitor that has a variation of -50% to +25%, and another that has tolerances of -10% to +5%. Note that both capacitors' tolerances are in the same general shape, i.e., both have negative excursions twice as large as their positive excursions.

```
.distribution cdistrib (-1,1) (.5, 1) (.5, 0) (1, 0)
c1 1 0 cmod 11u
c2 1 0 cmod2 1u
.model cmod1 cap (c=1 dev/cdistrib 50%)
.model cmod2 cap (c=1 dev/cdistrib 10%)
```

The steps taken for this example are as follows:

- 1. Generate a <temporary random value> of 0.3.
- **2.** Normalize the area under the cdistrib distribution (1.5) to 1.0.
- **3.** The <final random number> is therefore -0.55 (the point where the normalized area equals 0.3).
- **4.** For c1, this -0.55 is then scaled by 50%, resulting in -0.275; for c2, it is scaled by 10%, resulting in -0.055.

Note: Separate random numbers are generated for each parameter that has a tolerance unless a tracking number is specified.

Commands

.DMILIB (library file)

Purpose The . DMILIB command provides the path to an existing DMI model. The

DMI models are compiled PSpice models in the form of a dynamic linked

library (*.dll file on Windows, *.so file on Linux).

General form .DMILIB <file_name> | <folder_name>

Examples .DMILIB mymodel.dll .DMILIB c:\mymodels

Arguments and options

<file_name>

Any character string that is a valid file name for the computer system.

This implies that the simulator will load the DMI .dll of the specified name. If the absolute location of the .dll file is not specified, the .dll file will be picked up from the system *Path*.

```
<folder_name>
```

Any character string that is a valid folder name for the computer system.

This implies that the simulator will load all available DMI . dll files in this folder.

Commands

Comments

DMI devices (Y devices) point to a compiled model dll. This dll can be specified using .DMILIB, or in the DMI device statement directly (old usage).

For the syntax of the DMI device statement, see <u>Analog Device Model Interface (DMI)</u>.

Example:

```
.DMILIB linear.dll
Y1 N1 N2 CMI dmimodel1
```

Where:

- Y1 is the device name
- N1 and N2 are its terminals
- CMI is the mandatory keyword used with Y devices
- linear.dll is the name of the DMI model dll
- dmimodel1 is the model, which will be picked up by PSpice from linear.dll

In this example, the simulator first loads the linear.dll file, and then looks for dmimodell in its loaded dlls.

Old usage:

```
Y1 N1 N2 DMI linear.dll dmimodel1
```

The advantage of using the <code>.DMILIB</code> statement is that you can use the DMI device instance statements without hard-coding the <code>.dll</code> file name in them.

For moving from one platform to another, only the .DMILIB statement needs to be modified, rest of the netlist can be simulated as it is.

Commands

.END (end of circuit)

Purpose

The .END command marks the end of the circuit. All the data and every other command must come before it. When the .END command is reached, PSpice does all the specified analyses on the circuit.

General form

.END

Examples

```
* 1st circuit in file
... circuit definition
.END
* 2nd circuit in file
... circuit definition
.END
```

Comments

There can be more than one circuit in an input file. Each circuit is marked by an .END command. PSpice processes all the analyses for each circuit before going on to the next one.

Everything is reset at the beginning of each circuit. Having several circuits in one file gives the same results as having them in separate files and running each one separately. However, all the simulation results go into one . OUT file and one . DAT file. This is a convenient way to arrange a set of runs for overnight operation.

Note: The last statement in an input file must be an .END command.

Commands

.ENDS (end subcircuit)

Purpose The .ENDS command marks the end of a subcircuit definition (started by

a .SUBCKT (subcircuit) statement.

General form .ENDS [subcircuit name]

Examples .ENDS

.ENDS circuit_name

Comments It is a good practice to repeat the subcircuit name though this is not

required.

For a detailed explanation see .SUBCKT (subcircuit) on page 112.

Commands

.EXTERNAL (external port)

External ports are provided as a means of identifying and **Purpose**

> distinguishing those nets representing the outermost (or peripheral), connections to the circuit being simulated. The external port statement .EXTERNAL applies only to nodes that have digital devices attached to

them.

General form .EXTERNAL <attribute> <node-name>*

.EXTERNAL INPUT Data1, Data2, Data3 **Examples**

.EXTERNAL OUTPUT P1
.EXTERNAL BIDIRECTIONAL BPort1 BPort2 BPort3

Arguments and options

<attribute>

One of the keywords INPUT, OUTPUT, or BIDIRECTIONAL, describing the usage of the port.

<node name>

One or more valid PSpice A/D node names.

Comments

When a node is included in a .EXTERNAL statement it is identified as a primary observation point. For example, if you are modeling and simulating a PCB-level description, you could place an .EXTERNAL (or its symbol counterparts) on the edge pin nets to describe the pin as the external interface point of the network.

PSpice recognizes the nets marked as .EXTERNAL when reporting any sort of timing violation. When a timing violation occurs, PSpice analyzes the conditions that would permit the effects of such a condition to propagate through the circuit. If, during this analysis, a net marked external is encountered. PSpice reports the condition as a Persistent Hazard, signifying that it has a potential effect on the externally visible behavior of the circuit.

Commands

.FOUR (Fourier analysis)

Purpose Fourier analysis decomposes the results of a transient analysis into

Fourier components.

General form .FOUR <frequency value> [no. harmonics value] <output

variable>

Examples .FOUR 10kHz V(5) V(6,7) I(VSENS3)

.FOUR 60Hz 20 V[17]

.FOUR 10kHz V([OUT1],[OUT2])
.FOUR {10G * 3} 20 V(10) V(3)

Arguments and options

<output variable>

An output variable of the same form as in a <u>.PRINT (print)</u> command or <u>.PLOT (plot)</u> command for a transient analysis.

<frequency value>

The fundamental frequency. Not all of the transient results are used, only the interval from the end, back to $1/\langle frequency \ value \rangle$ before the end is used. This means that the transient analysis must be at least $1/\langle frequency \ value \rangle$ seconds long.

Comments

The analysis results are obtained by performing a Fourier integral on the results from a transient analysis. The analysis must be supplied with specified output variables using evenly spaced time points. The time interval used is *<pri>print step value>* in the .TRAN (transient analysis) command, or 1% of the *<fi>final time value>* (TSTOP) if smaller, and a 2^{nd} -order polynomial interpolation is used to calculate the output value used in the integration. The DC component, the fundamental, and the 2^{nd} through 9^{th} harmonics of the selected voltages and currents are calculated by default, although more harmonics can be specified.

A .FOUR command requires a .TRAN command, but Fourier analysis does not require .PRINT, .PLOT, or <u>.PROBE (Probe)</u> commands. The tabulated results are written to the output file (.out) as the transient analysis is completed.

Note: The results of the .FOUR command are only available in the output file. They cannot be viewed in Probe.

Note: Expressions and double value are supported in .FOUR command for <frequency value>.

Commands

.FUNC (function)

Purpose The .FUNC command defines functions used in expressions.

Besides their obvious flexibility, they are useful for where there are

several similar sub expressions in a circuit file.

General form

```
.FUNC <name> ([arg]*) \{ <body> \}
```

Examples

```
.FUNC E(x) {exp(x)}
.FUNC DECAY(CNST) {E(-CNST*TIME)}
.FUNC TRIWAV(x) {ACOS(COS(x))/3.14159}
.FUNC MIN3(A,B,C) {MIN(A,MIN(B,C))}
```

Arguments and options

```
. FUNC
```

Does not have to precede the first use of the function name. Functions cannot be redefined and the function name must not be the same as any of the predefined functions (e.g., SIN and SQRT). See Numeric expression conventions for a list of valid expressions.

These arguments cannot be node names.

```
<body>
```

Refers to other (previously defined) functions; the second example, DECAY, uses the first example, E.

```
[arg]
```

Specifies up to 10 arguments in a definition. The number of arguments in the use of a function must agree with the number in the definition. Functions can be defined as having no arguments, but the parentheses are still required. Parameters, TIME, other functions, and the Laplace variable s are allowed in the body of function definitions.

Commands

Comments

The < body> of a defined function is handled in the same way as any math expression; it is enclosed in curly braces $\{\}$. Previous versions of PSpice did not require this, so for compatibility the < body> can be read without braces, but a warning is generated.

Note: Creating a file of frequently used .FUNC definitions and accessing them using an .INC command near the beginning of the circuit file can be helpful. .FUNC commands can also be defined in subcircuits. In those cases they only have local scope.

Note: Currents or Voltages from the circuit should not be used in .FUNC command. Model such dependencies using behavioral sources (EFGH devices).

Commands

IC (initial bias point condition)

Purpose

The .IC command sets initial conditions for both small-signal and transient bias points. Initial conditions can be given for some or all of the circuit's nodes.

.IC sets the initial conditions for the bias point only. It does not affect a .DC (DC analysis) sweep.

General form

```
.IC < V(<node> [,<node>]) =<value> >*
.IC <I(<inductor>) =<value>>*
```

Examples

```
.IC V(2)=3.4 V(102)=0 V(3)=-1V I(L1)=2uAmp
.IC V(InPlus,InMinus)=1e-3 V(100,133)=5.0V
```

Arguments and options

```
<value>
```

A voltage assigned to < node> (or a current assigned to an inductor) for the duration of the bias point calculation.

Comments

The voltage between two nodes and the current through an inductor can be specified. During bias calculations, PSpice clamps the voltages to specified values by attaching a voltage source with a 0.002 ohm series resistor between the specified nodes. After the bias point has been calculated and the transient analysis started, the node is released.

If the circuit contains both the .IC command and .NODESET (set approximate node voltage for bias point) command for the same node or inductor, the .NODESET command is ignored (.IC overrides .NODESET).

Refer to your *PSpice User Guide* for more information on setting initial conditions.

Note: An .IC command that imposes nonzero voltages on inductors cannot work properly, since inductors are assumed to be short circuits for bias point calculations. However, inductor currents can be initialized.

Commands

.INC (include file)

Purpose The .INC command inserts the contents of another file.

General form .INC <file name>

Examples .INC "SETUP.CIR"

.INC "C:\LIB\VCO.CIR"

Arguments and options

<file name>

Any character string that is a valid file name for your computer system.

Comments

Including a file is the same as bringing the file's text into the circuit file. Everything in the included file is actually read in. The comments of the included file are then treated just as if they were found in the parent file.

Included files can contain any valid PSpice statements, with the following conditions:

- The included files should not contain title lines unless they are commented.
- Included files can be nested up to 4 levels.

Note: Every model and subcircuit definition, even if not needed, takes up memory.

Commands

.LIB (library file)

Purpose The .LIB command references a model or subcircuit library in another

file.

General form .LIB [file name]

Examples .LIB

.LIB linear.lib

.LIB "C:\lib\bipolar.lib"

Arguments and options

[file_name]

Any character string that is a valid file name for the computer system.

Comments

Library files can contain any combination of the following:

- comments
- .MODEL (model definition) commands
- subcircuit definitions (including the <u>.SUBCKT (subcircuit)</u> command)
- <u>.PARAM (parameter)</u> commands
- .FUNC (function) commands
- LIB commands

No other statements are allowed. For further discussion of library files, refer to your *PSpice User Guide*.

If [file_name] is left off, all references point to the master library file, nom.lib.

When any library is modified, PSpice creates an index file based on the first use of the library. The index file is organized so that PSpice can find a particular .MODEL or <u>.SUBCKT</u> (subcircuit) quickly, despite the size of the library file.

Note: The index files have to be regenerated each time the library is changed. Because of this, it is advantageous to configure separately any frequently changed libraries.

Nom.lib normally contains references to all parts in the PSpice Standard Model Library. You can edit nom.lib to include your custom model references.

Commands

.LOADBIAS (load bias point file)

Purpose The .LOADBIAS command loads the contents of a bias point file. It is

helpful in setting initial bias conditions for subsequent simulations. However, the use of .LOADBIAS does not guarantee convergence.

General form .LOADBIAS <file name>

Examples .LOADBIAS "SAVETRAN.NOD"

.LOADBIAS "C:\PROJECT\INIT.FIL"

Arguments and options

<file name>

Any character string which is a valid computer system file name, but it must be enclosed in quotation marks.

Comments

Normally, the bias point file is produced by a previous circuit simulation using the <u>.SAVEBIAS</u> (save bias point to file) command.

The bias point file is a text file that contains one or more comment lines and a .NODESET (set approximate node voltage for bias point) command setting the bias point voltage or inductor current values.

If a fixed value for a bias point needs to be set, this file can be edited to replace the .NODESET command with an <u>.IC (initial bias point condition)</u> command.

Note: Any nodes mentioned in the loaded file that are not present in the circuit are ignored, and a warning message will be generated.

To echo the .LOADBIAS file contents to the output file, use the EXPAND option on the <u>.OPTIONS (analysis options)</u> command.

.MC (Monte Carlo analysis)

Purpose

The .MC command causes a Monte Carlo (statistical) analysis of the circuit and causes PSpice to perform multiple runs of the selected analysis (DC, AC, or transient).

General form

Examples

.MC 10 TRAN V(5) YMAX

.MC 50 DC IC(Q7) YMAX LIST

.MC 20 AC VP(13,5) YMAX LIST OUTPUT ALL
.MC 10 TRAN V([OUT1],[OUT2]) YMAX SEED=9321

Arguments and options

<#runs value>

In PSpice A/D, the number of runs are limited to 10000. To modify the limit, change MCRUNLIMIT under PSPICE section in PSpice.ini.

<analysis>

Specifies at least one analysis type: <u>.DC (DC analysis)</u>, <u>Table</u> on page 30, or <u>.TRAN (transient analysis)</u>. This analysis is repeated in subsequent passes. All analyses that the circuit contains are performed during the nominal pass. Only the selected analysis is performed during subsequent passes.

<output variable>

Identical in format to that of a <u>.PRINT (print)</u> output variable.

<function>

Specifies the operation to be performed on the values of <output variable> to reduce these to a single value. This value is the basis for the comparisons between the nominal and subsequent runs. The <function> can be any one of the following:

| Function | Definition |
|----------|--|
| YMAX | Find the absolute value of the greatest difference in each |
| | waveform from the nominal run. |

PSpice A/D Reference Guide Commands

| Function | Definition | |
|-----------------------------|---|--|
| MAX | Find the maximum value of each waveform. | |
| MIN | Find the minimum value of each waveform. | |
| RISE_EDGE(<value>)</value> | Find the first occurrence of the waveform crossing above the threshold $< value >$. The waveform must have one or more points at or below $< value >$ followed by one above; the output value listed is the first point that the waveform increases above $< value >$. | |
| FALL_EDGE(<value>)</value> | Find the first occurrence of the waveform crossing below the threshold $\langle value \rangle$. The waveform must have one or more points at or above $\langle value \rangle$ followed by one below; the output value listed is where the waveform decreases below $\langle value \rangle$. | |

Commands

Note: < function > and all [option]s (except for < output type >) have no effect on the Probe data that is saved from the simulation. They are only applicable to the output file.

[option] *

Can include zero or more of the following options:

| Option | Definition | Example |
|---|--|--|
| LIST | Lists, at the beginning of each run, the model parameter values actually used for each component during that run. | |
| OUTPUT <output type=""></output> | Asks for an output from subsequent runs, after the nominal (first) run. The output from any run is governed by a .PRINT, .PLOT, and .PROBE command in the file. If OUTPUT is omitted, then only the nominal run produces output. | ALL forces all output to be generated (including the nominal run). |
| | | |
| | | $ \begin{array}{ll} {\tt EVERY} & <{\tt N}{\gt} \ \ \mbox{generates output} \\ \mbox{every } n^{th} \ \mbox{run}. \end{array} $ |
| | The <output type=""> is one of the ones shown in the examples to the right.</output> | RUNS <n>* does analysis and generates output only for the listed runs. Up to 25 values can be specified in the list.</n> |
| RANGE ¹ (<low value="">, <high value="">)</high></low> | Restricts the range over which <function> is evaluated. An asterisk (*) can be used in place of a <value> to show for all values.</value></function> | YMAX RANGE (*,.5) YMAX is evaluated for values of the sweep variable (e.g., time and frequency) of .5 or less. |
| | | MAX RANGE (-1, *) The maximum of the output variable is found for values of the sweep variable of -1 or more. |

1. If RANGE is omitted, then <function> is evaluated over the whole sweep range. This is equivalent to RANGE(*,*).

Commands

[SEED=value]

Defines the seed for the random number generator within the Monte Carlo analysis (*The Art of Computer Programming*, Donald Knuth, vol. 2, pg. 171, "subtractive method").

<value>

Must be an integer ranging from 1 to 32,767. If the seed value is not set, its default value is 17,533.

Note: For almost all analyses, the default seed value is adequate to achieve a constant set of results. The seed value can be modified within the integer value as required.

Comments

The first run uses nominal values of all components. Subsequent runs use variations on model parameters as specified by the DEV and LOT tolerances on each <u>.MODEL (model definition)</u> parameter.

The other specifications on the .MC command control the output generated by the Monte Carlo analysis.

For more information on Monte Carlo analysis, refer to your *PSpice User Guide*.

Commands

.MODEL (model definition)

Purpose The .MODEL command defines a set of device parameters that can be referenced by devices in the circuit.

Arguments and options

<model name>

The model name which is used to reference a particular model.

```
<reference model name>
```

The model types of the current model and the AKO (A Kind Of) reference model must be the same. The value of each parameter of the referenced model is used unless overridden by the current model, e.g., for QDR2 in the last example, the value of IS derives from QDRIV, but the values of BF and IKF come from the current definition. Parameter values or formulas are transferred, but not the tolerance specification. The referenced model can be in the main circuit file, accessed through a .INC command, or it can be in a library file; see .LIB (library file).

```
<model type>
```

Must be one of the types outlined in the table that follows.

Devices can only reference models of a corresponding type; for example:

- A JFET can reference a model of types NJF or PJF, but not of type NPN.
- There can be more than one model of the same type in a circuit, although they must have different names.

Commands

Following the < model type> is a list of parameter values enclosed by parentheses. None, any, or all of the parameters can be assigned values. Default values are used for all unassigned parameters. The lists of parameter names, meanings, and default values are found in the individual device descriptions.

PSpice A/D Reference Guide Commands

| Model type | Instance name | Type of device |
|------------|---------------|--|
| CAP | Cxxx | capacitor |
| CORE | Kxxx | nonlinear, magnetic core (transformer) |
| D | Dxxx | diode |
| DINPUT | Nxxx | digital input device (receive from digital) |
| DOUTPUT | Oxxx | digital output device (transmit to digital) |
| GASFET | Bxxx | N-channel GaAs MESFET |
| IND | Lxxx | inductor |
| ISWITCH | Wxxx | current-controlled switch |
| LPNP | Qxxx | lateral PNP bipolar transistor |
| NIGBT | Zxxx | N-channel insulated gate bipolar transistor (IGBT) |
| NJF | Jxxx | N-channel junction FET |
| NMOS | Mxxx | N-channel MOSFET |
| NPN | Qxxx | NPN bipolar transistor |
| PJF | Jxxx | P-channel junction FET |
| PMOS | Mxxx | P-channel MOSFET |
| PNP | Qxxx | PNP bipolar transistor |
| RES | Rxxx | resistor |
| TRN | Txxx | lossy transmission line |
| UADC | Uxxx | multi-bit analog-to-digital converter |
| UDAC | Uxxx | multi-bit digital-to-analog converter |
| UDLY | Uxxx | digital delay line |
| UEFF | Uxxx | edge-triggered flip-flop |
| UGATE | Uxxx | standard gate |
| UGFF | Uxxx | gated flip-flop |
| UIO | Uxxx | digital I/O model |
| UTGATE | Uxxx | tristate gate |
| | | |

PSpice A/D Reference Guide Commands

| Model type | Instance name | Type of device |
|------------|---------------|---------------------------|
| VSWITCH | Sxxx | voltage-controlled switch |

Commands

[tolerance specification]

Appended to each parameter, using the format:

```
[DEV [track&dist] <value>[%]] [LOT [track&dist] <value>[%]]
```

to specify an individual device (DEV) and the device lot (LOT) parameter value deviations. The tolerance specification is used by the .MC (Monte Carlo analysis) analysis only.

The LOT tolerance requires that all devices that refer to the same model use the same adjustments to the model parameter. DEV tolerances are independent, that is each device varies independently. The % shows a relative (percentage) tolerance. If it is omitted, <value> is in the same units as the parameter itself.

```
[track & dist]
```

Specifies the tracking and non-default distribution, using the format:

```
[/<lot #>][/<distribution name>]
```

These specifications must immediately follow the keywords DEV and LOT (without spaces) and are separated by /.

```
<1ot #>
```

Specifies which of ten random number generators, numbered 0 through 9, are used to calculate parameter value deviations. This allows deviations to be correlated between parameters in the same model, as well as between models. The generators for DEV and LOT tolerances are distinct: there are ten generators for DEV tracking and ten generators for LOT tracking. Tolerances without <10t #> are assigned individually generated random numbers.

```
<distribution name>
```

The distribution name is one of the following. The default distribution can be set by using the DISTRIBUTION parameter of the .OPTIONS (analysis options) command.

Note: Distribution defined at instance-level has more priority than the distribution defined at global-level.

Commands

| Distribution name | Function | | |
|--|--|--|--|
| UNIFORM | Generates uniformly distributed deviations over the range $\pm \langle value \rangle$. | | |
| GAUSS | Generates deviations using a Gaussian distribution over the range $\pm 3\sigma$ and $\langle value \rangle$ specifies the $\pm 1\sigma$ deviation (i.e., this generates deviations greater than $\pm \langle value \rangle$). | | |
| <user< td=""><td colspan="2">Generates deviations using a user-defined distribution and</td></user<> | Generates deviations using a user-defined distribution and | | |
| name> | $<$ $value>$ specifies the ± 1 deviation in the user definition; see the .DISTRIBUTION (user-defined distribution). | | |
| GAUSS_USER | Generates deviations with default distribution of $\pm 1\sigma$. The default distribution can be changed using the <code>.OPTIONS</code> command as follows: | | |
| | .OPTIONS DISTRIBUTION GAUSS_USER | | |
| | .OPTIONS USER_SIGMA_VAL= <value></value> | | |
| | Where, <value> can be any integer from 1 to 9.</value> | | |

Comments

The examples are for the .MODEL parameter. The last example uses the AKO syntax to reference the parameters of the model QDRIV in the third example.

For more information, refer to your *PSpice User Guide*.

Commands

Parameters for Setting Temperature

Some passive and semiconductor devices (C, L, R, B, D, J, M, and Q) have two levels of temperature attributes that can be customized on a model-by-model basis.

First, the temperature at which the model parameters were measured can be defined by using one of the following model parameter formats in the .MODEL command line:

```
T_MEASURED = teral value>
T_MEASURED = { <parameter> }
```

This overrides the nominal TNOM value which is set in the <u>.OPTIONS (analysis options)</u> command line (default = 27°C). All other parameters listed in the .MODEL command are assumed to have been measured at T_MEASURED.

Note: If you define TNOM specifically as a model parameter, then TNOM is treated exactly as T_MEASURED. There is no difference in the way these are treated. If you use.OPTIONS TNOM=<value>, this sets the nominal temperature of all models in the design. However, using .OPTIONS will not override temperature of any model, where TNOM or T_MEASURED are specified as model parameters.

In addition to the measured model parameter temperature, current device temperatures can be customized to override the circuit's global temperature specification defined by the .<u>TEMP (temperature)</u> command line (or equivalent .STEP TEMP or .DC TEMP). There are three forms, as described below.

Table 1-1 Model parameters for device temperature

| Description | .MODEL format | Parameter format | Referencing device temperature |
|-----------------------------------|------------------|-------------------------------|--|
| absolute temperature | standard | T_ABS=< <i>value</i> > | T_ABS |
| relative to current temperature | standard | T_REL_GLOBAL=< <i>value</i> > | global temperature + T_REL_GLOBAL |
| relative to AKO model temperature | AKO | T_REL_LOCAL=< <i>value</i> > | T_ABS(<i>AKO Model</i>) + T_REL_LOCAL |

For all formats, <value> can be a literal value or a parameter of the form {<parameter name>}. A maximum of one device temperature customization can coexist using the T_MEASURED customization. For example,

```
.MODEL PNP NEW PNP ( T ABS=35 T MEASURED=0 BF=90 )
```

Commands

defines a new model PNP_NEW, where BF was measured at 0°C. Any bipolar transistor referencing this model has an absolute device temperature of 35°C.

Examples

One

This example demonstrates device temperatures set relative to the global temperature of the circuit:

```
.TEMP 10 30 40
.MODEL PNP NEW PNP( T REL GLOBAL=-5 BF=90 )
```

This produces three PSpice runs where global temperature changes from 10° to 30° to 40°C, respectively, and any bipolar transistor that references the PNP_NEW model has a device temperature of 5°, 25°, or 35°C, respectively.

Two

This example sets the device temperature relative to a referenced AKO model:

```
.MODEL PNP_NEW AKO: PNP_OLD PNP T_REL_LOCAL=10
```

Any bipolar transistor referencing the PNP_NEW model has a device temperature of 30°C.

Special Considerations

There are a few special considerations when using these temperature parameters:

- If the technique for current device temperature is using the value relative to an AKO model's absolute temperature (T_ABS), and the AKO referenced model does not specify T_ABS, then the T_REL_LOCAL specification is ignored and the standard global temperature specification is used.
- These temperature parameters cannot be used with the DEV and LOT model parameter tolerance feature.
- A DC sweep analysis can be performed on these parameters so long as the temperature parameter assignment is to a variable parameter. For example:

```
.PARAM PTEMP 27
.MODEL PNP_NEW PNP ( T_ABS={PTEMP} )
.DC PARAM PTEMP 27 35 1
```

Commands

This method produces a single DC sweep in PSpice where any bipolar transistor referencing the PNP_NEW model has a device temperature which is swept from 27°C to 35°C in 1°C increments.

A similar effect can be obtained by performing a parametric analysis. For instance:

```
.PARAM PTEMP 27
.MODEL PNP_NEW PNP( T_ABS={PTEMP})
.STEP PARAM PTEMP 27 35 1
```

This method produces nine PSpice runs where the PNP_NEW model temperature steps from 27°C to 35°C in increments of 1°C, one step per run.

- The effect of a temperature parameter is evaluated once prior to the bias point calculation, unless parameters are swept by means of a .DC PARAM or .STEP PARAM analysis described above. In these cases, the temperature parameter's effect is reevaluated once for each value of the swept variable.
- If you want to exclude some components or models from the temperature sweep analysis, then you can specify the T_ABS parameter with the desired temperature value. This will ensure that these models remain fixed at this temperature and the rest of the design gets simulated as per the temperature sweep analysis.

Commands

.NODESET (set approximate node voltage for bias point)

Purpose

The .NODESET command helps calculate the bias point by providing an initial best guess for some node voltages and/or inductor currents. Some or all of the circuit's node voltages and inductor currents can be given the initial guess, and in addition, the voltage between two nodes can be specified.

General form

```
.NODESET < V(<node> [,<node>]) = <value> >*
.NODESET <I(<inductor>) = <value>>
```

Examples

```
.NODESET V(2)=3.4 V(102)=0 V(3)=-1V I(L1)=2uAmp.NODESET V(InPlus,InMinus)=1e-3 V(100,133)=5.0V
```

Comments

This command is effective for the bias point (both small-signal and transient bias points) and for the first step of the DC sweep. It has no effect during the rest of the DC sweep, nor during a transient analysis.

Unlike the <u>.IC (initial bias point condition)</u> command, .NODESET provides only an initial guess for some initial values. It does not clamp those nodes to the specified voltages. However, by providing an initial guess, .NODESET can be used to break the tie in, for instance, a flip-flop, and make it come up in a required state.

If both the .IC command and .NODESET command are present, the .NODESET command is ignored for the bias point calculations (.IC overrides .NODESET).

Commands

.NOISE (noise analysis)

Purpose The .NOISE command performs a noise analysis of the circuit.

General form .NOISE V(<node> [,<node>]) <name> [interval value]

Examples .NOISE V(5) VIN

.NOISE V(101) VSRC 20 .NOISE V(4,5) ISRC .NOISE V([OUT1]) V1 .NOISE V([OUT1],[OUT2]) V1

Note: For the node names starting with alphabets, square brackets should be used as in the last example.

Arguments and options

```
V(<node> [,<node>])
```

Output voltage. It has a form such as V(5), which is the voltage at the output node five, or a form such as V(4,5), which is the output voltage between two nodes four and five.

```
<name>
```

The name of an independent voltage or current source where the equivalent input noise is calculated. The < name > is not itself a noise generator, but only a place where the equivalent input noise is calculated.

```
[interval value]
```

Integer that specifies how often the detailed noise analysis data is written to the output file.

Commands

Comments

A noise analysis is performed in conjunction with an AC sweep analysis and requires an <u>.AC (AC analysis)</u> command. When .NOISE is used, noise data is recorded in the Probe .DAT file for each frequency in the AC sweep.

The simulator computes:

- Device noise for every resistor and semiconductor in the circuit (propagated to a specified output node)
- Total input and output noise

At each frequency, each noise generator's contribution is calculated and propagated to the output node. At that point, all the propagated noise values are RMS-summed to calculate the total output noise. The gain from the input source to the output voltage, the total output noise, and the equivalent input noise are all calculated.

For more information, refer to the AC Analyses chapter of your *PSpice User Guide*.

The output noise units are always volt/hertz^{1/2}.

Every nth frequency, where n is the print interval, a detailed table is printed showing the individual contributions of all the circuit's noise generators to the total noise. These values are the noise amounts propagated to the output node, not the noise amounts at each generator. If $[interval\ value]$ is not present, then no detailed table is printed.

The detailed table is printed while the analysis is being performed and does not need a <u>.PRINT (print)</u> command or a <u>.PLOT (plot)</u> command. The output noise and equivalent input noise can be printed in the output by using a .PRINT command or a .PLOT command.

68

.RESTART (Restart simulation from a CheckPoint)

Purpose Restarts a simulation from specified checkpoint instead of rerunning a

simulation from the start. CheckPoints are defined using the .CHKPT

command.

General form .restart <heckPoint name> <state number> [0/1]

Examples .restart "D:/simdata/checkset1" state20

Arguments and options

<checkPoint_name>

Name of the CheckPoint to be used.

<state_number>

The specific state from which to restart the simulation.

<0/1>

Specifies the time step to be used, where:

- 0 generates checkpoints closest to default time step of PSpice engine
- 1 generates checkpoints at user specified time points.

Commands

.OP (bias point)

Purpose The .OP command causes detailed information about the bias point to be

printed.

dissipation.

General form .OP

Examples .OP

This command does not write output to the Probe data file. The bias point is calculated regardless of whether there is a .OP command. Without the .OP command, the only information about the bias point in the output is a list of the node voltages, voltage source currents, and total power

Using a .OP command can cause the small-signal (linearized) parameters of all the nonlinear controlled sources and all the semiconductor devices to be printed in the output file.

The .OP command controls the output for the regular bias point only. The .TRAN (transient analysis) command controls the output for the transient analysis bias point.

Note: If no other analysis is performed, then no Probe data file is created.

Commands

.OPTIONS (analysis options)

Purpose The .OPTIONS command is used to set all the options, limits, and control

parameters for the simulator.

General form .OPTIONS [option name]* [<option name>=<value>]*

Examples .OPTIONS NOECHO NOMOD DEFL=12u DEFW=8u DEFAD=150p

+ DEFAS=150p

.OPTIONS ACCT RELTOL=.01
.OPTIONS DISTRIBUTION=GAUSS
.OPTIONS DISTRIBUTION=USERDEF1

Comments The options can be listed in any order. There are two kinds of options:

those with values, and those without values. Options without values are

flags that are activated by simply listing the option name.

The .OPTIONS command is cumulative. That is, if there are two (or more) of the .OPTIONS command, the effect is the same as if all the options were listed together in one .OPTIONS command. If the same option is listed more than once, only its last value is used.

For SPICE options not available in PSpice, see <u>Differences between</u> PSpice and Berkeley SPICE2 on page 136.

Option to Report Top Noise Contributor

You can use an option, PRINT_NOISE_CONTRIBUTORS to specify the number of top noise contributors to be reported for Noise Analysis.

If the number of devices are less than the number of top noise contributors, noise contribution of all the devices are printed.

Example: .options print_noise_contributors=5 prints the top 5 noise contributors in Noise Analysis result.

If this option is not specified, by default, the top 5 contributors are printed.

Option to Vary Temperature in Single Run

You can use ENABLE_TIME_VARYING_TEMPERATURE option to vary temperature as a function of time in a run.

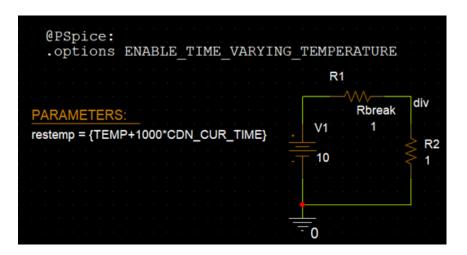
Commands

Syntax to use the option: .OPTIONS ENABLE_TIME_VARYING_TEMPERATURE

Model parameters such as T_ABS, T_REL_GLOBAL, and T_REL_LOCAL supports expression in the model definition for device temperatures.

In the expression, use CDN_CUR_TIME (alias of time) with temperature-dependent parameters of the components.

Let us take an example of a potential divider circuit as shown in the following figure:



In the model definition, define the following: R=1 TC1=0.05 TC2=5u T_ABS= {restemp}
where, restemp = {TEMP+1000*CDN_CUR_TIME}

```
.model Rbreak RES R=1 TC1=0.05 TC2=5u T_ABS={restemp}
```

To know more, refer to the Parameters for Setting Temperature section of this guide.

Enhanced Debugging of Convergence Error

Abnormal high or low values or floating point errors in complex circuits often lead to convergence errors. However, it is difficult to find the exact expression that causes the error.

You can use the EXPR_DEBUG option to include the expressions in the warning message that cause convergence errors.

Syntax to use the option: .OPTIONS EXPR_DEBUG

Commands

The following image shows a warning message (ORPSIM-16608) that lists the expression leading to the convergence error:

```
## Superior of the expression appears in context of device _U3X$MFX$MF.GMOS CONSTANT=27 CONSTANT=2450 CONSTANT=247.478 FUNC = {{([] - {Uth([]) + dVth + fpai66 - DIBL([]])}}}

ERROR(ORPSIM-1699) CONSTANT=2

ERROR(ORPSI
```

Flag Options

The default for any flag option is off or no (i.e., the opposite of specifying the option).

| Flag option | Meaning | |
|---------------|---|--|
| ACCT | Summary and accounting information is printed at the end of all the analyses (refer to your <i>PSpice User Guide</i> for further information on ACCT). | |
| ADVCONV | Enables all bias point convergence options such as PSEUDOTRAN, STEPGMIN, and source stepping algorithm. | |
| | The ADVCONV flag is ON by default. | |
| NOSTEPDEP | Suppresses stepping of dependent sources during source stepping. | |
| CONVAID | Generates .10P file for debugging purpose when convergence fails. | |
| DISABLENEGRES | Applies the absolute value of the resistor and displays a warning message for negative resistance. | |
| | For Analysis Type, Time Domain (Transient), DC Sweep, AC Sweep/Noise, and Bias Point, by default, the value of negative resistance is used as is. To change this behavior, use the flag, DISABLENEGRES. | |
| EXPAND | Lists devices created by subcircuit expansion and lists contents of the bias point file; see <u>.SAVEBIAS</u> (save bias point to file) and <u>.LOADBIAS</u> (load bias point file). | |

| Flag option, | Meaning, continued |
|------------------|---|
| ENABLENEGRESTEMP | Enables you to always use the computed negative resistor value of the resistor. |
| | During <i>Temperature (Sweep)</i> , when the resistor value gets computed to a negative value because of Temperature Coefficients (TCs), the GMIN value is used instead of the computed negative resistor value. This is the default behavior. To change this behavior, use the flag, ENABLENEGRESTEMP. |
| GMINSRC | Enables step GMIN inside source-stepping |
| IGNOREINDEXTIME | By default, PSpice always creates an index file if the time stamp of index is older than the corresponding library file. This option overrides that behavior. It is not recommended to use this flag. If you have to use this flag, ensure that you have updated the index file. |
| LIBRARY | Lists lines used from library files. |
| LIST | Lists a summary of the circuit elements (devices). |
| NOBIAS | Suppresses the printing of the bias point node voltages. |
| NODE | Lists a summary of the connections (node table). |
| NOECHO | Suppresses a listing of the input file(s). |
| NOGMINI | Specifies not to add GMIN across current sources. |

| Flag option, | Meaning, continued |
|---------------|---|
| NOICTRANSLATE | Suppresses the translation of initial conditions (IC attributes) specified on capacitors and inductors into .IC statements (IC pseudocomponents). This means that IC attributes are ignored if the keyword Skip Bias Point (SKIPBP) is not put at the end of the .TRAN statement. See .TRAN (transient analysis). |
| NOMOD | Suppresses listing of model parameters and temperature updated values. |
| NOOPITER | Switches off source stepping. |
| NOOUTMSG | Suppresses simulation error messages in output file. |
| NOPAGE | Suppresses paging and the banner for each major section of output. |
| NOPRBMSG | Suppresses simulation error messages in Probe data file. |
| NOSTEPSRC | Do not run source stepping algorithm for bias point convergence. |
| NOREUSE | Suppresses the automatic saving and restoring of bias point information between different temperatures, Monte Carlo runs, worst-case runs, DC Sweep and .STEP (parametric analysis). |
| | See also <u>.SAVEBIAS</u> (save bias point to file) and <u>.LOADBIAS</u> (load bias point file). |
| OPTS | Lists values for all options. |
| PREORDER | Uses preordering to reduce matrix fill-in |
| PREORDERMODE | Enables PREORDER before DC decomposition in sparse solver |
| PSEUDOTRAN | Uses pseudo-transient algorithm. |
| PSEUDOAUTO | When the flags ADVCONV and AutoConverge are set, pseudotransient algorithm is not run during auto-convergence. |
| | To run pseudo-transient algorithm during auto-convergence, set the PSEUDOAUTO option. Simulation may take significantly long time to complete if you set this option. |
| STEPGMIN | Enables GMIN stepping. This causes a GMIN stepping algorithm to be applied to circuits that fail to converge. GMIN stepping is applied first, and if that fails, the simulator falls back to supply stepping. |
| BRKDEPSRC | Sets automatic break-points for behavioral sources |
| TRANCONV | Enables alternate path search if transient simulation fails. |
| | |

Commands

| Flag option, | Meaning, continued |
|--------------|---|
| TRANCONV1 | Enables an internal continuation method to fix convergence failure during transient analysis. |

Option with a Double Value

The following option has a name as its value:

| Option | Meaning | Default |
|--------------|---|---------|
| DISTRIBUTION | default distribution for Monte Carlo deviations | UNIFORM |

Default distribution values

The default distribution is used for all of the deviations throughout the Monte Carlo analyses, unless specifically overridden for a particular tolerance. The default value for the default distribution is UNIFORM, but can also be set to GAUSS or to a user-defined ($<user\ name>$) distribution. If a user-defined distribution is selected (as illustrated in the last example under .OPTIONS (analysis options)), a .DISTRIBUTION (user-defined distribution) command must be included in the circuit file to define the user distribution for the tolerances. An example would be:

```
.DISTRIBUTION USERDEF1 (-1,1) (.5,1) (.5,0) (1,0) .OPTIONS DISTRIBUTION=USERDEF1
```

Options with a Name-value Pair

| Options | Description | Units | Default |
|---------------------|---|---------|-----------|
| ABSTOL ¹ | best accuracy of currents | amp | 1.0 pA |
| ВЈТСЈ | minimum value for BJT Base-collector zero- bias depletion capacitance (Cjc), Base-emitter zero-bias depletion capacitance (Cje), and zero-bias collector substrate capacitance (Cjs) | farad | 0 |
| CHGTOL | best accuracy of charges | coulomb | 0.01 pC |
| CPTIME ² | CPU time allowed for this run | sec | 0.0^{3} |

| Options | Description | Units | Default |
|---------------|--|--------------------|----------|
| CSHUNT | shunt capacitance added from all nodes of the design to GND. Recommended value is 1pF. For more details, see <u>CSHUNT</u> . | | 0 |
| DEFAD | MOSFET default drain area (AD). | meter ² | 0.0 |
| DEFAS | MOSFET default source area (AS). | meter ² | 0.0 |
| DEFL | MOSFET default length (L). | meter | 100.0 u |
| DEFW | MOSFET default width (W). | meter | 100.0 u |
| DIGFREQ | minimum digital time step is 1/DIGFREQ | hertz | 10.0 GHz |
| DIGDRVF | minimum drive resistance (Input/Output UIO type model, DRVH (high) and DRVL (low) values) | ohm | 2.0 |
| DIGDRVZ | maximum drive resistance (UIO type model, DRVH and DRVL values) | ohm | 20K |
| | Note: For ECL 100K devices (from the DIG_ECL.LIB library), DIGDRVZ should be set to higher than 100K to see the low-level output value at 0. For the default value of 20K, it will show up as Z. | | |
| DIGERRDEFAULT | default error limit per digital constraint device | - | 20.0 |
| DIGERRLIMIT | maximum digital error message limit | - | 03 |

| Options | Description | Units | Default |
|------------------------|---|-------|---------|
| DIGINITSTATE | sets initial state of all flip-flops and latches in circuit: 0=clear, 1=set, 2=X | - | 2.0 |
| | Note: When you set the initial state of a flip- flop or latch in the digital modeling application, this option is not honored. | | |
| | For example- If you instantiate a JK flip-flop from the <i>Modeling Application</i> panel, the flip-flop is initialized based on the <i>Initial Condition (IC)</i> parameter value set for the application model, instead of the DIGINITSTATE option configured from the <i>Simulation Settings</i> dialog box. | | |
| | Note: When you want to set the initial state, this option may not be honored for the default value of the <code>DIGDRVZ</code> option.For example, for ECL 100K devices (from the <code>DIG_ECL.LIB</code> library), <code>DIGDRVZ</code> needs to be set to higher than 100K to see the low-level output value at 0. | | |
| DIGIOLVL | default digital I/O level: 1-4; see UIO in .MODEL (model definition) on page 57 | - | 1.0 |
| DIGMNTYMX ⁴ | default delay selector: 1=min, 2-typical, 3=max, 4=min/max | - | 2.0 |
| DIGMNTYSCALE | scale factor used to derive minimum delays from typical delays | - | 0.4 |
| DIGOVRDRV | ratio of drive resistances required to allow one output to override another driving the same node | - | 3.0 |
| DIGTYMXSCALE | scale factor used to derive maximum delays from typical delays | - | 1.6 |
| DIODECJO | Minimum value for Diode junction capacitance | ohm | 0 |
| DIODERS | Minimum value for Diode ohmic resistance | ohm | 0 |

| Options | Description | Units | Default |
|-------------------|--|-------------------|------------------|
| DMFACTOR | Sets the relative factor for minimum delta. The value specifies the relative value by which the minimum time step size is changed. The value should be less than or equal to 1 and a factor of 10, such as .1, .001, or .0001. | - | 1 |
| GMIN ¹ | minimum conductance used for any branch | ohm ⁻¹ | 1.0E-12 |
| | Note: GMIN is added by default across some device nodes to aid in convergence. For details, see GMIN Usage in Simulation. | | |
| GMINSTEPS | the GMIN stepping size in integer (any positive value). Set to 0 for engine default. | - | Same as ITL1 |
| ITL1 | DC and bias point blind repeating limit (the first evaluation of the operating point of the system) | - | 150.0 |
| ITL2 | DC and bias point educated guess repeating limit (DC transfer curve iteration limit) | - | 20 |
| ITL4 ¹ | the limit at any repeating point in transient analysis | - | 10 |
| ITL5 ² | total repeating limit for all points for transient analysis (ITL5=0 means ITL5=infinity) | - | 0.0 ³ |
| ITL6 | the number of steps of the source stepping algorithm. Can have any positive integer value. Set to 0 for engine default. | - | Same as ITL1 |
| JFETCJ | minimum value for JFET gate-to-source capacitance (Cgs) and gate-to-drain capacitance (Cgd) | farad | 0 |
| LIMIT | the absolute voltage limit. The default, 0, specifies that there is no limit on data values. You can modify it to a large value, such as 1e12, to eliminate overflow errors, especially when using exponential sources. | - | 0 |
| | Note: This option is also used to limit the values of expressions. | | |

| Options | Description | Units | Default |
|------------------------|--|-------|------------------|
| LIMPTS ² | maximum points allowed for any print table or plot (LIMPTS=0 means LIMPTS=infinity) | - | 0.0 ³ |
| method | integration method (values can be either TRAPEZOIDAL or GEAR) | - | - |
| MINSIMPTS ⁵ | minimum number of time points used for a transient simulation | - | 50 |
| MOSCJ | minimum value for MOSFET gate-to-source overlap capacitance (Cgso), gate-to-drain overlap capacitance (Cgdo), zero-bias bulk-to-drain junction capacitance (Cbd), zero-bias bulk-to-source junction capacitance(Cbs), zero-bias bulk junction bottom capacitance(Cj), and zero-bias bulk junction sidewall capacitance(Cjsw) | farad | 0 |
| NUMDGT | number of digits output in print tables (maximum of 8 useful digits) | - | 4.0 |
| PIVREL ² | relative magnitude required for pivot in matrix solution | - | 1.0E-3 |
| PIVTOL ² | absolute magnitude required for pivot in matrix solution | - | 1.0E-13 |
| PTRANABSTOL | ABSTOL value used by pseudo-transient algorithm to decide the criterion for stabilizing capacitor currents. | amp | 1e-7 |
| PTRANVNTOL | VNTOL value used by pseudo-transient algorithm to decide the criterion for stabilizing inductor voltages. | volt | 1e-5 |
| PTRANSTABSTEPS | sets the maximum number of times pseudo- transient algorithm will be run to check for capacitor and inductor stabilization before giving convergence error. | - | 2100000 |
| PTRANSTEP | number of iterations for a pseudo transient algorithm to find the operating point. Can be any positive integer value. Set to 0 for engine default. | - | Same as |

| Options | Description | Units | Default |
|---------------------|--|-------|---------|
| PERF_CONV_DATA | prints statistics data in probe data file for performance and convergence debugging. | - | 0 |
| | To enable this option, set: | | |
| | .options PERF_CONV_DATA=1 | | |
| RELTOL ¹ | relative accuracy of V and I | - | 0.001 |
| RMIN | specifies the minimum timestep value | sec | 1e-18 |
| RNDSEED | generates different random number for random functions based on different seed value | - | 0 |
| SOLVER ⁶ | performance package solution algorithm | - | 1 |
| | (Solver = 0 selects the original solution algorithm; | | |
| | Solver = 1 selects the advanced solution algorithm) | | |
| SPEED_LEVEL | increases simulation performance by optimizing switching behavior of models. If increase in simulation performance is not needed, set SPEED_LEVEL=0. | - | 3 |
| SKIPTOPO | Skips the topology checks. By default, PSpice checks for netlist topology errors before starting the simulation. | - | 0 |
| | Use this option only when you find that PSpice is generating false topology check errors, and you want to ignore this check and proceed with simulation. It is recommended that you send such cases to Cadence Customer Support for further investigation. | | |
| | .options SKIPTOPO=1 implies the checks are skipped. | | |
| | .options ${\tt SKIPTOPO=0}$ implies that PSpice will check for topology errors. | | |

| Options | Description | Units | Default |
|------------|---|-------|---------|
| SUPRESSMSG | Suppresses the INFO messages in the output file. Set the value of this option to 1 in the circuit file to ensure that INFO messages do not appear in the corresponding output file. | - | 0 |
| TNOM | default nominal temperature (also the temperature at which model parameters are assumed to have been measured) | °C | 27.0 |
| THREADS | maximum number of threads. | - | 0 |
| | Setting .options THREADS=0 is the default value, which means the number of threads is determined by PSpice. | | |
| | PSpice creates a default number of simulation threads, depending on the following factors: | | |
| | Device count: Creating extra threads is not helpful if the device count is too low. Roughly, 1 thread per 10 devices is created. | | |
| | Number of cores on the system: Number of simulation threads does not exceed the number of available cores. | | |
| | If you specify a non-zero value, PSpice honors that, and creates the specified number of threads. | | |
| | For example: | | |
| | .options ${\tt THREADS=1}$ implies single thread is created. | | |
| | Note: This option parallelizes the computations for each time step of analog transient simulation. | | |
| | Note: Different runs of Parametric Sweep, Monte Carlo, and digital devices simulations are not parallelized. | | |

Commands

| Options | Description | Units | Default |
|--------------------|--|-------|---------|
| TRTOL | tolerance for integration error calculated using transient analysis. It is a relative tolerance where a higher TRTOL value results in bigger time steps and reduced accuracy. The TRTOL value should NOT be greater than 1/RELTOL. | - | 7 |
| VNTOL ¹ | best accuracy of voltages | volt | 1.0 uV |
| WCDEVIATION | worst case deviation. It can have double values between 0 and 1. | - | Same as |
| WIDTH | indicates the number of characters printed in the out file. | - | 80.0 |
| | Same as the .WIDTH OUT= statement (can be set to either 80 or 132) | | |

- 1. These options can have an expression that uses the SCHEDULE function, which is a function of time.
- 2. These options are available for modification in PSpice, but it is recommended that the program defaults be used.
- 3. For these options zero means infinity.
- 4. Setting the DIGMNTYMX=4 (min/max) directs PSpice to perform digital worst-case timing simulation. Refer to your *PSpice User Guide* for a complete description.
- 5. Expressions are supported for MINSIMPTS.
- 6. PSpice now contains two solution algorithms for simulation. Solver 1 increases simulation speed over Solver 0, particularly for larger circuits with substantial runtimes. Solver 1 has slightly better convergence characteristics than Solver 0. Having both algorithms available improves convergence, since there are two different algorithms that can perform the simulation.

GMIN Usage in Simulation

GMIN is added by default across the following device nodes to aid in convergence as explained in the following table:

| • | GMIN is added by default across output nodes. | |
|---|--|--|
| (I device) | If .OPTIONS NOGMINI is used, GMIN is not added. | |
| Dependent current sources (F and G devices) | | |
| Diode (D device) | GMIN is added to diode P-N junction conductance. | |

Commands

| BJT (Q device) GMIN is added to conductance across the junctions Base-Emitter, Base-Collector, Base-Substrate, and Collector-Substrate. |
|--|
| |
| JFET (J device) GMIN is added to conductance across the junctions Gate-Source and Gate-Drain. |
| MOS (M device) GMIN is added to conductance across the junctions Gate-Source and Gate-Drain. |
| GaAsFET (B device) GMIN is added to conductance across the junctions Gate-Source and Gate-Drain. |
| IGBT (Z device) GMIN is added to conductance across all semiconduct junctions. |
| Voltage Controlled Switch GMIN is added across control nodes. |
| (S device) |
| Current Controlled Switch GMIN is added across control nodes. (W device) |

Options for Scheduling Changes to Runtime Parameters

Purpose

The .OPTIONS command can be used to schedule automatic changes to certain runtime parameters during a simulation. A special command syntax is used for this (see **General Form** below).

Note: The ability to schedule such parameter changes only applies to transient analysis. You cannot interact with other analysis types.

General form

```
.OPTIONS <Parameter Name>={SCHEDULE(<time-value>, <parameter
    value>, <time-value>, <parameter value>, ...)}
```

Examples

```
.OPTIONS RELTOL={SCHEDULE( 0s,.001,2s,.005)}
```

indicates that RELTOL should have a value of .001 from time 0 up to time 2s, and a value of .005 from time 2s and beyond (that is: RELTOL=.001 for t, where $0 \le t \le 2s$, and RELTOL=.005 for t, where $t \ge 2s$).

Commands

PSpice A/D Digital Simulation Condition Messages

Other PSpice features produce warning messages in simulations (e.g., for the digital CONSTRAINT devices monitoring timing relationships of digital nodes). These messages are directed to the PSpice output file (and in Windows, to the Probe data file).

You can use options to control where and how many of these messages are generated. Below is a summary of the PSpice message types and a brief description of their meaning. The condition messages are specific to digital device timing violations and digital worst-case timing hazards. Refer to the Digital Simulation chapter of your *PSpice User Guide* for more information on digital worst-case timing.

| Message type | Meaning |
|------------------------------|---|
| | Timing violations |
| FREQUENCY | The minimum or maximum frequency specification for a signal has not been satisfied. Minimum frequency violations show that the period of the measured signal is too long, while maximum frequency violations describe signals changing too rapidly. |
| GENERAL | A boolean expression described within the GENERAL constraint checker was evaluated and produced a true result. |
| HOLD | The minimum time required for a data signal to be stable <i>after</i> the assertion of a clock, has not been met. |
| SETUP | The minimum time required for a data signal to be stable <i>prior</i> to the assertion of a clock, has not been met. |
| RELEASE | The minimum time for a signal that has gone inactive (usually a control such as CLEAR) to remain inactive before the asserting clock edge, has not been met. |
| WIDTH | The minimum pulse width specification for a signal has not been satisfied. That is, a pulse that is too narrow was observed on the node. |
| | Hazards |
| AMBIGUITY CONVERGEN CE | The convergence of conflicting rising and falling states (timing ambiguities) arriving at the inputs of a primitive, have produced a pulse (glitch) on the output. |

| CUMULATIVE AMBIGUITY | Signal ambiguities are additive, increased by propagation through each level of logic in the circuit. When the ambiguities associated with both edges of a pulse increase to the point where they would overlap, this is flagged as a cumulative ambiguity hazard. |
|-----------------------------|--|
| DIGITAL INPUT VOLTAGE | When a voltage is out of range on a digital pin, PSpice uses the state whose voltage range is closest to the input voltage and continues using the simulation. A warning message is reported. |
| NET-STATE CONFLICT | When two or more outputs attempt to drive a net to different states, <i>PSpice</i> represents the conflict as an X (unknown) state. This usually results from improper selection of a bus driver's enable inputs. |
| SUPPRESSE D GLITCH | A pulse applied to the input of a primitive that is shorter than the active propagation delay is ignored by <i>PSpice</i> . This can or cannot be significant, depending upon the nature of the circuit. The reporting of the suppressed glitch hazard shows that there might be a problem with either the stimulus, or the path delay configuration of the circuit. |
| PERSISTENT HAZARD | If the effects of any of the other logic hazard messages mentioned in the output file are able to propagate to either an EXTERNAL port, or to any storage device in the circuit, they are flagged as PERSISTENT HAZARDs. (Refer to your <i>PSpice User Guide</i> for more details on PERSISTENT HAZARDs.) |
| ZERO-DELAY- OSCILLATION | If the output of a primitive changes more than 50 times within a single digital time step, the node is considered to be oscillating. <i>PSpice</i> reports this and cancels the run. |

Commands

.PARAM (parameter)

Purpose The .PARAM statement defines the value of a parameter. A parameter

name can be used in place of most numeric values in the circuit description. Parameters can be constants, or expressions involving constants, or a combination of these, and they can include other

parameters.

General .PARAM < <name> = <value> >*

form .PARAM < <name> = { <expression> } >*

Examples .PARAM VSUPPLY = 5V

.PARAM VCC = 12V, VEE = -12V .PARAM BANDWIDTH = {100kHz/3}

 $.PARAM PI = 3.14159, TWO_PI = \{2*3.14159\}$

 $.PARAM\ VNUM = \{2*TWO_PI\}$

Arguments and options

<name>

Cannot begin with a number, and it cannot be one of the following predefined parameters, or TIME, or .<u>TEXT (text parameter)</u> names.

There are several predefined parameters. The parameter values must be either constants or expressions:

| Predefined parameter | Meaning |
|----------------------|---|
| TEMP | temperature (works using ABM expressions and digital models only) |
| VT | thermal voltage (reserved) |
| GMIN | shunt conductance for semiconductor p-n junctions |

<value>

Constants (<value>) do not need braces { }.

<expression>

Can contain constants or parameters. Need braces { }. See Examples.

Commands

Comments The .PARAM statements are order independent. They can be used inside a subcircuit definition to create local subcircuit parameters. Once defined, a parameter can be used in place of almost all numeric values in the circuit description with the following exceptions:

- *Not* in the *in-line* temperature coefficients for resistors (parameters can be used for the TC1 and TC2 resistor model parameters).
- **Not** in the PWL values for independent voltage and current source (V and I device) parameters.
- Not the E, F, G, and H device SPICE2G6 syntax for polynomial coefficient values and gain.

A .PARAM command can be in a library. The simulator can search libraries for parameters not defined in the circuit file, in the same way it searches for undefined models and subcircuits.

Note: Parameters cannot be used in place of node numbers, nor can the values on an analysis command (except for .TRAN and .FOUR) be parameterized. In addition the value cannot have the percent sign (%) at the end. A percent sign (%) is ignored by PSpice.

Note: Currents or Voltages from the circuit should not be used in .PARAM. Model such dependencies using behavioral sources (EFGH devices).

Commands

.PLOT (plot)

Purpose

The .PLOT command causes results from DC, AC, noise, and transient analyses to be line printer plots in the output file.

Note: This command is included for backward compatibility with earlier versions of PSpice. It is more effective to print plots from within Probe. Printing from Probe yields higher-resolution graphics and provides an opportunity to preview the plot before printing.

General form

Examples

```
.PLOT <analysis type> [output variable]*
+ ( [<lower limit value> , <upper limit value>] )*

.PLOT DC V[3] V([2],[3]) V[R1] I(VIN) I(R2) IB(Q13)

VBE(Q13)

.PLOT AC VM[2] VP[2] VM([3],[4]) VG[5] VDB[5] IR(D4)

.PLOT NOISE INOISE ONOISE DB(INOISE) DB(ONOISE)

.PLOT TRAN V[3] V([2],[3]) (0,5V) ID(M2) I(VCC) (-50mA,50mA)

.PLOT TRAN D(QA) D(QB) V[3] V([2],[3])
.PLOT TRAN V[3] V[R1] V([RESET])
```

Arguments and options

```
<analysis type>
DC, AC, NOISE, or TRAN. Only one analysis type can be specified.
```

```
<output variable>
```

Following the analysis type is a list of the output variables and (possibly) Y axis scales. A maximum of 8 output variables are allowed on one .PLOT command. However, an analysis can have any number of a .PLOT command. See <u>.PROBE (Probe)</u> for the syntax of the output variables.

```
(<lower limit value>, <upper limit value>)
Sets the range of the y-axis. This forces all output variables on the same y-axis to use the specified range.
```

The same form, (<lower limit value>, <upper limit value>), can also be inserted one or more times in the middle of a set of output variables. Each occurrence defines one Y axis that has the specified range. All the output variables that come between it and the next range to the left in the .PLOT command are put on its corresponding Y axis.

Commands

Comments

Plots are made by using text characters to draw the plot, which print on any kind of printer. However, plots printed from within Probe look much better.

The range and increment of the x-axis is fixed by the analysis being plotted. The y-axis default range is determined by the ranges of the output variables. In the fourth example, the two voltage outputs go on the y-axis using the range (0,5V) and the two current outputs go on the y-axis using the range (-5mMA, 50mA).

Note: Lower and upper limit values do not apply to AC Analysis.

If the different output variables differ considerably in their output ranges, then the plot is given more than one y-axis using ranges corresponding to the different output variables.

Note: The y-axis of frequency response plots (AC) is always logarithmic.

The last example illustrates how to plot the voltage at a node that has a name rather than a number. The first item to plot is a node voltage, the second item is the voltage across a resistor, and the third item is another node voltage, even though the second and third items both begin with the letter R. The square brackets force the interpretation of names to mean node names.

Commands

.PRINT (print)

Purpose

The .PRINT command allows results from DC, AC, noise, and transient analyses to be an output in the form of tables, referred to as print tables in the output file.

General form

```
.PRINT[/DGTLCHG] <analysis type> [output variable]*
```

Examples

```
.PRINT DC V[3] V[2],[3] V(R1) I(VIN) I(R2) IB(Q13) VBE(Q13)
.PRINT AC VM[2] VP[2] VM[3],[4] VG[5] VDB[5] IR[6] II[7]
.PRINT NOISE INOISE ONOISE DB(INOISE) DB(ONOISE)
.PRINT TRAN V[3] V([2],[3]) ID[M2] I[VCC]
.PRINT TRAN D(QA) D(QB) V[3] V([2],[3])
.PRINT/DGTLCHG TRAN QA QB RESET
.PRINT TRAN V[3] V(R1) V([RESET])
```

The last example illustrates how to print a node that has a name, rather than a number. The first item to print is a node voltage, the second item is the voltage across a resistor, and the third item to print is another node voltage, even though the second and third items both begin with the letter R. The square brackets force the names to be interpreted as node names.

Arguments and options

```
[/DGTLCHG]
```

For digital output variables only. Values are printed for each output variable whenever one of the variables changes.

```
<analysis type>
```

Only one analysis type— DC, AC, NOISE, or TRAN—can be specified for each .PRINT command.

```
<output variable>
```

Commands

Comments

The values of the output variables are printed as a table where each column corresponds to one output variable. You can change the number of digits printed for analog values by using the NUMDGT option of the .OPTIONS (analysis options) command.

An analysis can have multiple .PRINT commands.

Commands

.PROBE (Probe)

Purpose

The .PROBE command writes the results from DC, AC, and transient analyses to a data file used by Probe.

General form

```
.PROBE
```

Examples

```
.PROBE
```

```
.PROBE V[3] V([2],[3]) V(R1) I(VIN) I(R2) IB(Q13) VBE(Q13)
```

.PROBE/CSDF

.PROBE V[3] V(R1) V([RESET])

.PROBE[/CSDF][output variable]*

.PROBE D(QBAR)

.PROBE P(FREQ)

The first example (with no output variables) writes all the node voltages and all the device currents to the data file. The list of device currents written is the same as the device currents allowed as output variables.

The second example writes only those output variables specified to the data file, to restrict the size of the data file.

The third example creates a data file in a text format using the Common Simulation Data File (CSDF) format, not a binary format. This format is used for transfers between different computer families. CSDF files are larger than regular text files.

The fourth example illustrates how to specify a node that has a name rather than a number. The first item to output is a node voltage, the second item is the voltage across a resistor, and the third item to output is another node voltage, even though the second and third items both begin with the letter R. The square brackets force the interpretation of names to mean node names.

The fifth example writes only the output at digital node QBAR to the data file, to restrict the size of the data file.

The last example writes the parameter FREQ defined using the .PARAM command.

Commands

Arguments and options

[output variable]

This section describes the types of output variables allowed in a <u>.PRINT (print)</u>, <u>.PLOT (plot)</u>, and .PROBE command. Each .PRINT or .PLOT can have up to 8 output variables. This format is similar to that used when calling up waveforms while running Probe.

See the tables below for descriptions of the possible output variables. If .PROBE is used without specifying a list of output variables, all of the circuit voltages and currents are stored for post-processing. When an output variable list is included, the data stored is limited to the listed items. This form is intended for users who want to limit the size of the Probe data file.

Comments

Refer to your *PSpice User Guide* for a description of Probe, for information about using the Probe data file, and for more information on the use of text files in Probe. You can also consult Probe Help.

Use the ITERCOUNT keyword to add iteration count as a trace in the probe data file.

Note: Unlike the .PRINT and .PLOT commands, there are no analysis names before the output variables. Also, the number of output variables is unlimited.

DC Sweep and transient analysis output variables

For DC sweep and transient analysis, these are the available output variables:

| General form | Meaning of output variable |
|--------------------|--|
| D(<name>)</name> | digital value of <name> (a digital node)^{1 2}</name> |
| D(*) | all digital data ¹ |
| D(alias(*)) | all digital data except sub-circuit data ¹ |
| I(<name>)</name> | current through a two terminal device |
| lx(<name>)</name> | current into a terminal of a three or four terminal device (x is one of B, E, C, D, G, or S) |
| lz(<name>)</name> | current into one end of a transmission line (z is either A or B) |
| l(*) | all currents |

Commands

| General form | Meaning of output variable |
|-----------------------|--|
| I(alias(*)) | all currents except sub-circuit currents |
| P(<name>)</name> | parameter defined using .PARAM command |
| V(<node>)</node> | voltage at a node |
| V(<+ node>, <- node>) | voltage between two nodes |
| V(<name>)</name> | voltage across a two-terminal device |
| Vx(<name>)</name> | voltage at a non-grounded terminal of a device (x is one of B, E, C, D, G, or S) |
| Vz(<name>)</name> | voltage at one end of a transmission line (z is either A or B) |
| Vxy(<name>)</name> | voltage across two terminals of a three or four terminal device type |
| V(*) | all voltages |
| V(alias(*)) | all voltages except sub-circuit voltages |
| W(<name>)</name> | power dissipation of a device |
| W(*) | all power data |
| W(alias(*)) | all power data except sub-circuit data |

- These values are available for transient only.
 For the .PRINT/DGTLCHG statement, the D () is optional.

Note: The aliases must be defined in the circuit file to generate the .dat file.

| Example | Meaning |
|---------|--|
| D(QA) | the value of digital node QA |
| I(D5) | current through diode D5 |
| IG(J10) | current into gate of J10 |
| V(3) | voltage between node three and ground |
| V(3,2) | voltage between nodes three and two |
| V(R1) | voltage across resistor R1 |
| VA(T2) | voltage at port A of T2 |
| VB(Q3) | voltage between base of transistor Q3 and ground |

Commands

| Example | Meaning |
|----------|-------------------------------|
| VGS(M13) | gate-source voltage of M13 |
| W(U7) | power dissipated by device U7 |

Multiple-terminal devices

For the $V(\langle name \rangle)$ and $I(\langle name \rangle)$ forms, where $\langle name \rangle$ must be the name of a two-terminal device, the devices are:

| Character ID | Two-terminal device |
|--------------|------------------------------------|
| С | capacitor |
| D | diode |
| E | voltage-controlled voltage source |
| F | current-controlled current source |
| G | voltage-controlled current source |
| Н | current-controlled voltage source) |
| 1 | independent current source |
| L | inductor |
| R | resistor |
| S | voltage-controlled switch |
| V | independent voltage source |
| W | current-controlled switch |

For the $Vx(\langle name \rangle)$, $Vxy(\langle name \rangle)$, and $Ix(\langle name \rangle)$ forms, where $\langle name \rangle$ must be the name of a three or four-terminal device and x and y must each be a terminal abbreviation,

Commands

the devices and the terminals areas follows. For the Vz (< name >) and Iz (< name >) forms, < name > must be the name of a transmission line (T device) and z must be A or B.

| Three & four-terminal device type | Terminal abbreviation |
|-----------------------------------|------------------------|
| B (GaAs MESFET) | D (drain) |
| | G (gate) |
| | S (source) |
| J (Junction FET) | D (drain) |
| | G (gate) |
| | S (source) |
| M (MOSFET) | D (drain) |
| | G (gate) |
| | S (source) |
| | B (bulk, substrate) |
| Q (Bipolar transistor) | C (collector) |
| | B (base) |
| | E (emitter) |
| | S (substrate) |
| T (transmission line) | Va (near side voltage) |
| | la (near side current) |
| | Vb (far side voltage) |
| | Ib (far side current) |
| Z (IGBT) | C (collector) |
| | G (gate) |
| | E (emitter) |
| | |

Commands

AC Analysis

For AC analysis, these are the available output variables:

| General form | Meaning of output variable |
|------------------------------|--|
| I(<name>)</name> | current through a two terminal device |
| <pre>Ix(<name>)</name></pre> | current into a terminal of a three or four terminal device (x is one of E, B, C, D, G, or S) |
| Iz(<name>)</name> | current into one end of a transmission line (z is either A or B) |
| I(*) | all currents |
| I(alias(*)) | all currents except internal sub-circuit currents |
| Noise(*) | all analog noise components |
| Noise(alias(*)) | all except internal subcircuit analog noise components |
| V(<node>)</node> | voltage at a node |
| V(<+ node>, <- node>) | voltage between two nodes |
| V(<name>)</name> | voltage across a two-terminal device |
| Vx(<name>)</name> | voltage at a non-grounded terminal of a device (x is one of E, B, C, D, G, or S) |
| Vz(<name>)</name> | voltage at one end of a transmission line (z is either A or B) |
| Vxy(<name>)</name> | voltage across two terminals of a three or four terminal device type |
| V (*) | all voltages |
| V(alias(*)) | all voltages except internal sub-circuit voltages |
| W(<name>)</name> | power dissipation of a device |
| W (*) | all power data |
| W(alias(*)) | all power data except internal sub-circuit data |

For AC analysis, the output variables listed in the preceding table are augmented by adding a suffix.

Note: For AC analysis, the suffixes are ignored for a .PROBE command, but can be used in a .PRINT (print) on page 91 command and a .PLOT (plot) on page 89 command, and when

Commands

adding a trace in Probe. For example, in a .PROBE command, VDB(R1) is translated to V(R1), which is the raw data.

Current outputs are not available for devices, such as F device (current-controlled current sources) and G device (voltage-controlled current source). For these devices, you must first put a zero-valued voltage source in series with the device (or terminal) of interest and then print or plot the current through this voltage source.

| Suffix | Meaning of output variables |
|--------|----------------------------------|
| none | magnitude |
| DB | magnitude in decibels |
| G | group delay (-dPHASE/dFREQUENCY) |
| 1 | imaginary part |
| M | magnitude |
| Р | phase in degrees |
| R | real part |

| Example | Meaning of output variables for AC analysis |
|----------|---|
| II(R13) | imaginary part of current through R13 |
| IGG(M3) | group delay of gate current for M3 |
| IR(VIN) | real part of I through VIN |
| IAG(T2) | group delay of current at port A of T2 |
| V(2,3) | magnitude of complex voltage across nodes 2 & 3 |
| VDB(R1) | db magnitude of V across R1 |
| VBEP(Q3) | phase of base-emitter V at Q3 |
| VM(2) | magnitude of V at node 2 |
| WM(U7) | magnitude of power dissipated by device U7 |

Note: Current outputs for the F and G devices are not available for DC and transient analyses.

Commands

Noise analysis

For noise analysis, the output variables are predefined as follows:

| Output variable | Meaning of output variables for noise analysis |
|-----------------|--|
| INOISE | Total RMS summed noise at input node |
| ONOISE | INOISE equivalent at output node |
| DB(INOISE) | INOISE in decibels |
| DB (ONOISE) | ONOISE in decibels |

Note: <u>.PRINT (print)</u> on page 91 and <u>.PLOT (plot)</u> on page 89 cannot be used for the noise from any one device. However, the print interval on the <u>.NOISE (noise analysis)</u> on page 67 command can be used to output this information.

.SAVEBIAS (save bias point to file)

Purpose

The .SAVEBIAS command saves the bias point node voltages and inductor currents, to a file. It is used concurrently with .LOADBIAS (load bias point file) on page 52.

Only one analysis is specified in a .SAVEBIAS command, which can be OP, TRAN, or DC. However, a circuit file can contain a .SAVEBIAS command for each of the three analysis types. If the simulation parameters do not match the keywords and values in the .SAVEBIAS command, then no file is produced.

General form

```
.SAVEBIAS <"file_name"> <[OP] [TRAN] [DC]> [NOSUBCKT] + [TIME=<value> [REPEAT]] [TEMP=<value>] + [STEP=<value>] [MCRUN=<value>] [DC=<value>] + [DC1=<value>] [DC2=<value>]
```

Examples

.SAVEBIAS "OPPOINT" OP

For the first example, the small-signal operating point (.AC or .OP) bias point is saved.

```
.SAVEBIAS "TRANDATA.BSP" TRAN NOSUBCKT TIME=10u
```

In the second example, the transient bias point is written out at the time closest to, but not less than 10.0 u/sec. No bias point information for subcircuits is saved.

```
.SAVEBIAS "SAVETRAN.BSP" TRAN TIME=5n REPEAT TEMP=50.0
```

Use of the [REPEAT] keyword in the third example causes the bias point to be written out every 5.0 ns when the temperature of the run is 50.0 degrees.

```
.SAVEBIAS "DCBIAS.SAV" DC
```

In the fourth example, because there are no parameters supplied, only the very first DC bias point is written to the file.

```
.SAVEBIAS "SAVEDC.BSP" DC MCRUN=3 DC1=3.5 DC2=100
```

The fifth example saves the DC bias point when the following three conditions are all met: the first DC sweep value is 3.5, the second DC sweep value is 100, and the simulation is on the third Monte Carlo run. If only one DC sweep is being performed, then the keyword DC can be substituted for DC1.

Commands

Arguments and options

```
<"file name">
```

Any valid file name for the computer system, which must be enclosed in quotation marks.

```
[NOSUBCKT]
```

When used, the node voltages and inductor currents for subcircuits are not saved.

```
[TIME=<value> [REPEAT]]
```

Used to define the transient analysis time at which the bias point is to be saved.

```
[TEMP=<value>]
```

Defines the temperature at which the bias point is to be saved.

```
[STEP=<value>]
```

The step value at which the bias point is to be saved.

```
[MCRUN=<value>]
```

The number of the Monte Carlo or worst-case analysis run for which the bias point is to be saved.

```
[DC=\langle value \rangle], [DC1=\langle value \rangle], and [DC2=\langle value \rangle] Used to specify the DC sweep value at which the bias point is to be saved.
```

Comments

If REPEAT is not used, then the bias at the next time point greater than or equal to TIME=<value> is saved. If REPEAT is used, then TIME=<value> is the interval at which the bias is saved. However, only the latest bias is saved; any previous times are overwritten. The [TIME=<value> [REPEAT]] can only be used with a transient analysis.

The $[DC=\langle value \rangle]$ should be used if there is only one sweep variable. If there are two sweep variables, then $[DC1=\langle value \rangle]$ should be used to specify the first sweep value and $[DC2=\langle value \rangle]$ should be used to specify the second sweep value.

Commands

The saved bias point information is in the following format: one or more comment lines that list items such as:

- circuit name, title, date and time of run, analysis, and temperature, or
- a single .NODESET (set approximate node voltage for bias point) on page 66 command containing the bias point voltage values and inductor currents.

Only one bias point is saved to the file during any particular analysis. At the specified time, the bias point information and the operating point data for the active devices and controlled sources are written to the output file. When the supplied specifications on the .SAVEBIAS command line match the state of the simulator during execution, the bias point is written out.

Usage examples

A .SAVEBIAS command and a <u>.LOADBIAS (load bias point file)</u> command can be used to shorten the simulation time of large circuits, and also to aid in convergence.

A typical application for a .SAVEBIAS and a .LOADBIAS command is for a simulation that takes a considerable amount of time to converge to a bias point. The bias point is saved using a .SAVEBIAS command so that when the simulation is run again, the previous bias point calculated is used as a starting point for the bias solution, to save processing time.

The following example illustrates this procedure for a transient simulation.

```
.SAVEBIAS "SAVEFILE.TRN" TRAN
```

When the simulation is run, the transient analysis bias point information is saved to the file <code>savefile.trn</code> in the form of a .NODESET command. This .NODESET command provides the simulator with a starting solution for determining the bias point calculation for future simulations. To use this file, replace the .SAVEBIAS command in the circuit file using the following .LOADBIAS (Load Bias Point File) command.

```
.LOADBIAS "SAVEFMILE.TRN"
```

Note: A .SAVEBIAS and .LOADBIAS command should not refer to the same file during the same simulation run. Use the .SAVEBIAS during the first simulation and the .LOADBIAS for subsequent ones.

The simulator algorithms have been changed to provide an automatic saving and loading of bias point information under certain conditions. This automatic feature is used in the following analysis types: <u>.STEP (parametric analysis)</u> on page 106, <u>.DC (DC analysis)</u> on page 35,

Commands

<u>.WCASE (sensitivity/worst-case analysis)</u> on page 129, <u>.MC (Monte Carlo analysis)</u> on page 53, <u>.TEMP (temperature)</u> on page 117.

A typical application is a transient analysis where the bias point is calculated at several temperatures (such as .TEMP 0 10 20 30). As each new temperature is processed, the bias point for the previous temperature is used to find the new bias point. Since this process is automatic, the user does not have to change anything in the circuit file. However, there is some memory overhead since the bias point information is saved during the simulation. Disable the automatic saving feature, using the NOREUSE flag option in the .OPTIONS (analysis options) on page 71 command as follows:

```
.OPTIONS NOREUSE
```

Another application for the .LOADBIAS and .SAVEBIAS command is the handling of convergence problems. Consider a circuit which has difficulty in starting a DC sweep. The designer has added a .NODESET command as shown below to help the simulator determine the bias point solution.

```
.NODESET V(3) = 5.0V V(4) = 2.75V
```

Even though this helps the simulator determine the bias point, the simulator still has to compute the starting values for each of the other nodes. These values can be saved using the following statement:

```
.SAVEBIAS "DCOP.NOD" DC
```

The next time the simulation is run, the .NODESET and .SAVEBIAS command should be removed and replaced using the following:

```
.LOADBIAS "DCOP.NOD"
```

This provides the starting values for all of the nodes in the circuit, and can assist the simulator in converging to the correct bias point for the start of the sweep. If convergence problems are caused by a change in the circuit topology, the designer can edit the bias point save file to change the values for specific nodes or to add new nodes.

Commands

.SENS (sensitivity analysis)

Purpose The .SENS command performs a DC sensitivity analysis.

General form .SENS <output variable>*

Examples .SENS V(9) V(4,3) V(17) I(VCC)

Arguments and options

<output variable>

Same format and meaning as in the .PRINT command for DC and transient analyses. However, when <output variable> is a current, it is restricted to be the current through a voltage source.

Comments

By linearizing the circuit about the bias point, the sensitivities of each of the output variables to all the device values and model parameters is calculated and output data generated. This can generate large amounts of output data.

Device sensitivities are only provided for the following device types:

- resistors
- independent voltage and current sources
- voltage and current-controlled switches
- diodes
- bipolar transistors

Note: The results of the .SENS command are only available in the output file. They cannot be viewed in Probe.

.STEP (parametric analysis)

Purpose

The .STEP command performs a parametric sweep for all of the analyses of the circuit.

The .STEP command is similar to the <u>.TEMP (temperature)</u> command in that all of the typical analyses—such as <u>.DC (DC analysis)</u>, <u>.AC (AC analysis)</u>, and <u>.TRAN (transient analysis)</u>— are performed for each step.

Once all the runs finish, the specified <u>.PRINT (print)</u> table or <u>.PLOT (plot)</u> plot for each value of the sweep is an output, just as for the .TEMP or <u>.MC (Monte Carlo analysis)</u> command.

Probe displays nested sweeps as a family of curves.

General form

```
.STEP LIN <sweep variable name>
+ <start value> <end value> <increment value>
.STEP [DEC |OCT] <sweep variable name>
+ <start value> <end value> <points value>
.STEP <sweep variable name> LIST <value>*
```

The first general form is for doing a linear sweep. The second form is for doing a logarithmic sweep. The third form is for using a list of values for the sweep variable.

Examples

```
.STEP VCE 0V 10V .5V

.STEP LIN I2 5mA -2mA 0.1mA

.STEP RES RMOD(R) 0.9 1.1 .001

.STEP DEC NPN QFAST(IS) 1E-18 1E-14 5

.STEP TEMP LIST 0 20 27 50 80 100

.STEP PARAM CenterFreq 9.5kHz 10.5kHz 50Hz
```

The first three examples are for doing a linear sweep. The fourth example is for doing a logarithmic sweep. The fifth example is for using a list of values for the sweep variable.

Arguments and options

```
Sweep type
```

The sweep can be linear, logarithmic, or a list of values. For [linear sweep type], the keyword LIN is optional, but either OCT or DEC must be specified for the <logarithmic sweep type>. The sweep types are described below.

Commands

| Sweep types | Meaning |
|-------------|---|
| LIN | Linear sweep. The sweep variable is swept linearly from the starting to the ending value. The <increment value=""> is the step size</increment> |
| OCT | Sweep by octaves. The sweep variable is swept logarithmically by octaves. The <pre><pre><pre>cpoints</pre> value> is the number of steps per octave.</pre></pre> |
| DEC | Sweep by decades. The sweep variable is swept logarithmically by decades. The <pre><pre>cpoints value></pre> is the number of steps per decade.</pre> |
| LIST | Use a list of values. In this case there are no start and end values. Instead, the numbers that follow the keyword LIST are the values that the sweep variable is set to. |
| | Note: The LIST values must be in either ascending or descending order. |

<sweep variable name>

The < sweep variable name> can be one of the types described below.

| Sweep Variable Name | Meaning |
|---------------------|---|
| source | A name of an independent voltage or current source. During the sweep, the source's voltage or current is set to the sweep value. |
| model parameter | A model type and model name followed by a model parameter name in parenthesis. The parameter in the model is set to the sweep value. |
| temperature | Use the keyword TEMP for <sweep name="" variable="">. The temperature is set to the sweep value. For each value in the sweep, all the circuit components have their model parameters updated to that temperature.</sweep> |

Commands

| Sweep Variable Name | Meaning |
|---------------------|--|
| global parameter | Use the keyword PARAM, followed by the parameter name, |
| | for <sweep name="" variable="">. During the sweep, the</sweep> |
| | global parameter's value is set to the sweep value and all |
| | expressions are reevaluated. |

<start value>

Can be greater or less than <end value>: that is, the sweep can go in either direction.

<increment value> and <points value>
Must be greater than zero.

Comments

The .STEP command is similar to the .DC (DC analysis) command and immediately raises the question of what happens if both .STEP and .DC try to set the same value. The same question can come up using .MC (Monte Carlo analysis). The answer is that this is not allowed: no two analyses (.STEP, .TEMP (temperature), .MC, ..WCASE (sensitivity/worst-case analysis), and .DC) can try to set the same value. This is flagged as an error during read-in and no analyses are performed.

You can use the .STEP command to look at the response of a circuit as a parameter varies, for example, how the center frequency of a filter shifts as a capacitor varies. By using .STEP, that capacitor can be varied, producing a family of AC waveforms showing the variation. Another use is for propagation delay in transient analysis.

Usage examples

One

The .STEP command only steps the DC component of an AC source. In order to step the AC component of an AC source, a variable parameter has to be created. For example,

```
Vac 1 0 AC {variable}
.param variable=0
.step param variable 0 5 1
.ac dec 100 1000 1e6
```

Commands

Two

This is one way of stepping a resistor from 30 to 50 ohms in steps of 5 ohms, using a global parameter:

```
.PARAM RVAL = 1
R1 1 2 {RVAL}
.STEP PARAM RVAL 30,50,5
```

The parameter RVAL is global and PARAM is the keyword used by the .STEP command when using a global parameter.

Three

The following example steps the resistor model parameter R. This is another way of stepping a resistor from 30 to 50 ohms in steps of 5 ohms.

```
R1 1 2 RMOD 1
.MODEL RMOD RES(R=30)
.STEP RES RMOD(R) 30,50,5
```

Note: Do not use R={30}.

Here RMOD is the model name, RES is the sweep variable name (a model type), and R is the parameter within the model to step. To step the value of the resistor, the line value of the resistor is multiplied by the R parameter value to achieve the final resistance value, that is:

```
final resistor value = line resistor value · R
```

Therefore, if the line value of the resistor is set to one ohm, the final resistor value is $1 \cdot R$ or R. Stepping R from 30 to 50 ohms then steps the resistor value from $1 \cdot 30$ ohms to $1 \cdot 50$ ohms.

In examples 2 and 3, all of the ordinary analyses (e.g., .DC, .AC, and .TRAN) are run for each step.

Commands

.STIMLIB (stimulus library file)

Purpose The .STIMLIB command makes stimulus library files created by

StmEd available to PSpice.

General

.STMLIB <file name[.stl]>

form

Examples .STMLIB mylib.stl

.STMLIB volts.stl .STMLIB dgpulse

Arguments and options

<file name>

Specification that identifies a file containing .STIMULUS

commands.

Commands

.STIMULUS (stimulus)

Purpose The .STIMULUS command encompasses only the Transient

specification portion of what is allowed in the V or I device syntax.

General form .STIMULUS *<stimulus name> <type> <type-specific parameters>**

Examples .STIMULUS InputPulse PULSE (-1mv 1mv 2ns 2ns 50ns 100ns)

.STIMULUS DigitalPulse STIM (1,1) + 0S 1 + 10NS 0 + 20NS 1

.STIMULUS 50KHZSIN SIN (0 5 50KHZ 0 0 0)

Arguments and options

<stimulus name>

The name by which the stimulus is referred to by the source devices (V

or I), or by the digital STIM device.

Comments .STIMULUS commands generally appear within stimulus libraries

created by StmEd.

.SUBCKT (subcircuit)

Purpose

The .SUBCKT command/statement starts the subcircuit definition by specifying its name, the number and order of its terminals, and the names and default parameters that control its behavior. Subcircuits are instantiated using X (<u>Subcircuit instantiation</u> on page 346) devices. The .ENDS command marks the end of a subcircuit definition.

```
General form
```

Examples

```
.SUBCKT <name> [node] *
+ [OPTIONAL: < <interface node> = <default value> >*]
+ [PARAMS: < <name> = <value> >* ]
+ [TEXT: < <name> = <text value> >* ]
.ENDS
.SUBCKT OPAMP 1 2 101 102 17
.ENDS
.SUBCKT FILTER INPUT OUTPUT PARAMS: CENTER=100kHz,
+ BANDWIDTH=10kHz
.ENDS
.SUBCKT PLD IN1 IN2 IN3 OUT1
+ PARAMS: MNTYMXDLY=0 IO LEVEL=0
+ TEXT: JEDEC_FILE="PROG.JED"
.ENDS
.SUBCKT 74LS00 A B Y
+ OPTIONAL: DPWR=$G DPWR DGND=$G DGND
+ PARAMS: MNTYMXDLY=0 IO LEVEL=0
```

Arguments and options

<name>

The name is used by an X (Subcircuit Instantiation) device to reference the subcircuit.

```
[node] *
```

An optional list of nodes (pins). This is optional because it is possible to specify a subcircuit that has no interface nodes.

```
OPTIONAL:
```

Allows specification of one or more optional nodes (pins) in the subcircuit definition.

Commands

Comments

The subcircuit definition ends with a .ENDS command. All of the netlist between .SUBCKT and .ENDS is included in the definition. Whenever the subcircuit is used by an X (Subcircuit Instantiation) device, all of the netlist in the definition replaces the X device.

There must be the same number of nodes in the subcircuit calling statements as in its definition. When the subcircuit is called, the actual nodes (the ones in the calling statement) replace the argument nodes (the ones in the defining statement).

Note: Do not use 0 (zero) in this node list. Zero is reserved for the global ground node.

The optional nodes are stated as pairs consisting of an interface node and its default value. If an optional node is not specified in an X device, its default value is used inside the subcircuit; otherwise, the value specified in the definition is used.

This feature is particularly useful when specifying power supply nodes, because the same nodes are normally used in every device. This makes the subcircuits easier to use because the same two nodes do not have to be specified in each subcircuit statement. This method is used in the libraries provided with the Digital Simulation feature.

Subcircuits can be nested. That is, an X device can appear between .SUBCKT and .ENDS commands. However, subcircuit definitions cannot be nested. That is, a .SUBCKT statement cannot appear in the statements between a .SUBCKT and a .ENDS.

Subcircuit definitions should contain only device instantiations (statements without a leading period) and possibly these statements:

- <u>.IC (initial bias point condition)</u> on page 49
- <u>.NODESET (set approximate node voltage for bias point)</u> on page 66
- .MODEL (model definition) on page 57
- .PARAM (parameter) on page 87
- .FUNC (function) on page 47

Commands

Models, parameters, and functions defined within a subcircuit definition are available only within the subcircuit definition in which they appear. Also, if a .MODEL, .PARAM, or a .FUNC statement appears in the main circuit, it is available in the main circuit and all subcircuits.

Node, device, and model names are local to the subcircuit in which they are defined. It is acceptable to use a name in a subcircuit which has already been used in the main circuit. When the subcircuit is expanded, all its names are prefixed using the subcircuit instance name: for example, Q13 becomes X3.Q13 and node 5 becomes X3.5 after expansion. After expansion all names are unique. The only exception is the use of global node names (refer to your *PSpice User Guide*) that are not expanded.

The keyword PARAMS: passes values into subcircuits as arguments and uses them in expressions inside the subcircuit. The keyword TEXT: passes text values into subcircuits as arguments and uses them as expressions inside the subcircuit. Once defined, a text parameter can be used in the following places:

- To specify a JEDEC file name on a PLD device.
- To specify an Intel Hex file name to program a ROM device or initialize a RAM device.
- To specify a stimulus file name or signal name on a FSTIM device.
- To specify a text parameter to a (lower level) subcircuit.
- As part of a text expression used in one of the above.

Note: The text parameters and expressions are currently only used in Digital Simulation.

Usage examples

One

In the example of the 74LS00 subcircuit, the following subcircuit reference uses the default power supply nodes \$G_DPWR and \$G_DGND:

X1 IN1 IN2 OUT 74LS00

Commands

Two

To specify your own power supply nodes MYPOWER and MYGROUND, use the following subcircuit instantiation:

X2 IN1 IN2 OUT MYPOWER MYGROUND 74LS00

Three

If wanted, one optional node in the subcircuit instantiation can be provided. In the following subcircuit instantiation, the default \$G_DGND would be used:

X3 IN1 IN2 OUT MYPOWER 74LS00

Four

However, to specify values beyond the first optional node, all nodes previous to that node must be specified. For example, to specify your own ground node, the default power node before it must be explicitly stated:

X4 IN1 IN2 OUT \$G DPWR MYGROUND 74LS00

Commands

.TCLPOSTRUN(Runs TCL file post simulation)

Purpose The .TCLPOSTRUN command executes the TCL file after simulation run.

General form

.TCLPOSTRUN <TCL Filename>

Examples

.TCLPOSTRUN postrun.tcl

Comments

This command is called after the simulation is complete. Using this command any operation can be performed using the TCL file, such as

post-processing of the DAT file.

Note: tclsh file should be present at the path to run this command.

Commands

.TEMP (temperature)

Purpose The .TEMP command sets the temperature at which all analyses are done.

General form

.TEMP <temperature value>*

Examples

.TEMP 125 .TEMP 0 27 125

Comments

The temperatures are in degrees Centigrade. If more than one temperature is given, then all analyses are performed for each temperature.

It is assumed that the model parameters were measured or derived at the nominal temperature, TNOM (27°C by default). See the .OPTIONS (analysis options) command for setting TNOM.

.TEMP behaves similarly to the list variant of the .STEP (parametric analysis) statement, with the stepped variable being the temperature.

Note: To know more about the effective component values in case of *Temperature (Sweep)* analysis, see ENABLENEGRESTEMP in the section,

.

Commands

.TEXT (text parameter)

Purpose The .TEXT command precedes a list of names and text values.

```
General
form

TEXT < <name> = "<text value>" >*
TEXT < <name> = | <text expression> | >*

Examples

TEXT MYFILE = "FILENAME.EXT"
TEXT FILE = "ROM.DAT", FILE2 = "ROM2.DAT"
TEXT FILE = "ROM.DAT", FILE2 = "ROM2.DAT"
```

.TEXT PROGDAT = | "ROM"+TEXTINT(RUN_NO) + ".DAT" |
.TEXT DATA1 = "PLD.JED", PROGDAT = | "\PROG\DAT\"+FILENAME |

Arguments and options

<name>

Cannot be a .PARAM name, or any of the reserved parameters names.

<text expression>

Text expressions can contain the following:

| Text expressions | Definition |
|---|--|
| enclosed in " " | text constants |
| text parameters | previously defined parameters |
| + | the operator that concatenates two text values |
| TEXTINT (<value expression="" or="">)</value> | a function which returns a text string which is the integer value closest to the value of the < <i>value or expression</i> >; (< <i>value or expression</i> > is a floating-point value) |

Commands

Comments

The values can be text constants (enclosed in quotation marks " ") or text expressions (enclosed in I). Text expressions can contain only text constants or previously defined parameters. Once defined, a text parameter has the following uses:

- To specify a JEDEC file name on a PLD device.
- To specify an Intel Hex file name to program a ROM device or initialize a RAM device.
- To specify a stimulus file name or signal name on an FSTIM device.
- To specify a text parameter to a subcircuit.
- As part of a text expression used in one of the above.

Note: Text parameters and expressions are only used in digital simulation.

Commands

.TF (transfer)

Purpose The .TF command/statement causes the small-signal DC gain to

be calculated by linearizing the circuit around the bias point.

General form

.TF <output variable> <input source name>

Examples .TF V(5) VIN

.TF I (VDRIV) ICNTRL

Arguments and options

<output variable>

This has the same format and meaning as in the <u>.PRINT (print)</u> statement.

Comments

The gain from <input source name> to <output variable> and the input and output resistances are evaluated and written to the output file. This output does not require a .PRINT (print), .PLOT (plot), or .PROBE (Probe) statement.When <output variable> is a current, it is restricted to be the current through a voltage source.

Note: The results of the .TF command are only available in the output file. They cannot be viewed in Probe.

Commands

.TRAN (transient analysis)

Purpose The .TRAN command causes a transient analysis to be performed on the

circuit and specifies the time period for the analysis.

General form

.TRAN[/OP] <print step value> <final time value>
+[no-print value [step ceiling value]][SKIPBP]

Examples

```
.TRAN 1ns 100ns
.TRAN/OP 1ns 100ns 20ns SKIPBP
.TRAN 1ns 100ns 0ns .1ns
.TRAN 1ns 100ns 0ns {SCHEDULE(0,1ns,25ns,.1ns)}
.Tran {2*4ns+1ns} {5/param1+0.1m} {param2} 0.1ns
where param1, param2 are parameters defined using .param
```

Arguments and options

```
[/OP]
```

Causes the same detailed printing of the bias point that the <u>.OP (bias point)</u> command does for the regular bias point. Without using this option, only the node voltages are printed for the transient analysis bias point.

```
<print step value>
```

Sets the time interval used for printing (.PRINT), plotting (.PLOT), or performing a Fourier integral on (.FOUR) the results of the transient analysis.

Since the results are computed at different times than they are printed, a 2nd-order polynomial interpolation is used to obtain the printed values. This applies only to .PLOT (plot), and .FOUR (Fourier analysis)) outputs and does not affect Probe.

```
<final time value>
```

Sets the end time for the analysis.

```
[no-print value]
```

Sets the time interval (from TIME=0) that is not printed, plotted, or given to Probe.

```
[step ceiling value]
```

Overrides the default ceiling on the internal time step with a lower value.

The function SCHEDULE($x_1,y_1,x_2,y_2...x_n,y_n$) can be used in place of the step ceiling value to define a piecewise constant function (from time x forward use y).

Commands

[SKIPBP]

Skips calculation of the bias point.

When this option is used, the bias conditions are fully determined by the IC= specifications for capacitors and inductors.

Comments

The transient analysis calculates the circuit's behavior over time, always starting at TIME=0 and finishing at <final time value>, but you can suppress the output of a portion of the analysis. Use a .PRINT (print), .PLOT (plot), .FOUR (Fourier analysis), or .PROBE (Probe) to get the results of the transient analysis.

Prior to performing the transient analysis, PSpice computes a bias point for the circuit separate from the regular bias point. This is necessary because at the start of a transient analysis, the independent sources can have different values than their DC values.

The .TRAN command also sets the variables TSTEP and TSTOP, which are used in defaulting some waveform parameters. TSTEP is equal to tint step value> and TSTOP is equal to

Refer to your *PSpice User Guide* for more information on setting initial conditions.

Note: Expressions and double value are supported in .TRAN command for <print step value>, <final time value>, <no print value>.

Scheduling changes to runtime parameters with the .TRAN statement

Purpose

You can schedule automatic changes to the TMAX parameter for the .TRAN statement during a transient analysis.

Commands

General form

For TMAX only, the general form is:

.TRAN <time-value> <time-value> <step ceiling> {SCHEDULE(<time-value>, <parameter value>, <time-value>, <parameter value>, ...)

where the first value is time and the second value is step ceiling. For more details, see the <u>.TRAN (transient analysis)</u> command section.

Examples .TRAN .1ns 100ns Ons {SCHEDULE(0,1ns,25ns,.1ns)}

Note: For more information on scheduling runtime parameters during a simulation, see the .OPTIONS command section.

Commands

.VECTOR (digital output)

Purpose The .VECTOR command is used to create files containing digital simulation results.

```
General
form

.VECTOR <number of nodes> <node>*

+ [ POS = <column position> ]

+ [ FILE = <filename> ]

+ [ RADIX = "Binary" | "Hex" | "Octal"

+ [ BIT = <bit index> ] ]

+ [ SIGNAMES = <signal names> ]

Examples

.VECTOR 1 CLOCK SIGNAMES=SYSCLK
.VECTOR 4 DATA3 DATA2 DATA1 DATA0
.VECTOR 1 ADDR3 POS=2 RADIX=H BIT=4
.VECTOR 1 ADDR2 POS=2 RADIX=H BIT=3
.VECTOR 1 ADDR1 POS=2 RADIX=H BIT=2
.VECTOR 1 ADDR0 POS=2 RADIX=H BIT=1
```

Arguments and options

Commands

<number of nodes>

This means the number of nodes in the list.

<node>

This defines the nodes whose states are to be stored.

The optional parameters on the .VECTOR command can be used to control the file name, column order, radix of the state values, and signal names which appear in the file header. Each of the optional parameter is described below in detail.

POS < column position >

The optional parameter POS specifies the column position in the file. By default, the column position is determined through the order in which the .VECTOR command appears in the circuit file, and by the order of the signals within a .VECTOR command. Valid values for <column position> are 1-255.

FILE < filename >

Specifies the name of the file to which the simulation results are saved. By default, the .VECTOR command creates a file named <circuit filename>.vec. The name of the corresponding netlist file created is <circuit filename>.cir. You can use the FILE parameter to specify a different filename. Multiple .VECTOR commands can be used to specify nodes for the same file.

Commands

RADIX

The radix of the values for the specified nodes is defined if <number of nodes> is greater than one. Valid values are BINARY, OCTAL, or HEX (you can abbreviate to the first letter). If <number of nodes> is one, and a radix of OCTAL or HEX is specified, a bit position within the octal or hex digit via the BIT parameter can also be specified. A separate .VECTOR command can be used to construct multi-bit values out of single signals, provided the same POS value is specified. The default radix is BINARY if <number of nodes> is one. Otherwise, the default radix is HEX. If a radix of OCTAL or HEX is specified, the simulator creates dummy entries in the vector file header to fill out the value if <number of nodes> is not an even power of 2.

BIT <bit index>

Defines the bit position within a single hex or octal digit when the VECTOR symbol is attached to a wire. Valid values are 1 through 4 if RADIX=HEX, and 1 through 3 if RADIX=OCTAL.

SIGNAMES < signal names >

Defines the names of the signals which appear in the header of the vector file. If SIGNAMES is not specified, the <node> names are used in the vector file header. If <number of nodes> is greater than one, names are defined positionally, msb to lsb. If fewer signal names than <number of nodes> are specified, the <node> names are used for the remaining unspecified names.

Comments

The file created using the .VECTOR command contains time and state values for the circuit nodes specified in the statement. The file format is identical to that used by the digital file stimulus device (FSTIM). Thus, the results of one simulation can be used to drive inputs of a subsequent simulation. See <u>File stimulus</u> on page 446 for more information on the file stimulus file format.

Commands

.WATCH (watch analysis results)

Purpose The .WATCH command/statement outputs results from DC, AC,

and transient analyses to the Simulation Status window in the Probe display under the Watch tab in text format while the

simulation is running.

General .WATCH [DC] [AC] [TRAN]

form + [<output variable> [<lower limit value>,<upper limit</pre>

value>]]*

Examples .WATCH DC V(3) (-1V, 4V) V(2, 3) V(R1)

.WATCH AC VM(2) VP(2) VMC(Q1)

.WATCH TRAN VBE(Q13) (0V,5V) ID(M2) I(VCC) (0,500mA)

.WATCH DC V([RESET]) (2.5V,10V)

Arguments and options

DC, AC, and TRAN

The analysis types whose results are displayed during the simulation. You only need to specify one analysis type per .WATCH command, but there can be a .WATCH command for each analysis type in the circuit.

```
<output variable>
```

A maximum of eight output variables are allowed on a single .WATCH statement.

<lower limit value>, <upper limit value>
Specifies the normal operating range of that particular output variable. If the range is exceeded during the simulation, the simulator beeps and pauses. At this point, the simulation can be canceled or continued. If continued, the check for that output variable's boundary condition is eliminated. Each output variable can have its own value range.

Commands

Comments

The first example displays three output variables on the screen. The first variable, V(3), has an operating range set from minus one volt to four volts. If during the simulation the voltage at node three exceeds four volts, the simulation will pause. If the simulation is allowed to proceed, and node three continues to rise in value, the simulation is then not interrupted. However, if the simulation is allowed to continue and V(3) falls below -1.0 volt, the simulation would again pause because a new boundary condition was exceeded.

Up to three output variables can be seen on the display at one time. More than three variables can be specified, but they are not all displayed.

The possible output variables are given in <u>.PROBE (Probe)</u>, with the exception that digital nodes cannot be used and group delay is not available.

.WCASE (sensitivity/worst-case analysis)

Purpose The .WCASE statement causes a sensitivity and worst-case

analysis of the circuit to be performed.

General form

.WCASE <analysis> <output variable> <function>

[option]*

Examples

.WCASE TRAN V(5) YMAX

.WCASE DC IC(Q7) YMAX VARY DEV

.WCASE AC VP(13,5) YMAX DEVICES RQ OUTPUT ALL .WCASE TRAN V([OUT1],[OUT2]) YMAX RANGE(.4u,.6u)

+ LIST OUTPUT ALL VARY DEV HI

Arguments and options

<analysis>

Only one of DC, AC, or TRAN must be specified for <analysis>. This analysis is repeated in subsequent passes of the worst-case analysis. All requested analyses are performed during the nominal pass. Only the selected analysis is performed during subsequent passes.

<output variable>

Identical in format to that of a .PRINT (print) output variable.

<function>

Specifies the operation to be performed on the values of the $<output\ variable>$ to reduce these to a single value. This value is the basis for the comparisons between the nominal and subsequent runs. The <function> must be one of the following:

| Function | Meaning | | |
|----------|--|--|--|
| YMAX | Find the absolute value of the <i>greatest difference</i> in each waveform from the nominal run. | | |
| MAX | Find the maximum value of each waveform. | | |
| MIN | Find the <i>minimum value</i> of each waveform. | | |

PSpice A/D Reference Guide Commands

| Function | Meaning |
|-----------------------------|---|
| RISE_EDGE(<value>)</value> | Find the <i>first occurrence</i> of the waveform crossing <i>above</i> the threshold <value>. The waveform must have one or more points at or below <value> followed by one above; the output value listed is where the waveform increases above <value>.</value></value></value> |
| FALL_EDGE(<value>)</value> | Find the <i>first occurrence</i> of the waveform crossing <i>below</i> the threshold <value>. The waveform must have one or more points at or above <value> followed by one below; the output value listed is where the waveform decreases below <value>.</value></value></value> |

Commands

[option]*
Could have any number of the following.

| [option] | Meaning | | |
|--|---|--|--|
| LIST | Prints the updated model parameters for the sensitivity analysis. This does not affect the Probe data generated by the simulation. | | |
| OUTPUT ALL | Prints output from the sensitivity runs, after the nominal (first) run. The output from any run is governed by the .PRINT, .PLOT, and .PROBE command in the file. If OUTPUT ALL is omitted, then only the nominal and worst-case runs produce output. OUTPUT ALL ensures that all sensitivity information is saved for Probe. | | |
| RANGE ¹ (<low value="">, <high value="">)</high></low> | Restricts the range over which <function> can be evaluated. An asterisk * can be used in place of a <value> to show for all values. For example see the next two rows.</value></function> | | |
| YMAX RANGE(*,.5) | YMAX is evaluated for values of the sweep variable (e.g., time, and frequency) of .5 or less. | | |
| MAX RANGE(-1,*) | The maximum of the output variable is found for values of the sweep variable of -1 or more. | | |
| HI or LOW | Specify the direction which <function> should move for the worst-case run is to go (relative to the nominal). If <function> is YMAX or MAX, the default is HI, otherwise the default is LOW.</function></function> | | |
| VARY DEV VARY LOT VARY BOTH | By default, any device which has a model parameter specifying <i>either</i> a DEV tolerance or a LOT tolerance is included in the analysis. The analysis can be limited to only those devices which have DEV or LOT tolerances by specifying the appropriate option. The default is VARY BOTH. When VARY BOTH is used, sensitivity to parameters using both DEV and LOT specifications is checked only with respect to LOT variations. The parameter is then maximized or minimized using both DEV and LOT tolerances for the worst-case. All devices referencing the model have the same parameter values for the worst-case simulation. | | |

Commands

| [option] | Meaning |
|--------------------------------|---|
| DEVICES (list of device types) | By default, all devices are included in the sensitivity and worst-case analyses. The devices considered can be limited by listing the device types after the keyword DEVICES. Do not use any spaces or tabs in the devices list. For example, to only perform the analysis on resistors and MOSFETs, enter: |

DEVICES RM

1. If RANGE is omitted, then <function> is evaluated over the whole sweep range. This is equivalent to RANGE(*,*).

Comments

Multiple runs of the selected analysis (DC, AC, or transient) are performed while parameters are varied. Unlike .MC (Monte Carlo analysis), .WCASE varies only one parameter per run. This allows PSpice to calculate the sensitivity of the output waveform to each parameter. Once all the sensitivities are known, one final run is performed using all parameters varied so as to produce the worst-case waveform. The sensitivity and worst-case runs are performed using variations on model parameters as specified by the DEV and LOT tolerances on each .MODEL (model definition) parameter. Other specifications on the .WCASE command control the output generated by the analysis.

Note: You can run either .MC or .WCASE for a circuit, but not both in the same circuit.

Commands

* (comment)

Purpose

A statement beginning with an asterisk * is a comment line, which PSpice ignores.

General form

```
* [any text]
```

Examples

```
* This is an example of
* a multiple-line comment
```

Comments

Use an asterisk at the beginning of each line you want to be a comment. A single asterisk does not extend to subsequent lines. For example:

```
* .MODEL ABC NMOS (. . . . + . . . .)
```

produces an error message, because the second line is not covered by the first asterisk.

The use of comment statements throughout the input is recommended. It is good practice to insert a comment line just before a subcircuit definition to identify the nodes, for example:

```
* +IN -IN V+ V- +OUT -OUT .SUBCKT OPAMP 100 101 1 2 200 201
```

or to identify major blocks of circuitry.

Commands

; (in-line comment)

Purpose A semicolon; is treated as the end of a line.

General form

circuit file text ;[any text]

Examples

R13 6 8 10 ; R13 is a ; feedback resistor C3 15 0 .1U ; decouple supply

Comments

The simulator moves on to the next line in the circuit file. The text on the line after the semicolon; is a comment and has no effect. The use of comments throughout the input is recommended. This type of comment can also replace comment lines, which must start with * in the first column.

Trailing in-line comments that extend to more that one line can use a semicolon to mark the beginning of the subsequent comment lines, as shown in the example.

Commands

+ (line continuation)

Purpose A plus sign + is treated as the continuation of the previous line.

General circuit file text form + more text

Examples .DISTRIBUTION bi_modal (-1,1) (-.5,1) (-.5,0) (.5,0) + (.5,1) (1,1)

Comments Because the simulator reads the line preceded by a plus sign as

a continuation of the previous line, you can use the plus sign to

break up long lines of command text.

Differences between PSpice and Berkeley SPICE2

The version of SPICE2 referred to is SPICE2G.6 from the University of California at Berkeley.

PSpice runs any circuit that SPICE2 can run, with these exceptions:

- 1. Circuits that use .DISTO (small-signal distortion) analysis. U.C. Berkeley SPICE supports the .DISTO analysis, but contains errors. Also, the special distortion output variables (e.g., HD2 and DIM3) are not available. Instead of the .DISTO analysis, we recommend running a transient analysis and looking at the output spectrum using the Fourier transform mode in Probe. This technique shows the distortion (spectral) products for both small-signal and large-signal distortion.
- **2.** These options on the <u>.OPTIONS (analysis options)</u> statement are not available in PSpice:
 - □ LIMTIM: it is assumed to be 0.
 - LVLCOD: no in-line machine code is generated.
 - METHOD: a combination of trapezoidal and gear integration is always used.
 - □ MAXORD: a combination of trapezoidal and gear integration is always used.
 - □ LVLTIM: truncation error time step control is always used.
 - □ ITL3: truncation error time step control is always used.
- **3.** The IN= option on the .WIDTH statement is not available. PSpice always reads the entire input file regardless of how long the input lines are.
- **4.** Voltage coefficients for capacitors, and current coefficients for inductors must be put into a <u>.MODEL (model definition)</u> statement instead of on the device statement.
- **5.** PSpice does not allow the use of nested subcircuit definitions.

If this construct is used:

```
.SUBCKT ABC 1 2 3
...
.SUBCKT DEF 4 5 6
...
.ENDS
...
```

It is recommended that the definitions be separated into:

```
.SUBCKT ABC 1 2 3 ... X1 ... DEF
```

Commands

```
...
.ENDS
.SUBCKT DEF 4 5 6
...
```

Note: You can nest subcircuit calls.

- **6.** The .ALTER command is not supported in PSpice. Instead, use the .STEP (parametric analysis) on page 106 command to modify specific parameters over multiple PSpice runs.
- 7. The syntax for the *one-dimensional* POLY form of E, F, G, and H (<u>Voltage-controlled voltage source</u> on page 172 and <u>Current-controlled Voltage Source</u> on page 182) devices is different. PSpice requires a dimension specification of the form POLY(1), while SPICE does not.

PSpice produces basically the same results as SPICE. There can be some small differences, especially for values crossing zero, due to the corrections made for convergence problems.

The semiconductor device models are the same as in SPICE.

PSpice A/D Reference Guide Commands

Analog Devices

| Letter | Device type | Letter | Device type |
|--------|---|-----------|---------------------------------------|
| В | GaAsFET on page 145 | N | Digital input (N device) on page 455 |
| С | Capacitor on page 163 | 0 | Digital output (O Device) on page 460 |
| D | Diode on page 167 | Q | Bipolar transistor on page 285 |
| G | Voltage-controlled voltage source on page 172 | R | Resistor on page 320 |
| | Flux Source on page 184 | | |
| F | Current-controlled Voltage Source on page 182 | S | Voltage-Controlled Switch on page 325 |
| G | Charge source on page 186 | Т | Transmission line on page 330 |
| н | Current-controlled Voltage Source on page 182 | U | Digital primitive summary on page 363 |
| I | Independent voltage source & stimulus on page 188 | U STIM | Stimulus devices on page 438 |
| J | Junction FET on page 207 | V | Current-Controlled Switch on page 339 |

PSpice A/D Reference Guide Analog Devices

| Letter | Device type | Letter | Device type |
|-------------|--|--------|---|
| K | Coupling on page 215 | w | Current-Controlled Switch on page 339 |
| | Transmission line coupling on page 229 | | |
| L <u>In</u> | Inductor on page 232 | X | Subcircuit instantiation on page 346 |
| | | | Battery Model on page 359 |
| | | Y | Analog Device Model Interface (DMI) on page 349 |
| M | MOSFET on page 237 | Z | IGBT on page 351 |

Analog Devices

Analog devices

This chapter describes the different types of analog devices supported by PSpice and PSpice A/D. These device types include analog primitives, independent and controlled sources, and subcircuit calls. Each device type is described separately, and each description includes the following information as applicable:

- A description and an example of the proper netlist syntax.
- The corresponding model types and their description.
- The corresponding list of model parameters and their descriptions.
- The equivalent circuit diagram and characteristic equations for the model (as required).
- References to publications that the model is based on.

These analog devices include all of the standard circuit components that normally are not considered part of the two-state (binary) devices that are found in the digital devices.

The model library consists of analog models of off-the-shelf parts that you can use directly in your circuit designs. Refer to the online Library List for available device models and the libraries they are located in. You can also implement models using the .MODEL (model definition) on page 57 statement and implement macromodels as subcircuits using the .SUBCKT (subcircuit) on page 112 statement.

The <u>Device types</u> on page 142 summary table lists all of the analog device primitives supported by PSpice A/D. Each primitive is described in detail in the sections following the table.

Analog Devices

Device types

PSpice supports <u>Bipolar transistor</u> on page 285, many types of analog devices, including sources and general subcircuits. PSpice A/D also supports digital devices. The supported devices are categorized into device types. each of which can have one or more model types. For example, the BJT device type has three model types: NPN, PNP, and LPNP (Lateral PNP). The description of each devices type includes a description of any of the model types it supports.

The device declarations in the netlist always begin with the name of the individual device (instance). The first letter of the name determines the device type. What follows the name depends on the device type and its requested characteristics. Below is a summary of the device types and the general form of their declaration formats.

Note: The table below includes the designator (letter) used in device modeling for each device type.

Analog device summary

| Device type | Letter | Declaration format |
|---|--------|---|
| Bipolar transistor on page 285 | Q | <pre>Q<name> <collector node=""> <base node=""/> <emitter node=""> + [substrate node] <model name=""> [area value]</model></emitter></collector></name></pre> |
| Capacitor on page 163 | С | <pre>C<name> <+ node> <- node> [model name] <value> + [IC=<initial value="">]</initial></value></name></pre> |
| Voltage-controlled voltage source on page 172 | E | E <name> <+ node> <- node> <+ controlling node> + <- controlling node> <gain></gain></name> |
| | | (additional Analog Behavioral Modeling forms: VALUE, TABLE, LAPLACE, FREQ, and CHEBYSHEV; additional POLY form) |
| Voltage-controlled Government of voltage source on page 172 | G | G <name> <+ node> <- node> <+ controlling node> + <- controlling node> <transconductance></transconductance></name> |
| | | (additional Analog Behavioral Modeling forms: VALUE, TABLE, LAPLACE, FREQ, and CHEBYSHEV; additional POLY form) |
| Current-controlled Voltage Source on page 182 | F | F <name> <+ node> <- node> <controlling device="" name="" v=""> + <qain></qain></controlling></name> |
| | | (additional POLY form) |

Analog Devices

Analog device summary, continued

| Device type | Letter | Declaration format |
|---|-----------|--|
| Current-Controlled Switch on page 339 | W | W <name> <+ switch node> <- switch node> + <controlling device="" name="" v=""> <model name=""></model></controlling></name> |
| Current-controlled Voltage Source on | Н | <pre>H<name> <+ node> <- node> <controlling device="" name="" v=""> + <transresistance></transresistance></controlling></name></pre> |
| page 182 | | (additional POLY form) |
| <u>Digital input (N device)</u> on page 455 | N | <pre>N<name> <interface node=""> <low level="" node=""> <high level="" node=""> + <model name=""> <input specification=""/></model></high></low></interface></name></pre> |
| <u>Digital output (O Device)</u> on page 460 | 0 | <pre>O<name> <interface node=""> <low level="" node=""> <high level="" node=""> + <model name=""> <output specification=""></output></model></high></low></interface></name></pre> |
| <u>Digital primitive</u> <u>summary</u> on page 363 | U | <pre>U<name> <primitive type=""> ([parameter value]*) + <digital node="" power=""> <digital ground="" node=""> <node>* + <timing model="" name=""></timing></node></digital></digital></primitive></name></pre> |
| Stimulus devices on page 438* | U STIM | <pre>U<name> STIM (<width value="">, <format value="">) + <digital node="" power=""> <digital ground="" node=""> <node>* + <i model="" name="" o=""> [TIMESTEP=<stepsize value="">] + <waveform description=""></waveform></stepsize></i></node></digital></digital></format></width></name></pre> |
| <u>Diode</u> on page 167 | D | <pre>D<name> <anode node=""> <cathode node=""> <model name=""> [area value]</model></cathode></anode></name></pre> |
| GaAsFET on page 145 | В | <pre>B<name> <drain node=""> <gate node=""> <source node=""/> + <model name=""> [area value]</model></gate></drain></name></pre> |
| Independent current source & stimulus on page 189 | I | <pre>I<name> <+ node> <- node> [[DC] <value>] + [AC <magnitude value=""> [phase value]] [transient specification]</magnitude></value></name></pre> |
| Independent voltage source & stimulus on page 188 | V | <pre>V<name> <+ node> <- node> [[DC] <value>] + [AC <magnitude value=""> [phase value]] [transient specification]</magnitude></value></name></pre> |
| Inductor on page 232 | L | <pre>L<name> <+ node> <- node> [model name] <value> + [IC=<initial value="">]</initial></value></name></pre> |

Analog Devices

Analog device summary, continued

| Device type | Letter | Declaration format |
|---|--------|---|
| Coupling on page 215 | K | <pre>K<name> L<inductor name=""> <l<inductor name="">>* + <coupling value=""></coupling></l<inductor></inductor></name></pre> |
| | | <pre>K<name> <l<inductor name="">>* <coupling value=""> + <model name=""> [size value]</model></coupling></l<inductor></name></pre> |
| IGBT on page 351 | Z | <pre>Z<name> <collector> <gate> <emitter> <model name=""> + [AREA=<value>] [WB=<value>] [AGD=<value>]</value></value></value></model></emitter></gate></collector></name></pre> |
| | | + [KP= <value>] [TAU=<value>]</value></value> |
| <u>Junction FET</u> on page 207 | J | <pre>J<name> <drain node=""> <gate node=""> <source node=""/> + <model name=""> [area value]</model></gate></drain></name></pre> |
| MOSFET on page 237 | M | <pre>M<name> <drain node=""> <gate node=""> <source node=""/> + <bulk node="" substrate=""> <model name=""> + [common model parameter]*</model></bulk></gate></drain></name></pre> |
| Resistor on page 320 | R | <pre>R<name> <+ node> <- node> [model name] <value> + [TC=<linear coefficient="" temp.="">[,<quadratic coefficient]]<="" pre="" temp.=""></quadratic></linear></value></name></pre> |
| Subcircuit instantiation on page 346 | X | <pre>X<name> [node]* <subcircuit name=""> + [PARAMS: <<name>=<value>>*] [TEXT:<<name>=<text value="">>*]</text></name></value></name></subcircuit></name></pre> |
| <u>Transmission line</u> on page 330 | Т | <pre>T<name> <a +="" node="" port=""> <a -="" node="" port=""> + <b +="" node="" port=""> <b -="" node="" port=""> <ideal lossy="" or="" specification=""></ideal></name></pre> |
| <u>Transmission line</u> <u>coupling</u> on page 229 | К | <pre>K<name> T<line name=""> <t<line name="">>* + CM=<coupling capacitance=""> LM=<coupling inductance=""></coupling></coupling></t<line></line></name></pre> |
| Voltage-Controlled Switch on page 325 | S | <pre>S<name> <+ switch node> <- switch node> + <+ controlling node> <- controlling node> <model name=""></model></name></pre> |

GaAsFET

General form B<name> <drain node> <gate node> <source node> <model name> [area

value]

Examples

BIN 100 10 0 GFAST

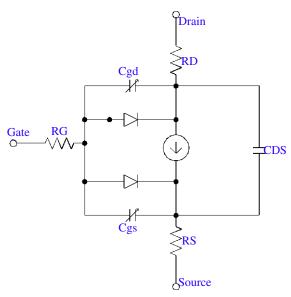
B13 22 14 23 GNOM 2.0

Model form .MODEL <model name> GASFET [model parameters]

Description The GaAsFET is modeled as an intrinsic FET using an ohmic resistance

(RD/area) in series with the drain, another ohmic resistance (RS/area) in series with the source, and another ohmic resistance (RG) in series with

the gate.



Arguments and options

[area value]

The relative device area. Its default value is 1.0.

Analog Devices

Comments

The LEVEL model parameter selects among different models for the intrinsic GaAsFET as follows:

LEVEL=1 "Curtice" model (see reference [1])

LEVEL=2 "Raytheon" or "Statz" model (see reference [3]), equivalent to

the GaAsFET model in SPICE3

LEVEL=3 "TOM" model by TriQuint (see reference [4])

LEVEL=4 "Parker-Skellern" model (see reference [5] and [6])

LEVEL=5 "TOM-2" model by TriQuint (see reference [7])

LEVEL=6 "TOM-3" model by TriQuint

For more information, see <u>References</u> on page 162.

Note: The TOM-2 model is based on the original TriQuint TOM model, retaining the desirable features of the TOM model, while improving accuracy in the subthreshold near cutoff and knee regions (Vds of 1 volt or less). Included are temperature coefficients related to the drain current and corrected behavior of the capacitance as a function of temperature.

Note: The TOM-3 model uses quasi-static charge conservation in the implanted layer of MESFET to improve the accuracy of the capacitance equations.

The following table lists the set of GaAsFET breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

| part name | Model type | Property | Property description |
|-----------|------------|---------------|--|
| BBREAK | GASFET | AREA MODEL | area scaling factor GASFET model name |

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter.

Analog Devices

Model Parameters

Table 2-1 GaAsFET model parameters for all levels

| Model parameter ¹ | Description | Units | Default |
|---------------------------------|--|-----------------------|---------|
| AF | flicker noise exponent | | 1 |
| BETA | transconductance coefficient | amp/volt ² | 0.1 |
| BETATCE | BETA exponential temperature coefficient | %/°C | 0 |
| CDS | drain-source capacitance | farad | 0 |
| CGD | zero-bias gate-drain p-n capacitance | farad | 0 |
| CGS | zero-bias gate-source p-n capacitance | farad | 0 |
| EG | band gap voltage (barrier height) | eV | 1.11 |
| FC | forward-bias depletion capacitance coefficient | | 0.5 |
| IS | gate p-n saturation current | amp | 1E-14 |
| KF | flicker noise coefficient | | 0 |
| LEVEL | model index (1, 2, 3, 4, or 5) | | 1 |
| N | gate p-n emission coefficient | | 1 |
| RD | drain ohmic resistance | ohm | 0 |
| RG | gate ohmic resistance | ohm | 0 |
| RS | source ohmic resistance | ohm | 0 |
| TRD1 | RD temperature coefficient (linear) | °C ⁻¹ | 0 |
| TRG1 | RG temperature coefficient (linear) | °C ⁻¹ | 0 |
| TRS1 | RS temperature coefficient (linear) | °C ⁻¹ | 0 |
| T_ABS | absolute temperature | °C | |
| T_MEASURED | measured temperature | °C | |
| T_REL_GLOBA L | relative to current temperature | °C | |
| T_REL_LOCAL | relative to AKO model temperature | °C | |
| VBI | gate p-n potential | volt | 1.0 |
| VTO | pinchoff voltage | volt | -2.5 |

Table 2-1 GaAsFET model parameters for all levels

| Model parameter ¹ | Description | Units | Default |
|---------------------------------|-----------------------------|---------|---------|
| VTOTC | vто temperature coefficient | volt/°C | 0 |
| XTI | is temperature exponent | | 0 |

^{1.} For information on T_ABS, T_MEASURED, T_REL_GLOBAL, and T_REL_LOCAL, see the <u>.MODEL (model definition)</u> on page 57 statement.

Table 2-2 GaAsFET model parameters specific to model levels

| Model parameter | Description | Units | Default |
|-----------------|--|--------------------------|---------|
| | level 1 | | |
| ALPHA | saturation voltage parameter | volt ⁻¹ | 2.0 |
| LAMBDA | channel-length modulation | volt ⁻¹ | 0 |
| M | gate p-n grading coefficient | | 0.5 |
| TAU | conduction current delay time | sec | 0 |
| | level 2 | | |
| ALPHA | saturation voltage parameter | volt ⁻¹ | 2.0 |
| В | doping tail extending parameter | volt ⁻¹ | 0.3 |
| LAMBDA | channel-length modulation | volt ⁻¹ | 0 |
| M | gate p-n grading coefficient | | 0.5 |
| TAU | conduction current delay time | sec | 0 |
| VDELTA | capacitance transition voltage | volt | 0.2 |
| VMAX | capacitance limiting voltage | volt | 0.5 |
| | level3 | | |
| ALPHA | saturation voltage parameter | volt ⁻¹ | 2.0 |
| BTRK | auxiliary parameter for Monte Carlo analysis* | amp/volt ³ | 0 |
| DELTA | output feedback parameter | (amp·volt) ⁻¹ | 0 |
| | | | |

Table 2-2 GaAsFET model parameters specific to model levels

| Model parameter | Description | Units | Default |
|-----------------|--|--------------------------|---------|
| DVT | auxiliary parameter for Monte Carlo analysis* | volt | 0 |
| DVTT | auxiliary parameter for Monte Carlo analysis* | volt | 0 |
| GAMMA | static feedback parameter | | 0 |
| M | gate p-n grading coefficient | | 0.5 |
| Q | power-law parameter | | 2 |
| TAU | conduction current delay time | sec | 0 |
| VDELTA | capacitance transition voltage | volt | 0.2 |
| VMAX | gate diode capacitance limiting voltage | volt | 0.5 |
| | level 4 | | |
| ACGAM | capacitance modulation | | 0 |
| DELTA | output feedback parameter | (amp·volt) ⁻¹ | 0 |
| HFETA | high-frequency VGS feedback parameter | | 0 |
| HFE1 | HFGAM modulation by VGD | volt ⁻¹ | 0 |
| HFE2 | HFGAM modulation by VGS | volt ⁻¹ | 0 |
| HFGAM | high-frequency VGD feedback parameter | | 0 |
| HFG1 | HFGAM modulation by VSG | volt ⁻¹ | 0 |
| HFG2 | HFGAM modulation by VDG | volt ⁻¹ | 0 |
| IBD | gate junction breakdown current | amp | 0 |
| LAMBDA | channel-length modulation | volt ⁻¹ | 0 |
| LFGAM | low-frequency feedback parameter | | 0 |
| LFG1 | LFGAM modulation by VSG | volt ⁻¹ | 0 |
| LFG2 | LFGAM modulation by VDG | volt ⁻¹ | 0 |
| MVST | subthreshold modulation | volt ⁻¹ | 0 |

Table 2-2 GaAsFET model parameters specific to model levels

| Model parameter | Description | Units | Default |
|-----------------|--|--------------------------|---------|
| MXI | saturation knee-potential modulation | | 0 |
| Р | linear-region power law exponent | | 2 |
| Q | power-law parameter | | 2 |
| TAUD | relaxation time for thermal reduction | sec | 0 |
| TAUG | relaxation time for GAM feedback | sec | 0 |
| VBD | gate junction breakdown potential | volt | 1 |
| VST | subthreshold potential | volt | 0 |
| XC | capacitance pinchoff reduction factor | | 0 |
| XI | saturation knee potential factor | | 1000 |
| Z | knee transition parameter | | 0.5 |
| | level 5 | | |
| ALPHA | saturation voltage parameter | volt ⁻¹ | 2.0 |
| ALPHATCE | ALPHA temperature coefficient | %/°C | 0 |
| BTRK | auxiliary parameter for Monte Carlo analysis ¹ | amp/volt ³ | 0 |
| CGDTCE | CGD temperature coefficient | °C ⁻¹ | 0 |
| CGSTCE | cgs temperature coefficient | °C ⁻¹ | 0 |
| DELTA | output feedback parameter | (amp·volt) ⁻¹ | 0 |
| DVT | auxiliary parameter for Monte Carlo analysis* | volt | 0 |
| DVTT | auxiliary parameter for Monte Carlo analysis* | volt | 0 |
| GAMMA | static feedback parameter | | 0 |
| GAMMATC | GAMMA temperature coefficient | °C ⁻¹ | 0 |
| | | | |

Table 2-2 GaAsFET model parameters specific to model levels

| Model parameter | Description | Units | Default |
|-----------------|--|--------------------|---------|
| ND | subthreshold slope drain pull parameter | volt ⁻¹ | 0 |
| NG | subthreshold slope gate parameter | | 0 |
| Q | power-law parameter | | 2 |
| TAU | conduction current delay time | sec | 0 |
| VBITC | vві temperature coefficient | volt/°C | 0 |
| VDELTA | capacitance transition voltage | volt | 0.2 |
| VMAX | gate diode capacitance limiting voltage | volt | 0.5 |
| | level 6 | | |
| | General Parameters | | |
| LAMBDA | Slope of drain characteristic in the saturated region. | volt ⁻¹ | 0.0 |
| VST | Subthreshold slope | volt | 1.0 |
| MST | Subthreshold slope drain parameter | volt ⁻¹ | 0.0 |
| IS | Forward gate diode saturation current | amp | 0.0 |
| N | Forward gate diode ideality factor | | 1.0 |
| ILK | Leakage diode current parameter | | 0.0 |
| PLK | Leakage diode potential parameter | | 1.0 |
| K | Knee-function parameter | | 2.0 |
| IS | As defined in TOM 2 | | |
| | Temperature Parameters | | |
| MSTTC | Linear temperature coefficient | | 0.0 |
| VSTTC | Linear temperature coefficient | | 0.0 |
| | Charge Parameters | | |

Analog Devices

Table 2-2 GaAsFET model parameters specific to model levels

| Model parameter | Description | Units | Default |
|-----------------|------------------|-------|-------------------------|
| QGQH | Charge parameter | | 2.0 * 10 ⁻¹⁶ |
| QGSH | Charge parameter | | 1.0 * 10 ⁻¹⁶ |
| QGDH | Charge parameter | | 0.0 |
| QGIO | Charge parameter | | 1.0 * 10 ⁻¹⁶ |
| QGQL | Charge parameter | | 5.0 * 10 ⁻¹⁶ |
| QGAG | Charge parameter | | 1.0 |
| QGAD | Charge parameter | | 1.0 |
| QGCL | Charge parameter | | 2.0 * 10 ⁻¹⁶ |
| QGGB | Charge parameter | | 100.0 |
| QGGO | Charge parameter | | 0.0 |
| | | | |

^{1.} See auxiliary model parameters BTRK, DVT, and DVTT.

Auxiliary model parameters BTRK, DVT, and DVTT

The parameters BTRK, DVT, and DVTT are auxiliary model parameters that are used to make the Monte Carlo analysis easier when using PSpice. In the analysis, these affect the parameters VTO and BETA as follows:

```
VTO = VTO + DVT + DVTT

BETA = BETA + BTRK · (DVT + DVTT)
```

In Monte Carlo analysis, DEV tolerances placed on the DVT or DVTT cause variations in both VTO and BETA. PSpice does not support correlated DEV variations in Monte Carlo analysis. Without DVT and DVTT, DEV tolerances placed on VTO and BETA can result in independent variations; there is a definite correlation between VTO and BETA on real devices.

The BTRK, DVT, and DVTT parameters are also used to provide tracking between distinct GaAsFETs, such as between depletion mode and enhancement mode. PSpice already provides a limited mechanism for this, but only allows one DEV and one LOT (or LOT/n and DEV/n) tolerance per model parameter. The added parameters circumvent this restriction by extending the capability of Monte Carlo to model correlation between the critical model parameters.

Analog Devices

GaAsFET equations

The equations in this section describe an N-channel GaAsFET. The following variables are used:

```
= intrinsic gate-intrit = area (nsic source voltage
Vgs
        = intrinsic gate-intrinsic drain voltage
Vqd
Vds
        = intrinsic drain-intrinsic source voltage
Cds
        = drain-source capacitance
        = gate-source capacitance
Cgs
Cgd
        = gate-drain capacitance
        = k \cdot T/q (thermal voltage)
Vt
        = Boltzmann constant
k
        = electron charge
a
        = analysis temperature (°K)
Thom= nominal temperature (set by using <u>OPTIONS</u> (analysis options) on page 71 TNOM=)
```

Note: Positive current is current flowing into a terminal (for example, positive drain current flows from the drain through the channel to the source).

GaAsFET equations for DC current: all levels

```
Ig = gate current = area · (Igs+Igd)
Id = drain current = area · (Idrain-Igd)
Is = source current = area · (-Idrain-Igs)
where
Igs = gate-source leakage current
Igd = gate-drain leakage current
```

GaAsFET equations for DC current: specific to model levels

Levels 1, 2, 3, and 5

$$I_{gs} = IS \cdot (e^{Vgs/(N \cdot Vt)} - 1)$$

 $I_{gd} = IS \cdot (e^{Vgd/(N \cdot Vt)} - 1)$

Level 4

$$Igs = Igs_f + Igs_r$$

where

$$Igs_{f} = IS \cdot \left[e^{\frac{Vgs}{N \cdot V_{t}}} - 1 \right] + Vgs \cdot GMIN$$

$$Igsr = IBD \cdot \left[1 - e^{-\frac{Vgs}{VBD}}\right]$$

$$Igd = Igd_f + Igd_r$$

where

$$\operatorname{Igd}_{\mathsf{f}} = \operatorname{IS} \cdot \left[e^{\frac{Vgd}{\mathbf{N} \cdot V_t}} - 1 \right] + \operatorname{Vgd} \cdot \operatorname{GMIN}$$

$$\operatorname{Igd}_{\mathbf{r}} = \operatorname{IBD} \cdot \left[1 - e^{-\frac{Vgd}{\mathbf{VBD}}} \right]$$

Level 1: Idrain

Normal mode: $Vds \ge 0$

Case 1

for cutoff region: Vgs - VTO < 0

then: Idrain = 0

Case 2

for linear & saturation region: Vgs - VTO ≥ 0

Analog Devices

then:

Idrain = BETA · (1+LAMBDA · Vds) · (Vgs-VTO)² · tanh (ALPHA · Vds)

Inverted mode: Vds < 0

Switch the source and drain in the Normal mode equations.

Level 2: Idrain

Normal mode: $Vds \ge 0$

Case 1

for cutoff region: Vgs - VTO < 0

then: Idrain = 0

Case 2

for linear & saturation region: Vgs - VTO ≥ 0

then:

Idrain = BETA · $(1+LAMBDA · Vds) · (Vgs-VTO)^2 · K_t / (1+B. (Vgs-VTO))$

Where

 K_t is a polynomial approximation of tanh.

for linear region:

0 < Vds < 3/ALPHA then

 $K_t = 1 - (1 - Vds \cdot ALPHA/3)^3$

for saturation region:

 $Vds \ge 3/ALPHA$ then

 $K_t = 1$

Inverted mode: Vds < 0

Switch the source and drain in the Normal mode equations.

Level 3: Idrain

Normal mode: $Vds \ge 0$

Case 1

for cutoff region: Vgs - VTO < 0

then: Idrain = 0

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Case 2

 K_+ is same as of level 2.

Level 4: Idrain

Normal mode: $Vds \ge 0$

$$\text{Idrain} = \frac{Ids}{1 + \text{DELTA} \cdot p_{avg}}$$

$$\label{eq:Vgst} \begin{array}{lll} \text{Vgst} &=& \text{Vgs-VTO-}\gamma_{\text{lf}} \cdot \text{Vgd}_{\text{avg}} - \gamma_{\text{hf}} \cdot (\text{Vgd-Vgd}_{\text{avg}}) - \eta_{\text{hf}} \cdot (\text{Vgs-Vgs}_{\text{avg}}) \\ \text{Vdst} &=& \text{Vds} \end{array}$$

Inverted mode: Vds < 0

$$\mbox{Idrain} = \frac{-Ids}{1 + \mbox{DELTA} \cdot p_{avg}}$$

$$\texttt{Vgst} = \texttt{Vgd} - \texttt{VTO} - \gamma \textit{If} \cdot \texttt{Vgd}_{avg} - \gamma \textit{hf} \cdot (\texttt{Vgs} - \texttt{Vgd}_{avg}) - \eta \texttt{hf} \cdot (\texttt{Vgd} - \texttt{Vgs}_{avg})$$

Vdst = -Vds

where

$$\begin{split} & \text{Ids = BETA} \cdot (1 + \text{LAMBDA} \cdot \text{Vdst}) \cdot (\text{Vgt}^Q - (\text{Vgt -Vdt})^Q) \\ & \text{Pavg = Vds} \cdot & \text{Ids - TAUD} \cdot d/d_t(\text{P}_{avg}) \\ & \text{γ} \\ & \text{f = LFGAM - LFG1} \cdot \text{V} \\ & \text{g = V$} \\ & \text{$g$ = V$} \\ & \text{$f$ = V$} \\ & \text{$f$$

Analog Devices

$$\text{Vgt= VST} \cdot (1 + \text{MVST} \cdot Vdst) \cdot \ln \left(\exp \left(\frac{Vgst}{\text{VST} \cdot (1 + \text{MVST} \cdot Vdst)} \right) + 1 \right)$$

$$Vdt = \frac{1}{2} \cdot \sqrt{\left(Vdp \cdot \sqrt{1+\mathbf{Z}} + Vsat\right)^2 + \mathbf{Z} \cdot Vsat^2} - \frac{1}{2} \cdot \sqrt{\left(Vdp \cdot \sqrt{1+\mathbf{Z}} - Vsat\right)^2 + \mathbf{Z} \cdot Vsat^2}$$

$$Vdp = Vdst \cdot \frac{P}{Q} \cdot \left(\frac{Vgt}{VBI - VTO}\right)^{P - Q}$$

$$Vsat = \frac{Vgt \cdot (Vgt \cdot MXI + XI \cdot (VBI - VTO))}{Vgt + Vgt \cdot MXI + XI \cdot (VBI - VTO)}$$

Level 5: Idrain

Normal mode: $Vds \ge 0$

Case 1

For cutoff region: $Vgs - VTO + GAMMA \cdot Vds \le 0$ AND $NG + ND \cdot Vds = 0$ then: Idrain = 0

For linear and saturation region:

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Idso = BETA
$$\cdot (Vg)^{\mathbf{Q}} \cdot \frac{\text{ALPHA} \cdot Vds}{\sqrt{1 + (\text{ALPHA} \cdot Vds)^2}}$$

$$\text{Vg} = \mathbf{Q} \cdot V_{st} \cdot \log \left(\exp \left(\frac{Vgs - (\text{VTO} + \text{GAMMA} \cdot Vds)}{\mathbf{Q} \cdot V_{st}} \right) + 1 \right)$$

$$V_{st} = (ng + nd \cdot Vds) \cdot \left(\frac{kT}{q}\right)$$

Inverted mode: Vds < 0

Switch the source and drain in the Normal mode equations.

GaAsFET equations for capacitance

All capacitances are between terminals of the intrinsic GaAsFET (i.e., to the inside of the ohmic drain, source, and gate resistances).

All Levels

For all conditions:

Level1

C_{gs} = gate-source capacitance

For:
$$Vgs \le FC \cdot VBI$$

Cgs = area
$$\cdot$$
CGS \cdot (1-Vgs/VBI) $^{-M}$

For:
$$Vgs > FC \cdot VBI$$

$$\texttt{Cgs} = \texttt{area} \cdot \textbf{CGS} \cdot (1 - \textbf{FC})^{-(1 + \textbf{M})} \cdot (1 - \textbf{FC} \cdot (1 + \textbf{M}) + \textbf{M} \cdot \texttt{Vgs} / \textbf{VBI})$$

C_{ad} = gate-drain capacitance

For:
$$Vgd \le FC \cdot VBI$$

$$C_{gd} = area \cdot CGD \cdot (1-Vgd/VBI)^{-M}$$

$$Cgd = area \cdot CGD \cdot (1-FC)^{-(1+M)} \cdot (1-FC \cdot (1+M) + M \cdot Vgd/VBI)$$

Analog Devices

Levels 2, 3, and 5

Cgs = gate-source capacitance

Cgs =
$$area \cdot (CGS \cdot K2 \cdot K1 / (1-Vn/VBI)^{1/2} + CGD \cdot K3)$$

C_{ad} = gate-drain capacitance

Cgd =
$$area \cdot (CGS \cdot K3 \cdot K1 / (1-Vn/VBI)^{1/2} + CGD \cdot K2)$$

Where:
 $K1 = (1 + (Ve-VTO) / ((Ve-VTO)^2 + VDELTA2)^{1/2}) / 2$
 $K2 = (1 + (Vgs-Vgd) / ((Vgs-Vgd)^2 + (1/ALPHA)^2)^{1/2}) / 2$
 $K3 = (1 - (Vgs-Vgd) / ((Vgs-Vgd)^2 + (1/ALPHA)^2)^{1/2}) / 2$
 $Ve = (Vgs + Vgd + ((Vgs-Vgd)^2 + (1/ALPHA)^2)^{1/2}) / 2$
if:
 $(Ve + VTO + ((Ve-VTO)^2 + VDELTA^2)^{1/2}) / 2 < VMAX$
then $Vn = (Ve + VTO + ((Ve-VTO)^2 + VDELTA^2)^{1/2}) / 2$
else $Vn = VMAX$

Level 4

Note: Charge storage is implemented using a modified Statz model.

Cgs = gate-source capacitance

$$\mathbf{Cgs} = \frac{1}{2} \cdot K1 \cdot \left(1 + 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 + 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}}\right)$$

Cgd = gate-drain capacitance

$$\mathbf{Cgd} = \frac{1}{2} \cdot K1 \cdot \left(1 - 2\mathbf{ACGAM} - \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \left(1 - 2\mathbf{ACGAM} + \frac{Vds}{\sqrt{Vds^2 + \alpha^2}} \right) + \frac{1}{2} \cdot \mathbf{CGD} \cdot area \cdot \mathbf{CGD} \cdot a$$

where:

$$K1 = \frac{1}{2} \frac{\text{cgs}}{\sqrt{1 - V_{ge}/\text{vBI}}} \left[1 + \text{xc} + (1 - \text{xc}) \frac{V_{gn}}{\sqrt{V_{gn}^2 + 0.2^2}} \right]$$

Analog Devices

if:
$$Vx < FC \cdot VBI$$

then $V_{ge} = V_X$
if: $Vx \ge FC \cdot VBI$

then
$$V_{ge} = VBI \left[1 - \frac{4(1 - FC)^3}{\left(2 - 3FC + \frac{V_x}{VBI}\right)^2} \right]$$

$$\mathbf{V_x} = \ \mathrm{Vgs} + \mathbf{ACGAM} \cdot \mathrm{Vds} - \frac{1}{2} (V_{gn} - \sqrt{V_{gn}^2 + 0.2^2}) - \frac{1}{2} (V_{gn} - \sqrt{V_{gn}^2 + 0.2^2})$$

$$\mathbf{V}_{\mathsf{gn}} = \ \left[(Vgs + \mathsf{ACGAM}) \cdot Vds - \mathsf{VTO} - \frac{1}{2}(Vds - \sqrt{Vds^{-2} + \alpha^2}) \right] \cdot (1 - \mathsf{XC})$$

where

$$\alpha = \frac{\mathbf{XI}}{\mathbf{XI} + 1} \cdot \frac{\mathbf{VBI} - \mathbf{VTO}}{2}$$

Note: If the source and drain potentials swap, the model reverses over a range set by α . The model maintains a straight line relation between gate-source capacitance and gate bias in the region Vgs > FC · VBI.

GaAsFET equations for temperature effect

All Levels

$$\begin{split} & \text{VTO}\left(\text{T}\right) = \text{VTO+VTOTC} \cdot (\text{T-Tnom}) \\ & \text{BETA}\left(\text{T}\right) = \text{BETA} \cdot 1.01 \\ & \text{BETATCE} \cdot (\text{T-Inom}) \\ & \text{IS}\left(\text{T}\right) = \text{IS} \cdot \boldsymbol{e}^{\left(\text{T/Inom-1}\right) \cdot \text{EG/(N \cdot Vt)}} \cdot \left(\text{T/Tnom}\right) \\ & \text{RG}\left(\text{T}\right) = \text{RG} \cdot \left(1 + \text{TRG1} \cdot (\text{T-Tnom})\right) \\ & \text{RD}\left(\text{T}\right) = \text{RD} \cdot \left(1 + \text{TRD1} \cdot (\text{T-Inom})\right) \\ & \text{RS}\left(\text{T}\right) = \text{RS} \cdot \left(1 + \text{TRS1} \cdot (\text{T-Inom})\right) \\ \end{split}$$

Analog Devices

Levels 1, 2, 3, and 4

```
CGS(T) = CGS \cdot (1+M \cdot (.0004 \cdot (T-Tnom) + (1-VBI(T)/VBI)))
CGD(T) = CGD \cdot (1+M \cdot (.0004 \cdot (T-Tnom) + (1-VBI(T)/VBI)))
VBI(T) = VBI \cdot T/Tnom - 3 \cdot Vt \cdot \ln(T/Tnom) - EG(Tnom) \cdot T/Tnom + EG(T)
where:
EG(T) = silicon bandgap energy = 1.16 - .000702 \cdot T^2/(T+1108)
Level 5
```

ALPHA(T) = ALPHA · 1.01ALPHATCE · (T-Tnom) GAMMA(T) = GAMMA + GAMMATC · (T-Tnom) VBI(T) = VBI + VBITC · (T-Tnom) VMAX(T) = VMAX + VBITC · (T-Tnom) CGS(T) = CGS · (1 + CGSTCE · (T-Tnom)) CGD(T) = CGD · (1 + CGDTCE · (T-Tnom))

GaAsFET equations for noise

Noise is calculated assuming a 1.0-hertz bandwidth, using the following spectral power densities (per unit bandwidth).

Parasitic resistance thermal noise

$$Is^{2} = 4 \cdot k \cdot T / (RS/area)$$

$$Id^{2} = 4 \cdot k \cdot T / (RD/area)$$

$$Ig^{2} = 4 \cdot k \cdot T / RG$$

Intrinsic GaAsFET shot and flicker noise

$$Id^2 = 4 \cdot k \cdot T \cdot gm \cdot 2/3 + KF \cdot Id^{AF}/FREQUENCY$$

where:
 $gm = d Idrain/d Vgs$ (at the DC bias point)

Analog Devices

References

For more information on this GaAsFET model, refer to:

- [1] W. R. Curtice, "A MESFET model for use in the design of GaAs integrated circuits," *IEEE Transactions on Microwave Theory and Techniques*, MTT-28, 448-456 (1980).
- [2] S. E. Sussman-Fort, S. Narasimhan, and K. Mayaram, "A complete GaAs MESFET computer model for SPICE," *IEEE Transactions on Microwave Theory and Techniques*, MTT-32, 471-473 (1984).
- [3] H. Statz, P. Newman, I. W. Smith, R. A. Pucel, and H. A. Haus, "GaAs FET Device and Circuit Simulation in SPICE," *IEEE Transactions on Electron Devices*, ED-34, 160-169 (1987).
- [4] A. J. McCamant, G. D. McCormack, and D. H. Smith, "An Improved GaAs MESFET Model for SPICE," *IEEE Transactions on Microwave Theory and Techniques*, vol. 38, no. 6, 822-824 (June 1990).
- [5] A. E. Parker and D. J. Skellern "Improved MESFET Characterization for Analog Circuit Design and Analysis," 1992 <u>IEEE GaAs IC Symposium Technical Digest</u>, pp. 225-228, Miami Beach, October 4-7, 1992.
- [6] A. E. Parker, "Device Characterization and Circuit Design for High Performance Microwave Applications," IEE EEDMO'93, London, October 18, 1993.
- [7] D. H. Smith, "An Improved Model for GaAs MESFETs," Publication forthcoming. (Copies available from TriQuint Semiconductors Corporation or Cadence.)

Capacitor

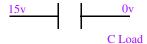
General form C<name> <(+) node> <(-) node> [model name] <value>

[IC=<initial value>]

Examples CLOAD 15 0 20pF

C2 1 2 .2E-12 IC=1.5V CFDBCK 3 33 CMOD 10pF

Model form .MODEL <model name> CAP [model parameters



Arguments and options

(+) and (-) nodes

Define the polarity when the capacitor has a positive voltage across it. The first node listed (or pin one in) is defined as positive. The voltage across the component is therefore defined as the first node voltage, less the second node voltage.

[model name]

If [model name] is left out, then <value> is the *capacitance* in farads. If [model name] is specified, then the value is given by the model parameters; see <u>Capacitor value formula</u> on page 166.

<initial value>

The initial voltage across the capacitor during the bias point calculation. It can also be specified in a circuit file using a .IC command as follows:

.IC V(+node, -node) <initial value>

Analog Devices

Comments

Positive current flows from the (+) node through the capacitor to the (-) node. Current flow from the first node through the component to the second node is considered positive.

For details on using the .IC command in a circuit file, see .IC (initial bias point condition) on page 49 and refer to your *PSpice User Guide* for more information.

The initial voltage across the capacitor can also be set inby using the IC1 part if the capacitor is connected to ground or by using the IC2 part for setting the initial conditions between two nodes. These parts can be found in SPECIAL.

For standard C parts, the effective value of the part is set directly by the VALUE property. For the variable capacitor, C_VAR, the effective value is the product of the base value (VALUE) and multiplier (SET).

In general, capacitors should have positive component values (VALUE property). In all cases, components must not be given a value of zero.

However, there are cases when negative component values are desired. This occurs most often in filter designs that analyze an RLC circuit equivalent to a real circuit. When transforming from the real to the RLC equivalent, it is possible to end up with negative component values.

PSpice A/D allows negative component values for bias point, DC sweep, AC, and noise analyses. A transient analysis may fail for a circuit with negative components. Negative capacitors may create instabilities in time that the analysis cannot handle.

| Part name | Model type | Property | Property description |
|-----------|------------|----------|--|
| С | capacitor | VALUE | capacitance |
| | | IC | initial voltage across the capacitor during bias point calculation |
| C_VAR | | VALUE | base capacitance |
| | | SET | multiplier |

Analog Devices

Breakout parts

For non-stock passive and semiconductor devices, provides a set of breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters. Another approach is to use the model editor to derive an instance model and customize this. For example, you could add device and/or lot tolerances to model parameters.

Basic breakout part names consist of the intrinsic PSpice A/D device letter plus the suffix BREAK. By default, the model name is the same as the part name and references the appropriate device model with all parameters set at their default. For instance, the DBREAK part references the DBREAK model which is derived from the intrinsic PSpice A/D D model (.MODEL DBREAK D).

For breakout part CBREAK, the effective value is computed from a formula that is a function of the specified VALUE property.

| Device type | Part name | Part library | Property | Property description |
|-------------|-----------|--------------|----------|--|
| capacitor | CBREAK | breakout | VALUE | capacitance |
| | | | IC | initial voltage across the capacitor during bias point calculation |
| | | | MODEL | CAP model name |

Capacitor Model Parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-----------------------------------|-------|---------|
| C | capacitance multiplier | | 1.0 |
| TC1 | linear temperature coefficient | °C-1 | 0.0 |
| TC2 | quadratic temperature coefficient | °C-2 | 0.0 |
| T_ABS | absolute temperature | °C | |
| $T_{MEASURED}$ | measured temperature | °C | |
| T_REL_GLOBAL | relative to current temperature | °C | |

Analog Devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-----------------------------------|--------|---------|
| T_REL_LOCAL | relative to AKO model temperature | °C | |
| VC1 | linear voltage coefficient | volt-1 | 0.0 |
| VC2 | quadratic voltage coefficient | volt-2 | 0.0 |

^{1.} For information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see <u>.MODEL (model definition)</u> on page 57.

Capacitor equations

Capacitor value formula

If [model name] is specified, then the value is given by:

$$\langle value \rangle \cdot C \cdot (1+VC1 \cdot V+VC2 \cdot V^2) \cdot (1+TC1 \cdot (T-Tnom) +TC2 \cdot (T-Tnom)^2)$$

where <value> is normally positive (though it can be negative, but *not* zero). *Tnom* is the nominal temperature (set using TNOM option).

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Capacitor equation for noise

The capacitor does not have a noise model.

Diode

General

D<name> <(+) node> <(-) node> <model name> [area value]

form

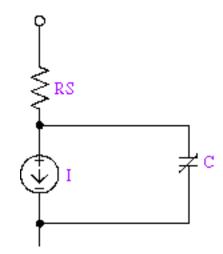
Examples DCLAMP 14 0 DMOD D13 15 17 SWITCH 1.5

Model form

.MODEL <model name> D [model parameters]

Description

The diode is modeled as an ohmic resistance (RS/area) in series with an intrinsic diode. Positive current is current flowing from the anode through the diode to the cathode.



Arguments and options

<(+) node>

The anode.

<(-) node>

The cathode.

[area value]

Scales IS, ISR, IKF,RS, CJO, and IBV, and has a default value of 1. IBV and BV are both specified as positive values.

Analog Devices

The following table lists the set of diode breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

| Part name | Model type | Property | Property description |
|--|------------|----------|----------------------|
| DBREAK DBREAK3 DBREAKCR DBREAKVV DBREAKZ | D, X | MODEL | D model name |

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter. For more information, see <u>Special Considerations</u> on page 64.

Diode Model Parameters

| Model | Description | Unit | Default |
|-------------------------|--|-------|----------|
| parameters ¹ | • | | |
| AF | flicker noise exponent | | 1.0 |
| BV | reverse breakdown knee voltage | volt | infinite |
| CJO | zero-bias p-n capacitance | farad | 0.0 |
| EG | bandgap voltage (barrier height) | eV | 1.11 |
| FC | forward-bias depletion capacitance coefficient | | 0.5 |
| IBVL | low-level reverse breakdown knee current | amp | 0.0 |
| IBV | reverse breakdown knee current | amp | 1E-10 |
| IKF | high-injection knee current | amp | infinite |
| IS | saturation current | amp | 1E-14 |

Analog Devices

| Model parameters ¹ | Description | Unit | Default |
|----------------------------------|---|------|---------|
| ISR | recombination current parameter | amp | 0.0 |
| KF | flicker noise coefficient | | 0.0 |
| M | p-n grading coefficient | | 0.5 |
| N | emission coefficient | | 1.0 |
| NBV | reverse breakdown ideality factor | | 1.0 |
| NBVL | low-level reverse breakdown ideality factor | | 1.0 |
| NR | emission coefficient for isr | | 2.0 |
| RS | parasitic resistance | ohm | 0.0 |
| TBV1 | bv temperature coefficient (linear) | °C-1 | 0.0 |
| TBV2 | by temperature coefficient (quadratic) | °C-2 | 0.0 |
| TIKF | ikf temperature coefficient (linear) | °C-1 | 0.0 |
| TRS1 | rs temperature coefficient (linear) | °C-1 | 0.0 |
| TRS2 | rs temperature coefficient (quadratic) | °C-2 | 0.0 |
| TT | transit time | sec | 0.0 |
| T_ABS | absolute temperature | °C | |
| $T_{MEASURED}$ | measured temperature | °C | |
| T_REL_GLOBAL | relative to current temperature | °C | |
| T_REL_LOCAL | Relative to AKO model temperature | °C | |
| VJ | <i>p-n</i> potential | volt | 1.0 |
| XTI | IS temperature exponent | | 3.0 |

^{1.} For more information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see .MODEL (model definition) on page 57.

Diode Equations

The equations in this section use the following variables:

Vd = voltage across the intrinsic diode only

Analog Devices

```
Vt = k·T/q (thermal voltage)
k = Boltzmann's constant
q = electron charge
T = analysis temperature (°K)
Tnom = nominal temperature (set using TNOM option)
```

Other variables are listed in <u>Diode Model Parameters</u> on page 168.

Diode equations for DC current

```
\begin{split} & \text{Id} = \textit{area} \cdot (\text{Ifwd - Irev}) \\ & \text{Ifwd} = \text{forward current} = \text{Inrm} \cdot \text{Kinj} + \text{Irec} \cdot \text{Kgen} \\ & \text{Inrm} = \text{normal current} = \text{IS} \cdot (e^{\text{Vd/(N \cdot Vt)}} - 1) \\ & \text{if: } \textit{IKF} > 0 \\ & \text{then: Kinj} = \text{high-injection factor} = (\textit{IKF/(IKF+Inrm)})^{1/2} \\ & \text{else: Kinj} = 1 \\ & \text{Irec} = \text{recombination current} = \text{ISR} \cdot (e^{\text{Vd/(NR \cdot Vt)}} - 1) \\ & \text{Kgen} = \text{generation factor} = ((1 - \text{Vd/VJ})^2 + 0.005)^{\text{M/2}} \\ & \text{Irev} = \text{reverse current} = \text{Irev}_{\text{high}} + \text{Irev}_{\text{low}} \\ & \text{Irev}_{\text{low}} = \text{IBV} \cdot e^{-(\text{Vd+BV})/(\text{NBV \cdot Vt)}} \\ & \text{Irev}_{\text{low}} = \text{IBVL} \cdot e^{-(\text{Vd+BV})/(\text{NBV \cdot Vt)}} \end{split}
```

Diode equations for capacitance

$$\begin{split} Cd &= Ct + \textit{area} \cdot Cj \\ Ct &= transit \ time \ capacitance = TT \cdot Gd \\ Gd &= DC \ conductance = area \cdot \frac{d(Inrm \cdot Kinj + Irec \cdot Kgen)}{dVd} \\ Kinj &= high-injection \\ factor \\ Cj &= CJO \cdot (1-Vd/VJ)^{-M} \qquad IF: \ Vd \leq FC \cdot VJ \\ Cj &= CJO \cdot (1-FC)^{\cdot (1+M)} \cdot (1-IF: \ Vd > FC \cdot VJ) \\ FC \cdot (1+M) + M \cdot Vd/VJ) \\ Cj &= junction \ capacitance \end{split}$$

Diode equations for temperature effects

$$IS(T) = IS \cdot e^{(T/Tnom-1) \cdot EG/(N \cdot Vt)} \cdot (T/Tnom)^{XTI/N}$$

$$ISR(T) = ISR \cdot e^{(T/Tnom-1) \cdot EG/(NR \cdot Vt)} \cdot (T/Tnom)^{XTI/NR}$$

$$IKF(T) = IKF \cdot (1 + TIKF \cdot (T-Tnom))$$

$$BV(T) = BV \cdot (1 + TBV1 \cdot (T-Tnom) + TBV2 \cdot (T-Tnom)^2)$$

$$RS(T) = RS \cdot (1 + TRS1 \cdot (T-Tnom) + TRS2 \cdot (T-Tnom)^2)$$

$$VJ(T) = VJ \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)$$

$$Eg(T) = silicon \ bandgap \ energy = 1.16 - .000702 \cdot T^2/(T+1108)$$

$$CJO(T) = CJO \cdot (1 + M \cdot (.0004 \cdot (T-Tnom) + (1-VJ(T)/VJ)))$$

Diode equations for noise

Noise is calculated assuming a 1.0-hertz bandwidth, using the following spectral power densities (per unit bandwidth).

parasitic resistance thermal noise

$$In^2 = 4 \cdot k \cdot T/(RS/area)$$

intrinsic diode shot and flicker noise

$$In^2 = 2 \cdot q \cdot Id + KF \cdot Id^{AF}/FREQUENCY$$

References

For a detailed description of p-n junction physics, refer to:

[1] A. S. Grove, *Physics and Technology of Semiconductor Devices*, John Wiley and Sons, Inc., 1967.

Also, for a generally detailed discussion of the U.C. Berkeley SPICE models, including the diode device, refer to, [2] P. Antognetti and G. Massobrio, *Semiconductor Device Modeling with SPICE*, McGraw-Hill, 1988.

Voltage-controlled voltage source

General form

```
E|G name node1 node2 controlling node1 controlling node2
+ gain
E<name><(+) node><(-) node><(+) controlling node><(-)
controlling node> <gain>
E<name> <(+) node> <(-) node> POLY(<value>)
+ < <(+) controlling node> <(-) controlling node> >*
+ < <polynomial coefficient value> >*
E<name> <(+) <node> <(-) node> VALUE = {<expression>}
+ [error= {<warn (<condition>, "<warning statement>")}
+ error= {<error (<condition>, "<error statement>")}]
E<name><(+)<node><(-) node> TABLE { <expression> } =
+ < <input value>, <output value> >*
E<name> <(+) node> <(-) node> LAPLACE { <expression> } =
+ { <transform> }
E<name> <(+) node> <(-) node> FREQ { <expression> } = [KEYWORD]
+ < <frequency value>, <magnitude value>, <phase value> >*
+ [DELAY = <delay value>]
+ [error= {<warn (<condition>, "<warning statement>")}
+ error= {<error (<condition>, "<error statement>")}]
E<name><(+) node><(-) node> CHEBYSHEV { <expression> } =
+ <[LP] [HP] [BP] [BR]>, <cutoff frequencies>*, <attenuation>*
+ [error= {<warn (<condition>, "<warning statement>")}
+ error= {<error (<condition>, "<error statement>")}]
```

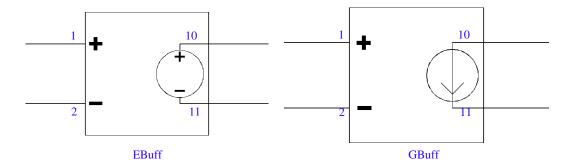
Analog Devices

Examples

```
EBUFF 10 11 1 2 1.0
EAMP 13 0 POLY(1) 26 0 0 500
ENONLIN 100 101 POLY(2) 3 0 4 0 0.0 13.6 0.2 0.005
ESQROOT 5 0 VALUE = \{5V*SQRT(V(3,2))\}
ET2 2 0 TABLE \{V(ANODE, CATHODE)\} = (0,0) (30,1)
ERC 5 0 LAPLACE \{V(10)\} = \{1/(1+.001*s)\}
ELOWPASS 5 0 FREQ \{V(10)\}=(0,0,0)(5kHz,0,0)(6kHz-60,0)
DELAY=3.2ms
ELOWPASS 5 0 CHEBYSHEV \{V(10)\} = LP 800 1.2K .1dB 50dB
Exy 0 7 F = 2*V(5)
Exy 3 0 FREQ VALUE = \{V(10) \mid EXP(1)*(2)/(S+2)\} error =
{warn(V(10)>10, "Voltage is greater than 10 volts.")}
Exy 3 0 FREQ VALUE = \{V(10) \mid EXP(1)*(2)/(S+2)\} error =
{error(V(10)>10, "Voltage greater than 10V. Cannot proceed.")}
GBUFF 10 11 1 2 1.0
GAMP 13 0 POLY(1) 26 0 0 500
GNONLIN 100 101 POLY(2) 3 0 4 0 0.0 13.6 0.2 0.005
GPSK 11 6 VALUE = {5MA*SIN(6.28*10kHz*TIME+V(3))}
GT ANODE CATHODE VALUE = \{200E-6*PWR(V(1)*V(2),1.5)\}
GLOSSY 5 0 LAPLACE \{V(10)\} = \{\exp(-\operatorname{sqrt}(C*s*(R+L*s)))\}
```

Description

The voltage-controlled voltage source (E) and the voltage-controlled current source (G) devices have the same syntax. For a voltage-controlled current source just substitute G for E. G generates a current, whereas E generates a voltage.



Analog Devices

Arguments and options

Analog Devices

POLY(<value>)

Specifies the number of dimensions of the polynomial. The number of pairs of controlling nodes must be equal to the number of dimensions.

(+) and (-) nodes

Output nodes. Positive current flows from the (+) node through the source to the (-) node.

<(+) controlling node> and <(-) controlling node>

Are in pairs and define a set of controlling voltages. A particular node can appear more than once, and the output and controlling nodes need not be different. The TABLE form has a maximum size of 2048 input/output value pairs.

FREQ

If a DELAY value is specified, the simulator modifies the phases in the FREQ table to incorporate the specified delay value. This is useful for cases of tables which the simulator identifies as being non-causal. When this occurs, the simulator provides a delay value necessary to make the table causal. The new syntax allows this value to be specified in subsequent simulation runs, without requiring the user to modify the table.

If a KEYWORD is specified for FREQ tables, it alters the values in the table.

The KEYWORD can be one of the following:

- MAG causes magnitude of frequency response to be interpreted as a raw value instead of dB.
- MAG_FILE, used instead of MAG, specifies frequency tables using a CSV (comma separated value) file. The external CSV file is specified as a parameter within double quotes.
- DB causes magnitude to be interpreted as dB (the default).
- RAD causes phase to be interpreted in radians.
- RAD_FILE, used instead of RAD, specifies frequency tables using a CSV (comma separated value) file. The external CSV file is specified as a parameter within double quotes.
- DEG causes phase to be interpreted in degrees (the default).
- R_I causes magnitude and phase values to be interpreted as real and imaginary magnitudes.

Analog Devices

R_I_FILE, used instead of R_I, specifies frequency tables using a CSV (comma separated value) file. The external CSV file is specified as a parameter within double quotes.

The keywords MAG_FILE, RAD_FILE, and R_I_FILE need the path to the external CSV file specified as a parameter within double quotes. Following are two examples:

This is an optional argument to be used when you want to throw a warning or an error message to the user. The warn and the error keywords indicate whether a warning or an error is to be displayed. While using this argument, ensure that the message statements are in one line. The message text should not be too long and entire argument including the message must be less than 132 characters.

During a simulation, if the warning condition specified in the Error statement is encountered, simulator displays the predefined warning message. In case error conditions are met, PSpice simulator will stop the simulation.

/Important

Special characters, such as semi colon (;), comma (,), parenthesis, and curly braces should not be used within the error and warning message statements. In case any of these characters is used in the message statement, PSpice simulator will throw an invalid expression error.



Error conditions are not supported for digital values

Comments

Analog Devices

The first form and the first two examples apply to the linear case; the second form and the third example are for the nonlinear case. The last five forms and examples are analog behavioral modeling (ABM) that have expression, look up table, Laplace transform, frequency response, and filtering. Refer to your *PSpice User Guide* for more information on analog behavioral modeling.

Chebyshev filters have two attenuation values, given in dB, which specify the pass band ripple and the stop band attenuation. They can be given in either order, but must appear after all of the cutoff frequencies have been given. Low pass (LP) and high pass (HP) have two cutoff frequencies, specifying the pass band and stop band edges, while band pass (BP) and band reject (BR) filters have four. Again, these can be given in any order.

Note: You can get a list of the filter Laplace coefficients for each stage by enabling the LIST option in the Simulation Settings dialog box. (Click the Options tab, then select the Output file Category and select Device Summary.) The output is written to the .out file after the simulation is complete.

For the linear case, there are two controlling nodes and these are followed by the gain. For all cases, including the nonlinear case (POLY), refer to your *PSpice User Guide*.

Expressions *cannot* be used for linear and polynomial coefficient values in a voltage-controlled voltage source device statement.

Analog Devices

Basic SPICE polynomial expressions (POLY)

PSpice A/D (and SPICE) use the following syntax:

```
<controlled source> <connecting nodes>
+ POLY(<dimension>) <controlling input> <coefficients>
```

where

| <controlled source=""></controlled> | is $<$ [E][F][G][H]device name>, meaning the device type is one of E, F, G, or H |
|--------------------------------------|--|
| <connecting nodes=""></connecting> | specifies <(+node_name, -node_name)> pair between which the device is connected |
| <dimension></dimension> | is the dimension <value> of the polynomial describing the controlling function</value> |
| <controlling input=""></controlling> | specifies <(+node_name, -node_name)>* pairs used as input to the voltage controlled source (device types E and G), or <v device="" name="">* for the current controlled source (device types F and H), and where the number of controlling inputs for either case equals <dimension></dimension></v> |
| <coefficients></coefficients> | specifies the coefficient <values>* for the polynomial transfer function</values> |

If the source is one-dimensional (there is only one controlling source), POLY(1) is required unless the linear form is used. If the source is multidimensional (there is more than one controlling source), the dimension needs to be included in the keyword, for instance POLY(2).

Caution must be exercised with the POLY form. For instance,

```
EWRONG 1 0 POLY(1) (1,0) .5 1.0
```

tries to set node 1 to .5 volts greater than node 1. In this case, any analyses which you specify will fail to calculate a result. In particular, PSpice A/D cannot calculate the bias point for a circuit containing EWRONG. This also applies to the VALUE form of EWRONG:

```
(EWRONG 1 0 VALUE = \{0.5 * V(1)\}).
```

Basic controlled source properties

| Part name | Property | Description |
|-------------------------------|----------|------------------------|
| Е | GAIN | gain |
| F | | gain |
| G | | transconductance |
| Н | | transresistance |
| EPOLY, FPOLY, GPOLY, HPOLY | COEFF | polynomial coefficient |

PSpice A/D has a built-in capability allowing controlled sources to be defined with a polynomial transfer function of any degree and any dimension. Polynomials have associated coefficients for each term. Consider a voltage-controlled source with voltages V_1 , V_2 , ... V_n . The coefficients are associated with the polynomial according to this convention:

The above is written for a voltage-controlled voltage source, but the form is similar for the other sources.

The POLY device types shown in <u>Basic controlled source properties</u> on page 179 are defined with a dimension of one, meaning there is only one controlling source. However, similar devices can be defined of any degree and dimension by creating parts with appropriate coefficient and TEMPLATE properties and the appropriate number of input pins.

The current-controlled device models (F, FPOLY, H, and HPOLY) contain a current-sensing voltage source. When netlisted, they generate two device declarations to the circuit file set: one for the controlled source and one for the independent current-sensing voltage source.

Analog Devices

When defining a current-controlled source part of higher dimension, the TEMPLATE property must account for the same number of current-sensing voltage sources (equal to the dimension value). For example, a two dimensional current-controlled voltage source is described by the following polynomial equation:

```
V_{out} = C_0 + C_1I_1 + C_2I_2 + C_{11}I_1^2 + C_{12}I_1I_2 + C_{22}I_2^2
```

To create the two dimensional HPOLY2 part, these properties must be defined:

The TEMPLATE definition is actually contained on a single line. The VH1 and VH2 fragments after the \n characters represent the device declarations for the two current-sensing voltage sources required by this part. Also, the part graphics must have the appropriate number of pins. When placing an instance of HPOLY2 in your schematic, the COEFF*n* properties must be appropriately set.

Implementation examples

Following are some examples of traditional SPICE POLY constructs and equivalent ABM parts which could be used instead.

Example 1: four-input voltage adder

This is an example of a device which takes four input voltages and sums them to provide a single output voltage.

The representative polynomial expression would be as follows:

```
V_{out} = 0.0 + (1.0)V_1 + (1.0)V_2 + (1.0)V_3 + (1.0)V_4
```

The corresponding SPICE POLY form would be as follows:

```
ESUM 100 101 POLY(4) (1,0) (2,0) (3,0) (4,0) 0.0 1.0 1.0 + 1.0 1.0
```

This could be represented with a single ABM expression device configured with the following expression properties:

```
EXP1 = V(1,0) + EXP2 = V(2,0) + EXP3 = V(3,0) + EXP4 = V(4,0)
```

Analog Devices

Following template substitution for the ABM device, the output becomes:

$$V(OUT) = \{ V(1,0) + V(2,0) + V(3,0) + V(4,0) \}$$

Example 2: two-input voltage multiplier

This is an example of a device which takes two input voltages and multiplies them together resulting in a single output voltage.

The representative polynomial expression would be as follows:

$$V_{out} = 0.0 + (0.0)V_1 + (0.0)V_2 + (0.0)V_1^2 + (1.0)V_1V_2$$

The corresponding SPICE POLY form would be as follows:

```
EMULT 100 101 POLY(2) (1,0) (2,0) 0.0 0.0 0.0 0.0 1.0
```

This could be represented with a single MULT device. For additional examples of a voltage multiplier device, refer to the Analog Behavioral Modeling chapter of your *PSpice User Guide*.

Example 3: voltage squarer

This is an example of a device that outputs the square of the input value.

For the one-dimensional polynomial, the representative polynomial expression reduces to:

Vout =
$$P_0 + P_1 \cdot V + P_2 \cdot V^2 + \dots P_n \cdot V^n$$

The corresponding SPICE POLY form would be as follows:

```
ESQUARE 100 101 POLY(1) (1,0) 0.0 0.0 1.0
```

This could be represented by a single instance of the MULT part, with both inputs from the same net. This results in the following:

$$V_{out} = (V_{in})^2$$

Current-controlled Voltage Source

General form F<name> <(+) node> <(-) node>

+ <controlling V device name> <gain>

F<name> <(+) node> <(-) node> POLY(<value>)

+ <controlling V device name>*

+ < <polynomial coefficient value> >*

Examples

FSENSE 1 2 VSENSE 10.0 FAMP 13 0 POLY(1) VIN 0 500

FNONLIN 100 101 POLY(2) VCNTRL1 VCINTRL2 0.0 13.6 0.2 0.005

Description

The Current-Controlled Current Source (F) and the Current-Controlled Voltage Source (H) devices have the same syntax. For a Current-Controlled Voltage Source just substitute an H for the F. The H device generates a voltage, whereas the F device generates a current.

Arguments and options

(+) and (-)

Output nodes. A positive current flows from the (+) node through the source to the (-) node. The current through the controlling voltage source determines the output current. The controlling source must be an independent voltage source (V device), although it need not have a zero DC value.

POLY(<value>)

Specifies the number of dimensions of the polynomial. The number of controlling voltage sources must be equal to the number of dimensions.

Comments

The first General form and the first two examples apply to the linear case. The second form and the last example are for the nonlinear case.

For the linear case, there must be one controlling voltage source and its name is followed by the gain. For all cases, including the nonlinear case (POLY), refer to your *PSpice User Guide*.

Note: In a current-controlled current source device statement, expressions cannot be used for linear and polynomial coefficient values.

Note: Defining controlling voltage device names for the voltage nodes results in incorrect output for the F devices. Therefore, controlling voltage device names should only be defined for the F devices.

Analog Devices

Basic SPICE polynomial expressions (POLY)

For more information on the POLY form, see <u>Basic SPICE polynomial expressions (POLY)</u> on page 178.

Analog Devices

Flux Source

General form

```
E<name> <(+) <node> <(-) node> F = { <expression> }

E<name> <(+) <node> <(-) node> F = { <expression> }
+ [error= {<warn (<condition>, "<warning statement>")} + error= {<error (<condition>, "<error statement>")}]
```

Examples

Description

The flux source can be modeled using a E- device. The output of a flux source modeled using a E device is a voltage calculated using the following equation.

$$V = \frac{d\phi}{dt}$$

where ϕ is the flux.

Arguments and options

```
(+) and (-) nodes
```

Output nodes. Positive current flows from the (+) node through the source to the (-) node.

F

Specifies a Flux source.

```
error= {<warn|error (<condition>, "<statement>")}
```

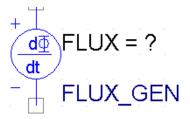
This is an optional argument to be used when you want to throw a warning or an error message to the user. The warn and the error keywords indicate whether a warning or an error is to be displayed.

During simulation if the condition specified in the Error statement gets violated, simulator displays the predefined error or the warning statement.

Analog Devices

Comments

To simulate a charge source, instantiate the FLUX_GEN part from the FUNCTION library in your design.



The value of the source is defined by the value of the CHARGE parameter.

Analog Devices

Charge source

General form

```
G<name> <(+) <node> <(-) node> Q = { <expression> }

G<name> <(+) <node> <(-) node> Q = { <expression> }
+ [error= {<warn (<condition>, "<warning statement>")}
+ error= {<error (<condition>, "<error statement>")}]
```

Examples

Gbc 2b 0 $Q=\{(1e-3)*V(2b)\}$

Description

A charge source can be modeled using a G device. The output of such a device is current source, calculated using the following equation.

$$I = \frac{dq}{dt}$$
 where q is the charge.

Arguments and options

(+) and (-) nodes

Output nodes. Positive current flows from the (+) node through the source to the (-) node.

Q

Specifies a voltage controlled charge source

```
error= {<warn|error (<condition>, "<statement>")}
```

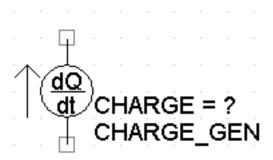
This is an optional argument to be used when you want to throw a warning or an error message to the user. The warn and the error keywords indicate whether a warning or an error is to be displayed.

During simulation if the condition specified in the Error statement gets violated, simulator displays the predefined error or the warning statement.

Analog Devices

Comments

To simulate a charge source, instantiate the CHARGE_GEN part from the FUNCTION library in your design.



The value of the source is defined by the value of the CHARGE parameter.

Analog Devices

Independent voltage source & stimulus

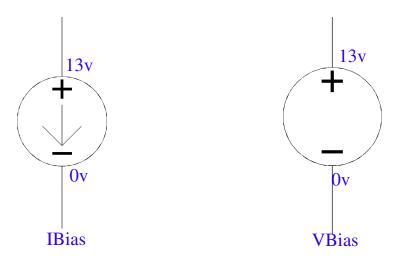
The independent current source & stimulus (I) and the independent voltage source & stimulus (V) devices have the same syntax. For an independent voltage source & stimulus just substitute a V for the I. The V device functions identically and has the same syntax as the I device, except that it generates voltage instead of current.

For information on independent current source and stimulus, see <u>Independent current source</u> <u>& stimulus</u>.

Independent current source & stimulus

Description

This element is a current source. Positive current flows from the (+) node through the source to the (-) node: in the first example, IBIAS drives node 13 to have a *negative* voltage. The default value is zero for the DC, AC, and transient values. None, any, or all of the DC, AC, and transient values can be specified. The AC phase value is in degrees. The pulse and exponential examples are explained later in this section.



Note: The independent current source & stimulus (I) and the independent voltage source & stimulus (V) devices have the same syntax. For an independent voltage source & stimulus just substitute a V for the I. The V device functions identically and has the same syntax as the I device, except that it generates voltage instead of current.

Analog Devices

The variables TSTEP and TSTOP, which are used in defaulting some waveform parameters, are set by the .TRAN (transient analysis) on page 121 command. TSTEP is <pri>print step value> and TSTOP is <final time value>. The .TRAN command can be anywhere in the circuit file; it need not come after the voltage source.

Arguments and options

<stimulus name>

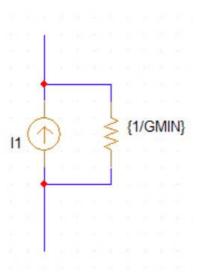
References a .STIMULUS (stimulus) on page 111 definition.

[transient specification]

| Use this value | To produce this result |
|---------------------------------------|--------------------------------|
| EXP (<parameters>)</parameters> | an exponential waveform |
| PULSE (<parameters>)</parameters> | a pulse waveform |
| PWL (<parameters>)</parameters> | a piecewise linear waveform |
| SFFM (<parameters>)</parameters> | a frequency-modulated waveform |
| SIN (<parameters>)</parameters> | a sinusoidal waveform |

Analog Devices

Note: For all independent current sources, PSpice adds GMIN by default across independent current sources to aid in convergence as shown in the following diagram:



To stop PSpice from adding GMIN across independent current sources, use the option: .OPTIONS NOGMINI

September 2023

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Analog Devices

Independent current source & stimulus (EXP)

General EXP (<i1> <i2> <td1> <tc1> <td2> <tc2>)

form

Examples IRAMP 10 5 EXP(1 5 1 .2 2 .5)

Waveform parameters

| Parameter | Description | Units | Default |
|-------------|---------------------------|-------|-------------------|
| <i1></i1> | Initial current | amp | none |
| <i2></i2> | Peak current | amp | none |
| <td1></td1> | Rise (fall) delay | sec | 0 |
| <tc1></tc1> | Rise (fall) time constant | sec | TSTEP |
| <td2></td2> | Fall (rise) delay | sec | <td1>+TSTEP</td1> |
| <tc2></tc2> | Fall (rise) time constant | sec | TSTEP |

Description

The EXP form causes the current to be <i1> for the first <td1> seconds. Then, the current decays exponentially from <i1> to <i2> using a time constant of <tc1>. The decay lasts td2-td1 seconds. Then, the current decays from <i2> back to <i1> using a time constant of <tc2>. Independent current source and stimulus, exponential waveform formulas on page 193 describe the EXP waveform.

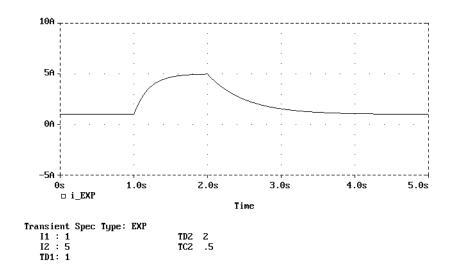


Table 2-3 Independent current source and stimulus, exponential waveform formulas

| Time period | Value |
|----------------------------|--|
| 0 to <td1></td1> | i1 |
| <td1> to <td2></td2></td1> | i1 + (i2-i1) · (1-e ^{-(TIME-td1)/tc1)} |
| <td2> to TSTOP</td2> | $i1 + (i2-i1) \cdot ((1-e^{-(TIME-td1)/tc1}) - (1-e^{-(TIME-td2)/tc2}))$ |

Parameters Supported for Exponential Sources

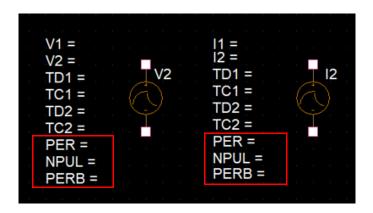
To model exponential voltage or a current source, two components, $\texttt{IEXP_B}$ and $\texttt{VEXP_B}$ are provided in source.olb. These components support the following parameters that you can configure, if required:

- PER: Defines the pulse period.
- NPUL: Defines the number of pulses in each burst.

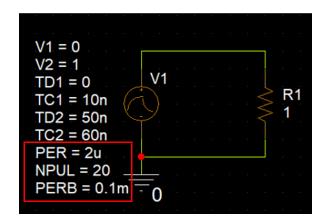
Analog Devices

PERB: Defines the repeat burst period.

The following figure shows the exponential voltage and current sources:

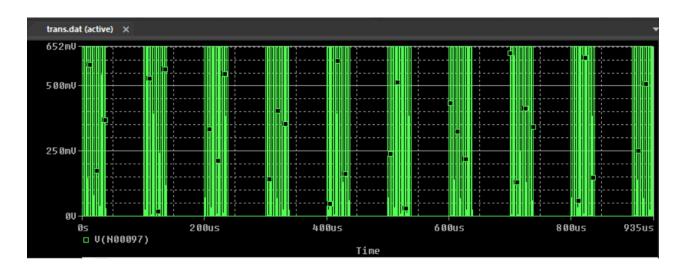


You can define pulse period (PER), number of pulse (NPUL) and repeat burst period (PERB) in a exponential voltage or a current source and use the model in a design as shown in the following example:



Analog Devices

Simulating this design shows a transient response of the enhanced exponential source V1.



Analog Devices

Independent current source & stimulus (PULSE)

General PULSE (<i1> <i2> <tf> <pw> <per>)

form

Examples ISW 10 5 PULSE(1A 5A 1sec .1sec .4sec .5sec 2sec)

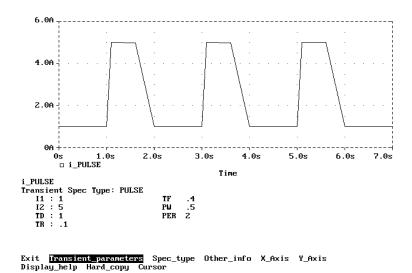
Waveform parameters

| Parameters | Description | Units | Default |
|-------------|-----------------|-------|---------|
| <i1></i1> | Initial current | amp | none |
| <i2></i2> | Pulsed current | amp | none |
| > | Delay | sec | 0 |
| <tf></tf> | Fall time | sec | TSTEP |
| | Rise time | sec | TSTEP |
| <pw></pw> | Pulse width | sec | TSTOP |
| <per></per> | Period | sec | TSTOP |

Analog Devices

Description

The PULSE form causes the current to start at <i1>, and stay there for seconds. Then, the current goes linearly from <i1> to <i2> during the next seconds, and then the current stays at <i2> for <pw> seconds. Then, it goes linearly from <i2> back to <i1> during the next <tf> seconds. It stays at <i1> for per-(tr+pw+tf) seconds, and then the cycle is repeated except for the initial delay of seconds. Independent current source and stimulus pulse waveform formulas describe the PULSE waveform.



Independent current source and stimulus pulse waveform formulas

| Time | Value |
|-------------|-------|
| 0 | i1 |
| td | i1 |
| td+tr | i2 |
| td+tr+pw | i2 |
| td+tr+pw+tf | i1 |
| td+per | i1 |
| td+per+tr | i2 |

Analog Devices

Default Value Usage of Zero Rise Time and Fall Time

With the rise time (Tr) or fall time (Tf) value of zero, an oblique trace can be seen in the output waveform if a time-point is not created immediately after the transition.

To avoid this situation, it is recommended that you set the default value to a non-zero positive integer for both Tr and Tf using the DEFTR and DEFTF options. For example, you can set the value as 10 nm for both Tr and Tf.

You can use the DISABLE_DEFAULT_PULSE_PARAMS variable to disable the default values of Tr and Tf.

Analog Devices

Independent current source & stimulus (PWL)

```
General
                  PWL
                  + [TIME SCALE FACTOR=<value>]
form
                  + [VALUE SCALE FACTOR=<value>]
                  + (corner_points) *
              where corner_points are:
              (<tn>, <in>) to specify a point
              FILE <filename>to read point values from a file
              REPEAT FOR <n> (corner_points)*
              ENDREPEATto repeat <n> times
              REPEAT FOREVER (corner_points)*
              ENDREPEATto repeat forever
Examples
                  v1 1 2 PWL (0,1) (1.2,5) (1.4,2) (2,4) (3,1)
                  \nabla 2
                          3 4 PWL REPEAT FOR 5 (1,0) (2,1) (3,0) ENDREPEAT
                          5,6 PWL REPEAT FOR 5 FILE DATA1.TAB
                  v3
                                  ENDREPEAT
                          7 8 PWL TIME SCALE FACTOR=0.1
                  \nabla 4
```

REPEAT FOREVER

ENDREPEAT

ENDREPEAT

n volt square wave (where *n* is 1, 2, 3, 4, then 5); 75% duty cycle; 10 cycles; 1 microseconds per cycle:

REPEAT FOR 5 FILE DATA1.TAB

REPEAT FOR 5 (1,0) (2,1) (3,0) ENDREPEAT

```
.PARAM N=1
.STEP PARAM N 1,5,1
V1 1 0 PWL
+ TIME_SCALE_FACTOR=1e-6; all time units are scaled to
+ microseconds
+ REPEAT FOR 10
+ (.25, 0)(.26, {N})(.99, {N})(1, 0)
+ ENDREPEAT
```

Analog Devices

5 volt square wave; 75% duty cycle; 10 cycles; 10 microseconds per cycle; followed by 50% duty cycle n volt square wave (where n is 1, 2, 3, 4, then 5) lasting until the end of simulation:

```
.PARAM N=.2
.STEP PARAM N
                  .2, 1.0, .2
V1 1 0 PWL
        TIME SCALE FACTOR=1e-5 ; all time units are
        scaled to \overline{10} us
        VALUE SCALE FACTOR=5
        REPEAT FOR \overline{1}0
        (.25, 0)(.26, 1)(.99, 1)(1, 0)
        ENDREPEAT
        REPEAT FOREVER
        (+.50, 0)
        (+.01, \{N\}); iteration time .51
        (+.48, \{N\}); iteration time .99
        (1, 0)
        ENDREPEAT
```

Assuming that a PWL specification has been given for a device to generate two triangular waveforms:

```
V3 1 0 PWL (1ms, 1) (2ms, 0) (3ms, 1) (4ms, 0)
```

Or, to replace the above with

```
V3 1 0 PWL FILE TRIANGLE.IN
```

where the file triangle.in would need to contain:

```
(1ms, 1) (2ms, 0) (3ms, 1) (4ms, 0)
```

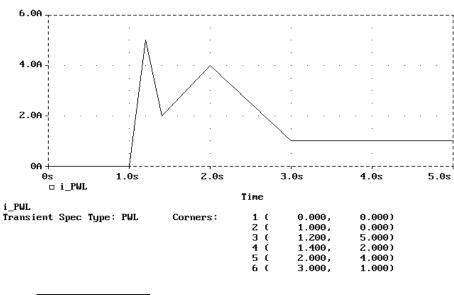
Waveform parameters

| Parameter ¹ | Description | Units | Default |
|------------------------|-----------------------|----------------------------|---------|
| <tn></tn> | time at corner | seconds | none |
| <vn></vn> | voltage at corner | volts | none |
| <n></n> | number of repetitions | positive integer, 0, or -1 | none |

1. <tn> and <n> cannot be expressions; <vn> may be an expression.

Description

The PWL form describes a piecewise linear waveform. Each pair of timecurrent values specifies a corner of the waveform. The current at times between corners is the linear interpolation of the currents at the corners.



Arguments and options

<time scale factor> and/or <value scale factor>

Can be included immediately after the PWL keyword to show that the time and/or current value pairs are to be multiplied by the appropriate scale factor. These scale factors can be expressions, in which case they are evaluated once per outer simulation loop, and thus should be composed of expressions not containing references to voltages or currents.

<tn> and <in>

The transient specification corner points for the PWL waveform, as shown in the first example. The <*in*> can be an expression having the same restrictions as the scaling keywords, but <*tn*> must be a literal.

Analog Devices

<file name>

The text file that supplies the time-current ($\langle tn \rangle \langle in \rangle$) pairs. The contents of this file are read by the same parser that reads the circuit file, so that engineering units (e.g., 10us) are correctly interpreted. Note that the continuation + signs in the first column are unnecessary and therefore discouraged.

A typical file can be created by editing an existing PWL specification, replacing all + signs with blanks (to avoid unintentional +time). Only numbers (with units attached) can appear in the file; expressions for < tn > and < n > values are invalid. All absolute time points in < file name> are with respect to the last (< tn > < in >) entered. All relative time points are with respect to the last time point.

REPEAT ... ENDREPEAT

These loops permit repetitions.

They can appear anywhere a (<tn> <in>) pair can appear. Absolute times within REPEAT loops are with respect to the start of the current iteration. The REPEAT ... ENDREPEAT specifications can be nested to any depth. Make sure that the current value associated with the beginning and ending time points (within the same REPEAT loop or between adjacent REPEAT loops), are the same when 0 is specified as the first point in a REPEAT loop.

<*n*>

A REPEAT FOR -1 ... ENDREPEAT is treated as if it had been REPEAT FOREVER ... ENDREPEAT. A REPEAT FOR 0 ... ENDREPEAT is ignored (other than syntax checking of the enclosed corner points).

Independent current source & stimulus (SFFM)

General SFFM (<ioff> <iampl> <fc> <mod> <fm>)

form

September 2023

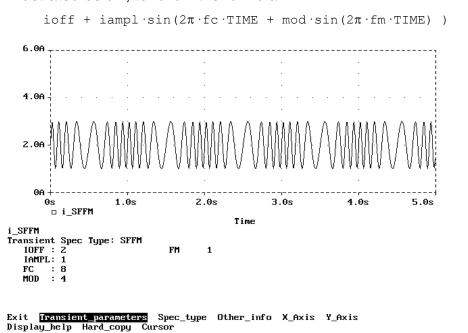
© 2023

Examples IMOD 10 5 SFFM(2 1 8Hz 4 1Hz)

Waveform parameters

| Parameters | Description | Units | Default |
|-------------------|---------------------------|-------|-----------------|
| <ioff></ioff> | offset current | amp | none |
| <iampl></iampl> | peak amplitude of current | amp | none |
| <fc></fc> | carrier frequency | hertz | 1/TSTOP |
| <mod></mod> | modulation index | | 0 |
| <fm></fm> | modulation frequency | hertz | 1 /TSTOP |

Description The SFFM (Single-Frequency FM) form causes the current, as illustrated below, to follow the formula:



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Analog Devices

Independent current source & stimulus (SIN)

Examples ISIG 10 5 SIN(2 2 5Hz 1sec 1 30)

Multiple SIN sources can be used in conjunction with switches and controlled sources to generate speific

waveforms. For example, to generate 0v till 10ms;10v and 50Hz for 2 cycles; then 20v and 50Hz for 2 cycles; followed

by 10v **and** 50Hz:

v1 1 2 SIN 0 10 50 10m 0 0 v2 2 3 SIN 0 10 50 50m 0 0 v3 3 0 SIN 0 -10 50 90m 0 0

R1 1 0 1

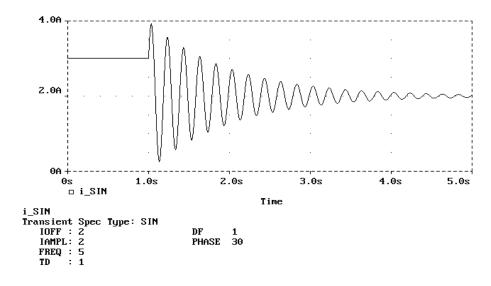
Waveform parameters

| Parameters | Description | Units | Default |
|-----------------|---------------------------|--------|-----------------|
| <ioff></ioff> | offset current | amp | none |
| <iampl></iampl> | peak amplitude of current | amp | none |
| <freq></freq> | frequency | hertz | 1 /TSTOP |
| | delay | sec | 0 |
| <df></df> | damping factor | SeC-1 | 0 |
| <phase></phase> | phase | degree | 0 |

Description

The sinusoidal (SIN) waveform causes the current to start at <ioff> and stay there for seconds.

Then, the current becomes an exponentially damped sine wave. Independent current source and stimulus sinusoidal waveform formulas describe the SIN waveform.



The SIN waveform is *for transient analysis only*. It does not have any effect on AC analysis. To give a value to a current during AC analysis, use an AC specification, such as:

```
IAC 3 0 AC 1mA
```

where IAC has an amplitude of one milliampere during AC analysis, and can be zero during transient analysis. For transient analysis use, for example:

```
ITRAN 3 0 SIN(0 1mA 1kHz)
```

where ITRAN has an amplitude of one milliampere during transient analysis and is zero during AC analysis. Refer to your *PSpice User Guide*.

Analog Devices

Table 2-4 Independent current source and stimulus sinusoidal waveform formulas

| Time period | Value |
|-------------|---|
| to | $ioff+iampl \cdot sin(2\pi \cdot phase/360°)$ |
| to TSTOP | $ioff+iampl \cdot sin (2\pi \cdot (freq \cdot (TIME-td) + phase/360°)) \cdot e^{-(TIME-td) \cdot df}$ |

Junction FET

General J<name> <drain node> <gate node> <source node> <model name>

+[area value] form

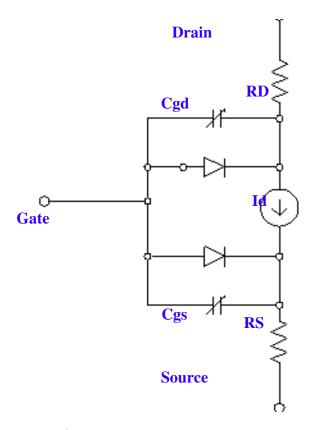
Examples JIN 100 1 0 JFAST J13 22 14 23 JNOM 2.0

Model form .MODEL <model name> NJF [model parameters] .MODEL <model name> PJF [model parameters]

Description The JFET is modeled as an intrinsic FET using an ohmic resistance (RD/

> area) in series with the drain, and using another ohmic resistance (RS/ area) in series with the source. Positive current is current flowing into a

terminal.



Arguments and options

[area value]

The relative device area. It has a default value of 1.0.

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Analog Devices

parts

The following table lists the set of JFET breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

| Part name | Model type | Property | Property description |
|-----------|------------|---------------|---------------------------------------|
| JBREAKN | NJF | AREA MODEL | area scaling factor NJF model name |
| JBREAKP | PJF | AREA MODEL | area scaling factor PJF model name |

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter. For more information, see <u>Model parameters</u>.

PSpice A/D Reference Guide Analog Devices

Model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-----------|---------|
| AF | flicker noise exponent | | 1 |
| ALPHA | ionization coefficient | volt-1 | 0 |
| BETA | transconductance coefficient | amp/volt2 | 1E-4 |
| BETATCE | BETA exponential temperature coefficient | %/°C | 0 |
| CGD | zero-bias gate-drain p-n capacitance | farad | 0 |
| CGS | zero-bias gate-source p-n capacitance | farad | 0 |
| FC | forward-bias depletion capacitance coefficient | | 0.5 |
| IS | gate <i>p-n</i> saturation current | amp | 1E-14 |
| ISR | gate p-n recombination current parameter | amp | 0 |
| KF | flicker noise coefficient | | 0 |
| LAMBDA | channel-length modulation | volt-1 | 0 |
| M | gate <i>p-n</i> grading coefficient | | 0.5 |
| N | gate <i>p-n</i> emission coefficient | | 1 |
| NR | emission coefficient for isr | | 2 |
| PB | gate <i>p-n</i> potential | volt | 1.0 |
| RD | drain ohmic resistance | ohm | 0 |
| RS | source ohmic resistance | ohm | 0 |
| T_ABS | absolute temperature | °C | |
| $T_{MEASURED}$ | measured temperature | °C | |
| T_REL_GLOBAL | relative to current temperature | °C | |
| T_REL_LOCAL | relative to AKO model temperature | °C | |
| VK | ionization knee voltage | volt | 0 |
| VTO | threshold voltage | volt | -2.0 |
| VTOTC | VTO temperature coefficient | volt/°C | 0 |

Analog Devices

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|----------------------------|-------|---------|
| XTI | IS temperature coefficient | | 3 |

^{1.} For information on $T_MEASURED$, T_ABS , T_REL_GLOBAL , and T_REL_LOCAL , see.MODEL (model definition) on page 57..

Note: VTO < 0 means the device is a depletion-mode JFET (for both N-channel and P-channel) and VTO > 0 means the device is an enhancement-mode JFET. This conforms to U.C. Berkeley SPICE.

Analog Devices

JFET equations

The equations in this section describe an N-channel JFET. For P-channel devices, reverse the sign of all voltages and currents.

The following variables are used:

```
Vgs
       = intrinsic gate-intrinsic source voltage
Vgd
       = intrinsic gate-intrinsic drain voltage
Vds
       = intrinsic drain-intrinsic source voltage
Cgs
       = gate-source capacitance
Cgd
       = gate-drain capacitance
Vt
       = k \cdot T/q (thermal voltage)
k
       = Boltzmann's constant
q
       = electron charge
Т
       = analysis temperature (°K)
Tnom = nominal temperature (set using TNOM option)
```

Other variables are listed in Model parameters.

Note: Positive current is current flowing into a terminal (for example, positive drain current flows from the drain through the channel to the source).

JFET equations for DC current

All levels

```
Ig = gate current = area (Igs + Igd)
Igs = gate-source leakage current = In + Ir · Kg
In = normal current = IS · (e<sup>Vgs/(N·Vt)</sup>-1)
Ir = recombination current = ISR · (e<sup>Vgs/(NR·Vt)</sup>-1)
Kg = generation factor = ((1-Vgs/PB)<sup>2</sup>+0.005)<sup>M/2</sup>
Igd = gate-drain leakage current = In + Ir · Kg + Ii
```

Analog Devices

```
In = normal current = IS \cdot (e^{Vgd/(N \cdot Vt)}-1)
            Ir = recombination current = ISR \cdot (e^{Vgd/(NR \cdot Vt)} - 1)
           Kg = generation factor = ((1-Vgd/PB)^2+0.005)^{M/2}
            Ii = impact ionization current
               for forward saturation region:
                      0 < Vqs-VTO < Vds
                then: Ii = Idrain·ALPHA·vdif·e^{-VK/vdif}
                  where vdif = Vds - (Vqs-VTO)
                else: Ii = 0
    Id = drain current = area · (Idrain-Igd)
    Is = source current = area · (-Idrain-Igs)
All levels: Idrain
    Normal mode: Vds \ge 0
        Case 1
            for cutoff region: Vgs-VTO ≤ 0
             then Idrain = 0
        Case 2
            for linear region: Vds < Vgs-VTO
              then: Idrain = BETA · (1+LAMBDA · Vds) · Vds · (2 · (Vgs - VTO) - Vds)
        Case 3
            for saturation region: 0 < Vgs-VTO < Vds
             then: Idrain = BETA · (1+LAMBDA · Vds) · (Vgs-VTO)<sup>2</sup>
    Inverted mode: Vds < 0
```

Switch the source and drain in the normal mode equations above.

JFET equations for capacitance

All capacitances are between terminals of the intrinsic JFET (that is, to the inside of the ohmic drain and source resistances).

Analog Devices

Gate-source depletion capacitance

For:
$$Vgs \le FC \cdot PB$$

 $Cgs = area \cdot CGS \cdot (1 - Vgs/PB)^{-M}$
For: $Vgs > FC \cdot PB$
 $Cgs = area \cdot CGS \cdot (1 - FC)^{-(1+M)} \cdot (1 - FC \cdot (1+M) + M \cdot Vgs/PB)$

Gate-drain depletion capacitance

JFET equations for temperature effects

The drain and source ohmic (parasitic) resistances have no temperature dependence.

```
\label{eq:total_variation} \begin{split} \text{VTO}\left(\mathbf{T}\right) &= \text{VTO+VTOTC}\cdot\left(\mathbf{T-Tnom}\right) \\ \text{BETA}\left(\mathbf{T}\right) &= \text{BETA}\cdot\mathbf{1}.01 \\ \text{BETATCE}\cdot\left(\mathbf{T-Tnom}\right) \\ \text{IS}\left(\mathbf{T}\right) &= \text{IS}\cdot\boldsymbol{e}^{\left(\mathbf{T/Tnom-1}\right)\cdot\text{EG/(N\cdot Vt)}}\cdot\left(\mathbf{T/Tnom}\right) \\ \text{Where EG} &= 1.11 \\ \text{ISR}\left(\mathbf{T}\right) &= \text{ISR}\cdot\boldsymbol{e}^{\left(\mathbf{T/Tnom-1}\right)\cdot\text{EG/(NR\cdot Vt)}}\cdot\left(\mathbf{T/Tnom}\right) \\ \text{Where EG} &= 1.11 \\ \text{PB}\left(\mathbf{T}\right) &= \text{PB}\cdot\mathbf{T/Tnom} - 3\cdot\text{Vt}\cdot\boldsymbol{ln}\left(\mathbf{T/Tnom}\right) - \text{Eg}\left(\mathbf{Tnom}\right)\cdot\mathbf{T/Tnom} + \text{Eg}\left(\mathbf{T}\right) \\ \text{Where} \\ &= \text{Eg}\left(\mathbf{T}\right) = \text{silicon bandgap energy} = 1.16 - .000702\cdot\mathbf{T}^2/\left(\mathbf{T+1108}\right) \\ \text{CGS}\left(\mathbf{T}\right) &= \text{CGS}\cdot\left(1+\mathbf{M}\cdot\left(.0004\cdot\left(\mathbf{T-Tnom}\right)+\left(1-\mathbf{PB}\left(\mathbf{T}\right)/\mathbf{PB}\right)\right)\right) \\ \text{CGD}\left(\mathbf{T}\right) &= \text{CGD}\cdot\left(1+\mathbf{M}\cdot\left(.0004\cdot\left(\mathbf{T-Tnom}\right)+\left(1-\mathbf{PB}\left(\mathbf{T}\right)/\mathbf{PB}\right)\right)\right) \end{split}
```

Analog Devices

JFET equations for noise

Noise is calculated assuming a 1.0-hertz bandwidth, using the following spectral power densities (per unit bandwidth).

Parasitic resistance thermal noise

Is²=
$$4 \cdot k \cdot T / (RS/area)$$

Id²= $4 \cdot k \cdot T / (RD/area)$

Intrinsic JFET shot and flicker noise

Idrain²=
$$4 \cdot k \cdot \text{T} \cdot \text{gm} \cdot 2/3 + \text{KF} \cdot \text{Idrain}^{AF}/\text{FREQUENCY}$$

where gm = $d \cdot \text{Idrain}/d \cdot \text{Vgs}$ (at the DC bias point)

Reference

For more information about the U.C. Berkeley SPICE models, including the JFET device, refer to:

[1] P. Antognetti and G. Massobrio, *Semiconductor Device Modeling with SPICE*, McGraw-Hill, 1988.

Analog Devices

Coupling

General form

K<name> L<inductor name> <L<inductor name>>* <coupling</pre>

value>

 $\label{eq:Kname} $$K<name> < L<inductor name>>* <coupling value> <model$

name> [size value]

K<name>T<transmission line name>T<transmission line

name>

+ Cm=<capacitive coupling> Lm=<inductive coupling>

Examples

KTUNED L3OUT L4IN .8

KTRNSFRM LPRIMARY LSECNDRY 1

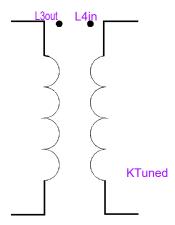
KXFRM L1 L2 L3 L4 .98 KPOT_3C8

K2LINES T1 T2 Lm=1m Cm=.5p

Model form

.MODEL <model name> CORE [model parameters]

Description



This device can be used to define coupling between inductors (transformers) or between transmission lines. This device also refers to a nonlinear magnetic core (CORE) model to include magnetic hysteresis effects in the behavior of a single inductor (winding), or in multiple coupled windings.

Analog Devices

Inductor coupling

Arguments and options

K<name> L<inductor name>

Couples two or more inductors.

Using the "Dot" convention, place a "DOT" on the first node of each inductor. For example:

```
I1 1 0 AC 1mA
L1 1 0 10uH
L2 2 0 10uH
R2 2 0 .1
K12 L1 L2 1
```

The current through L2 is in the opposite direction as the current through L1. The polarity is determined by the order of the nodes in the L devices and not by the order of inductors in the K statement.

```
<coupling value>
```

This is the coefficient of mutual coupling, which must be between 0 and 1.0.

This coefficient is defined by the equation

```
<coupling value> = Mij/(Li \cdot Lj)^{1/2}
```

where

 $L_i, L_j = a$ coupled-pair of inductors

 M_{ij} = the mutual inductance between L_i and L_j

For transformers of normal geometry, use 1.0 as the value. Values less than 1.0 occur in air core transformers when the coils do not completely overlap.

Analog Devices

<model name>

If <model name> is present, four things change:

- The mutual coupling inductor becomes a nonlinear, magnetic core device. The magnetic core's B-H characteristics are analyzed using either the Jiles-Atherton model (see Inductor coupling: Jiles-Atherton model) or the Spice Plus model (see Inductor coupling: Spice Plus model.").
- The inductors become windings, so the number specifying inductance now specifies the number of turns.
- The list of coupled inductors could be just one inductor.
- A model statement is required to specify the model parameters.

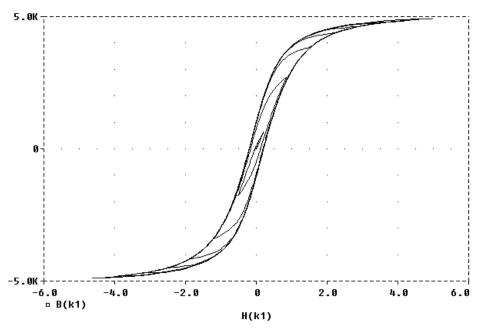
[size value]

Has a default value of 1.0 and scales the magnetic cross-section. It is intended to represent the number of lamination layers, so only one model statement is needed for each lamination type. For example:

```
L1 5 9 20 ; inductor having 20 turns
K1 L1 1 K528T500_3C8; Ferroxcube toroid core
L2 3 8 15 ; primary winding having
; 15 turns
L3 4 6 45 ; secondary winding having
; 45 turns
K2 L2 L3 1 K528T500_3C8; another core (not the same as K1)
```

Analog Devices

Here is a Probe B-H display of 3C8 ferrite (Ferroxcube).



Comments

The linear branch relation for transient analysis is

$$V_{i} = L_{i} \cdot \frac{dI_{i}}{dt} + M_{ij} \cdot \frac{dI_{j}}{dt} + M_{ik} \cdot \frac{dI_{k}}{dt} + \cdots$$

For U.C. Berkeley SPICE2: if there are several coils on a transformer, then there must be K statements coupling all combinations of inductor pairs. For instance, a transformer using a center-tapped primary and two secondaries could be written:

* PRIMARY
L1 1 2 10uH
L2 2 3 10uH
* SECONDARY
L3 11 12 10uH
L4 13 14 10uH
* MAGNETIC COUPLING
K12 L1 L2 1
K13 L1 L3 1
K14 L1 L4 1
K23 L2 L3 1
K24 L2 L4 1
K34 L3 L4 1

Analog Devices

This older technique is still supported, but *not required*, for simulation. The same transformer can also be written:

```
* PRIMARY
L1 1 2 10uH
L2 2 3 10uH
* SECONDARY
L3 11 12 10uH
L4 13 14 10uH
* MAGNETIC COUPLING
KALL L1 L2 L3 L4 1
```

Note: Do not mix the two techniques.

The simulator uses either the Jiles-Atherton model (see <u>2-4</u>) or SpicePlus model (see "Inductor coupling: Spice Plus model.") to analyze the B-H curve of the magnetic core and calculate values for inductance and flux for each of the windings.

The state of the nonlinear core can be viewed in Probe by specifying B(Kxxx) for the magnetization or H(Kxxx) for the magnetizing influence. These values are not available for .PRINT (print) on page 91 or .PLOT (plot) on page 89 output.

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Analog Devices

parts

See *PSpice User Guide* for information about using nonlinear magnetic cores with transformers.

| Part name | Model type | Property | Property description |
|----------------|-------------|----------------------|---|
| XFRM_LINEAR | transformer | L1_VALUE L2_VALUE | winding inductances in Henries |
| | | COUPLING | coefficient of mutual coupling (must lie between 0 and 1) |
| K_LINEAR | transformer | Ln | inductor reference designator |
| XFRM_NONLINEAR | transformer | L1_TURNS L2_TURNS | number of turns on each winding |
| | | COUPLING | coefficient of mutual coupling (must lie between 0 and 1) |
| | | MODEL | nonlinear CORE model name |

Breakout parts

For non-stock passive and semiconductor devices, provides a set of breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters. Another approach is to use the model editor to derive an instance model and customize this. For example, you could add device and/or lot tolerances to model parameters.

Basic breakout part names consist of the intrinsic PSpice A/D device letter plus the suffix BREAK. By default, the model name is the same as the part name and references the appropriate device model with all parameters set at their default. For instance, the DBREAK part references the DBREAK model which is derived from the intrinsic PSpice A/D D model (.MODEL DBREAK D)

Analog Devices

Using the KBREAK part

The inductor coupling part, KBREAK, can be used to couple up to six independent inductors on a schematic. A MODEL property is provided for using nonlinear magnetic core (CORE) models, if desired. By default, KBREAK references the KBREAK model contained in breakout.lib; this model, in turn, uses the default CORE model parameters.

| Device type | Part name | Part library | Property | Description |
|----------------------|--------------|--------------|--------------|-------------------------------------|
| inductor coupling | KBREAK | breakout | COUPLIN G | coupling factor |
| | | | Li | inductor reference designator |

The KBREAK part can be used to:

- Provide linear coupling between inductors.
- Reference a CORE model in a configured model library file.
- Define a user-defined CORE model with custom model parameter values.

The dot convention for the coupling is related to the direction in which the inductors are connected. The dot is always next to the first pin to be netlisted. For example, when the inductor part L is placed without rotation, the dotted pin is the left one. Rotate on the Edit menu (C+r) rotates the inductor +90°, making this pin the bottom pin.

For nonlinear coupling

L1 (inductor) must have a value; the rest may be left blank. The model must reference a CORE model such as those contained in MAGNETIC.LIB or other user-defined models. To specify the CORE model, use the Implementation property in *Property Editor*. The inductor value is set to the number of windings.

For linear coupling

L1 and at least one other Li must have values; the rest may be left blank. For linear coupling, the model reference, which is the Implementation property in *Property Editor* must be blank. If you specify a value for the Implementation property, the model is referred to with this value and the coupling becomes non-linear. The value of Li must be in Henries.

Analog Devices

Inductor coupling (and magnetic core)

PSpice supports two models for inductor coupling. These are:

- Inductor coupling: Jiles-Atherton model on page 222
- Inductor coupling: Spice Plus model on page 224

Inductor coupling: Jiles-Atherton model

In PSpice, the Jiles-Atherton model is supported as level 2 model. The model parameters are listed below.

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-------------------------------------|-----------------|---------|
| A | Thermal energy parameter | amp/meter | 1E+3 |
| AREA | Mean magnetic cross-section | cm ² | 0.1 |
| C | Domain flexing parameter | | 0.2 |
| GAP | Effective air-gap length | cm | 0 |
| K | Domain anisotropy parameter | amp/meter | 500 |
| LEVEL | Model index | | 2 |
| MS | Magnetization saturation | amp/meter | 1E+6 |
| PACK | Pack ² (stacking) factor | | 1.0 |
| PATH | Mean magnetic path length | cm | 1.0 |

- 1. See .MODEL (model definition) on page 57.
- 2. Flux is proportional to PACK.

The Jiles-Atherton model is based on existing ideas of domain wall motion, including flexing and translation. The model derives an anhysteric magnetization curve by using a mean field technique, in which any domain is coupled to the magnetic field ($\mathbb H$) and the bulk magnetization ($\mathbb M$). This anhysteric value is the magnetization that would be reached in the absence of domain wall pinning. Hysteresis is modeled by the effects of pinning of domain walls on material defect sites. This impedance to motion and flexing due to the differential field exhibits all of the main features of real, nonlinear magnetic devices, such as the initial magnetization curve (initial permeability), saturation of magnetization, coercivity, and hysteresis loss.

Analog Devices

A magnetic material that is comprised of loosely coupled domains has an equilibrium B-H curve, called the anhysteric. This curve is the locus of B-H values generated by superimposing a DC magnetic bias and a large AC signal that decays to zero. It is the curve representing minimum energy for the domains and is modeled, in theory, by

$$M_{an} = MS \cdot H / (|H| + A)$$

where

 $M_{\rm an}$ = the anhysteric magnetization

MS= the saturation magnetization

H =the magnetizing influence (after GAP correction)

A = a thermal energy parameter

For a given magnetizing influence (H), the anhysteric magnetization is the global flux level the material would attain if the domain walls could move freely. The walls, however, are stopped or pinned on dislocations in the material. The wall remains pinned until enough magnetic potential is available to break free, and travel to the next pinning site. The theory supposes a mean energy required, per volume, to move domain walls. This is analogous to mechanical drag. A simplified equation of this is

```
change-in-magnetization = potential/drag
```

The irreversible domain wall motion can, therefore, be expressed as

$$dM_{irr}/dH = (M_{an} - M)/K$$

where K is the pinning energy per volume (drag).

Reversible wall motion comes from flexing in the domain walls, especially when it is pinned at a dislocation due to the magnetic potential (that is, the magnetization is not the anhysteric value).

The theory supposes spherical flexure to calculate energy values and arrives at the (simplified) equation:

$$dM_{rev}/dH = C \cdot d(M_{an}-M)/dH$$

where C is the domain flexing parameter.

The equation for the total magnetization is the sum of these two state equations:

$$dM/dH = (1/(1 + C)) \cdot (M_{an} - M)/K) + (C/(1 + C)) \cdot dM_{an}/dH$$

Including air-gap effects in the inductor coupling model

If the gap thickness is small compared with the other dimensions of the core, you can assume that all of the magnetic flux lines go through the gap directly and that there is little fringing flux

Analog Devices

(having a modest amount of fringing flux only increases the effective air-gap length). Checking the field values around the entire magnetic path gives the equation:

```
Hcore ·Lcore + Hgap ·Lgap = n ·I
```

where n·I is the sum of the amp-turns of the windings on the core. Also, the magnetization in the air-gap is negligible, so that Bgap = Hgap and Bgap = Bcore. These combine in the previous equation to yield:

```
Hcore ·Lcore + Bcore ·Lgap = n ·I
```

This is a difficult equation to solve, especially for the Jiles-Atherton model, which is a state equation model rather than an explicit function (which one would expect, because the B-H curve depends on the history of the material). However, there is a graphical technique that solves for Bcore and Hcore, given $n \cdot I$, which is to:

- **1.** Take the non-gapped B-H curve.
- **2.** Extend a line from the current value of $n \cdot I$ having a slope of -Lcore/Lgap (this would be vertical if Lgap = 0).
- **3.** Find the intersection of the line using the B-H curve.

The intersection is the value for Bcore and Hcore for the $n \cdot I$ of the gapped core. The $n \cdot I$ value is the apparent or external value of Hcore, but the real value of Hcore is less. The result is a smaller value for Bcore and for the sheared-over B-H curves of a gapped core. The simulator implements the numerical equivalent of this graphical technique.

The resulting B-H values are recorded in the Probe data file as B_{core} and H_{apparent}.

Getting core inductor coupling model values

Characterizing core materials can be performed using Parts, and verified by using PSpice and Probe. The model uses MKS (metric) units, however the results for Probe are converted to Gauss and Oersted, which can be displayed using $B(K\times X\times X)$ and $B(K\times X\times X)$. The traditional B-H curve is made by a transient run, ramping current through a test inductor, then displaying $B(K\times X\times X)$ and setting the X axis to $B(K\times X\times X)$.

For more information on the Jiles-Atherton model, see Reference [1] of References on page 231.

Inductor coupling: Spice Plus model

Spice Plus models are treated as level 3 models in PSpice.

Winding in Spice Plus models

Analog Devices

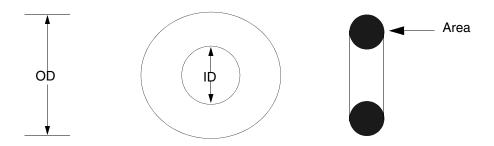
In PSpice windings are expressed using the L device.

The general syntax used is:

The magnetic core model parameters based on Spice plus model are listed below:

| Model parameters | Description | Units | Default |
|------------------|--------------------------------|-----------------|---------|
| OD | Outer diameter | cm | 1 |
| ID | Inner diameter | cm | 0 |
| AREA | Effective cross sectional area | cm ² | 1 |
| GAP | Effective core air gap length | cm | NULL |
| BR | Residual flux density | Gauss | 1000 |
| ВМ | Saturated flux density | Gauss | 2000 |
| HC | Coercive magnetic force | Oersted | 0.2 |

For Nonlinear Ferrite cores path length represented by LENGTH is used instead of the inner and outer diameters. The following figure illustrates the diameters and area specifications. Geometry of Cores



The formula used to calculate magnetic path length is:

$$(\underline{OD + ID}) \pi$$

Apart from the magnetic path length calculation, there is no difference between the toroidal and nonlinear ferrite core models.

Analog Devices

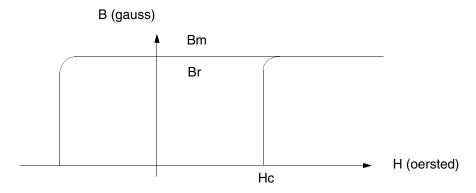
Defining Static Behavior

In Spice Plus core models, following three parameters describe the DC hysteresis loop:

- *Br* is the permanent flux density (where the loop intersects the y-axis).
- \blacksquare Bm is the saturation flux density.
- \blacksquare Hc is the coercive magnetic force at 0 (where the loop intersects the x-axis).

These parameters must be specified in CGS (centimeter-gram-second) units. The figure below illustrates the static B-H hysteresis loop parameters.

Figure 2-1 Static B-H Loop Parameters



Converting Units

You can use the following table to convert units in data sheets to the unit used in the menu, and vice-versa. The table gives conversion factors for changing between MKS, CGS, and FPS units.

| Magnetic Quantity | Data Sheet Units | Menu Units |
|-------------------|-------------------------|-------------------------|
| Н | 1 amp-turn per inch | 0.495 oersteds |
| Н | 1 amp-turn per cm | 1.257 oersteds |
| В | 1 line per square inch | 0.155 gauss |
| В | 1 tesla | 10,000 gauss |
| В | 1 maxwell per square cm | 1 gauss |
| | Menu Units | Data Sheet Units |
| Н | 1 oersted | 2.02 amp-turns per inch |

Analog Devices

| Magnetic Quantity | Data Sheet Units | Menu Units |
|-------------------|------------------|-----------------------------|
| Н | 1 oersted | 0.796 amp-turns per cm |
| В | 1 gauss | 6.452 lines per square inch |
| В | 1 gauss | 1/10,000 tesla |
| В | 1 gauss | 1 maxwell per square cm |

Core Model Theory

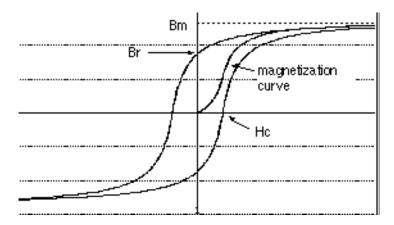
The ideal core has no current or voltage dependency; it is perfectly linear and never saturates. In a core constructed out of non-linear material, however, the effective inductance of a coil depends upon the current through the coil and on the history of the magnetizing currents applied to the coil. The permeability (change in flux density per change in magnetic field strength) varies as a function of magnetic field strength, and depends upon the previous application of magnetic fields.

To describe the behavior of a non-linear material, the flux density (B) is plotted as a function of field strength (H). In such a representation, the permeability (μ) is the slope of the B-H curve. Assuming an initially demagnetized core, the flux density rises steeply as field strength increases, until the saturation region of the material is approached. Physically, saturation of a non-linear material occurs as the majority of magnetic moments within the core become aligned with the magnetic field. Upon saturation, the flux density reaches a limiting value (Bm) which remains constant with further increases in field strength.

If the field strength is reduced following saturation of the core, the B-H curve follows a different path, returning to a positive finite value of magnetization as H falls to zero. The flux density remaining in the core following saturation defines the remanent point (Br) of the B-H curve. To reduce the value of B to zero once the core has been magnetized, a negative field strength must be applied to the material. The value of the field strength required to return the flux density to zero defines the coercive point (Hc) of the B-H loop.

The B-H characteristic of a magnetic material forms a symmetrical curve, so that if the magnetic field strength is increased in the negative direction, the flux density eventually reaches a limiting value of negative Bm. Like the positive characteristic, the negative B-H curve returns to a remaining point (minus Br) when H is reduced to zero, and requires a magnetic field of value Hc to return the magnetic flux density to zero. The total B-H characteristic of a material will form a hysteresis loop, as shown in <u>Figure 2-2</u>.

Figure 2-2 Hysteresis Loop Depicting B-H Characteristics of a Ferrite Core Material



Limitations of Spice Plus Core Model

The following limitations apply Spice Plus level3 core model:

- 1. The Spice Plus cores are static DC models. Frequency of operation during the simulation does not affect the B-H characteristic.
- 2. The Spice Plus core model defines saturation flux density (Bm) as an asymptote, or limiting value to the B-H curve.

Core manufacturers typically define saturation as a point on the B-H curve above which the core's loss of permeability begins to severely impact the intended application.

If you copy Bm values directly from the tables in manufacturers' databooks the Spice Plus core models will yield unexpectedly low Bm values. To account for the different definitions of saturation density, do not use the Bm values listed in the databook tables; instead read Bm values from the saturated regions of the accompanying B-H plots.

3. The air-gap model is inaccurate under DC and very low frequency operation (usually < 100 Hz).

The inaccuracy is caused by a one milliohm resistor placed in series with the core inductance. To ensure accurate modeling of air gap, make sure that one of the following conditions is met:

- **a.** The winding resistance is greater than or equal to 100 milliohms.
- **b.** The inductive component of the impedance (Z_I) is greater than or equal to 100 milliohms. The magnitude of the inductive component of the impedance is given as:

$$|Z_L| = \omega * L_{eq}$$

where ω is radian frequency, and L $_{\rm eq}$ is equivalent inductance.

Analog Devices

Replacing $L_{\mbox{eq}}$ with an equivalent expression (2 μ An) yields:

$$|Z_{\mathbf{I}}| = 2\omega\mu$$
An / L

where μ is permeability, A is area, n is number of turns and L is length.

4. Circuits containing cores with Bm greater than 10⁶ x Hc sometimes have convergence problems.

If you encounter convergence problems when modeling a core with very high saturation flux and very low density, substitute an ideal core, which models infinite saturation flux and zero coercive force.

Transmission line coupling

If a K device is used to couple two transmission lines, then two coupling parameters are required.

| Device | Description | Units | Default |
|--------|---------------------|---------------------------|---------|
| Cm | capacitive coupling | farad/length ¹ | none |
| Lm | inductive coupling | henries/length* | none |

1. Length units must be consistent using the LEN parameter for the transmission lines being coupled.

These parameters can be thought of as the off-diagonal terms of a capacitive coupling matrix, [C], and an inductive coupling matrix, [L], respectively. [C] and [L] are both symmetric matrices, and for two coupled lines, the following relationships hold:

$$\begin{bmatrix} C \end{bmatrix} = \begin{bmatrix} C_{11} & C_{12} \\ C_{21} & C_{22} \end{bmatrix} \qquad \begin{bmatrix} L \end{bmatrix} = \begin{bmatrix} L_{11} & L_{12} \\ L_{21} & L_{22} \end{bmatrix}$$

$$Cm = C12 = C21 \text{ and } Lm = L12 = L21$$

 C_{12} represents the charge induced on the first conductor when the second conductor has a potential of one volt. In general, for a system of N coupled lines, C_{ij} is the charge on the ith conductor when the jth conductor is set to one volt, and all other conductors are grounded. The diagonal of the matrix is determined with the understanding that the self-capacitance is really the capacitance between the conductor and ground, so that:

Analog Devices

$$C_{ii} = C_{ig} + \sum |C_{ij}|$$

where C_{ig} is equal to the capacitance per unit length for the i^{th} transmission line, and is provided along with the T device that describes the i^{th} line. The simulator calculates C_{ii} from this.

The values of C_{ij} in the matrix are negative values. Note that the simulator assigns -|Cm| to the appropriate C_{ij} , so that the sign used when specifying C_m is ignored.

 L_{12} is defined in terms of the flux between the 1st conductor and the ground plane, when the 2nd conductor carries a current of one ampere. If there are more than two conductors, all other conductors are assumed to be open.

 L_{11} is equal to the inductance per unit length for the 1st line and is obtained directly from the appropriate T device.

Example

The following circuit fragment shows an example using two coupled lines:

This fragment leads to the following [C] and [L]:

$$\begin{bmatrix} C \end{bmatrix} = \begin{bmatrix} 76p & -6p \\ -6p & 71p \end{bmatrix} \qquad \begin{bmatrix} L \end{bmatrix} = \begin{bmatrix} 0.38u & 0.04u \\ 0.04u & 0.33u \end{bmatrix}$$

The model used to simulate this system is based on the approach described by Tripathi and Rettig in Reference [1] of References on page 231 and is extended for lossy lines by Roychowdhury and Pederson in Reference [2]. The approach involves computing the system propagation modes by extracting the eigenvalues and eigenvectors of the matrix product [L][C].

Note: This model is not general for lossy lines.

Lossy lines

For the lossy line case, the matrix product to be decoupled is actually:

where:

Analog Devices

s = the Laplace variable

R = the resistance per unit length matrix

G = the conductance per unit length matrix.

The modes obtained from [L][C] represent a high frequency asymptote for this system. Simulation results should be good approximations for low-loss lines. However, as shown in reference [2], the approximation becomes exact for homogeneous, equally-spaced lossy lines, provided that coupling beyond immediately adjacent lines is negligible (i.e., the coupling matrices are tridiagonal and Toeplitz).

Note: Coupled ideal lines can be modeled by setting R and G to zero. The Z0/TD parameter set is not supported for coupled lines.

References

For a further description of the Jiles-Atherton model, refer to:

[1] D.C. Jiles, and D.L. Atherton, "Theory of ferromagnetic hysteresis," *Journal of Magnetism and Magnetic Materials*, 61, 48 (1986).

For more information on transmission line coupling, refer to:

- [1] Tripathi and Rettig, "A SPICE Model for Multiple Coupled Microstrips and Other Transmission Lines," *IEEE MTT-S Internal Microwave Symposium Digest*, 1985.
- [2] Roychowdhury and Pederson, "Efficient Transient Simulation of Lossy Interconnect," Design Automation Conference, 1991.

Analog Devices

Inductor

General form L<name> <(+) node> <(-) node> [model name] <value>

+ [IC=<initial value>]

Examples LLOAD 15 0 20mH

L2 1 2 .2E-6

LCHOKE 3 42 LMOD .03 LSENSE 5 12 2UH IC=2mA

Model form .MODEL <model name> IND [model parameters]



Arguments and options

(+) and (-) nodes

Define the polarity when the inductor has a positive voltage across it.

The first node listed (or pin one in), is defined as positive. The voltage across the component is therefore defined as the first node voltage less the second node voltage.

Positive current flows from the (+) node through the inductor to the (-) node. Current flow from the first node through the component to the second node is considered positive.

[model name]

If [model name] is left out, then the effective value is <value>.

If [model name] is specified, then the effective value is given by the model parameters; see <u>Inductance value formula</u> on page 235.

If the inductor is associated with a Core model, then the effective value is the number of turns on the core. Otherwise, the effective value is the inductance. See the Model Form statement for the K device in <u>Coupling</u> on page 215 for more information on the Core model.

Analog Devices

<initial value>

Is the initial current through the inductor during the bias point calculation.

It can also be specified in a circuit file using a .IC statement as follows:

.IC I(L<name>) <initial value>

For details on using the .IC statement in a circuit file, see .IC (initial bias point condition) on page 49 and refer to your *PSpice User Guide* for more information.

parts

For standard L parts, the effective value of the part is set directly by the VALUE property.

In general, inductors should have positive component values (VALUE property). In all cases, components must not be given a value of zero.

However, there are cases when negative component values are desired. This occurs most often in filter designs that analyze an RLC circuit equivalent to a real circuit. When transforming from the real to the RLC equivalent, it is possible to end up with negative component values.

PSpice A/D allows negative component values for bias point, DC sweep, AC, and noise analyses. A transient analysis may fail for a circuit with negative components. Negative inductors may create instabilities in time that the analysis cannot handle.

| Part name | Model type | Property | Property description |
|-------------|-------------|----------------------|--|
| L | inductor | VALUE | inductance |
| | | IC | initial current through the inductor during bias point calculation |
| XFRM_LINEAR | transformer | L1_VALUE L2_VALUE | winding inductances in Henries |
| | | COUPLING | coefficient of mutual coupling (must be between 0 and 1) |
| K_LINEAR | transformer | Ln | inductor reference designator |

Analog Devices

Breakout parts

For non-stock passive and semiconductor devices, provides a set of breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters. Another approach is to use the model editor to derive an instance model and customize this. For example, you could add device and/or lot tolerances to model parameters.

Basic breakout part names consist of the intrinsic PSpice A/D device letter plus the suffix BREAK. By default, the model name is the same as the part name and references the appropriate device model with all parameters set at their default. For instance, the DBREAK part references the DBREAK model, which is derived from the intrinsic PSpice A/D D model (.MODEL DBREAK D).

For breakout part LBREAK, the effective value is computed from a formula that is a function of the specified VALUE property.

| Device type | Part name | Part library file | Property | Description |
|----------------|--------------|-------------------|----------|--|
| inductor | LBREA K | breakout | VALUE | inductance |
| | | | IC | initial current through the inductor during bias point calculation |
| | | | MODEL | IND model name |

| Model parameters ¹ | Description U | | Defaul t |
|----------------------------------|-----------------------------------|-------|-------------|
| L | Inductance multiplier | | 1.0 |
| IL1 | Linear current coefficient | amp-1 | 0.0 |
| IL2 | Quadratic current coefficient | amp-2 | 0.0 |
| TC1 | Linear temperature coefficient | °C-1 | 0.0 |
| TC2 | Quadratic temperature coefficient | °C-2 | 0.0 |
| T_ABS | Absolute temperature | °C | |
| $T_{MEASURED}$ | Measured temperature | °C | |

Analog Devices

| Model parameters ¹ | Description | Units | Defaul t |
|----------------------------------|-----------------------------------|-------|-------------|
| T_REL_GLOBAL | Relative to current temperature | °C | |
| T_REL_LOCAL | Relative to AKO model temperature | °C | |

^{1.} For information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see <u>.MODEL (model definition)</u> on page 57.

Inductor equations

Inductance value formula

If [model name] is specified, then the effective value is given by:

```
<value> ·L · (1+IL1 ·I+IL2 ·I2) · (1+TC1 · (T-Tnom) +TC2 · (T-Tnom) 2)
```

where < value> is normally positive (though it can be negative, but *not* zero). Tnom is the nominal temperature (set using TNOM option).

Inductor equation for noise

The inductor does not have a noise model.

Inductor as Winding

General form L<name> <+node> <-node> <TURNS> [RESIS = val] [IC=val]

Examples L1 2 0 103 resis=40m

12 6 0 5 resis=40m

Arguments and options

Analog Devices

```
(+) and (-) nodes
```

Define the polarity when the inductor has a positive voltage across it.

The first node listed (or pin one in), is defined as positive. The voltage across the component is therefore defined as the first node voltage less the second node voltage.

Positive current flows from the (+) node through the inductor to the (-) node. Current flow from the first node through the component to the second node is considered positive.

<TURNS>

Defines the number of windings around the core

[RESIS]

Defines the winding resistance.

[IC]

Defines the initial current through the inductor.

Example of windings coupled to a core

A sample of Spice plus level-1 core model with multiple windings is shown below.

```
L1 2 0 103 resis=40m

L2 6 0 5 resis=40m

K1 L1 L2 1.0 N1

.model N1 core(Level=3 od=2.88 id=0.0 area=1.38 gap=0.04 br=2300 bm=4850 +hc=0.188)
```

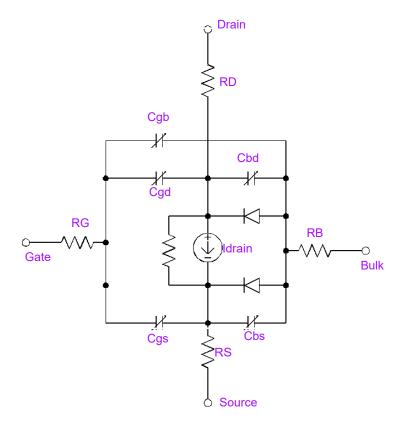
To know more about .MODEL, see .MODEL (model definition) on page 57.

MOSFET

Description

The MOSFET is modeled as an intrinsic MOSFET using ohmic resistances in series with the drain, source, gate, and bulk (substrate). There is also a shunt resistance (RDS) in parallel with the drain-source channel.

.MODEL <model name> PMOS [model parameters]



Analog Devices

Arguments and options

L and W

are the channel length and width, which are decreased to get the effective channel length and width. They can be specified in the device, .MODEL (model definition) on page 57, or .OPTIONS (analysis options) on page 71 statements. The value in the device statement supersedes the value in the model statement, which supersedes the value in the .OPTIONS statement. Defaults for L and W can be set in the .OPTIONS statement. If L or W defaults are not set, their default value is 100 u.

Note: $[L=\langle value \rangle]$ $[W=\langle value \rangle]$ cannot be used in conjunction with Monte Carlo analysis.

AD and AS

The drain and source diffusion areas. Defaults for AD and AS can be set in the .OPTIONS statement. If AD or AS defaults are not set, their default value is 0.

PD and PS

The drain and source diffusion perimeters. Their default value is 0.

NRD, NRS, NRG, and NRB

Multipliers (in units of squares) that can be multiplied by RSH to yield the parasitic (ohmic) resistances of the drain (RD), source (RS), gate (RG), and substrate (RB), respectively. NRD, NRS, NRG, and NRB default to 0.

Consider a square sheet of resistive material. Analysis shows that the resistance between two parallel edges of such a sheet depends upon its composition and thickness, but is *independent* of its size as long as it is *square*. In other words, the resistance will be the same whether the square's edge is 2 mm, 2 cm, or 2 m. For this reason, the sheet resistance of such a layer, abbreviated $\underline{\text{RSH}}$ on page 253, has units of ohms per square.

Analog Devices

M (NP)

A parallel device multiplier (default = 1), which simulates the effect of multiple devices in parallel. (NP is an alias for M.)

The effective width, overlap and junction capacitances, and junction currents of the MOSFET are multiplied by M. The parasitic resistance values (e.g., RD and RS) are divided by M. Note the third example: it shows a device twice the size of the second example.

N (NS)

A series device multiplier (default value= 1.0) for the Level 5 model only, which simulates an approximation of the effect of multiple devices in series. NS is an aliased name for N.

There are some things to keep in mind while using this parameter. The parameter N is used to derive the effective length, Leff = N \cdot (L+DL), of a transistor drawn as N elements of width W and length L in series (in other words, the drain of element [K] is the source of element [K+1], and the gates are tied together). The short-channel effects included in the pinch-off voltage calculation, however, are evaluated using the effective length L+DL of each element. Except for this, everything is calculated as if the transistor were laid out as a single element of length L=Leff-DL=N \cdot (L+DL)-DL.

In this compact formulation, the intermediate drain/source diffusions appearing along the channel are ignored (that is, junction capacitance and diffusion resistances are assumed to be zero). As a consequence, DC, AC and transient analyses can yield different results compared with the standard device declaration, particularly at higher frequencies. A closer match is obtained for long devices, or devices with low RS and RD and high UCRIT. Be sure to evaluate the accuracy of this compact formulation and to check the validity of the underlying approximations.

JS

Can specify the drain-bulk and source-bulk saturation currents. JS is multiplied by AD and AS.

IS

Can also specify the drain-bulk and source-bulk saturation currents. IS is an absolute value.

Analog Devices

CJ

Can specify the zero-bias depletion capacitances. CJ is multiplied by AD and AS.

CJSW

Can also specify the zero-bias depletion capacitances. CJSW is multiplied by PD and PS.

CBD and CBS

Can also specify the zero-bias depletion capacitances. CBD and CBS are absolute values.

Note: Parameters IS, JS, CJ, CJSW, CBD, and CBS are model parameters. These parameters are specified in the *model* parameters section of <u>MODEL</u> statement.

Comments

The simulator provides eight MOSFET device models, which differ in the formulation of the I-V characteristic. The LEVEL parameter selects among different models as shown below. For more information, see <u>References</u> on page 283.

LEVEL=1 Shichman-Hodges model (see reference [1])

LEVEL=2 geometry-based, analytic model (see reference [2])

LEVEL=3 semi-empirical, short-channel model (see reference [2])

LEVEL=4 BSIM model (see reference [3])

LEVEL=5 EKV model version 2.6 (see reference [10])

LEVEL=6 BSIM3 model version 2.0 (see reference [7])

LEVEL=7 BSIM3 model version 3.2 (see reference [8])

LEVEL=8 BSIM4 model version 4.1.0 (see reference [11])

Analog Devices

parts

The following table lists the set of MOSFET breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

| Part name | Model type | Property | Property description |
|-----------|---------------|----------|---|
| MBREAKN | NMOS | L | channel length |
| MBREAKN3 | | W | channel width |
| MBREAKN4 | | AD | drain diffusion area |
| MBREAKP | PMOS | AS | source diffusion area |
| MBREAKP3 | | PD | drain diffusion perimeter |
| MBREAKP4 | | PS | source diffusion perimeter |
| | | NRD | relative drain resistivity (in squares) |
| | | NRS | relative source resistivity (in squares) |
| | | NRG | relative gate resistivity (in squares) |
| | | NRB | relative substrate resistivity (in squares) |
| | | M | device multiplier (simulating parallel devices) |
| | | MODEL | NMOS or PMOS model name |
| MganN | NMOS | MODEL | model name |
| MganP | PMOS | MODEL | model name |

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter. For more information, see <u>MOSFET model parameters</u> on page 242.

MOSFET model parameters

For all model levels

The parameters common to all model levels are primarily parasitic element values such as series resistance, overlap and junction capacitance, and so on.

Model levels 1, 2, and 3

The DC characteristics of the first three model levels are defined by the parameters VTO, KP, LAMBDA, PHI, and GAMMA. These are computed by the simulator if process parameters (e.g., TOX, and NSUB) are given, but the user-specified values always override. VTO is positive (negative) for enhancement mode and negative (positive) for depletion mode of N-channel (P-channel) devices.

Note: The default value for TOX is 0.1 μ for Levels 2 and 3, but is unspecified for Level 1, which discontinues the use of process parameters.

For MOSFETs the capacitance model has been changed to conserve charge, affecting only the Level 1, 2, and 3 models.

Effective length and width for device parameters are calculated with the formula:

```
P_i = P_0 + P_L/L_e + P_W/W_e
```

where:

```
L_e = effective length = L - (LD · 2)

W_e = effective width = W - (WD · 2)
```

See <u>.MODEL (model definition)</u> on page 57 for more information.

Model level 4

Note: Unlike the other models in PSpice, the BSIM model is designed for use with a process characterization system that provides all parameters. Therefore, there are no defaults specified for the parameters, and leaving one out can cause problems.

The LEVEL=4 (BSIM1) model parameters are all values obtained from process characterization, and can be generated automatically. Reference [4] of <u>References</u> on page 283 describes a means of generating a process file, which *must* then be converted into <u>MODEL (model definition)</u> on page 57 statements for inclusion in the Model Library or circuit file. (The simulator *does not* read process files.)

Analog Devices

The level 4 (BSIM) and level 6 (BSIM3 version 2) models have their own capacitance model, which conserves charge and remains unchanged. References [6] and [7] describe the equations for the capacitance due to channel charge.

In the following MOSFET model parameters on page 251 list, parameters marked with a ζ in the Default column also have corresponding parameters with a length and width dependency. For example, VFB is a basic parameter using units of volts, and LVFB and WVFB also exist and have units of volt· μ . The formula

```
P_i = P_0 + P_L/L_e + P_W/W_e
```

is used to evaluate the parameter for the actual device, where:

```
L_e = effective length = L - DL W_e = effective width = W - DW
```

Model level 5 (EKV version 2.6)

The EKV model is a scalable and compact model built on fundamental physical properties of the device. Use this model to design low-voltage, low-current analog, and mixed analog-digital circuits that use sub-micron technologies. The charge-based static, quasi-static dynamic, and noise models are all derived from the normalized transconductance-to-current ratio, which is accurately described for all levels of current, including the moderate inversion region. A single I-V expression preserves the continuity of first- and higher-order derivatives with respect to any terminal voltage in all regions of device operation.

Version 2.6 models the following:

- geometrical and process related aspects of the device (oxide thickness, junction depth, effective channel length and width, and so on)
- effects of doping profile and substrate effects
- weak, moderate, and strong inversion behavior
- mobility effects due to vertical and lateral fields and carrier velocity saturation
- short-channel effects such as channel-length modulation, source and drain charge sharing, and the reverse short channel effect
- thermal and flicker noise modeling
- short-distance geometry and bias-dependent device matching for Monte Carlo analysis.

For more detailed model information, see reference [10] of <u>References</u> on page 283.

Analog Devices

Additional notes

- The EKV noise model is used rather than the PSpice noise model. The NLEV parameter is not used with this model.
- The DL and DW parameters usually have a negative value.
- **0** (zero) and O (the letter O) are not interchangeable. For example, use VTO, not VTO (VTO is referenced to the bulk); use EO, not EO; use QO, not QO.
- Use the AVTO, AKP, and AGAMMA model parameters with a DEV tolerance to perform Monte Carlo and Sensitivity/Worst-Case analyses. Their default values cannot be changed.

The device-to-device matching of MOSFETs depends on the gate area, W · L. Using AVTO, AKP, and AGAMMA with a DEV tolerance applies the matching scaling law for the model equations and derives the device matching statistics (DEV tolerance) from a single normalized parameter. (Without these parameters, you would need to use a dedicated .MODEL card with a DEV tolerance for VTO, KP and GAMMA for each value of the gate area used in your design.)

Do not apply the LOT specification, which is a measure of the ability of the process to control the absolute value of a model parameter, to AVTO, AKP, and AGAMMA, because this would be redundant with the LOT specification for VTO, KP, and GAMMA.

■ Use the model parameter *HDIF* with the device parallel multiplier, M, to set default values for *AD*, *AS*, *PD*, and *PS*. Use *HDIF* only for the MOSEKV (Level 5) model.

When *HDIF* is specified, the following equations are used.

$${\sf NRD} = {\sf HDIF}/W$$
 ${\sf NRS} = {\sf HDIF}/W$

For M = 1, the following equations are used.

$$\mathbf{AD} = (2 \cdot \mathbf{HDIF}) \cdot W$$

$$\mathbf{AS} = (2 \cdot \mathbf{HDIF}) \cdot W$$

$$\mathbf{PD} = 2 \cdot ((2 \cdot \mathbf{HDIF}) + W)$$

$$\mathbf{PS} = 2 \cdot (2 \cdot \mathbf{HDIF}) + W$$

For $M \ge 2$ and even:

$$\begin{aligned} \mathbf{AD} &= \mathbf{HDIF} \cdot W \\ \mathbf{AS} &= (\mathbf{HDIF} + (2 \cdot \mathbf{HDIF})/M) \cdot W \\ \mathbf{PD} &= (2 \cdot \mathbf{HDIF}) + W \end{aligned}$$

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$$\begin{aligned} \mathbf{PS} &= (2 \cdot \mathbf{HDIF}) + W + 2 \cdot ((2 \cdot \mathbf{HDIF}) + W) / M \\ \end{aligned}$$
 For $\mathbf{M} \geq \mathbf{2}$ and odd:
$$\mathbf{AD} &= (\mathbf{HDIF} + (\mathbf{HDIF} / M)) \cdot W \\ \mathbf{AS} &= (\mathbf{HDIF} + (\mathbf{HDIF} / M)) \cdot W \\ \mathbf{PD} &= (2 \cdot \mathbf{HDIF}) + W + ((2 \cdot \mathbf{HDIF}) + W) / M \\ \mathbf{PS} &= (2 \cdot \mathbf{HDIF}) + W + ((2 \cdot \mathbf{HDIF}) + W) / M \end{aligned}$$

- If RGSH is specified, the default value for NRG is set to $0.5 \cdot W/L$.
- The model parameters *TOX*, *NSUB*, *VFB*, *UO*, and *VMAX* accommodate scaling behavior of the process and basic intrinsic model parameters, as well as statistical circuit simulation. These parameters are only used if *COX*, *GAMMA*, and/or *PHI*, *VTO*, *KP*, and *UCRIT* are not specified, respectively. Furthermore, a simpler mobility reduction model due to vertical field is accessible through the mobility reduction coefficient, *THETA*. *THETA* is only used if *E0* is not specified.

Model level 6 (BSIM3 version 2.0)

Note: The Level 6 Advanced parameters should not be changed unless the detail structure of the device is known and has specific, meaningful values.

The BSIM3 model is a physical model using extensive built-in dependencies of important dimensional and processing parameters. It includes the major effects that are important to modeling deep-submicrometer MOSFETs, such as threshold voltage reduction, nonuniform doping, mobility reduction due to the vertical field, bulk charge effect, carrier velocity saturation, drain-induced barrier lowering (DIBL), channel length modulation (CLM), hot-carrier-induced output resistance reduction, subthreshold conduction, source/drain parasitic resistance, substrate current induced body effect (SCBE), and drain voltage reduction in LDD structure. For additional, detailed model information, see <u>References</u> on page 283.

Additional notes

- The BSIM3v3 noise model (NOIMOD and its parameters) is used rather than the PSpice noise model (NLEV).
- If any of the following BSIM3 version 2.0 model parameters are not explicitly specified, they are calculated using the following equations.

VTH0 = VFB + PHI +
$$K\sqrt{PHI}$$

K1 = GAMMA2 - 2 · K2 $\sqrt{(PHI - VBM)}$

$$\text{K2} = \frac{(\text{GAMMA1} - \text{GAMMA2})(\sqrt{\text{PHI}} - \text{VBX}} - \sqrt{\text{PHI}})}{2\sqrt{\text{PHI}}(\sqrt{\text{PHI}} - \text{VBX}} - \sqrt{\text{PHI}}) + \text{VBM}}$$

$$PHI = 2V_{tm} \ln \left(\frac{NPEAK}{n_i} \right)$$

$$GAMMA1 = \frac{\sqrt{2q\varepsilon_{si}NPEAK}}{COX}$$

$$GAMMA2 = \frac{\sqrt{2q\varepsilon_{si}NSUB}}{COX}$$

$$VBX = PHI - q \cdot NPEAK \cdot XT^{2}/(2\varepsilon_{si})$$

$$LITL = \sqrt{\frac{\varepsilon_{si} TOXX_j}{\varepsilon_{ox}}}$$

■ Default values listed for the BSIM3 version 2.0 parameters UA, UB, UC, UA1, AB1, and UC1 are used for simplified mobility modeling.

Model level 7 (BSIM3 version 3.2)

The BSIM3 version 3.2 model was developed by the University of California, Berkeley, as a deep submicron MOSFET model for use in deep-submicron digital and analog circuit designs. The BSIM3 version 3.2 model is an extension of the BSIM3 model, with the following enhancements and improvements:

- a new intrinsic capacitance model (the Charge Thickness Model), considering the finite charge layer thickness determined by quantum effect, is introduced as capMod 3. It is very accurate in all operating regions.
- improved modeling of C-V characteristics at the weak-to-inversion transition
- addition of TOX dependence into the threshold voltage (VTH) model
- addition of flat-band voltage (VFB) as a new model parameter to accurately model MOSFET's with different gate materials
- improved substrate current scalability with the channel length, controlled through parameter ALPHA1

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- the non-quasi-static (NQS) model is restructured to improve model accuracy and simulation efficiency
- temperature dependence is added to the diode junction capacitance model where both the unit area junction capacitance and built-in potential are now temperature dependent
- the DC junction diode model now supports a resistance-free diode model and a current limiting feature
- addition of the option of using C-V inversion charge equations of CAPMOD 0, 1, 2 or 3 to calculate the thermal noise when NOIMOD == 2 or 4
- the small negative capacitance of CGS and CGD in the accumulation-depletion regions is eliminated
- a separate set of length/width-dependence parameters is introduced in the C-V model for CV channel length and width to better fit the capacitance data
- parameter checking is added to avoid invalid values for certain parameters

The BSIM3 version 3.2 model has the same physical basis as the BSIM3 version 2.0 model and retains the extensive built-in dependencies of dimensional and processing parameters of BSIM3 version 2.0.

For additional, detailed model information, see Reference [8] of References on page 283.

Additional notes

Note 1

If any of the following BSIM3 version 3.2 model parameters are not explicitly specified, they are calculated using the following equations:

Note: In the model template add the parameter, VERSION = 3.2. By default, version 3.1 is used.

If VTHO is not specified, then: THO = VFB + ϕ_s + K1 $\sqrt{\phi}$ where: VFB=-1.0, if not specified If VTHO is specified, then: $VFB = VTHO - \phi_s - K1\sqrt{\phi_s}$

Note 2

If K1 AND K2 are not specified, they are calculated using the following equations:

$$\mathbf{K1} = \mathbf{GAMMA2} - 2\mathbf{K2}\sqrt{\phi_s - \mathbf{VBM}}$$

$$\mathbf{2} = \frac{(\mathbf{GAMMA1} - \mathbf{GAMMA2})(\sqrt{\phi_s - \mathbf{VBX}} - \sqrt{\phi_s})}{2\sqrt{\phi_s}(\sqrt{\phi_s - \mathbf{VBM}} - \sqrt{\phi_s}) + \mathbf{VBM}}$$
where:
$$\phi_s = 2Vt \cdot \ln\left(\frac{\mathbf{NCH}}{n_i}\right)$$

$$Vt = \frac{k \cdot Tnom}{q}$$

$$\left(n_i = 1.45 \cdot 10^{10} \left(\frac{Tnom}{300.15}\right)^{1.5}\right) \exp\left(21.5565981 - \frac{E_{g0}}{2Vtmo}\right)$$

where E_{g0} =the energy bandgap at temperature $T_{nom}=1.16-\frac{(7.02\cdot 10^{-4}\cdot T_{nom}^2)}{(T_{nom}+1108)}$

Note 3

If NCH is not given and GAMMA1 is given, then:

$$NCH = \frac{GAMMA1^2 \cdot (Cox)^2}{2q \cdot \varepsilon_{si}}$$

If neither GAMMA1 nor NCH is given, then NCH has a default value of 1.7e23 $1/m^3$ and GAMMA1 is calculated from NCH:

$$GAMMA1 = \frac{\sqrt{2q \cdot \varepsilon_{si} \cdot NCH}}{Cox}$$

If GAMMA2 is not given, then:

$$\mathbf{GAMMA2} = \frac{\sqrt{2q \cdot \varepsilon_{si} \cdot \mathbf{NSUB}}}{Cox}$$

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Note 4

If VBX is not given, it is calculated by:

$$\mathbf{VBX} \, = \, \phi_s - \frac{q \cdot \mathbf{NCH} \cdot XT^2}{2 \cdot \varepsilon_{si}}$$

Note 5

If CGSO is not given and DLC>0, then:

$$\mathbf{CGSO} = (\mathbf{DLC} \cdot Cox) - \mathbf{CGSL}$$

If the previously calculated CGSO<0, then:

CGSO=0

Else:

 $CGSO=0.6 \cdot XJ \cdot Cox$

Note 6

If CGDO is not given and DLC>0, then:

$$CGDO = (DLC \cdot Cox) - CGSL$$

If the previously calculated CGDO<0, then

CGDO=0

Else:

 $CGDO=0.6 \cdot XJ \cdot Cox$

Note 7

If CF is not given, it is calculated by:

$$\mathbf{CF} = \left(\frac{2\varepsilon_{ox}}{\pi}\right) \ln\left(1 + \frac{4 \times 10^{-7}}{\mathbf{TOX}}\right)$$

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Note 8

In BSIM3 version 3.0 and 3.1, NQSMOD was a model parameter. From BSIM3 version 3.2, NQSMOD is an (element) instance parameter. In the absence of an instance NQSMOD parameter, the model parameter NQSMOD, if any, will be considered.

Note 9

If the following parameters are not specified, their corresponding parameters, if specified, will be used.

| If following parameter is not specified | Then its corresponding parameter is used |
|---|--|
| LLC | LL |
| LWC | LW |
| LWLC | LWL |
| WLC | WL |
| WWC | WW |
| WWLC | WWL |

Note 10

Error or warning messages are reported if invalid values are specified for the following parameters:

- If PSCBE2 <= 0.0, a warning message is reported</p>
- If (MOIN < 5.0) or (MOIN > 25.0), a warning message is reported
- If (ACDE < 0.4) or (ACDE > 1.6), a warning message is reported
- If (NOFF < 0.1) or (NOFF > 4.0), a warning message is reported
- If (VOFFCV < -0.5) or (VOFFCV > 0.5), a warning message is reported
- If (IJTH < 0.0), a fatal error message is reported</p>
- If $(TOXM \le 0.0)$, a fatal error message is reported

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Model Level 8 (BSIM4 version 4.1.0)

BSIM4 is an extension of BSIM3 model and provides robust and predictive simulations with increased accuracies in modeling various functions, such as tunneling and thermal noise. As specified by University of California, Berkeley, BSIM4 has the following improvements and enhancements:

- An accurate gate direct tunneling model
- A better model for pocket-implanted devices in Vth, bulk charge effect model, and Rout
- An asymmetrical and bias-dependent source/drain resistance, either internal or external to the intrinsic MOSFET, at the user's discretion
- An acceptance of either the electrical or physical gate oxide thickness as the model input in a physically accurate manner
- The quantum mechanical charge-layer-thickness model for both IV and CV
- A more accurate mobility model for predictive modeling
- A gate-induced drain leakage (GIDL) current model, available in BSIM for the first time
- Different diode IV and CV characteristics for source and drain junctions
- A junction diode breakdown with or without current limiting
- A dielectric constant of the gate dielectric as a model parameter

Note: Flicker and Thermal Noise models and High-Speed/RF models should not be used as model or instance parameters as they are not included in the current implementation of BSIM4. The High-Speed/RF model parameters are XRCRG1, XRCRG2, GBMIN, RBPB, RBPD, RBPS, RBDB, and RBSB. The Flicker and Thermal Noise model parameters are:NOIA, NOIB, NOIC, EM, EF, KF, NTNOI, TNOIA, and TNOIB.

For additional, detailed model information, see Reference [11] of "References" on page 283.

MOSFET model parameters

| Parameter ¹ | Description | Unit | Default | |
|------------------------|---|-------|---------|--|
| all levels | | | | |
| AF | flicker noise exponent | | 1 | |
| CBD | zero-bias bulk-drain <i>p-n</i> capacitance | farad | 0 | |
| CBS | zero-bias bulk-source p-n capacitance | farad | 0 | |

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MOSFET model parameters, continued

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|------------------------------|---------|
| CGBO | gate-bulk overlap capacitance/channel length | farad/ meter | 0 |
| CGDO | gate-drain overlap capacitance/channel width | farad/ meter | 0 |
| CGS0 | gate-source overlap capacitance/channel width | farad/ meter | 0 |
| CJ | bulk <i>p-n</i> zero-bias bottom capacitance/area | farad/ meter ² | 0 |
| CJSW | bulk <i>p-n</i> zero-bias sidewall capacitance/length | farad/ meter | 0 |
| FC | bulk <i>p-n</i> forward-bias capacitance coefficient | | 0.5 |
| GDSNOI | channel shot noise coefficient (use with NLEV=3) | | 1 |
| IS | bulk <i>p-n</i> saturation current | amp | 1E-14 |
| JS | bulk <i>p-n</i> saturation current/area | amp/ meter² | 0 |
| JSSW | bulk <i>p-n</i> saturation sidewall current/length | amp/ meter | 0 |
| KF | flicker noise coefficient | | 0 |
| L | channel length | meter | DEFL |
| LEVEL | model index | | 1 |
| MJ | bulk <i>p-n</i> bottom grading coefficient | | 0.5 |
| MJSW | bulk <i>p-n</i> sidewall grading coefficient | | 0.33 |
| N | bulk <i>p-n</i> emission coefficient | | 1 |
| NLEV | noise equation selector | | 2 |
| PB | bulk <i>p-n</i> bottom potential | volt | 0.8 |
| PBSW | bulk <i>p-n</i> sidewall potential | volt | PB |
| RB | bulk ohmic resistance | ohm | 0 |
| | | | |

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|---------------------|--|
| RDS | drain-source shunt resistance | ohm | infinite |
| RG | gate ohmic resistance | ohm | 0 |
| RS | source ohmic resistance | ohm | 0 |
| RSH | drain, source diffusion sheet resistance | ohm/ square | 0 |
| TT | bulk p-n transit time | sec | 0 |
| T_ABS † | absolute temperature | °C | |
| T_MEASURED † | measured temperature | °C | |
| T_REL_GLOB AL † | relative to current temperature | °C | |
| T_REL_LOCA L † | relative to AKO model temperature | °C | |
| W | channel width | meter | DEFW |
| | levels 1, 2, and 3 | | |
| DELTA | width effect on threshold | | 0 |
| ETA | static feedback (Level 3) | | 0 |
| GAMMA | bulk threshold parameter | volt ^{1/2} | see <u>Model</u> levels 1, 2, and 3 on page 242 |
| KP | transconductance coefficient | amp/volt2 | 2.0E-5 |
| KAPPA | saturation field factor (Level 3) | | 0.2 |
| LAMBDA | channel-length modulation (Levels 1 and 2) | volt-1 | 0.0 |
| LD | lateral diffusion (length) | meter | 0.0 |
| NEFF | channel charge coefficient (Level 2) | | 1.0 |
| NFS | fast surface state density | 1/cm² | 0.0 |
| NSS | surface state density | 1/cm² | none |
| NSUB | substrate doping density | 1/cm³ | none |

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| Parameter ¹ | Description | Unit | Default |
|------------------------|--|------------------|---|
| PHI | surface potential | volt | 0.6 |
| THETA | mobility modulation (Level 3) | volt-1 | 0.0 |
| TOX | oxide thickness | meter | see Model levels 1, 2, and 3 on page 242 |
| TPG | Gate material type: | | +1 |
| | +1 = opposite of substrate | | |
| | -1 = same as substrate | | |
| | 0 = aluminum | | |
| UCRIT | mobility degradation critical field (Level 2) | volt/cm | 1.0E4 |
| UEXP | mobility degradation exponent (Level 2) | | 0.0 |
| UTRA | (not used) mobility degradation transverse field coefficient | | 0.0 |
| UO | surface mobility (The second character is the letter O, not the numeral zero.) | cm²/ volt·sec | 600 |
| VMAX | maximum drift velocity | meter/sec | 0 |
| VTO | zero-bias threshold voltage | volt | 0 |
| WD | lateral diffusion (width) | meter | 0 |
| XJ | metallurgical junction depth (Levels 2 and 3) | meter | 0 |
| XQC | fraction of channel charge attributed to drain | | 1.0 |
| | level 4 ² | | |
| DL | Channel shortening | mu-m (1E-6*m) | |
| DW | Channel narrowing | mu-m (1E-6*m) | |
| ETA | Zero-bias drain-induced barrier lowering coefficient | | ζ |

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|---------------------|---------|
| K1 | Body effect coefficient | volt ^{1/2} | ζ |
| K2 | Drain/source depletion charge sharing coefficient | | ζ |
| MUS | Mobility at zero substrate bias and Vds=Vdd | cm²/ volt·sec | ζ |
| MUZ | Zero-bias mobility | cm²/ volt·sec | |
| N0 | Zero-bias subthreshold slope coefficient | | ζ |
| NB | Sens. of subthreshold slope to substrate bias | | ζ |
| ND | Sens. of subthreshold slope to drain bias | | ζ |
| PHI | Surface inversion potential | volt | ζ |
| TEMP | Temperature at which parameters were measured | °C | |
| TOX | Gate-oxide thickness | mu-m (1E-6*m) | |
| U0 | Zero-bias transverse-field mobility degradation | volt-1 | ζ |
| U1 | Zero-bias velocity saturation | μ/volt | ζ |
| VDD | Measurement bias range | volts | |
| VFB | Flat-band voltage | volt | ζ |
| WDF | Drain, source junction default width | meter | |
| X2E | Sens. of drain-induced barrier lowering effect to substrate bias | volt-1 | ζ |
| X2MS | Sens. of mobility to substrate bias @ Vds=0 | cm²/ volt²·sec | ζ |
| X2MZ | Sens. of mobility to substrate bias @ Vds=0 | cm²/ volt²·sec | ζ |
| X2U0 | Sens. of transverse-field mobility degradation effect to substrate bias | volt-2 | ζ |
| X2U1 | Sens. of velocity saturation effect to substrate bias | μ/volt² | ζ |

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| Parameter ¹ | Description | Unit | Default |
|------------------------|---|--------------------------|--|
| ХЗЕ | Sens. of drain-induced barrier lowering effect to drain bias @ Vds = Vdd | volt-1 | ζ |
| X3MS | Sens. of mobility to drain bias @ Vds=Vdd | cm²/ volt²·sec | ζ |
| X3U1 | Sens. of velocity saturation effect on drain | μ /volt ² | ζ |
| XPART | Gate-oxide capacitance charge model flag. | | |
| | XPART=0 selects a 40/60 drain/source charge partition in saturation, while XPART=1 selects a 0/100 drain/source charge partition. | | |
| | level 5: process parameters | | |
| COX | gate oxide capacitance per unit area | F/m ² | 0.7E-3 |
| XJ | junction depth | m | 0.1E-6 |
| DW | channel width correction | m | 0.0 see <u>Model</u> level 5 (EKV version 2.6) on page 243 |
| DL | channel length correction | m | 0.0 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 |
| HDIF | length of heavily doped diffusion contact to gate | m | 0.0 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 |

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|------------|--|
| | level 5: basic intrinsic parameters | | |
| VTO | long-channel threshold voltage | V | 0.5 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 |
| GAMMA | body effect parameter | \sqrt{V} | 1.0 |
| PHI | bulk Fermi potential (-2) | V | 0.7 |
| KP | transconductance parameter | A/V^2 | 50.0E-6 |
| E0 | mobility reduction coefficient | V/m | 1.0E12 see <u>Model</u> level 5 (EKV version 2.6) on page 243 |
| UCRIT | longitudinal critical field | V/m | 2.0E6 |
| level | 5: channel length modulation and charge sha | ring paran | neters |
| LAMBDA | depletion length coefficient (channel length modulation) | | 0.5 |
| WETA | narrow-channel effect coefficient | | 0.25 |
| LETA | short-channel effect coefficient | | 0.1 |
| | level 5: impact ionization related parame | eters | |
| IBA | first impact ionization coefficient | 1/m | 0.0 |
| IBB | second impact ionization coefficient | V/m | 3.0E8 |
| IBN | saturation voltage factor for impact ionization | | 1.0 |
| | level 5: intrinsic temperature paramet | ers | |
| TCV | threshold voltage temperature coefficient | V/K | 1.0E-3 |
| BEX | mobility temperature exponent | | -1.5 |
| UCEX | longitudinal critical field temperature exponent | | 8.0 |
| IBBT | temperature coefficient for IBB | 1/K | 9.0E-4 |

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| Parameter ¹ | Description | Unit | Default | | |
|------------------------|--|--------------------|---|--|--|
| | level 5: matching parameters | | | | |
| AVTO | area related threshold voltage temperature coefficient | V∙m | 1.0E-6 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 | | |
| AKP | area related gain mismatch parameter | m | 1.0E-6 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 | | |
| AGAMMA | area related body effect mismatch parameter | $\sqrt{V \cdot m}$ | 1.0E-6 see <u>Model</u> <u>level 5 (EKV</u> <u>version 2.6)</u> on page 243 | | |
| | level 5: resistance parameters | | | | |
| RBC | bulk contact resistance | ohm | 0.0 | | |
| RBSH | bulk layer sheet resistance | ohm/ square | 0.0 | | |
| RDC | drain contact resistance | ohm | 0.0 | | |
| RGC | gate contact resistance | ohm | 0.0 | | |
| RGSH | gate layer sheet resistance | ohm/ square | 0.0 | | |
| RSC | source contact resistance | ohm | 0.0 | | |

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| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-------------------------------|--|
| | level 5: temperature parameters | | |
| TR1 | first-order temperature coefficient for drain, source series resistance | °C ⁻¹ | 0.0 |
| TR2 | second-order temperature coefficient for drain, source series resistance | °C ⁻² | 0.0 |
| TRB | temperature coefficient for bulk series resistance | °C ⁻¹ | 0.0 |
| TRG | temperature coefficient for gate series resistance | °C ⁻¹ | 0.0 |
| XTI | drain, source junction current temperature exponent | | 0.0 |
| | level 5: optional parameters | | |
| NSUB | channel doping | meter | see <u>Additional</u> <u>Notes</u> |
| THETA | mobility reduction coefficient | volt ⁻¹ | see <u>Additional</u> <u>Notes</u> |
| TOX | oxide thickness | meter | see <u>Additional</u> <u>Notes</u> |
| UO | low-field mobility | $\frac{cm^2}{volt \cdot sec}$ | see <u>Additional</u> <u>Notes</u> |
| VFB | flat-band voltage | volt | see <u>Additional</u> <u>Notes</u> |
| VMAX | saturation velocity | meter/sec | see <u>Additional</u> <u>Notes</u> |
| | level 5: setup parameters | | |
| SATLIM | ratio defining the saturation limit i _f / i _r | | 54.6 |
| | 101010 | | |

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| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-------------------|---------|
| A0 | bulk charge effect coefficient NMOS | | 1.0 |
| | bulk charge effect coefficient PMOS | | 4.4 |
| A1 | first non-saturation coefficient NMOS | 1/V | 0.0 |
| | first non-saturation coefficient PMOS | 1/V | 0.23 |
| A2 | second non-saturation coefficient NMOS | | 1.0 |
| | second non-saturation coefficient PMOS | | 0.08 |
| AT | saturation velocity temperature coefficient | m/sec | 3.3E4 |
| BULKMOD | bulk charge model selector: | | |
| | NMOS | | 1 |
| | PMOS | | 2 |
| CDSC | drain/source and channel coupling capacitance | F/m ² | 2.4E-4 |
| CDSCB | body bias sensitivity of CDSC | F/Vm ² | 0.0 |
| DL | channel length reduction on one side | m | 0.0 |
| DROUT | channel length dependent coefficient of the DIBL effect on Rout | | 0.56 |
| DSUB | subthreshold DIBL coefficient exponent | | DROUT |
| DVT0 | first coefficient of short-channel effect on threshold voltage | | 2.2 |
| DVT1 | second coefficient of short-channel effect on threshold voltage | | 0.53 |
| DVT2 | body bias coefficient of short-channel effect on threshold voltage | 1/V | -0.032 |

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| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-------------------|--|
| DW | channel width reduction on one side | m | 0.0 |
| ETA0 | DIBL coefficient in subthreshold region | | 0.08 |
| ETAB | body bias coefficient for the subthreshold DIBL coefficient | 1/V | -0.07 |
| K1 | first-order body effect coefficient | \sqrt{V} | see <u>Model</u> <u>level 6</u> (<u>BSIM3</u> <u>version 2.0)</u> on page 245 |
| K2 | second-order body effect coefficient | | see <u>Model</u> <u>level 6</u> (<u>BSIM3</u> <u>version 2.0)</u> on page 245 |
| K3 | narrow width effect coefficient | | 80.0 |
| K3B | body effect coefficient of K3 | 1/V | 0.0 |
| KETA | body bias coefficient of the bulk charge effect. | 1/V | -0.047 |
| KT1 | temperature coefficient for threshold voltage | V | -0.11 |
| KT1L | channel length sensitivity of temperature coefficient for threshold voltage. | V-m | 0.0 |
| KT2 | body bias coefficient of the threshold voltage temperature effect | | 0.022 |
| NFACTOR | subthreshold swing coefficient | | 1.0 |
| NGATE | poly gate doping concentration | 1/cm ³ | |
| NLX | lateral nonuniform doping coefficient | m | 1.74E-7 |
| NPEAK | peak doping concentration near interface | 1/cm ³ | 1.7E17 |
| NSUB | substrate doping concentration | 1/cm ³ | 6.0E16 |
| PCLM | channel length modulation coefficient | | 1.3 |
| PDIBL1 | first output resistance DIBL effect coefficient | | 0.39 |

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| - | | | |
|------------------------|--|--------------|-----------|
| Parameter ¹ | Description | Unit | Default |
| PDIBL2 | second output resistance DIBL effect coefficient | | 0.0086 |
| PSCBE1 | first substrate current body effect coefficient | V/m | 4.24E8 |
| PSCBE2 | second substrate current body effect coefficient | m/V | 1.0E-5 |
| PVAG | gate dependence of Early voltage | | 0.0 |
| RDS0 | contact resistance | ohms | 0.0 |
| RDSW | parasitic resistance per unit width | ohms/ μ m | 0.0 |
| SATMOD | saturation model selector: | | 2 |
| | For semi-empirical output: resistance model 1 | | |
| | For physical output: resistance model 2 | | |
| SUBTHMOD | subthreshold model selector: | | 2 |
| | no subthreshold model 0 BSIM1 subthreshold model 1 BSIM3 subthreshold model 2 BSIM3 subthreshold model using log current 3 | | |
| TNOM | temperature at which parameters are extracted. | deg. C | 27 |
| TOX | gate oxide thickness | m | 1.5E-8 |
| UA | first-order mobility degradation coefficient | m/V | 2.25E-9 |
| UA1 | temperature coefficient for UA | m/V | 4.31E-9 |
| UB | second-order mobility degradation coefficient | $(m/V)^2$ | 5.87E-19 |
| UB1 | temperature coefficient for UB | $(m/V)^2$ | -7.61E-18 |
| UC | body effect mobility degradation coefficient | 1/V | 0.0465 |
| UC1 | temperature coefficient for uc | 1/V | -0.056 |
| UTE | mobility temperature exponent | | -1.5 |
| | | | |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|--------|----------------------------------|
| VOFF | offset voltage in subthreshold region | V | -0.11 |
| VSAT | saturation velocity at Temp=тиом | cm/sec | 8.0E6 |
| VTH0 | threshold voltage at Vbs=0 for large channel length | V | see Additional notes on page 245 |
| W0 | narrow width effect parameter | m | 2.5E-6 |
| XJ | junction depth | m | 1.5E-7 |
| XPART | charge partitioning coefficient: | | 0.0 |
| | no charge model < 0.0 | | |
| | 40/60 partition = 0.0 | | |
| | 50/50 partition = 0.5 | | |
| | 0/100 partition = 1.0 | | |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-----------------------------------|---|
| | level 6 advanced | | |
| CIT | capacitance due to interface trapped charge | F/m ² | 0.0 |
| EM | critical electrical field in channel | V/m | 4.1E7 |
| ETA | drain voltage reduction coefficient due to LDD | | 0.3 |
| GAMMA1 | body effect coefficient near the interface | \sqrt{V} | see Additional notes on page 245 |
| GAMMA2 | body effect coefficient in the bulk | \sqrt{V} | see <u>Additional</u> <u>notes</u> on page 245 |
| LDD | total length of the LDD region | m | 0.0 |
| LITL | characteristic length related to current depth | m | see <u>Additional</u> <u>notes</u> on page 245 |
| PHI | surface potential under strong inversion | V | see <u>Additional</u> <u>notes</u> on page 245 |
| U0 | mobility at Temp=TNOM: | | |
| | NMOS | cm ² /V- | 670.0 |
| | PMOS | sec cm ² /V- sec | 250.0 |
| VBM | maximum applied body bias | V | -5.0 |
| VBX | vbs at which the depletion width equals XT | V | see Additional notes on page 245 |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|------|----------------------------------|
| VFB | flat-band voltage | V | see Additional notes on page 245 |
| VGHIGH | voltage shift of the higher bound of the transition region | V | 0.12 |
| VGLOW | voltage shift of the lower bound of the transition region | V | -0.12 |
| XT | doping depth | m | 1.55E-7 |
| | level 7: control parameters | | |
| CAPMOD | flag for the short-channel capacitance model | none | 2 |
| MOBMOD | mobility model selector | none | 1 |
| NOIMOD | flag for noise model | none | 1 |
| NQSMOD | flag for NQS model | none | 0 |
| PARAMCHK | flag for model parameter checking | none | 0 |
| | level 7: AC and capacitance paramete | ers | |
| ACDE | exponential coefficient for charge thickness in CAPMOD=3 model for accumulation and depletion regions | m/V | 1.0 |
| CF | fringing field capacitance | F/m | see <u>Note 1</u> on page 247 |
| CKAPPA | coefficient for lightly doped region overlap capacitance fringing field capacitance | F/m | 0.6 |
| CLC | constant term for the short-channel model | m | 0.1E-6 |
| CLE | exponential term for the short-channel model | none | 0.6 |
| CGBO | gate-bulk overlap capacitance per unit channel length | F/m | 0.0 |
| CGDL | light-doped drain-gate region overlap capacitance | F/m | 0.0 |
| CGDO | non-LDD region drain-gate overlap capacitance per channel length | F/m | see <u>Note 6</u> on page 249 |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|------------------|----------------------------------|
| CGSL | light-doped source-gate region overlap capacitance | F/m | 0.0 |
| CGSO | non-LDD region source-gate overlap capacitance per channel length | F/m | see <u>Note 5</u> on page 249 |
| CJ | bottom junction capacitance per unit area | F/m ² | 5.0E-4 |
| CJSW | source/drain side junction capacitance per unit periphery | F/m | 5.0E-10 |
| CJSWG | source/drain gate sidewall junction capacitance per unit width | F/m | CJSW |
| DLC | length offset fitting parameter from C-V | m | LINT |
| DWC | width offset fitting parameter from C-V | m | WINT |
| MJ | bottom junction capacitance grading coefficient | none | 0.5 |
| MJSW | source/drain side junction capacitance grading coefficient | none | 0.33 |
| MJSWG | source/drain gate sidewall junction capacitance grading coefficient | none | MJSW |
| MOIN | coefficient for the gate-bias dependent surface potential | V ^{0.5} | 15.0 |
| NOFF | CV parameter in Vgsteff, CV for weak to strong inversion region | none | 1.0 |
| PB | bottom built-in potential | V | 1.0 |
| PBSW | source/drain side junction built-in potential | V | 1.0 |
| PBSWG | source/drain gate sidewall junction built-in potential | V | PBSW |
| VFBCV | flat-band voltage parameter (for CAPMOD = 0 only) | V | -1.0 |
| VOFFCV | CV parameter in Vgsteff, CV for weak to strong inversion region | volt | 0.0 |
| XPART | charge partitioning rate flag | none | 0.0 |

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|-------------------|---------|
| | level 7: bin description parameters | | |
| BINUNIT | bin unit scale selector | none | 1.0 |
| LMAX | maximum channel length | m | 1.0 |
| LMIN | minimum channel length | m | 0.0 |
| WMAX | maximum channel width | m | 1.0 |
| WMIN | minimum channel width | m | 0.0 |
| | level 7: DC parameters | | |
| A0 | bulk charge effect coefficient for channel length | none | 1.0 |
| A1 | first non-saturation effect parameter | 1/V | 0.0 |
| A2 | second non-saturation factor | none | 1.0 |
| AGS | gate-bias coefficient of Abulk | 1/V | 0.0 |
| ALPHA0 | first parameter of impact-ionization current | m/V | 0.0 |
| ALPHA1 | Isub parameter for length scaling | 1/V | 0.0 |
| B0 | bulk charge effect coefficient for channel width | m | 0.0 |
| B1 | bulk charge effect width offset | m | 0.0 |
| BETA0 | second parameter of impact-ionization current | V | 30.0 |
| CDSC | drain/source to channel coupling capacitance | F/m ² | 2.4E-4 |
| CDSCB | body-bias sensitivity of CDSC | F/Vm ² | 0.0 |
| CDSCD | drain-bias sensitivity of CDSC | F/Vm ² | 0.0 |
| CIT | interface trap capacitance | F/m ² | 0.0 |
| DELTA | effective Vds parameter | V | 0.01 |
| DROUT | L-dependence coefficient of the DIBL correction parameter in Rout | none | 0.56 |
| DSUB | DIBL coefficient exponent in subthreshold region | none | DROUT |
| DVT0 | first coefficient of short-channel effect on threshold voltage | none | 2.2 |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|--------------------|---------|
| DVT0W | first coefficient of narrow-width effect on threshold voltage for small-channel length | 1/m | 0.0 |
| DVT1 | second coefficient of short-channel effect on threshold voltage | none | 0.53 |
| DVT2 | body-bias coefficient of short-channel effect on threshold voltage | 1/V | -0.032 |
| DVT1W | second coefficient of narrow-width effect on threshold voltage for small channel length | 1/m | 5.3E6 |
| DVT2W | body-bias coefficient of narrow-width effect for small channel length | 1/V | -0.032 |
| DWB | coefficient of substrate body bias dependence of Weff | m/V ^{1/2} | 0.0 |
| DWG | coefficient of gate dependence of Weff | m/V | 0.0 |
| ETA0 | DIBL coefficient in subthreshold region | none | 0.08 |
| ETAB | body-bias coefficient for the subthreshold DIBL effect | 1/V | -0.07 |
| IJTH | diode limiting current | amp | 0.1 |
| JS | source-drain junction saturation current per unit area | A/m ² | 1.0E-4 |
| JSW | sidewall saturation current per unit length | A/m | 0.0 |
| K1 | first-order body effect coefficient | $V^{1/2}$ | 0.5 |
| K2 | second-order body effect coefficient | none | 0.0 |
| K3 | narrow width coefficient | none | 80.0 |
| КЗВ | body effect coefficient of K3 | 1/V | 0.0 |
| KETA | body-bias coefficient of bulk charge effect | 1/V | -0.047 |
| LINT | length offset fitting parameter from I-V without bias | m | 0.0 |
| NFACTOR | subthreshold swing factor | none | 1.0 |
| NGATE | poly gate doping concentration | cm ⁻³ | 0.0 |
| | | | |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|----------------------------|--------------------------|
| NLX | lateral non-uniform doping parameter | m | 1.74E-7 |
| PCLM | channel length modulation parameter | none | 1.3 |
| PDIBLC1 | first output resistance DIBL effect correction parameter | none | 0.39 |
| PDIBLC2 | second output resistance DIBL effect correction parameter | none | 0.0086 |
| PDIBLCB | body effect coefficient of DIBL correction parameter | 1/V | 0.0 |
| PRWB | body effect coefficient of RDSW | 1/V ^{1/2} | 0.0 |
| PRWG | gate-bias effect coefficient of RDSW | 1/V | 0.0 |
| PSCBE1 | first substrate current body effect parameter | V/m | 4.24E8 |
| PSCBE2 | second substrate current body effect parameter | V/m | 1.0E-5 |
| PVAG | gate dependence of Early voltage | none | 0.0 |
| RDSW | parasitic resistance per unit width | Ω - μ m WR | 0.0 |
| RSH | source-drain sheet resistance | Ω /square | 0.0 |
| U0 | mobility at Temp=тnом NMOS PMOS | 670.0 250.0 | cm ² /(V·sec) |
| UA | first-order mobility degradation coefficient | m/V | 2.25E-9 |
| UB | second-order mobility degradation coefficient | $(m/V)^2$ | 5.87E-19 |
| UC | body effect of mobility degradation coefficient | m/V ² | -4.65E-11 when |
| | | 1/V | MOBMOD=1 or 2 |
| | | | -0.046 when мовмор=3 |
| VBM | maximum applied body-bias in threshold voltage calculation | V | -3.0 |
| VFB | DC flatband voltage | volt | |

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-------|--|
| VOFF | offset voltage in the subthreshold region at large W and L | V | -0.08 |
| VSAT | saturation velocity at Temp=тиом | m/sec | 8.0E 4 |
| VTH0 | threshold voltage@Vbs=0 for large L | V | 0.7 (NMOS) -0.7 (PMOS) see Model level 7 (BSIM3 version 3.2) on page 246 |
| W0 | narrow-width parameter | m | 2.5E-6 |
| WINT | width-offset fitting parameter from I-V without bias | m | 0.0 |
| WR | width-offset from Weff for Rds calculation | none | 1.0 |
| | Level 7: flicker noise parameters | | |
| AF | frequency exponent | none | 1.0 |
| EF | flicker exponent | none | 1.0 |
| EM | saturation field | V/m | 4.1E7 |
| KF | flicker noise parameter | none | 0.0 |
| NOIA | noise parameter A | none | 1.0E20 (NMOS) 9.9E18 (PMOS) |
| NOIB | noise parameter B | none | 5.0E4 (NMOS) 2.4E3 (PMOS) |
| NOIC | noise parameter C | none | -1.4E- 12(NMOS) 1.4E-12 (PMOS) |
| | level 7: NQS parameter | | |
| ELM | Elmore constant of the channel | none | 5.0 |

Analog Devices

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|-------------------|----------------------------------|
| | level 7: process parameters | | |
| GAMMA1 | body effect coefficient near the surface | V ^{1/2} | see <u>Note 3</u> on page 248 |
| GAMMA2 | body effect coefficient in the bulk | V ^{1/2} | see <u>Note 3</u> on page 248 |
| NCH | channel doping concentration | 1/cm ³ | 1.7E17 |
| NSUB | substrate doping concentration | 1/cm ³ | 6.0E16 |
| TOX | gate-oxide thickness | m | 1.5E-8 |
| TOXM | gate-oxide thickness at which parameters are extracted | m | TOX |
| VBX | Vbs at which the depletion region = xT | V | |
| XJ | junction depth | m | 1.5E-7 |
| XT | doping depth | m | 1.55E-7 |
| | level 7: temperature parameters | | |
| AT | temperature coefficient for saturation velocity | m/sec | 3.3E4 |
| KT1 | temperature coefficient for threshold voltage | V | -0.11 |
| KT1L | channel length dependence of the temperature coefficient for threshold voltage | V*m | 0.0 |
| KT2 | body-bias coefficient of threshold voltage temperature effect | none | 0.022 |
| NJ | emission coefficient of junction | none | 1.0 |
| PRT | temperature coefficient for RDSW | Ω-μm | 0.0 |
| TNOM | temperature at which parameters are extracted | °C | 27.0 |
| TCJ | temperature coefficient of CJ | 1/K | 0.0 |
| TCJSW | temperature coefficient of CJSW | 1/K | 0.0 |
| TCJSWG | temperature coefficient of CJSWG | 1/K | 0.0 |
| TPB | temperature coefficient of PB | V/K | 0.0 |
| TPBSW | temperature coefficient of PBSW | V/K | 0.0 |

| Parameter ¹ | Description | Unit | Default |
|------------------------|--|--------------------------|----------------------------------|
| TPBSWG | temperature coefficient of PBSWG | V/K | 0.0 |
| UA1 | temperature coefficient for UA | m/V | 4.31E-9 |
| UB1 | temperature coefficient for ∪B | $(m/V)^2$ | -7.61E-18 |
| UC1 | temperature coefficient for uc | m/V ² | -5.6E -11 when MOBMOD=1 or |
| | | 1/V | 2 |
| | | | -0.056 when мовмор=3 |
| UTE | mobility temperature exponent | none | -1.5 |
| XTI | junction current temperature exponent coefficient | none | 3.0 |
| | level 7: W and L parameters | | |
| LL | coefficient of length dependence for length offset | m ^{LLN} | 0.0 |
| LLC | coefficient for length dependence for CV channel length offset | LI | m ^{Lln} |
| LLN | power of length dependence for length offset | none | 1.0 |
| LW | coefficient of width dependence for length offset | m ^{LWN} | 0.0 |
| LWC | coefficient for width dependence for CV channel length offset | m ^{Lwn} | Lw |
| LWL | coefficient of length and width cross term for length offset | m ^{LWN+LL} N | 0.0 |
| LWLC | coefficient for length and width dependence for CV channel length offset | m ^{Lln+Lwn} | Lwl |
| LWN | power of width dependence for length offset | none | 1.0 |
| WL | coefficient of length dependence for width offset | m ^{WLN} | 0.0 |
| WLC | coefficient of length dependence for CV channel width offset | m ^{Wln} | WI |
| | | | |

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|--|------------------------|
| WLN | power of length dependence of width offset | none | 1.0 |
| WW | coefficient of width dependence for width offset | m ^{WWN} | 0.0 |
| WWC | coefficient for width dependence for CV channel width offset | m ^{Wwn} | Ww |
| WWL | coefficient of length and width cross term for width offset | m ^{WWN+W} LN | 0.0 |
| WWLC | coefficient for length and width dependence for CV channel width offset | m ^{WIn+Wwn} | WwI |
| WWN | power of width dependence of width offset | none | 1.0 |
| | Level 8: Gate-Induced Drain Leakage Para | meters | |
| AGIDL | Pre-exponential coefficient for GIDL | Mho | 0.0 |
| BGIDL | Exponential coefficient for GIDL | V/m | 2.3e9 |
| CGIDL | Paramter for body-bias effect on GIDL | V^3 | 0.5 |
| DGIDL | Fitting parameter for band bending for GIDL | V | 0.8 |
| | Level 8: Gate Dielectric Tunneling Current Pa | arameters | |
| AIGBACC | Parameter for I _{gb} in accumulation | (Fs ² / g) ^{0.5} m ⁻¹ | 0.43 |
| BIGBACC | Parameter for I _{gb} in accumulation | (Fs ² / g) ^{0.5} m ⁻¹ V ⁻ | 0.054 |
| CIGBACC | Parameter for Igb in accumulation | V ⁻¹ | 0.075 |
| NIGBACC | Parameter for I _{gb} in accumulation | none | 1.0 |
| AIGBINV | Parameter for I _{gb} in inversion | (Fs ² / g) ^{0.5} m ⁻¹ | 0.35 (Fs2/ g)0.5m-1 |
| BIGBINV | Parameter for I _{gb} in inversion | $(Fs^2/g)^{0.5}$ $m^{-1}V^{-1}$ | 0.03 |
| CIGBINV | Parameter for I _{gb} in inversion | V ⁻¹ | 0.006 |
| EIGBINV | Parameter for I _{gb} in inversion | V | 1.1 |
| NIGBINV | Parameter for I _{gb} in inversion | none | 3.0 |

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|---|--|
| AIGC | Parameter for I _{gcs} and I _{gcd} | (Fs ² / g) ^{0.5} m ⁻¹ | 0.054 (NMOS) and 0.31 (PMOS) |
| | Level 8: Charge and Capacitance Param | eters | |
| CKAPPAS | Coefficient of bias-dependent overlap capacitance for the source side | V | 0.6 |
| CKAPPAD | Coefficient of bias-dependent overlap capacitance for the drain side | | CKAPPAS |
| Leve | el 8: Asymmetric Source/Drain Junction Dioc | de Paramet | ters |
| IJTHSREV IJTHDREV | Limiting current in reverse bias region | Α | IJTHSREV =0.1 IJTHDREV =IJTHSREV |
| IJTHSFWD IJTHDFWD | Limiting current in forward bias region | Α | IJTHSFWD =0.1 IJTHDFWD =IJTHS¬FW D |
| XJBVS XJBVD | Fitting parameter for diode breakdown | none | XJBVS=1.0 XJBVD =XJBVS |
| BVS BVD | Breakdown voltage | V | BVS=10.0 BVD=BVS |
| JSS JSD | Bottom junction reverse saturation current density | A/m ² | JSS= 1.0e-4 JSD=JSS |
| JSWS JSWD | Isolation-edge sidewall reverse saturation current density | A/m | JSWS =0.0 JSWD =JSWS |
| JSWGS JSWGD | Gate-edge sidewall reverse saturation current density | A/m | JSWGS =0.0 JSWGD =JSWGS |
| CJS CJD | Bottom junction capacitance per unit area at zero bias | F/m ² | CJS=5.0e-4 CJD=CJS |

Analog Devices

MOSFET model parameters, continued

| Parameter ¹ | Description | Unit | Default |
|------------------------|---|--------|--------------------------------------|
| MJS MJD | Bottom junction capacitance grating coefficient | none | MJS=0.5 MJD=MJS |
| MJSWS MJSWD | Isolation-edge sidewall junction capacitance grading coefficient | none | MJSWS =0.33 MJSWD =MJSWS |
| CJSWS CJSWD | Isolation-edge sidewall junction capacitance per unit area | F/m | CJSWS= 5.0e-10 CJSWD =CJSWS |
| CJSWGS CJSWGD | Gate-edge sidewall junction capacitance per unit length | F/m | CJSWGS =CJSWS CJSWGD =CJSWS |
| MJSWGS MJSWGD | Gate-edge sidewall junction capacitance grading coefficient | none | MJSWGS =MJSWS MJSWGD =MJSWS |
| РВ | Bottom junction built-in potential | V | PBS=1.0 PBD=PBS |
| PBSWS PBSWD | Isolation-edge sidewall junction built-in potential | V | PBSWS =1.0 PBSWD =PBSWS |
| PBSWGS PBSWGD | Gate-edge sidewall junction built-in potential | V | PBSWGS =PBSWS PBSWGD =PBSWS |
| | Level 8: Temperature Dependence Param | neters | |
| NJS, NJD | Emission coefficients of junction for source and drain junctions, respectively | none | NJS=1.0; NJD=NJS |
| XTIS, XTID | Junction current temperature exponents for source and drain junctions, respectively | none | XTIS=3.0; XTID=XTIS |

^{1.} See .MODEL (model definition) on page 57.

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- 2. A ζ in the Default column indicates that the parameter may have corresponding parameters exhibiting length and width dependence. See <u>Model level 4</u> on page 242.
- † For information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see <u>.MODEL (model definition)</u> on page 57.

Analog Devices

MOSFET Equations

These equations describe an N-channel MOSFET. For P-channel devices, reverse the signs of all voltages and currents.

In the following equations:

Vbs = intrinsic substrate-intrinsic source voltage

Vbd = intrinsic substrate-intrinsic drain voltage

Vds = intrinsic drain-intrinsic source voltage

Vdsat = saturation voltage

Vgs = intrinsic gate-intrinsic source voltage

Vgd = intrinsic gate-intrinsic drain voltage

Vt = $k \cdot T/q$ (thermal voltage)

Vth = threshold voltage

C_{ox} = the gate oxide capacitance per unit area.

f = noise frequency

k = Boltzmann's constant

q = electron charge

Leff = effective channel length

Weff = effective channel width

T = analysis temperature ($^{\circ}$ K)

Tnom = nominal temperature (set using TNOM option)

Other variables are from MOSFET model parameters on page 242.

Note: Positive current is current flowing into a terminal (for example, positive drain current flows from the drain through the channel to the source).

MOSFET equations for DC current

All levels

Analog Devices

```
Ig = gate current = 0
    Ib = bulk current = Ibs+Ibd
         where
         Ibs = bulk-source leakage current = Iss·(e^{Vbs/(N\cdot Vt)}-1)
         Ibd = bulk-drain leakage current = Ids \cdot (e^{Vbd/(N\cdot Vt)}-1)
            where
             if:
                  JS = 0, or AS = 0, or AD = 0
             then:
                 Iss = IS
                 Ids = IS
             else
                 Iss = AS \cdot JS + PS \cdot JSSW
                 Ids = AD \cdot JS + PD \cdot JSSW
    Id = drain current = Idrain-Ibd
    Is = source current = -Idrain-Ibs
Level 1: Idrain
Normal mode: Vds > 0
    Case 1
         for cutoff region: Vgs-Vto < 0
            then: Idrain = 0
    Case 2
         for linear region: Vds < Vgs-Vto
          Idrain = (W/L) \cdot (KP/2) \cdot (1 + LAMBDA \cdot Vds) \cdot Vds \cdot (2 \cdot (Vgs - Vto) - Vds)
    Case 3
         for saturation region: 0 ≤ Vgs-Vto ≤ Vds
         then: Idrain = (W/L) \cdot (KP/2) \cdot (1+LAMBDA \cdot Vds) \cdot (Vgs-Vto)^2
             where
            Vto = VTO+GAMMA \cdot ((PHI-Vbs)^{1/2}-PHI^{1/2})
```

Analog Devices

Inverted mode: Vds < 0

Switch the source and drain in the normal mode equations above.

Levels 2 and 3: Idrain

See reference [2] of References on page 283 for detailed information.

MOSFET equations for capacitance

Note: All capacitances are between terminals of the intrinsic MOSFET, in other words, to the inside of the ohmic drain and source resistances. For levels 1, 2, and 3, the capacitance model has been changed to conserve charge.

Levels 1, 2, and 3

```
Cbs = bulk-source capacitance
    = area cap. + sidewall cap. + transit time cap.
Cbd = bulk-drain capacitance
    = area cap. + sidewall cap. + transit time cap.
   where:
   if: CBS = 0 AND CBD = 0
   then
       Cbs = AS·CJ·Cbsj + PS·CJSW·Cbss + TT·Gbs
       Cbd = AD·CJ·Cbdj + PD·CJSW·Cbds + TT·Gds
   else
       Cbs = CBS·Cbsj + PS·CJSW·Cbss + TT·Gbs
       Cbd = CBD·Cbdj + PD·CJSW·Cbds + TT·Gds
          where:
          Gbs = DC bulk-source conductance = dIbs/dVbs
          Gbd = DC bulk-drain conductance = dIbd/dVbd
   if: Vbs \leq FC \cdot PB
   then
      Cbsj = (1-Vbs/PB)^{-MJ}
      Cbss = (1-Vbs/PBSW)-MJSW
   if: Vbs > FC · PB
```

Analog Devices

```
then

Cbsj = (1-FC)-(1+MJ). (1-FC·(1+MJ)+MJ·Vbs/PB)
Cbss = (1-FC)-(1+MJSW). (1-FC·(1+MJSW)+MJSW·Vbs/PBSW)

if: Vbd \leq FC·PB

then

Cbdj = (1-Vbd/PB)-MJ
Cbds = (1-Vbd/PBSW)-MJSW

if: Vbd > FC·PB

then

Cbdj = (1-FC)-(1+MJ). (1-FC·(1+MJ)+MJ·Vbd/PB)
Cbds = (1-FC)-(1+MJSW). (1-FC·(1+MJSW))

Cgs = gate-source overlap capacitance = CGSO·W

Cgd = gate-bulk overlap capacitance = CGBO·L
```

Levels 4 and 6

See references [6] and [7] of References on page 283.

MOSFET equations for temperature effects

Note: The ohmic (parasitic) resistances have no temperature dependence.

All Levels

```
IS(T) = IS \cdot e^{(Eg(Tnom) \cdot T/Tnom - Eg(T))/Vt}
JS(T) = JS \cdot e^{(Eg(Tnom) \cdot T/Tnom - Eg(T))/Vt}
JSSW(T) = JSSW \cdot e^{(Eg(Tnom) \cdot T/Tnom - Eg(T))/Vt}
PB(T) = PB \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
PBSW(T) = PBSW \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
PHI(T) = PHI \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
where
Eg(T) = silicon bandgap energy = 1.16 - .000702 \cdot T^2/(T+1108)
```

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```
CBD(T) = CBD · (1+MJ · (.0004 · (T-Tnom) + (1-PB(T) / PB)))

CBS(T) = CBS · (1+MJ · (.0004 · (T-Tnom) + (1-PB(T) / PB)))

CJ(T) = CJ · (1+MJ · (.0004 · (T-Tnom) + (1-PB(T) / PB)))

CJSW(T) = CJSW · (1+MJSW · (.0004 · (T-Tnom) + (1-PB(T) / PB)))

KP(T) = KP · (T/Tnom) -3/2

UO(T) = UO · (T/Tnom) -3/2

MUS(T) = MUS · (T/Tnom) -3/2

X3MS(T) = X3MS · (T/Tnom) -3/2
```

MOSFET equations for noise

Noise is calculated assuming a 1.0-hertz bandwidth, using the following spectral power densities (per unit bandwidth).

The model parameter NLEV is used to select the form of shot and flicker noise, and GDSNOI is the channel shot noise coefficient model parameter. When NLEV<3, the original SPICE2 shot noise equation is used in both the linear and saturation regions, but the use of this equation may produce inaccurate results in the linear region. When NLEV=3, a different equation is used that is valid in both linear and saturation regions.

Note: For level 7 BSIM3 version 3.1 devices, the noise model NOIMOD (and its parameters) is used rather than the PSpice noise model NLEV.

The model parameters AF and KF are used in the small-signal AC noise analysis to determine the equivalent MOSFET flicker noise.

For more information, see reference [5] of References on page 283.

MOSFET channel shot and flicker noise

$$Ichan^2 = Ishot^2 + Iflick^2$$

Intrinsic MOSFET flicker noise

for
$$NLEV = 0$$

$$Iflick^2 = \frac{\mathbf{KF} \cdot Idrain^{\mathbf{AF}}}{COX \cdot Leff^2 \cdot f}$$

for NLEV = 1

$$Iflick^2 = \frac{\mathbf{KF} \cdot Idrain^{\mathbf{AF}}}{COX \cdot Weff \cdot Leff \cdot f}$$

for NLEV = 2, NLEV = 3

$$Iflick^{2} = \frac{\mathbf{KF} \cdot gm^{2}}{COX \cdot Weff \cdot Leff \cdot f^{\mathbf{AF}}}$$

Intrinsic MOSFET shot noise

for NLEV < 3

$$Ishot^2 = \frac{8 \cdot k \cdot T \cdot gm}{3}$$

for NLEV = 3

and

for NOIMOD < 3 (BSIM3 level 7)</pre>

Ishot²
$$\equiv \frac{8 \cdot k \cdot T}{3} \times \beta \times (Vgs - Vth) \frac{1 + a + a^2}{1 + a} \times GDSNOI$$

where:

for linear region: a = 1 - (Vds/Vdsat)

for saturation region: a = 0

parasitic resistance thermal noise

RD
$$Id^2 = 4 \cdot k \cdot T / RD$$

RG
$$Iq^2 = 4 \cdot k \cdot T/RG$$

RS
$$Is^2 = 4 \cdot k \cdot T/RS$$

$$RB Ib^2 = 4 \cdot k \cdot T / RB$$

Note:

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References

For a more complete description of the MOSFET models, refer to:

- [1] H. Shichman and D. A. Hodges, "Modeling and simulation of insulated-gate field-effect transistor switching circuits," *IEEE Journal of Solid-State Circuits*, SC-3, 285, September 1968.
- [2] A. Vladimirescu, and S. Lui, "The Simulation of MOS Integrated Circuits Using SPICE2," Memorandum No. M80/7, February 1980.
- [3] B. J. Sheu, D. L. Scharfetter, P.-K. Ko, and M.-C. Jeng, "BSIM: Berkeley Short-Channel IGFET Model for MOS Transistors," *IEEE Journal of Solid-State Circuits*, SC-22, 558-566, August 1987.
- [4] J. R. Pierret, "A MOS Parameter Extraction Program for the BSIM Model," Memorandum No. M84/99 and M84/100, November 1984.]
- [5] P. Antognetti and G. Massobrio, *Semiconductor Device Modeling with SPICE*, McGraw-Hill, 1993.
- [6] Ping Yang, Berton Epler, and Pallab K. Chatterjee, "An Investigation of the Charge Conservation Problem for MOSFET Circuit Simulation," *IEEE Journal of Solid-State Circuits*, Vol. SC-18, No.1, February 1983.
- [7] J.H. Huang, Z.H. Liu, M.C. Jeng, K. Hui, M. Chan, P.K. KO, and C. Hu, "BSIM3 Manual," Department of Electrical Engineering and Computer Science, University of California, Berkeley, CA 94720.
- [8] Department of Electrical Engineering and Computer Science, "BSIM3v3.2 MOSFET Model User's Manual," University of California, Berkeley, CA 94720.
- [9] J. C. Bowers, and H. A. Neinhaus, *SPICE2 Computer Models for HEXFETs*, Application Note 954A, reprinted in HEXFET Power MOSFET Databook, International Rectifier Corporation #HDB-3.
- [10] M. Bucher, C. Lallement, C. Enz, F. Theodoloz, F. Krummenacher. <u>The EPFL–EKV MOSFETModel Equations for Simulation Technical Report: Model Version 2.6</u>. Electronics Laboratories, Swiss Federal Institute of Technology (EPFL), Lausanne, Switzerland. Updated September, 1997.
- [11] Department of Electrical Engineering and Computer Science, BSIM4.1.0 MOSFET Model Users Manual, University of California, Berkeley, CA 94720.

For more information on References [2] and [4], contact:

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Bipolar transistor

General form Q<name> < collector node> <base node> <emitter node>

+ [substrate node] <model name> [area value]

Examples Q1 14 2 13 PNPNOM

Q13 15 3 0 1 NPNSTRONG 1.5 Q7 VC 5 12 [SUB] LATPNP

Model form .MODEL <model name> NPN [model parameters]

.MODEL <model name> PNP [model parameters]
.MODEL <model name> LPNP [model parameters]

Arguments and options

[substrate node]

is optional, and if not specified, the default is the ground.

Because the simulator allows alphanumeric names for nodes, and because there is no easy way to distinguish these from the model names, the name (not a number) used for the substrate node needs to be enclosed with square brackets []. Otherwise, nodes would be interpreted as model names. See the third example.

[area value]

is the relative device area and has a default value of 1.

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Comments

The simulator supports the following two models for a bipolar transistor:

Level 1: Gummel-Poon model

Level 2: Mextram model

Mextram is an extended model that can describe various features of the modern down-scaled transistor, such as avalanche, collector epilayer current, and overlap capacitances. The Mextram model supported by this simulator is level 504. For more information about Mextram 504, you can visit http://www.semiconductors.philips.com/Philips_Models/bipolar/mextram/.

Note: Simulations might take more time for circuit involving the Mextram model in comparison to Gummel-Poon due to the complex nature of the equations. The convergence issues might also be more.

Following is a list of effects that are better modelled by Mextram:

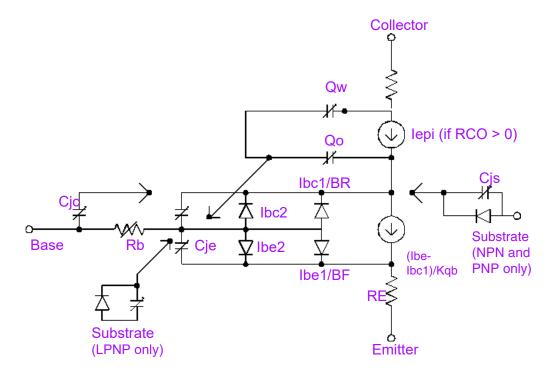
- Temperature
- Charge storage
- Substrate
- Parasitic PNP
- Low-level, non-ideal base currents
- Hard- and quasi-saturation
- Weak avalanche
- Hot carrier effects in the collector epilayer
- Explicit modelling of inactive regions
- Split base-collector depletion capacitance
- Current crowding and conductivity modulation for base resistance
- Distributed high frequency effects in the intrinsic base (high frequency current crowding and excess phase shift)
- High-injection
- Built-in electric field in base region
- Bias-dependent Early effect

Note: The self heating effect of Mextram model level 504 is not supported in release 10.5. As a result, the self heating effect equations and parameters are not implemented in this simulation

Description

The bipolar transistor is modeled as an intrinsic transistor using ohmic resistances in series with the collector (RC/area), with the base (value varies with current, see Bipolar transistor equations on page 306), and with the emitter (RE/area).

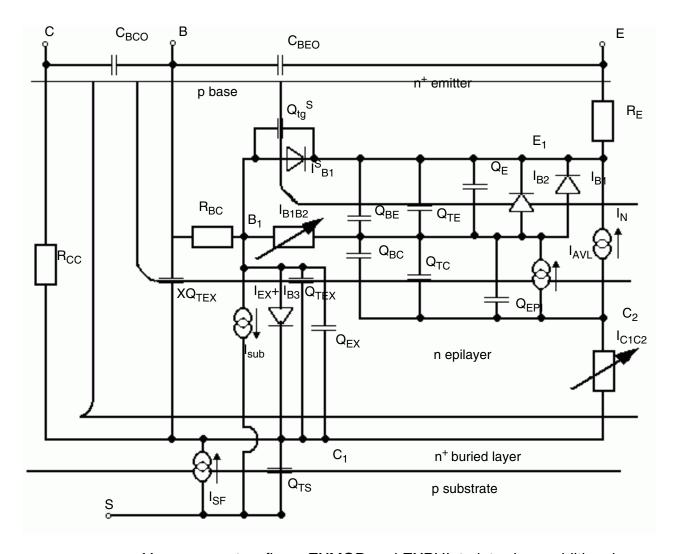
Model Level 1



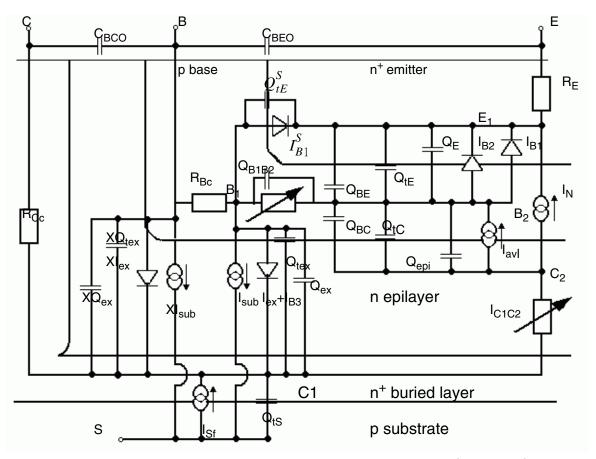
Note: Positive current is current flowing into a terminal.

Model Level 2

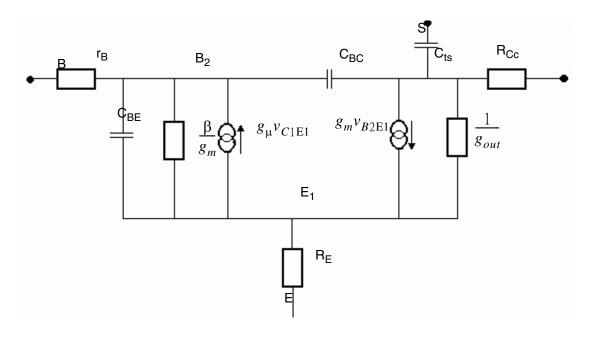
The equivalent circuit for model level 2 shows the intrinsic part of the transistor and the base, emitter, and the collector or epilayer resistance.



You can use two flags, EXMOD and EXPHI, to introduce additional elements to the schematic of a transistor in model level 2.



The small signal equivalent circuit is shown by the following figure.



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The small signal model uses the following small-signal parameters:

Note: The conductances are derivatives with respect to three different biases, namely, base-emitter denoted by the subscript x, internal base-collector denoted by the subscript y, and base-collector denoted by the subscript z.

The transconductance, g_m , is given by the following equation:

$$g_{m} = \frac{g_{\text{Rcv,y}}(g_{x} - g_{\mu, x} + g_{z} - g_{\mu, z}) - (g_{\text{Rcv,x}} + g_{\text{Rcv,z}})(g_{y} - g_{\mu, y})}{g_{\text{Rcv,y}} + g_{\mu, y} - g_{y}}$$

The base conductance, g_{π} , is given by the following equation:

$$g_{\pi} = gS_{\pi} + g_{\pi, x} + g_{\mu, x} + g_{\pi, z} + g_{\mu, z} + (g_{\pi, y} + g_{\mu, y}) \left[\frac{dy}{dx} + \frac{dy}{dz} \right]$$

The current amplification, β , is given by the following equation:

$$\beta = g_m/g_{\pi}$$

The output conductance, g_{out} , is given by the following equation:

$$g_{out} = \frac{(g_y - g_{\mu, y})g_{Rcv, z} - (g_z - g_{\mu, z})g_{Rcv, y}}{g_{Rcv, y} + g_{\mu, y} - g_y}$$

The feedback transconductance, g_{μ} , is given by the following equation:

$$g_{\mu} = g_{\pi, z} + g_{\mu, z} + (g_{\pi, y} + g_{\mu, y}) \cdot \frac{dy}{dz} + g_{\mu ex} + Xg_{\mu ex}$$

The base-emitter capacitance, C_{BE} , is given by the following equation:

$$C_{BE} = C_{\text{BE,x}} + C_{BE}^{S} + C_{\text{BC,x}} + (C_{\text{BE,y}} + C_{\text{BC,y}}) \cdot \frac{dy}{dx} + C_{BEO}$$

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The base-collector capacitance, C_{BC} , is given by the following equation:

$$C_{BC} = (C_{\text{BE,y}} + C_{\text{BC,y}}) \cdot \frac{dy}{dz} + C_{\text{BC,z}} + C_{\text{BCex}} + XC_{\text{BCex}} + C_{BCO}$$

In addition to the listed parameters, the cut-off frequency f_T is another important design parameter. The cut-off frequency is a compound small-signal quantity and can be represented in terms of the total transit time, as given by the following equation:

$$f_T = 1/(2\pi\tau_T)$$

The total transit time, τ_T , is given by the following equation:

$$\begin{split} \tau_T &= \left. C_{BE}^{\quad S} \cdot (r_x + r_{b1b2}) + (C_{\text{BE},x} + C_{\text{BC},x}) \cdot r_x \right. \\ &\left. \left(C_{\text{BE},y} + C_{\text{BC},y} \right) \cdot r_y + (C_{\text{BE},z} + C_{\text{BC},z}) \cdot r_z + C_{\text{BCex}} r_{ex} \right. \\ &\left. X C_{\text{BCex}} X r_{ex} + (C_{BEO} + C_{BCO}) (X r_{ex} - R_{Cc}) \right. \end{split}$$

For model parameters with alternate names, such as VAF and VA (the alternate name is shown by using parentheses), either name can be used.

For model types NPN and PNP, the isolation junction capacitance is connected between the intrinsic-collector and substrate nodes. This is the same as in SPICE2, or SPICE3, and works well for vertical IC transistor structures. For lateral IC transistor structures there is a third model, LPNP, where the isolation junction capacitance is connected between the intrinsic-base and substrate nodes.

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parts

The following table lists the set of bipolar transistor breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

Table 2-5 Bipolar Transistor Breakout Parts

| Part name | Model type | Property | Property description |
|---------------------------------|------------|---------------|---------------------------------------|
| QBREAKL | LPNP | AREA MODEL | area scaling factor LNP model name |
| QBREAKN QBREAKN3 QBREAKN4 | NPN | AREA MODEL | area scaling factor NPN model name |
| QBREAKP QBREAKP3 QBREAKP4 | PNP | AREA MODEL | area scaling factor PNP model name |
| QVBICN ¹ | NPN | MODEL | NPN Model Name |

^{1.} Model Defination of QVBICN - .model QVBICN CMI VBIC npn=1 Netlist instance - Y_Q1 C B E S CMI orPSpiceDevices64.dll QVBICN.

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter. See <u>Bipolar transistor model parameters</u> on page 293 for more information.

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Bipolar transistor model parameters

Model level 1

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|----------------------------|
| AF | flicker noise exponent | | 1.0 |
| BF | ideal maximum forward beta | | 100.0 |
| BR | ideal maximum reverse beta | | 1.0 |
| CJC | base-collector zero-bias p-n capacitance | farad | 0.0 |
| CJE | base-emitter zero-bias p-n capacitance | farad | 0.0 |
| CJS (CCS) | substrate zero-bias p-n capacitance | farad | 0.0 |
| CN | quasi-saturation temperature coefficient for hole mobility | | 2.42 NPN 2.20 PNP |
| D | quasi-saturation temperature coefficient for scattering-limited hole carrier velocity | | 0.87 NPN 0.52 PNP |
| EG | bandgap voltage (barrier height) | eV | 1.11 |
| FC | forward-bias depletion capacitor coefficient | | 0.5 |
| GAMMA | epitaxial region doping factor | | 1E-11 |
| IKF (IK) | corner for forward-beta high-current roll-off | amp | infinite |
| IKR | corner for reverse-beta high-current roll-off | amp | infinite |
| IRB | current at which Rb falls halfway to | amp | infinite |
| IS | transport saturation current | amp | 1E-16 |
| ISC (C4) † | base-collector leakage saturation current | amp | 0.0 |
| ISE (C2) † | base-emitter leakage saturation current | amp | 0.0 |
| ISS | substrate p-n saturation current | amp | 0.0 |
| ITF | transit time dependency on Ic | amp | 0.0 |

| | Description | 11! | Deferri |
|-------------------------------|---|-------------|---------|
| Model parameters ¹ | Description | Units | Default |
| KF | flicker noise coefficient | | 0.0 |
| MJC (MC) | base-collector p-n grading factor | | 0.33 |
| MJE (ME) | base-emitter p-n grading factor | | 0.33 |
| MJS (MS) | substrate p-n grading factor | | 0.0 |
| NC | base-collector leakage emission coefficient | | 2.0 |
| NE | base-emitter leakage emission coefficient | | 1.5 |
| NF | forward current emission coefficient | | 1.0 |
| NK | high-current roll-off coefficient | | 0.5 |
| NR | reverse current emission coefficient | | 1.0 |
| NS | substrate p-n emission coefficient | | 1.0 |
| PTF | excess phase @ $1/(2\pi \cdot TF)Hz$ | degree | 0.0 |
| QCO | epitaxial region charge factor | coulom b | 0.0 |
| QUASIMOD | quasi-saturation model flag for temperature dependence | | 0 |
| | if QUASIMOD = 0, then no GAMMA, RCO, VO temperature dependence | | |
| | if QUASIMOD = 1, then include GAMMA, RCO, VO temperature dependence | | |
| RB | zero-bias (maximum) base resistance | ohm | 0.0 |
| RBM | minimum base resistance | ohm | RB |
| RC | collector ohmic resistance | ohm | 0.0 |
| RCO‡ | epitaxial region resistance | ohm | 0.0 |
| RE | emitter ohmic resistance | ohm | 0.0 |
| TF | ideal forward transit time | sec | 0.0 |
| TR | ideal reverse transit time | sec | 0.0 |
| TRB1 | RB temperature coefficient (linear) | °C-1 | 0.0 |
| TRB2 | RB temperature coefficient (quadratic) | °C-2 | 0.0 |
| | | | |

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| Model parameters ¹ | Description | Units | Default |
|-------------------------------|--|-------|----------|
| TRC1 | RC temperature coefficient (linear) | °C-1 | 0.0 |
| TRC2 | RC temperature coefficient (quadratic) | °C-2 | 0.0 |
| TRE1 | RE temperature coefficient (linear) | °C-1 | 0.0 |
| TRE2 | RE temperature coefficient (quadratic) | °C-2 | 0.0 |
| TRM1 | RBM temperature coefficient (linear) | °C-1 | 0.0 |
| TRM2 | RBM temperature coefficient (quadratic) | °C-2 | 0.0 |
| T_ABS | absolute temperature | °C | |
| T_MEASURED | measured temperature | °C | |
| T_REL_GLOBAL | relative to current temperature | °C | |
| T_REL_LOCAL | relative to AKO model temperature | °C | |
| VAF (VA) | forward Early voltage | volt | infinite |
| VAR (VB) | reverse Early voltage | volt | infinite |
| VG | quasi-saturation extrapolated bandgap voltage at $0^{\circ}\ \text{K}$ | V | 1.206 |
| VJC (PC) | base-collector built-in potential | volt | 0.75 |
| VJE (PE) | base-emitter built-in potential | volt | 0.75 |
| VJS (PS) | substrate p-n built-in potential | volt | 0.75 |
| VO | carrier mobility knee voltage | volt | 10.0 |
| VTF | transit time dependency on Vbc | volt | infinite |
| XCJC | fraction of cuc connected internally to Rb | | 1.0 |
| XCJC2 | fraction of cuc connected internally to Rb | | 1.0 |
| XCJS | fraction of cJs connected internally to Rc | | |
| XTB | forward and reverse beta temperature coefficient | | 0.0 |
| XTF | transit time bias dependence coefficient | | 0.0 |
| XTI (PT) | IS temperature effect exponent | | 3.0 |

^{1.} For information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see <u>.MODEL (model definition)</u> on page 57.

[†] The parameters ISE (C2) and ISC (C4) can be set to be greater than one. In this case, they are

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interpreted as multipliers of IS instead of absolute currents: that is, if ISE is greater than one, then it is replaced by ISE·IS. Likewise for ISC.

‡ If the model parameter RCO is specified, then quasi-saturation effects are included.

Distribution of the CJC capacitance

The distribution of the CJC capacitance is specified by xCJC and XCJC2. The model parameter xCJC2 is used like XCJC. The differences between the two parameters are as follows.

| Branch | XCJC | XCJC2 |
|--|------------------|-------------------|
| intrinsic base to intrinsic collector | XCJC*CJC | XCJC2*CJC |
| extrinsic base to intrinsic collector | (1.0 – XCJC)*CJC | not applicable |
| extrinsic base to extrinsic collector | not applicable | (1.0 - XCJC2)*CJC |

When xcJc2 is specified in the range 0 < xcJc2 < 1.0, xcJc is ignored. Also, the extrinsic base to extrinsic collector capacitance (Cbx2) and the gain-bandwidth product (Ft2) are included in the operating point information (in the output listing generated during a Bias Point Detail analysis, .OP (bias point) on page 70). For backward compatibility, the parameter xcJc and the associated calculation of Cbx and Ft remain unchanged. Cbx and Ft appears in the output listing only when xcJc is specified.

The use of xcJc2 produces more accurate results because Cbx2 (the fraction of cJc associated with the intrinsic collector node) now equals the ratio of the device's emitter area-to-base area. This results in a better correlation between the measured data and the gain bandwidth product (Ft2) calculated by PSpice.

xcJs, which is valid in the range $0 \le xcJs \le 1.0$, specifies a portion of the cJs capacitance to be between the external substrate and external collector nodes instead of between the external substrate and internal collector nodes. When xJcs is 1, cJs is applied totally between the external substrate and internal collector nodes. When xCJs is 0, cJs is applied totally between the external substrate and external collector codes.

Model level 2

| Model Parameters | Description | Units | Default Value |
|---------------------|-------------|-------|---------------|
| | | | |

Level 2: general parameters

| Model Parameters | Description | Units | Default Value |
|-----------------------|--|---------|---------------|
| EXAVL | flag for the extended modelling of avalanche currents | | 0 |
| EXMOD | flag for the extended modelling of the external regions | | 0 |
| EXPHI | flag for the extended modelling of distributed HF effects in transients | | 0 |
| MULT | number of parallel transistors modelled together | | 1.0 |
| Level 2: intrinsic ar | nd extrinsic charge and current split param | eters | |
| XCJC | sidewall fraction collector-base depletion capacitance that is under the emitter | farad | 32E-03 |
| XCJE | sidewall fraction of the emitter-base depletion capacitance | farad | 0.4 |
| XEXT | fraction of external charges between B and C1 | coulomb | 0.63 |
| XIBI | sidewall fraction of the ideal base current | amp | 0.0 |
| Level 2: current pa | rameters | | |
| BF | current gain of ideal forward base current | t | 215.0 |
| BRI (BR) | current gain of ideal reverse base current | t | 7.0 |
| IBF | saturation current of the non-ideal forward base current | | 2.7E-15 |
| IBR | saturation current of the non-ideal reverse base current | amp | 1.0E-15 |
| IK (IKF) | intrinsic transistor high-injection knee current | amp | 0.1 |
| IKS | parasitic PNP transistor high-knee current | amp | 250.0E-6 |
| IS | intrinsic transistor saturation current | amp | 22.0E-18 |
| ISS | parasitic PNP transistor saturation current | amp | 48.0E-18 |

| Model Parameters | Description | Units | Default Value |
|---------------------|--|-------|---------------|
| MLF | non-ideality factor of the non-ideal forward base current | | 2.0 |
| SFH | Voltage describing the curvature of the avalanche current | volt | 0.3 |
| VAVL | Voltage for the curvature of the avalanche current | volt | 3.0 |
| VEF (VAF) | forward early voltage of the intrinsic transistor | volt | 44.0 |
| VER (VAR) | reverse early voltage of the intrinsic transistor | volt | 2.5 |
| VLR | non-ideal base current cross-over voltage | volt | 0.2 |
| WAVL | effective width of epilayer for avalanche current | m | 1.1E-6 |
| Level 2: resistance | e parameters (variable and constant) | | |
| AXI | smoothing parameters for the epilayer model | | 0.3 |
| IHC | epilayer critical current for hot-carriers | amp | 4.0E-3 |
| RBC | external base constant resistance | ohm | 23.0 |
| RBV | pinched base low current resistance (under the emitter) | ohm | 18.0 |
| RCC (RC) | external collector constant resistance | ohm | 12 |
| RCV | epilayer low current resistance | ohm | 150.0 |
| RE | external emitter constant resistance | ohm | 5.0 |
| SCRCV | epilayer space charge resistance | ohm | 1250.0 |
| Level 2: depletion | capacitance parameters | | |
| CBCO | base-collector overlap capacitance | farad | 0.0 |
| CBEO | base-emitter overlap capacitance | farad | 0.0 |
| CJC | collector-base junction depletion capacitance at zero bias | farad | 78.0E-15 |

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| Model Parameters | Description | Units | Default Value | |
|---------------------------------|---|-------|---------------|--|
| CJE | emitter-base junction depletion capacitance at zero bias | farad | 73.0E-15 | |
| CJS | collector-substrate junction depletion capacitance at zero bias | farad | 315.0E-15 | |
| MC (MJC) | collector depletion charge current modulation factor | | 0.5 | |
| PC (VJC) | collector-base depletion capacitance grading coefficient | | 0.5 | |
| PE (VJE) | emitter-base depletion capacitance grading coefficient | | 0.4 | |
| PS (VJS) | collector-substrate depletion capacitance grading coefficient | | 0.34 | |
| VDC | built-in diffusion voltage collector-base | volt | 0.68 | |
| VDE | built-in diffusion voltage emitter-base | volt | 0.95 | |
| VDS | built-in diffusion voltage emitter- substrate | volt | 0.62 | |
| XP (XC) | constant fraction of collector-base depletion capacitance | farad | 0.35 | |
| Level 2: transit time | e parameters (diffusion charges) | | | |
| TAUB | base transmit time | sec | 4.2E-12 | |
| TAUE | emitter charge transmit time | sec | 2.0E-12 | |
| TEPI | collector epilayer transmit time | sec | 41.0E-12 | |
| TAUR | reverse transmit time | sec | 520.0E-12 | |
| MTAU | emitter charge non-ideality factor | | 1.0 | |
| Level 2: noise parameters | | | | |
| AF | flickernoise exponent | | 2.0 | |
| KF | ideal base current flickernoise coefficient | t | 2.0E-11 | |
| KFN | non-ideal base current flickernoise coefficient | | 2.0E-11 | |
| Level 2: temperature parameters | | | | |

| Model | | | |
|------------|---|------------------|---------------|
| Parameters | Description | Units | Default Value |
| AB | temperature coefficient of RB (pinched base low current resistance) | °C ⁻¹ | 1.0 |
| AC | temperature coefficient of RCC (external collector constant resistance) | °C ⁻¹ | 2.0 |
| AE | temperature coefficient of RE (external emitter constance resistance) | °C ⁻¹ | 0.0 |
| AEPI | temperature coefficient of RCV (epilayer low current resistance) | °C ⁻¹ | 2.5 |
| AEX | temperature coefficient of RBC (external base constant resistance) | °C ⁻¹ | 0.62 |
| AQBO | zero bias base charge temperature coefficient | °C ⁻¹ | 0.3 |
| AS | temperature coefficient of the mobility related to the substrate currents | °C ⁻¹ | 1.58 |
| DVGBF | band-gap voltage difference for forward current gain | volt | 0.05 |
| DVGBR | band-gap voltage difference for reverse current gain | volt | 0.045 |
| DVGTE | band-gap voltage difference for emitter charge | volt | 0.05 |
| DTA | difference between device and ambient temperature | $^{\circ}C$ | 0.0 |
| TREF | reference temperature | $^{\circ}C$ | 25.0 |
| | if a value is defined for .temp, it will override the value specified in the TREF parameter | | |
| VGB | base band-gap voltage | volt | 1.17 |
| VGC | collector band-gap voltage | volt | 1.18 |
| VGJ | base-emitter junction recombination band-gap voltage | volt | 1.15 |
| VGS | substrate band-gap voltage | volt | 1.20 |

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| Model Parameters | Description | Units | Default Value | |
|--------------------------|------------------------------|-------|---------------|--|
| Level 2: SiGe parameters | | | | |
| DEG | base band-gap difference | | 0.0 | |
| XREC | base recombination prefactor | | 0.0 | |

VBIC (QVBICN) Model parameters

| Model Parameter | Description | Units | Default Value |
|-----------------|--|-------|---------------|
| TNOM | nominal parameter measurement temperature | С | 27.0 |
| RCX | extrinsic collector resistance | Ohm | 0.0 |
| RCI | intrinsic collector resistance | Ohm | 0.0 |
| VO | EPI drift saturation voltage | V | 0.0 |
| GAMM | EPI doping parameter | - | 0.0 |
| HRCF | high current collector resistance factor | V | 0.0 |
| RBI | intrinsic base resistance | Ohm | 0.0 |
| RBX | extrinsic base resistance | Ohm | 0.0 |
| RE | extrinsic emitter resistance | Ohm | 0.0 |
| RS | extrinsic substrate resistance | Ohm | 0.0 |
| RBP | parasitic transistor base resistance | Ohm | 0.0 |
| IS | transport saturation current | Α | 1.0e-16 |
| NF | forward emission coefficient (ideality factor) | - | 1.0 |
| NR | reverse emission coefficient (ideality factor) | - | 1.0 |
| FC | forward bias depletion capacitance limit | - | 0.9 |
| CBEO | extrinsic base-emitter overlap capacitance | F | 0.0 |
| CJE | zero-bias base-emitter depletion capacitance | F | 0.0 |

| Model Parameter | Description | Units | Default Value | |
|-----------------|---|-------|---------------|--|
| PE | base-emitter built-in potential | V | 0.75 | |
| ME | base-emitter grading coefficient | - | 0.33 | |
| AJE | base-emitter capacitance smoothing factor | - | -0.5 | |
| CBCO | extrinsic base-collector overlap capacitance | F | 0.0 | |
| CJC | zero-bias intrinsic base-collector depletion cap | F | 0.0 | |
| QCO | EPI charge parameter | С | 0.0 | |
| CJEP | zero-bias extrinsic base-collector depletion cap | F | 0.0 | |
| PC | base-collector built-in potential | V | 0.75 | |
| MC | base-collector grading coefficient | - | 0.33 | |
| AJC | base-collector capacitance smoothing factor | - | -0.5 | |
| CJCP | zero-bias collector-substrate depletion capacitance | F | 0.0 | |
| PS | collector-substrate built-in potential | V | 0.75 | |
| MS | collector-substrate grading coefficient | - | 0.33 | |
| AJS | collector-substrate capacitance smoothing factor | - | -0.5 | |
| IBEI | ideal base-emitter saturation current | Α | 1.0e-18 | |
| WBE | partitioning of Ibe/Ibex and QBE/QBEX | - | 1.0 | |
| NEI | ideal base-emitter emission coefficient | - | 1.0 | |
| IBEN | non-ideal base-emitter saturation current | Α | 0.0 | |
| NEN | non-ideal base-emitter emission coefficient | - | 2.0 | |
| IBCI | ideal base-collector saturation current | Α | 1.0e-16 | |
| NCI | ideal base-collector emission coefficient | | 0.0 | |
| IBCN | non-ideal base-collector saturation current | Α | 2.0 | |
| NCN | non-ideal base-collector emission coefficient | - | 0.0 | |

| Model Parameter | Description | Units | Default Value |
|-----------------|---|-------|---------------|
| AVC1 | base-collector weak avalanche parameter 1 | /V | 0.0 |
| AVC2 | base-collector weak avalanche parameter 2 | - | 0.0 |
| ISP | parasitic transport saturation current | Α | 0.0 |
| WSP | partitioning of Iccp between VBEP and VBCI | - | 1.0 |
| NFP | parasitic emission coeff (ideality FCTR) | - | 1.0 |
| IBEIP | ideal parasitic base-emitter saturation current | Α | 0.0 |
| IBENP | non-ideal parasitic base-emitter saturation current | Α | 0.0 |
| IBCIP | ideal parasitic base-collector saturation current | Α | 0.0 |
| NCIP | ideal parasitic base-collector emission coefficient | - | 1.0 |
| IBCNP | non-ideal parasitic base-collector saturation current | Α | 0.0 |
| NCNP | non-ideal parasitic base-collector emission coeff | - | 2.0 |
| VEF | forward Early voltage (zero=infinite) | V | 0.0 |
| VER | reverse Early voltage (zero=infinite) | V | 0.0 |
| IKF | forward knee current (zero=infinite) | Α | 0.0 |
| IKR | reverse knee current (zero=infinite) | Α | 0.0 |
| IKP | parasitic knee current (zero=infinite | Α | 0.0 |
| TF | forward transit time | sec | 0.0 |
| QTF | variation of TF with base-width modulation | - | 0.0 |
| XTF | TF bias dependence coefficient | - | 0.0 |
| VTF | TF coefficient of VBCI dependence | V | vtf |
| ITF | TF coefficient of Ic dependence | Α | 0.0 |
| TR | reverse transit time | sec | 0.0 |
| TD | forward excess-phase delay time | sec | 0.0 |

| Model Parameter | Description | Units | Default Value |
|-----------------|---|-------|---------------|
| KFN | base-emitter flicker noise constant | - | 0.0 |
| AFN | base-emitter flicker noise current exponent | - | 1.0 |
| BFN | base-emitter flicker noise 1/f dependence | - | 1.0 |
| XRE | temperature exponent of RE | - | 0.0 |
| XRBI | temperature exponent of RBI | - | 0.0 |
| XRCI | temperature exponent of RCI | - | 0.0 |
| XRS | temperature exponent of RS | - | 0.0 |
| XVO | temperature exponent of VO | - | 0.0 |
| EA | activation energy for IS | V | 1.12 |
| EAIE | activiation energy for IBEI | V | 1.12 |
| EAIC | activiation energy for IBCI and IBEIP | V | 1.12 |
| EAIS | activiation energy for IBCIP | V | 1.12 |
| EANE | activiation energy for IBEN | V | 1.12 |
| EANC | activiation energy for IBCN and IBENP | V | 1.12 |
| EANS | activiation energy for IBCNP | V | 1.12 |
| XIS | temperature exponent of IS | - | 3.0 |
| XII | temp exponent of IBEI, IBCI, IBEIP, IBCIP | - | 3.0 |
| XIN | temp exponent of IBEN, IBCN, IBENP, IBCNP | - | 3.0 |
| TNF | temperature exponent of NF and NR | /C | 0.0 |
| TAVC | temperature exponent of AVC2 | /C | 0.0 |
| RTH | thermal resistance | C/W | 0.0 |
| CTH | thermal capacitance | J/C | 0.0 |
| VRT | reach-through voltage for Cbc limiting | V | 0.0 |
| ART | smoothing parameter for reach-through | | 0.1 |
| CCSO | extrinsic collector-substrate overlap capacitance | F | 0.0 |
| QBM | base charge model selection parameter | - | 0.0 |
| | | | |

| Model Parameter | Description | Units | Default Value | |
|-----------------|---|-------|---------------|--|
| NKF | high current beta roll-off parameter | - | 0.5 | |
| XIKF | temperature exponent of IKF - | | 0.0 | |
| XRCX | temperature exponent of RCX | - | 0.0 | |
| XRBX | temperature exponent of RBX | - | 0.0 | |
| XRBP | temperature exponent of RBP | - | 0.0 | |
| ISRR | ratio of IS(reverse) to IS(forward) | - | 1.0 | |
| XISR | temperature exponent for ISRR | - | 0.0 | |
| DEAR | delta activation energy for ISRR | V | 0.0 | |
| EAP | activiation energy for ISP | V | 1.12 | |
| VBBE | base-emitter breakdown voltage | V | 0.0 | |
| NBBE | base-emitter breakdown emission coefficient | - | 1.0 | |
| IBBE | base-emitter breakdown current | Α | 1.0e-6 | |
| TVBBE1 | linear temperature coefficient of VBBE | /C | 0.0 | |
| TVBBE2 | quadratic temperature coefficient of VBBE | /C^2 | 0.0 | |
| TNBBE | temperature coefficient of nbbe | - | 0.0 | |
| EBBE | calculated exp(-VBBE/(nbbe*Vtv)) | - | 0.0 | |
| DTEMP | local temperature rise | С | 0.0 | |
| VERS | version number | - | 1.2 | |
| VREV | revision number | - | 1.0 | |
| XRB | temp exponent of RBX/I, XRBX/I not given | - | 0.0 | |
| XRC | temp exp RCX/I&RBP, XRCX/I&XRBP not given | - | 0.0 | |
| NPN | model type flag for npn | - | 0.0 | |
| PNP | model type flag for pnp | - | 0.0 | |
| M | multiplicity scale factor | - | 1.0 | |
| MAG | multiplicity scale factor | - | 1.0 | |
| PNJMAXI | - | - | 1.0 | |
| | | | | |

Analog Devices

| Model Parameter | Description | Units | Default Value |
|-----------------|--------------------------------------|-------|---------------|
| GMIN | - | - | 1.0e-12 |
| TMIN | minimum temperature | K | -1.0e+02 |
| TMAX | maximum temperature | K | 5.0e+02 |
| SHRINK | shrink factor | - | 0.0 |
| SHRINK2 | shrink2 factor | - | 0.0 |
| OFF | Device initially off | - | 1.0 |
| AREA | area factor | - | 1.0 |
| MAXEXP | maximum allowed value of exponential | - | 1.0e22 |

Bipolar transistor equations

Model level 1

The equations in this section describe an NPN transistor. For the PNP and LPNP devices, reverse the signs of all voltages and currents.

The following variables are used:

Vbe = intrinsic base-intrinsic emitter voltage

Vbc = intrinsic base-intrinsic collector voltage

Vbs = intrinsic base-substrate voltage

Vbw = intrinsic base-extrinsic collector voltage (quasi-saturation only)

Vbx = extrinsic base-intrinsic collector voltage

Vce = intrinsic collector-intrinsic emitter voltage

Vjs = (NPN) intrinsic collector-substrate

voltage

= (PNP) intrinsic substrate-collector

voltage

= (LPNP) intrinsic base-substrate

voltage

Vt = $k \cdot T/q$ (thermal voltage)

k = Boltzmann's constant

q = electron charge

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Τ = analysis temperature (°K)

Tnom = nominal temperature (set using the TNOM option)

Other variables are listed in <u>Bipolar transistor model parameters</u> on page 293.

Note: Positive current is current flowing into a terminal.

Bipolar transistor equations for DC current

```
Ib = base current = area \cdot (Ibe1/BF + Ibe2 + Ibc1/BR + Ibc2)
Ic = collector current = area \cdot (Ibe1/Kqb - Ibc1/Kqb - Ibc1/BR - Ibc2)
     Ibe1 = forward diffusion current = IS \cdot (e^{Vbe/(NF \cdot Vt)} - 1)
     Ibe2 = non-ideal base-emitter current = ISE \cdot (e^{\text{Vbe/(NE \cdot Vt)}} - 1)
     Ibc1 = reverse diffusion current = IS \cdot (e^{Vbc/(NR \cdot Vt)} - 1)
     Ibc2 = non-ideal base-collector current = ISC·(e^{\text{Vbc/(NC·Vt)}}-1)
     Kqb = base charge factor = Kq1 \cdot (1 + (1 + 4 \cdot Kq2)^{NK})/2
        Kq1 = 1/(1 - Vbc/VAF - Vbe/VAR)
        Kq2 = Ibe1/IKF + Ibc1/IKR
```

Is = substrate current = $area \cdot ISS \cdot (e^{Vjs/(NS \cdot Vt)} - 1)$

Rb = actual base parasitic

Case 1

resistance

for: IRB = infinite (default value)

then:
$$Rb = (RBM + (RB-RBM)/Kqb)/area$$

Case 2

For:
$$IRB > 0$$

Rb = (RBM + 3·(RB-RBM)·
$$\frac{\tan(x) - x}{x \cdot (\tan(x))^2}$$
)/area

where:

$$x = \frac{(1 + (144/\pi^2) \cdot \text{Ib}/(area \cdot \text{IRB}))^{1/2} - 1}{(24/\pi^2) \cdot (\text{Ib}/(area \cdot \text{IRB}))^{1/2}}$$

Analog Devices

Bipolar transistor equations for capacitance

All capacitances, except Cbx, are between terminals of the intrinsic transistor which is inside of the collector, base, and emitter parasitic resistances. Cbx is between the intrinsic collector and the extrinsic base.

base-emitter capacitance

Cbe = base-emitter capacitance = Ctbe + $area \cdot Cjbe$

Ctbe = transit time capacitance = $tf \cdot Gbe$

 $tf = effective TF = TF \cdot (1 + XTF \cdot (Ibe1/(Ibe1 + area \cdot ITF))^2 \cdot e^{Vbc/(1.44 \cdot VTF)})$

Gbe = DC base-emitter conductance = (dIbe)/(dVb)

Ibe = Ibe1 + Ibe2

 $Cjbe = CJE \cdot (1 - Vbe/VJE)^{-MJE}$

IF Vbe \leq FC·VJE

 $Cjbe = CJE \cdot (1-FC) \cdot (1-FC) \cdot (1-FC) \cdot (1+MJE) + MJE \cdot Vbe/VJE$

 $IF Vbe > FC \cdot VJE$

base-collector capacitance

Cbc = base-collector capacitance = Ctbc + $area \cdot XCJC \cdot Cjbc$

Ctbc = transit time capacitance = TR·Gbc

Gbc = DC base-collector conductance = (dIbc)/(dVbc)

 $Cibc = CJC \cdot (1 - Vbc/VJC)^{-MJC}$

 $IF \ Vbc < FC \cdot VIC$

 $Cibc = CJC \cdot (1-FC)^{-(1+MJC)} \cdot (1 FC \cdot (1+MJC) + MJC \cdot Vbc/VJC)$

 $IF Vbc > FC \cdot VJC$

extrinsic-base to intrinsic-collector capacitance

Cbx = extrinsic-base to intrinsic-collector capacitance = $area \cdot (1-xCJC) \cdot Cjbx$

 $Cjbx = CJC \cdot (1 - Vbx/VJC)^{-MJC}$

IF $Vbx \le FC \cdot VJC$

 $Cjbx = CJC \cdot (1-FC) \cdot (1-FC) \cdot (1-FC) \cdot (1+MJC) + MJC \cdot Vbx/VJC$

 $IF Vbx > FC \cdot VIC$

substrate junction capacitance

Cjs = substrate junction capacitance = $area \cdot Cjjs$

Cjjs = CJS·(1-Vjs/VJS)-MJS (assumes FC = 0)

IF $Vis \leq 0$

 $Cjjs = CJS \cdot (1+MJS \cdot Vjs/VJS)$

IF Vis > 0

Analog Devices

Bipolar transistor equations for quasi-saturation effect

Quasi-saturation is an operating region where the internal base-collector metallurgical junction is forward biased, while the external base-collector terminal remains reverse biased.

This effect is modeled by extending the intrinsic Gummel-Poon model, adding a new internal node, a controlled current source, lepi, and two controlled capacitances, represented by the charges Qo and Qw. These additions are only included if the model parameter RCO is specified. See reference [3] of Model level 2 on page 311 for the derivation of this extension.

```
Iepi = area \cdot (VO \cdot (Vt \cdot (K(Vbc) - K(Vbn) - ln((1+K(Vbc))/(1+K(Vbn)))) + Vbc - Vbn))/RCO \cdot (|Vbc - Vbn| + VO)

Qo = area \cdot QCO \cdot (K(Vbc) - 1 - GAMMA/2)

Where
K(v) = (1 + GAMMA \cdot e^{(v/Vi)})^{1/2}
```

Bipolar transistor equations for temperature effect

```
= IS \cdot e^{(T/T_{nom-1}) \cdot EG/(N \cdot Vt)} \cdot (T/T_{nom})^{XTI/N}
IS(T)
           where N = 1
ISE(T) = (ISE/(T/Tnom)^{XTB}) \cdot e^{(T/Tnom-1) \cdot EG/(NE \cdot Vt)} \cdot (T/Tnom)^{XTI/NE}
ISC(T) = (ISC/(T/Tnom)^{XTB}) \cdot e^{(T/Tnom-1) \cdot EG/(NC \cdot Vt)} \cdot (T/Tnom)^{XTI/NC}
ISS(T) = (ISS/(T/Tnom)^{XTB}) \cdot e^{(T/Tnom-1) \cdot EG/(NS \cdot Vt)} \cdot (T/Tnom)^{XTI/NS}
BF(T) = BF \cdot (T/Tnom)^{XTB}
BR(T) = BR \cdot (T/Tnom)^{XTB}
RE(T) = RE \cdot (1 + TRE1 \cdot (T - Tnom) + TRE2 \cdot (T - Tnom)^2)
RB(T) = RB \cdot (1 + TRB1 \cdot (T - Tnom) + TRB2 \cdot (T - Tnom)^{2})
RBM(T) = RBM \cdot (1 + TRM1 \cdot (T - Tnom) + TRM2 \cdot (T - Tnom)^{2})
RC(T) = RC \cdot (1 + TRC1 \cdot (T - Tnom) + TRC2 \cdot (T - Tnom)^2)
VJE(T) = VJE \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
VJC(T) = VJC \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
VJS(T) = VJS \cdot T/Tnom - 3 \cdot Vt \cdot ln(T/Tnom) - Eg(Tnom) \cdot T/Tnom + Eg(T)
             where Eg(T) = silicon bandgap energy = 1.16 - .000702 \cdot T^2/(T+1108)
```

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Bipolar transistor equations for temperature effect, continued

```
CJE(T) = CJE \cdot (1 + MJE \cdot (.0004 \cdot (T-Tnom) + (1-VJE(T)/VJE)))
CJC(T) = CJC \cdot (1 + MJC \cdot (.0004 \cdot (T-Tnom) + (1-VJC(T)/VJC)))
CJS(T) = CJS \cdot (1 + MJS \cdot (.0004 \cdot (T-Tnom) + (1-VJS(T)/VJS)))
```

Note: The development of the temperature dependencies for the quasi-saturation model parameters GAMMA, RCO, and VO are described in <u>Model level 2</u> on page 311, (reference [3]). These temperature dependencies are only used when the model parameter QUASIMOD = 1.0.

$$GAMMA(T) = GAMMA(Tnom) \cdot (T/Tnom)^{3} \cdot exp(-qVG/k \cdot (1/T - 1/Tnom))$$

$$RCO(T) = RCO(Tnom) \cdot (T/Tnom)^{CN}$$

$$VO(T) = VO(Tnom) \cdot (T/Tnom)^{CN - D}$$

Bipolar transistor equations for noise

Noise is calculated assuming a 1.0-hertz bandwidth, using the following spectral power densities (per unit bandwidth):

| parasitic resistances thermal noise | | | |
|--|--|--|--|
| RC | $Ic^2 = 4 \cdot k \cdot T/(RC/area)$ | | |
| RB | $Ib^2 = 4 \cdot k \cdot T/RB$ | | |
| RE | $Ie^2 = 4 \cdot k \cdot T/(RE/area)$ | | |
| base and collector currents shot and flicker noise | | | |
| IB | $Ib^{2} = 2 \cdot q \cdot Ib + KF \cdot Ib^{AF}/FREQUENCY$ | | |
| IC | $Ic^2 = 2 \cdot q \cdot Ic$ | | |

Analog Devices

Model level 2

The equations in this section describe a NPN transistor and use the following variables:

I_{c1c2} =epilayer current

I_{b1b2} =pinched-base current

I_{b1} =ideal forward base current

I_{b2} =non-ideal forward base current

I_{sb1} =ideal side-wall base current

I_{sub} =substrate current

V_{b2e1} =internal base-emitter bias

V_{b2c2} =internal base-collector bias

V_{b2c1} =internal base-collector bias including

epilayer

V_{b1c1} =external base-collector bias without

contact resistances

V_{e1e} =bias over emitter resistance

 $V_t = k \cdot T/q$ (thermal voltage)

k =Boltzmann's constant

q =electron charge

Main current

The Early effect current due to the variation in the width of the base is given by the following equations.

Forward current

$$If = Is \cdot e^{(Vb2e1)/(Vt)}$$

Reverse current

$$Ir = Is \cdot e^{(Vb2c2)/(Vt)}$$

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Main current

$$In = \frac{If - Ir}{Qb}$$

The base currents are given by the following equations.

Ideal forward base current

$$Ib1 = \frac{Is}{Bf} \cdot (e^{(Vb2e1)/(Vt)} - 1)$$

Non-ideal forward base current

$$Ib2 = Ibf \cdot (e^{(Vb2e1)/(Mlf \cdot Vt)} - 1)$$

Ideal reverse base current

$$Iex = \frac{Is}{Bri} \cdot \frac{2 \cdot (e^{(Vb1c1)/(Vt)} - 1)}{1 + \sqrt{1 + (Is \cdot e^{(Vb1c1)/(Vt)})/(Ik)}}$$

Non-ideal reverse base current

$$I_{b3} = I_{br} \cdot \frac{e^{(Vb1c1)/(Vt)} - 1}{e^{(Vb1c1)/(2 \cdot Vt)} + e^{(Vlr)/(2 \cdot Vt)}}$$

In addition to main and base current, this model has an avalanche current, given by the following equation.

$$Iavl = Ic1c2 \times G \cdot (Vb1c1, Ic1c2)$$

where G is the generation factor.

The substrate current, Isub models the parasitic PNP main current in reverse bias.

$$Isub = \frac{2 \cdot Iss \cdot (e^{(Vb1c1)/(Vt)} - 1)}{1 + \sqrt{1 + (Is \cdot e^{(Vb1c1)/(Vt)})/(Ikb)}}$$

The base resistance is modeled as an extrinsic part, RBC, and a variable intrinsic part, RBV. The current through the base resistance is a function of the applied voltage and is given by the following equation.

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$$Ib1b2 = \frac{Qb}{3 \cdot Rbv} \cdot [2 \cdot Vt \cdot (e^{(Vb1b2)/(Vt)} - 1) + Vb1b2]$$

Depletion capacitance

The depletion capacitance at the emitter-base junction is given by the following equation

$$Cje_T = (Cje) \left(\frac{Vde}{Vde_T}\right)^{PE}$$

The depletion capacitance at the collector -substrate junction is given by the following equation:

$$Cjs_T = Cjs \left(\frac{Vds}{Vds_T}\right)^{PS}$$

The depletion capacitance at the collector-base junction capacitance is given by the following equation:

$$Cjc_T = C_{jc} \left[(1 - Xp) \left(\frac{Vdc}{Vdc_T} \right)^{PC} + Xp \right]$$

Diffusion charges

Equations for diffusion charges depend upon the current transit time. In low current, the base and the emitter contributions are modelled by the following equations.

Base contribution

$$Qbe = Q1Tb \cdot If \cdot \frac{2}{1 + \sqrt{1 + 4 \cdot (If)/(Ik)}}$$

Emitter contribution

$$Qe = Te \cdot Is \cdot e^{(Vb2e1)/(Mt \cdot Vt)}$$

The high current contributions are due to a finite voltage drop in the collector epilayer and base widening given by the following equations.

$$Qbc = q1 \cdot Tb \cdot Ir \cdot \frac{2}{1 + \sqrt{1 + 4 \cdot (Ir)/(Ik)}}$$

$$Qepi = Tepi \cdot \left(\frac{Xi}{Wepi}\right)^2 \cdot Iepi$$

Excess phase shift

The excess phase shift is an optional effect in Mextram and is modelled only if EXPHI is 1. Both the collector and emitter contributes to the phase shift.

The phase shift is given by the following equations:

$$Qbe = q \cdot Aem \int_{0}^{Wb} n(X)(1 - x/(Wb)) dx$$

$$Qbc = q \cdot Aem \int_{0}^{Wb} n(X)(x/(Wb)) dx$$

Where,

$$n(X) = n(0) \cdot (\sinh[\lambda(1-x/(Wb))])/(\sinh\lambda)$$

and

$$\lambda = (j\omega Wb^2)/(Dn)$$

The current to the emitter and the collector are given by:

$$I(0) = Idc + j\omega \frac{2}{3}Qtot = \left[Idc + \frac{d\left(\frac{2}{3}Qtot\right)}{dt}\right]$$

$$I(Wb) = Idc - j\omega \frac{1}{3}Qtot = \left[Idc - \frac{d\left(\frac{1}{3}Qtot\right)}{dt}\right]$$

The AC current crowding or the extra effect in the lateral direction is modelled by the following equation:

$$Qb1b2 = \frac{1}{5} \cdot Vb1b2 \cdot (Cte + Cbe + Ce)$$

Noise model equations

The two types of noise, thermal noise due to parasitic resistance and flicker noise due to base and collector currents, are modelled by the following equations.

Parasitic resistances thermal noise

$$Ic = 4 \cdot k \cdot T/((Rc)/(MULT))$$

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$$Ib = 4 \cdot k \cdot T/(Rb)$$

$$Ie = 4 \cdot k \cdot T/((Re)/(MULT))$$

Base and collector currents shot and flicker noise

$$Ib = 2 \cdot q \cdot Ib + (Kf \cdot (lb)^{Af}) / (FREQUENCY)$$

$$Ic = 2 \cdot q \cdot Ic$$

Bipolar transistor equations for temperature effect

$$Ist = Is(Tn)^{4-Ab-Abq0}e^{(-Vgb)/V\Delta t}$$

$$Ibft = Ibf(Tn)^{6-2Mlf}e^{(-Vgf)/((Mlf)(V\Delta t))}$$

$$Ibrt = Ibr(Tn)^{2}e^{(-VGC)/(2V\Delta T)}$$

$$Isst = Iss(Tn)^{4-AS}e^{(-VGS)/(V\Delta T)}$$

For power gains, the model uses bandgap difference between emitter and base $(dVG\beta F)$ or base and collector $(dVG\beta R)$.

$$\beta ft = \beta f(Tn)^{Ae-Ab-Aqb0} e^{(-dVG\beta F)/(V\Delta T)}$$

$$\beta rit = \beta rIe^{(-dVG\beta R)/(V\Delta T)}$$

Resistances are not constant over temperature. As a result, the resistances have parameters linked to the temperature dependence.

$$Ret = Re(Tn)^{Ae}$$

$$Rbvt = Rbv(Tn)^{Ab - Aqb0}$$

$$Rbct = Rbc(Tn)^{Aex}$$

$$Rcct = Rcc(Tn)^{Ac}$$

$$Rcvt = Rcv(Tn)^{Aepi}$$

$$Vdt = (-3Vt) \ln Tn + (Vd)(Tn) + (1 - Tn)Vg$$

The following equation gives the scaling factor of capacitances after temperature scaling of the diffusion voltages is done.

$$Cjt = Cj \left(\frac{Vd}{Vdt}\right)^{\rho}$$

where ρ is the grading coefficient.

Quasi saturation/high injection effect equations

Quasi saturation or high injection effect can occur due ohmic resistance or space-charge limited resistance in the epilayer region. If the resistance is due to space-charge, the effect is also known as Kirk effect.

The guasi saturation voltage drop is given by the following equation:

$$Vqs = Vdc - Vb2c1 = -\int_0^{Wepi} E(X)dx$$

The current is given by the following equation:

$$Iqs = (Vqs)/(Rcv)$$

For higher currents, the equation is given by:

$$Iqs = (Vqs)/(SCRcv)$$

Current crowding equations

Following is the general DC current crowding equation:

$$I(x) = \frac{2 \cdot Vt \cdot Lem}{\rho \cdot Hem} Z \tan [Z(1 - x/(Hem))]$$

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where,

$$\rho$$
 =pinch resistance

For the boundary condition, I(x=Hem)=0, the equation is:

$$Ib = \frac{2 \cdot Vt \cdot Lem}{\rho \cdot Hem} Z \tan Z$$

The voltage is given by the following equation:

$$e^{V/(Vt)} = \frac{Z}{\tan Z \cos^2[Z(1-x/(Hem))]}$$

In the low current limit Z is small and the equation is:

$$\frac{Vb1b2}{Ib} = \frac{\rho Hem}{3Lem} = Rbv$$

In the high current limit $Z \rightarrow \pi/2$ and the equation is:

$$\left(e^{(Vb1b2)/(Vt)} = \frac{Z \tan Z}{\sin Z}\right) \rightarrow \left(Z \tan Z = Ib \frac{\rho Hem}{2VtLem}\right)$$

The current is given by:

$$Ib = \frac{2Vt}{3Rbv}e^{(Vb1b2)/(Vt)}$$

By interpolating between the high and low current limits, we can derive the following equation:

$$Ib = \frac{1}{3Rbv} [2Vt(e^{(Vb1b2)/(Vt)} - 1) + Vb1b2]$$

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The resistance seen by the current is given by the following equations:

$$Rb2 = \frac{3Rbv}{qb}$$

$$Ib1b2 = \frac{1}{Rb2} [2Vt(e^{(Vb1b2)/(Vt)} - 1) + Vb1b2]$$

Bipolar transit time equations

The transit time for the base for closely related knee current is given by the following equation:

$$TAUb = TAUb \cdot tn^{Aqb(0 + Ab - 1)}$$

Similarly, the transit time for the epilayer is given by the following equation:

$$TAUepit = TAUepi \cdot tn^{Aepi-1}$$

The reverse transmit time is given by the following equation:

$$TAUrt = TAUr \cdot \frac{TAUbt + TAUepit}{TAUb + TAUepi}$$

The emitter charge is given by the following equation:

$$Qe = TAUe \cdot \sqrt{IsIk} \cdot e^{(Vb2e1)/(2Vt)}$$

Therefore, the emitter transit time is given by the following equation:

$$TAUet = TAUe \cdot tn^{Ab-2} \cdot \exp[(-dVgtaue)/(V\Delta t)]$$

References

For more information on bipolar transistor models, refer to:

[1] Ian Getreu, Modeling the Bipolar Transistor, Tektronix, Inc. part# 062-2841-00.

For a generally detailed discussion of the U.C. Berkeley SPICE models, including the bipolar transistor, refer to:

Analog Devices

[2] P. Antognetti and G. Massobrio, *Semiconductor Device Modeling with SPICE*, McGraw-Hill, 1988.

For a description of the extension for the quasi-saturation effect, refer to:

[3] G. M. Kull, L. W. Nagel, S. W. Lee, P. Lloyd, E. J. Prendergast, and H. K. Dirks, "A Unified Circuit Model for Bipolar Transistors Including Quasi-Saturation Effects," *IEEE Transactions on Electron Devices*, ED-32, 1103-1113 (1985).

For more information on the Mextram model, refer to:

[3]J.C.J. Paasschens, W.J. Kloosterman, and R. v.d. Toorn, *Model derivation of Mextram 504* - *The physics behind the model*, Koinklijke Philips Electronics N.V. 2002

For a comparison of Mextram and the Gummel-Poon model, refer to:

[4]J.C.J. Paasschens and R. v.d. Toorn, *Introduction to and Usage of the Bipolar Transistor Model Mextram*, Koninklijke Philips Electronics N.V. 2002

Analog Devices

Resistor

General form R<name> <(+) node> <(-) node> [model name] <value>

+ [TC = <TC1> [, <TC2>]]

Examples RLOAD 15 0 2K

R2 1 2 2.4E4 TC=.015,-.003

RFDBCK 3 33 RMOD 10K



Arguments and options

(+) and (-) nodes

Define the polarity when the resistor has a positive voltage across it.

[model name]

Affects the resistance value; see <u>Resistor value formulas</u> on page 324.

Comments

The first node listed (or pin 1 in) is defined as positive. The voltage across the component is therefore defined as the first node voltage minus the second node voltage.

Positive current flows from the (+) node through the resistor to the (-) node. Current flow from the first node through the component to the second node is considered positive.

Temperature coefficients for the resistor can be specified in-line, as in the second example. If the resistor *has a model specified*, then the coefficients from the model are used for the temperature updates; otherwise, the in-line values are used. In both cases the temperature coefficients have default values of zero. Expressions *cannot be used* for the in-line coefficients.

parts

For standard R parts, the effective value of the part is set directly by the VALUE property. For the variable resistor, R_VAR, the effective value is the product of the base value (VALUE) and

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multiplier (SET).

In general, resistors should have positive component values (VALUE property). You can simulate circuits with zero value resistors. All zero values are replaced by GMIN, which is set to 1.0E-12 by default. You can edit the value of GMIN, if required.

However, there are cases when negative component values are desired. This occurs most often in filter designs that analyze an RLC circuit equivalent to a real circuit. When transforming from the real to the RLC equivalent, it is possible to end up with negative component values.

PSpice A/D allows negative component values for bias point, DC sweep, AC, and noise analyses. In the case of resistors, the noise contribution from negative component values come from the absolute value of the component (components are not allowed to generate negative noise). A transient analysis may fail for a circuit with negative components. Negative components may create instabilities in time that the analysis cannot handle.

| Part name | Model type | Property | Property description |
|-----------|----------------------|---------------|--|
| R | resistor | VALUE | resistance |
| | | TC | linear and quadratic temperature coefficients |
| | | TOLERANC E | device tolerance (see <u>[tolerance</u> specification] on page 61) |
| R_VAR | variable resistor | VALUE | base resistance |
| | | SET | multiplier |

Note: The RBREAK part must be used if you want a LOT tolerance. In that case, use the Model Editor to edit the RBREAK instance.

Breakout parts

For non-stock passive and semiconductor devices, has a set of breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo

Analog Devices

and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

Basic breakout part names consist of the intrinsic PSpice A/D device letter plus the suffix BREAK. By default, the model name is the same as the part name and references the appropriate device model with all parameters set at their default. For instance, the DBREAK part references the DBREAK model, which is derived from the intrinsic PSpice A/D D model (.MODEL DBREAK D). Another approach is to use the model editor to derive an instance model and customize this. For example, you could add device and/or lot tolerances to model parameters.

For breakout part RBREAK, the effective value is computed from a formula that is a function of the specified VALUE property.

| Device type | Part name | Part library file | Property | Description |
|----------------|-----------|-------------------|----------|----------------|
| resistor | RBREAK | breakout | VALUE | resistance |
| | | | MODEL | RES model name |

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Resistor model parameters

| Model parameters ¹ | Description | Units | Defau It |
|----------------------------------|-------------------------------------|-------|-------------|
| R | resistance multiplier | | 1.0 |
| TC1 | linear temperature coefficient | °C-1 | 0.0 |
| TC2 | quadratic temperature coefficient | °C-2 | 0.0 |
| TCE | exponential temperature coefficient | %/°C | 0.0 |
| T_ABS | absolute temperature | °C | |
| T_MEASURED | measured temperature | °C | |
| T_REL_GLOBAL | relative to current temperature | °C | |
| T_REL_LOCAL | relative to AKO model temperature | °C | |

For information on T_MEASURED, T_ABS, T_REL_GLOBAL, and T_REL_LOCAL, see <u>.MODEL (model definition)</u> on page 57.

Note: To know how the effective value of the resistor is affected while performing *Temperature (Sweep)* analysis, see ENABLENEGRESTEMP in the section.

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Resistor equations

Resistor value formulas

One

If [model name] is included and TCE is specified, then the resistance is given by:

<value>-R-1.01TCE-(T-Tnom)

where <value> is normally positive (though it can be negative, but *not* zero). Thom is the nominal temperature (set using TNOM option).

Two

If [model name] is included and TCE is not specified, then the resistance is given by:

<value>-R·(1+TC1·(T-Tnom)+TC2·(T-Tnom)2)

where <value> is usually positive (though it can be negative, but *not* zero).

Resistor equation for noise

Noise is calculated assuming a 1.0-hertz bandwidth. The resistor generates thermal noise using the following spectral power density (per unit bandwidth):

 $i^2 = 4 \cdot k \cdot T/\text{resistance}$

Voltage-Controlled Switch

General form S<name> <(+) switch node> <(-) switch node>

+ <(+) controlling node> <(-) controlling node>

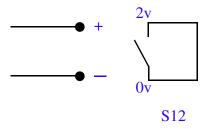
+ <model name>

Examples S12 13 17 2 0 SMOD

SESET 5 0 15 3 RELAY

Model form .MODEL <model name> VSWITCH [model parameters]

The voltage-controlled switch can function either as a variableresistance switch or a short-transition switch. The type of switching
characteristic is determined by the specific model parameters used.
Under most circumstances it is recommended that the variableresistance mode be used. The switch model was designed to minimize
numerical problems. However, there are a few things to consider; see
Special considerations on page 327.



Comments

The resistance between the <(+) switch node> and <(-) switch node> depends on the voltage between the <(+) controlling node> and <(_) controlling node>. In the variable-resistance mode, the resistance varies continuously between **RON** and **ROFF** during the switching transition. For the short-transition switch, the resistance switches between **RON** and **ROFF** in the shortest possible time or voltage increment.

A resistance of 1/GMIN is connected between the controlling nodes to keep them from floating. See the <u>.OPTIONS (analysis options)</u> on page 71 statement for setting GMIN.

Although very little computer time is required to evaluate switches, during transient analysis the simulator must step through the transition region using a fine enough step size to get an accurate waveform. Applying many transitions can produce long run times when evaluating the other devices in the circuit at each time step.

Analog Devices

parts

Ideal switches

Summarized below are the available voltage-controlled switch part types in the analog library. To create a time-controlled switch, connect the switch control pins to a voltage source with the appropriate voltage vs. time values (transient specification).

| Part type | Part Name | Model type |
|---------------------------|-----------|------------|
| Voltage-Controlled Switch | S, S_ST | VSWITCH |

The S part defines the on/off resistance and the on/off control voltage thresholds for the variable-resistance switch. This switch has a finite on resistance and off resistance, and it changes smoothly between the two as its control voltage changes. This behavior is important because it allows PSpice A/D to find a continuous set of solutions for the simulation. You can make the on resistance very small in relation to the other circuit impedances, and you can make the off resistance very large in relation to the other circuit impedances.

The S_ST part defines the on/off resistance, the threshold and hysteresis control voltage, and the time delay for the short-transition switch. This switch transitions rapidly between states. As a result, the on and off resistance should have as small a dynamic range as practical.

Variable-Resistance switch model parameters

| Model Parameters ¹ | Description | Units | Default |
|-------------------------------|-------------------------------|-------|---------|
| ROFF ² | off resistance | ohm | 1E+6 |
| RON | on resistance | ohm | 1.0 |
| VOFF | control voltage for off state | volt | 0.0 |
| VON | control voltage for on state | volt | 1.0 |

- See <u>.MODEL (model definition)</u> on page 57.
- 2. RON and ROFF must be greater than zero and less than 1/GMIN.

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Short-Transition switch model parameters

| Model Parameters ¹ | Description | Units | Default |
|-------------------------------|----------------------------|-------------|---------|
| ROFF ² | off resistance | ohm | 1E+12 |
| RON | on resistance | ohm | 1.0 |
| VT | threshold control voltage | volt | 0.0 |
| VH | hysteresis control voltage | volt | 0.0 |
| TD ³ | time delay | secon ds | 0.0 |

- 1. See .MODEL (model definition) on page 57.
- 2. RON and ROFF must be greater than zero and less than 1/GMIN.
- 3. TD shifts the switching transition to a later time

Special considerations

- Using double precision numbers, the simulator can only handle a dynamic range of about 12 decades. Making the ratio of ROFF to RON greater than 1E+12 is not recommended.
- For the variable-resistance switch, it is not recommended to make the transition region too narrow. Remember that in the transition region the switch has gain. The narrower the region, the higher the gain and the greater the potential for numerical problems. The smallest allowed value for |VON-VOFF| is RELTOLI(MAX(|VON|, |VOFF|))+ VNTOL.
- The short-transition switch is highly non-linear and can cause large discontinuities to occur in the circuit node voltages and branch currents. A rapid change such as that associated with a switch changing state can cause tolerance problems, leading to erroneous results or time step difficulties. Use switch resistances that are close to ideal, setting them only high and low enough to be negligible with respect to other circuit elements.

Analog Devices

Switch equations

In the following equations:

```
Vc = voltage across control nodes

Lm = log-mean of resistor values = ln((RON \cdot ROFF)^{1/2})

Lr = log-ratio of resistor values = ln(RON/ROFF)

Vm = mean of control voltages = (VON+VOFF)/2

Vd = difference of control voltages = VON-VOFF

k = Boltzmann's constant

T = analysis temperature (°K)

Ss = switch state

Rs = switch resistance
```

Variable-Resistance equations for switch resistance

```
For: VON > VOFF
Vc ≥ VON
then:
Rs = RON
if:
Vc < voff
then:
Rs = ROFF
if:
VOFF < VC < VON
then:
Rs = exp(Lm + 3 \cdot Lr \cdot (Vc - Vm)/(2 \cdot Vd) - 2 \cdot Lr \cdot (Vc - Vm)^3/Vd^3)
For: VON < VOFF
if:
Vc < von
then:
Rs = RON
if:
Vc > VOFF
```

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```
then: 
Rs = ROFF

if: 

VOFF > VC > VON

then: 
Rs = exp(Lm - 3 \cdot Lr \cdot (Vc - Vm)/(2 \cdot Vd) + 2 \cdot Lr \cdot (Vc - Vm)^3/Vd^3)
```

Short-Transition equations for switch resistance

```
If: Ss = off

for:

Vc \ge VT + VH

then:

Rs = RON

Ss = on

Else if: Ss = on

for:

Vc < VT - VH

then:

Rs = ROFF

Ss = off

Else: (use the current state)

Rs = Rs

Ss = Ss
```

Voltage-Controlled switch equation for noise

Noise is calculated assuming a 1.0-hertz bandwidth. The voltage-controlled switch generates thermal noise as if it were a resistor having the same resistance that the switch has at the bias point, using the following spectral power density (per unit bandwidth):

$$i^2 = 4 \cdot k \cdot T/Rs$$

Analog Devices

Transmission line

Description

The transmission line device is a bidirectional delay line with two ports, A and B. The (+) and (-) nodes define the polarity of a positive voltage at a port.

Comments

During transient (.TRAN (transient analysis) on page 121) analysis, the internal time step is limited to be no more than one-half the smallest transmission delay, so short transmission lines cause long run times.

The simulation status window displays the properties of the three shortest transmission lines in a circuit if a transient run's time step ceiling is set more frequently by one of the transmission lines. This is helpful when you have a large number of transmission lines. The properties displayed are:

- % loss: percent attenuation at the characteristic delay (i.e., the degree to which the line is lossy)
- time step ceiling: induced by the line
- % of line delay: time step size at percentage of characteristic delay

These transmission line properties are displayed only if they are slowing down the simulation.

For a line that uses a model, the electrical length is given after the model name. Example T5 of <u>Lossy line Examples</u> uses TMOD to specify the line parameters and has an electrical length of one unit.

All of the transmission line parameters from either the ideal or lossy parameter set can be expressions. In addition, R and G can be general Laplace expressions. This allows the user to model frequency dependent effects, such as skin effect and dielectric loss. However, this adds to the computation time for transient analysis, since the impulse responses must be obtained by an inverse FFT instead of analytically.

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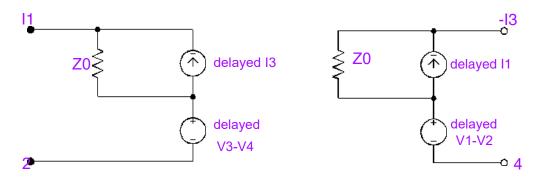
Ideal line

General form

```
T<name> <A port (+) node> <A port (-) node>
+ <B port (+) node> <B port (-) node>
+ [model name]
+ Z0=<value> [TD=<value>] [F=<value> [NL=<value>]]
+ IC= <near voltage> <near current> <far voltage> <far current>
```

Description

As shown below, port A's (+) and (-) nodes are 1 and 2, and port B's (+) and (-) nodes are 3 and 4, respectively.



Comments

For the ideal line, IC sets the initial guess for the voltage or current across the ports. The *<near voltage>* value is the voltage across A(+) and A(-) and the *<far voltage>* is the voltage across B(+) and B(-). The *<near current>* is the current through A(+) and A(-) and the *<far current>* is the current through B(+) and B(-).

For the ideal case, Z0 is the characteristic impedance. The transmission line's length can be specified either by TD, a delay in seconds, or by F and NL, a frequency and a relative wavelength at F. NL has a default value of 0.25 (F is the quarter-wave frequency). Although TD and F are both shown as optional, one of the two must be specified.

Note: Both Z0 (Z-zero) and ZO (Z-O) are accepted by the simulator.

PSpice A/D Reference Guide Analog Devices

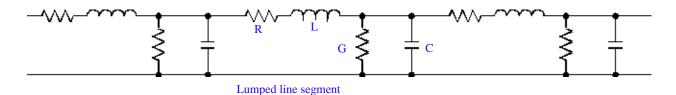
Lossy line

| General form | <pre>T<name> <a (+)="" node="" port=""> <a (-)="" node="" port=""> + <b (+)="" node="" port=""> <b (-)="" node="" port=""> + [<model name=""> [electrical length value]] + LEN=<value> R=<value> L=<value> + G=<value> C=<value></value></value></value></value></value></model></name></pre> | | | |
|--------------|---|--|--|--|
| Examples | T1 1 2 3 4 Z0=220 TD=115ns T2 1 2 3 4 Z0=220 F=2.25MEG T3 1 2 3 4 Z0=220 F=4.5MEG NL=0.5 T4 1 2 3 4 LEN=1 R=.311 L=.378u G=6.27u C=67.3p T5 1 2 3 4 TMOD 1 | | | |
| Model form | .MODEL <model name=""> TRN [model parameters]</model> | | | |
| Description | | | | |

Analog Devices

The simulator uses a distributed model to represent the properties of a lossy transmission line. That is, the line resistance, inductance, conductance, and capacitance are all continuously apportioned along the line's length. A common approach to simulating lossy lines is to model these characteristics using discrete passive elements to represent small sections of the line.

This is the lumped model approach, and it involves connecting a set of many small subcircuits in series as shown below:



This method requires that there is enough lumps to adequately represent the distributed character of the line, and this often results in the need for a large netlist and correspondingly long simulation times. The method also produces spurious oscillations near the natural frequencies of the lumped elements.

An additional extension allows systems of coupled transmission lines to be simulated. Transmission line coupling is specified using the K device. This is done in much the same way that coupling is specified for inductors. See the description of <u>Transmission line</u> coupling on page 229 for further details.

The distributed model allows freedom from having to determine how many lumps are sufficient, and eliminates the spurious oscillations. It also allows lossy lines to be simulated in a fraction of the time necessary when using the lumped approach, for the same accuracy.

Comments

For a lossy line, LEN is the electrical length. R, L, G, and C are the per unit length values of resistance, inductance, conductance, and capacitance, respectively.

Example T4 specifies a lossy line one meter long. The lossy line model is similar to that of the ideal case, except that the delayed voltage and current values include terms which vary with frequency. These terms are computed in transient analysis using an impulse response convolution method, and the internal time step is limited by the time resolution required to accurately model the frequency characteristics of the line. As with ideal lines, short lossy lines cause long run times.

Analog Devices

parts

Ideal and lossy transmission lines

Listed below are the properties that you can set per instance of an ideal (T) or lossy (TLOSSY) transmission line. The parts contained in the TLINE.OLB part library contain a variety of transmission line types. Their part properties vary.

| Part name | Model type | Property | Property description |
|---------------------|----------------------|----------|--------------------------------------|
| T | transmission line | Z0 | characteristic impedance |
| | | TD | transmission delay |
| | | F | frequency for NL |
| | | NL | number of wavelengths or wave number |
| TLOSSY ¹ | transmission line | LEN | electrical length |
| | | R | per unit length resistance |
| | | L | per unit length inductance |
| | | G | per unit length conductance |
| | | С | per unit length capacitance |

1.

PSpice A/D uses a distributed model to represent the properties of a lossy transmission line. That is, the line resistance, inductance, conductance, and capacitance are all continuously apportioned along the line's length.

A common approach to simulating lossy lines is to model these characteristics using discreet passive elements to represent small sections of the line. This is the lumped model approach, and it involves connecting a set of many small subcircuits in series. This method requires that enough lumps exist to adequately represent the distributed characteristic of the line. This often results in the need for a large netlist and correspondingly long simulation time. The method also produces spurious oscillations near the natural frequencies of the lumped elements.

Analog Devices

The distributed model used in PSpice A/D frees you from having to determine how many lumps are sufficient, and eliminates the spurious oscillations. It also allows lossy lines to be simulated with the same accuracy in a fraction of the time required by the lumped approach.

In addition, you can make R and G general Laplace expressions. This allows frequency dependent effects to be modeled, such as skin effect and dielectric loss.

Coupled transmission lines

Listed below are the properties that you can set per instance of a coupled transmission line part. The part library provides parts that can accommodate up to five coupled transmission lines. You can also create new parts that have up to ten coupled lines.

| Part name | Model type | Property | Property description |
|------------------------------------|--------------------------------------|----------|------------------------------------|
| T2COUPLED | coupled transmission line— | - LEN | electrical length |
| T3COUPLED T4COUPLED | symmetric | R | per unit length resistance |
| T5COUPLED | | L | per unit length inductance |
| | | G | per unit length conductance |
| T2COUPLEDX ¹ T3COUPLEDX | coupled transmission line—asymmetric | - LEN | electrical length |
| T4COUPLEDX T5COUPLEDX | | R | per unit length resistance |
| 100001 2257 | | L | per unit length inductance |
| | | G | per unit length conductance |
| | | С | per unit length capacitance |
| | | LM | per unit length mutual inductance |
| | | CM | per unit length mutual capacitance |
| KCOUPLE2 | transmission line coupling matrix | T1 | name of first coupled line |
| | | T2 | name of second coupled line |
| | | LM | per unit length mutual inductance |

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| | СМ | per unit length mutual capacitance |
|----------------------|------|--|
| KCOUPLE3 | T1 | name of first coupled line |
| KCOUPLE4 KCOUPLE5 | T2 | name of second coupled line |
| | Т3 | name of third coupled line |
| | LMij | per unit length mutual inductance between line Ti and line Tj |
| | СМіј | per unit length mutual capacitance between line Ti and line Tj |

^{1.} T2COUPLEDX is functionally identical to T2COUPLED. However, the T2COUPLEDX implementation uses the expansion of the subcircuit referenced by T2COUPLED.

Simulating coupled lines

Use the K device to simulate coupling between transmission lines. Each of the coupled transmission line parts provided in the standard part library translate to K device and T device declarations in the netlist. PSpice A/D compiles a system of coupled lines by assembling capacitive and inductive coupling matrices from all of the K devices involving transmission lines. Though the maximum order for any one system is ten lines, there is no explicit limitation on the number of separate systems that may appear in one simulation.

The simulation model is accurate for:

- ideal lines
- low-loss lossy lines
- systems of homogeneous, equally spaced high-loss lines

For more information, see <u>Transmission line coupling</u> on page 229.

Simulation considerations

When simulating, transmission lines with short delays can create performance bottlenecks by setting the time step ceiling to a very small value.

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If one transmission line sets the time step ceiling frequently, PSpice A/D reports the three lines with the shortest time step. The status window displays the percentage attenuation, step ceiling, and step ceiling as percentage of transmission line delay.

If your simulation is running reasonably fast, you can ignore this information and let the simulation proceed. If the simulation is slowed significantly, you may want to cancel the simulation and modify your design. If the line is lossy and shows negligible attenuation, model the line as ideal instead.

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Transmission line model parameters

| Model parameters ¹ | Description | Units ² | Defaul t |
|----------------------------------|---|------------------------|-------------|
| | for all transmission lines | | |
| IC | Sets the initial condition and all four values must be entered. | | |
| | Four values are expected when IC is specified: the near-end voltage, the near-end current, the far-end voltage, and the far-end current, given in that order. | | |
| | for ideal transmission lines | | |
| ZO | characteristic impedance | ohms | none |
| TD | transmission delay | seconds | none |
| F | frequency for NL | Hz | none |
| NL | relative wavelength | none | 0.25 |
| | for lossy transmission lines | | |
| R | per unit length resistance | ohms/unit length | none |
| L | per unit length inductance | henries/unit length | none |
| G | per unit length conductance | mhos/unit length | none |
| С | per unit length capacitance | farads/unit length | none |
| LEN*** | physical length | agrees with RLGC * | none |

^{1.} See.MODEL (model definition) on page 57. The order is from the most commonly used to the least commonly used parameter.

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- 2. Any length units can be used, but they must be consistent. For instance, if LEN is in feet, then the units of R must be in ohms/foot.
- *** A lossy line with R=G=0 and LEN=1 is equivalent to an ideal line with $ZO = \sqrt{\frac{L}{C}}$ and $TD = LEN \cdot \sqrt{L \cdot C}$.

References

For more information on how the lossy transmission line is implemented, refer to:

[1] Roychowdhury and Pederson, "Efficient Transient Simulation of Lossy Interconnect," Design Automation Conference, 1991.

Current-Controlled Switch

General
form

W<name> <(+) switch node> <(-) switch node>
+ <controlling V device name> <model name>

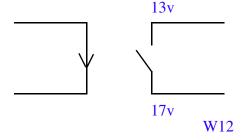
Examples W12 13 17 VC WMOD

WRESET 5 0 VRESET RELAY

Model form .MODEL <model name> ISWITCH [model parameters]

Description

The current-controlled switch can function either as a variable-resistance switch or a short-transition switch. The type of switching characteristic is determined by the specific model parameters used. Under most circumstances it is recommended that the variable-resistance mode be used. The switch model was designed to minimize numerical problems. However, there are a few things to consider; see Special considerations on page 342.



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Comments

The resistance between the <(+) switch node> and <(-) switch node> depends on the current through the <controlling V device name> source. In the variable-resistance mode, the resistance varies continuously between **RON** and **ROFF** during the switching transition. For the short-transition switch, the resistance switches between **RON** and **ROFF** in the shortest possible time or voltage increment.

A resistance of 1/GMIN is connected between the controlling nodes to keep them from floating. See <u>.OPTIONS (analysis options)</u> on page 71 for information on setting GMIN.

Although very little computer time is required to evaluate switches, during transient analysis the simulator must step through the transition region using a fine enough step size to get an accurate waveform. Having many transitions can produce long run times when evaluating the other devices in the circuit for many times.

Analog Devices

parts

Ideal switches

Summarized below are the available current-controlled switch part types in the analog library. To create a time-controlled switch, connect the switch control pins to a voltage source with the appropriate voltage vs. time values (transient specification).

| Part type | Part name | Model type |
|---------------------------|-----------|------------|
| Current-controlled switch | W, W_ST | ISWITCH |

The W part defines the on/off resistance and the on/off control current thresholds for the variable-resistance switch. This switch has a finite on resistance and off resistance, and it changes smoothly between the two as its control current changes. This behavior is important because it allows PSpice A/D to find a continuous set of solutions for the simulation. You can make the on resistance very small in relation to the other circuit impedances, and you can make the off resistance very large in relation to the other circuit impedances.

The W_ST part defines the on/off resistance, the threshold and hysteresis control current, and the time delay for the short-transition switch. This switch transitions rapidly between states. As a result, the on and off resistance should have as small a dynamic range as practical.

As with current-controlled sources (F, FPOLY, H, and HPOLY), the W part and the W_ST part contain a current-sensing voltage source, which when netlisted, generate two device declarations to the circuit file set:

- one for the controlled switch
- one for the independent current-sensing voltage source

If you want to create a new part for a current-controlled switch (with, for example, different on/ off resistance and current threshold settings in the ISWITCH model), the TEMPLATE property must account for the additional current-sensing voltage source.

Variable-Resistance switch model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|-------------------------------|-------|---------|
| IOFF | control current for off state | amp | 0.0 |
| ION | control current for on state | amp | 1E-3 |
| ROFF ² | off resistance | ohm | 1E+6 |
| RON | on resistance | ohm | 1.0 |

- 1. See <u>.MODEL (model definition)</u> on page 57.
- 2. RON and ROFF must be greater than zero and less than 1/GMIN

Short-Transition switch model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|----------------------------|-------|---------|
| IT | threshold control current | amp | 0.0 |
| IH | hysteresis control current | amp | 0.0 |
| ROFF ² | off resistance | ohm | 1E+12 |
| RON | on resistance | ohm | 1.0 |
| TD ³ | time delay | ohm | 0.0 |

- 1. See <u>.MODEL (model definition)</u> on page 57.
- 2. RON and ROFF must be greater than zero and less than 1/GMIN
- 3. TD shifts the switching transition to a later time

Special considerations

Using double precision numbers, the simulator can handle only a dynamic range of about 12 decades. Therefore, it is not recommended making the ratio of ROFF to RON greater than 1.0E+12.

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For the variable-resistance switch, it is not recommended making the transition region too narrow. Remember that in the transition region the switch has gain. The narrower the region, the higher the gain and the greater the potential for numerical problems. The smallest allowed value for | ION - IOFF | is Reltol-(MAX(| ION |, | IOFF |))+ ABSTOL.

The short-transition switch is highly non-linear and can cause large discontinuities to occur in the circuit node voltages and branch currents. A rapid change such as that associated with a switch changing state can cause tolerance problems, leading to erroneous results or time step difficulties. Use switch resistances that are close to ideal, setting them only high and low enough to be negligible with respect to other circuit elements.

Switch equations

In the following equations:

Ic= controlling current Lm= log-mean of resistor values = $ln(RON \cdot ROFF)^{1/2}$

Lr= log-ratio of resistor values = In(RON/ROFF)Im= mean of control currents = (ION+IOFF)/2Id= difference of control currents = ION-IOFF k= Boltzmann's constant T= analysis temperature (°K) Ss= switch state Rs= switch resistance

Analog Devices

Variable-Resistance equations for switch resistance

```
For: ION > IOFF
    if:
       Ic > ION
    then:
       Rs = RON
    if:
       Ic < IOFF
    then:
       Rs = ROFF
    if:
       IOFF < Ic < ION
    then:
       Rs = exp(Lm + 3 \cdot Lr \cdot (Ic-Im)/(2 \cdot Id) - 2 \cdot Lr \cdot (Ic-Im)^3/Id^3)
For: ION < IOFF
    if:
       Ic \le ION
    then:
       Rs = RON
    if:
       Ic > IOFF
    then:
       Rs = ROFF
    if:
       IOFF > Ic > ION
    then:
       Rs = exp(Lm - 3 \cdot Lr \cdot (Ic-Im)/(2 \cdot Id) + 2 \cdot Lr \cdot (Ic-Im)^3/Id^3)
```

Short-Transition equations for switch resistance

Analog Devices

Current-Controlled switch equation for noise

Noise is calculated assuming a 1.0-hertz bandwidth. The current-controlled switch generates thermal noise as if it were a resistor using the same resistance as the switch has at the bias point, using the following spectral power density (per unit bandwidth):

$$i^2 = 4 \cdot k \cdot T/Rs$$

Analog Devices

Subcircuit instantiation

Purpose

This statement causes the referenced subcircuit to be inserted into the circuit using the given nodes to replace the argument nodes in the definition. It allows a block of circuitry to be defined once and then used in several places.

General form

Examples

XNANDI 25 28 7 MYPWR MYGND PARAMS: IO_LEVEL=2

+ TEXT: JEDEC FILE=MYJEDEC.JED

Arguments and options

<subcircuit name>

The name of the subcircuit's definition. See <u>.SUBCKT (subcircuit)</u> on page 112.

PARAMS:

Passes values into subcircuits as arguments and into expressions inside the subcircuit.

TEXT:

Passes text values into subcircuits and into text expressions inside the subcircuit.

Comments

There must be the same number of nodes in the call as in the subcircuit's definition.

Subcircuit references can be nested; that is, a call can be given to subcircuit A, whose definition contains a call to subcircuit B. The nesting can be to any level, but *must not be circular*: for example, if subcircuit A's definition contains a call to subcircuit B, then subcircuit B's definition must not contain a call to subcircuit A.

PSpice A/D Reference Guide Analog Devices

Operational Amplifiers (OpAmp) Model Parameters

| - | | | |
|---------------------|--|-------|---------------|
| Model parameters | Description | Units | Default |
| BF1 | input stage gain | | 75 |
| BF2 | output stage gain | | 75 |
| C1 | phase control capacitor | F | 8.6e- 012 |
| C2 | compensation capacitor | F | 3e-011 |
| CEE | slew-rate limiting capacitor | F | 0 |
| GA | interstage transconductance | Н | 0.00018 8 |
| GB | output stage transconductance | | 424 |
| GCM | common-mode transconductance | | 1.88e- 009 |
| IEE | input stage current | Α | 1.5e- 005 |
| IS1 | saturation current | Α | 8e-016 |
| IS2 | saturation current | Α | 8e-016 |
| RC | series collector resistance | Ohm | 5300 |
| RE | input stage emitter resistance | Ohm | 1800 |
| REE | input stage current source output resistance | Ohm | 130000 00 |
| RO1 | output resistor #1 | Ohm | 50 |
| RO2 | output resistor #2 | Ohm | 25 |

PSpice A/D Reference Guide Analog Devices

| Model parameters | Description | Units | Default |
|---------------------|--------------------------------|-------|---------|
| RP | power dissipation | | 18000 |
| VC | output limiter offset (to Vcc) | | 2 |
| VE | output limiter offset (to Vee) | | 2 |

Analog Device Model Interface (DMI)

Purpose This statement adds the device model interface (DMI) model, a

generic Y device, in PSpice using model dynamic-link library (.dll)

files.

General form

Y <node1> <node2> ... CMI [<DMI Model DLL File Name>]

<model template name>

Examples Y1 c b e dt CMI vbic.dll NVBIC

Model form .MODEL <model template name> CMI <Model Type Name>

[model parameters]

Arguments and Options

<model template name>

It is a user-defined model template with a predefined set of parameters.

<Model Type Name>

Model Type Name is the actual device model name used in the DMI model .DLL file.

CMI

CMI is a mandatory keyword used for DMI models.

Description

Note: By default, the model .DLL files are accessed from the PATH variable. If you want to access them from a location other than the PATH variable, set the CDN_PSPICE_MODEL_PATH environment variable to the Model .DLL files location.

The DMI model is a generic model that is used to generate various types of devices, such as Bipolar Junction Transistor (BJT), Voltage-controlled Voltage Source (VCVS), and Thin-film Transistor (TFT), using the model dll files.

Refer to the following documentation to generate different model .dll files:

- PSpice Device Model Interface API Reference
- PSpice Device and System Modeling with C/C++ and SystemC

Analog Devices

Create Capture Symbols from a Model DLL file

To use a Y device in the Capture–PSpice flow, do the following steps in the Model Editor:

1. Place the Y device inside a subcircuit and save it as a . 1 i b file. For example:

```
.subckt myCap N1 N2
Y1 N1 N2 CMI vbic.dll NVIBIC
.ends
```

2. Select *File – Export to Capture Part Library* to generate the .olb file with capture symbols.

Using the generated .olb file, you can add the Capture symbols in the schematic design using OrCAD Capture. For PSpice simulation, add the .lib file created in step 1.

Note: QVBICN (Bipolar Transistor Breakout Parts on page 292), which is a BJT, is an example of the Y device.

IGBT

General z<name> <collector> <gate> <emitter> <model name> + [AREA=<value>] [WB=<value>] [AGD=<value>]

form + [AREA=<*value*>] [WB=<*value*>] + [KP=<*value*>] [TAU=<*value*>]

Examples ZDRIVE 1 4 2 IGBTA AREA=10.1u WB=91u AGD=5.1u

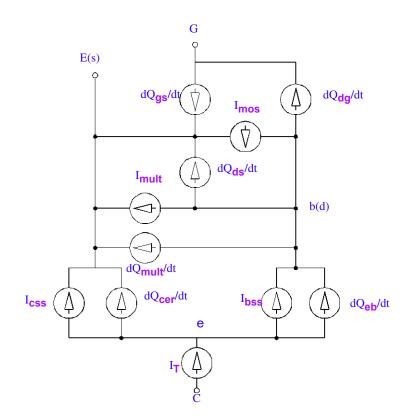
KP=0.381

Z231 3 2 9 IGBT27

Model form .MODEL < model name > NIGBT [model parameters]

Description

The equivalent circuit for the IGBT is shown below. It is modeled as an intrinsic device (not as a subcircuit) and contains five DC current components and six charge (capacitive) components. An overview of the model equations is included below. For a more detailed description of the defining equations see references [1] through [4] of <u>References</u>.



Analog Devices

parts

The following table lists the set of IGBT breakout parts designed for customizing model parameters for simulation. These are useful for setting up Monte Carlo and worst-case analyses with device and/or lot tolerances specified for individual model parameters.

| Part name | Model type | Property | Property description |
|-----------|------------|----------|----------------------------------|
| ZBREAKN | IGBT | AGD | gate-drain overlap area |
| | | AREA | area of the device |
| | | KP | MOS transconductance |
| | | TAU | ambipolar recombination lifetime |
| | | WB | Metallurgical base width |
| | | MODEL | NIGBT model name |

Setting operating temperature

Operating temperature can be set to be different from the global circuit temperature by defining one of the model parameters: T_ABS, T_REL_GLOBAL, or T_REL_LOCAL. Additionally, model parameters can be assigned unique measurement temperatures using the T_MEASURED model parameter. For more information, see <u>IGBT model parameters</u> on page 353.

Analog Devices

IGBT device parameters

The general form of the IGBT syntax allows for the specification of five device parameters.

These device parameters and their associated default values are defined in previous table. The IGBT model parameters and their associated default values are defined in the table that follows. Model parameters can be extracted from data sheet information by using the model editor. Also, a library of model parameters for commercially available IGBTs is supplied with the software.

The parameters AGD, AREA, KP, TAU, and WB are specified as both device and model parameters, and they cannot be used in a Monte Carlo analysis.

When specified as device parameters, the assigned values take precedence over those which are specified as model parameters. Also, as device parameters (but not as model parameters), they can be assigned a parameter value and used in conjunction with a .DC or .STEP analysis.

| Device parameters | Description | Units | Default |
|-------------------|----------------------------------|----------------|---------|
| AGD | gate-drain overlap area | m ² | 5.0E-6 |
| AREA | area of the device | m^2 | 1.0E-5 |
| KP | MOS transconductance | A/V^2 | 0.38 |
| TAU | ambipolar recombination lifetime | sec | 7.1E-6 |
| WB | metallurgical base width | m | 9.0E-5 |

IGBT model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|-----------------------------------|-------|---------|
| AGD | gate-drain overlap area | m^2 | 5.0E-6 |
| AREA | area of the device | m^2 | 1.0E-5 |
| BVF | avalanche uniformity factor | none | 1.0 |
| BVN | avalanche multiplication exponent | none | 4.0 |

Analog Devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|--|-------------------|---------|
| CGS | gate-source capacitance per unit area | F/cm ² | 1.24E-8 |
| JSNE | emitter saturation current density | A/cm ² | 6.5E-13 |
| KF | triode region factor | none | 1.0 |
| KP | MOS transconductance | A/V^2 | 0.38 |
| NB | base doping | 1/cm ³ | 2.E14 |
| TAU | ambipolar recombination lifetime | sec | 7.1E-6 |
| THETA | transverse field factor | 1/V | 0.02 |
| VT | threshold voltage | V | 4.7 |
| VTD | gate-drain overlap depletion threshold | V | 1.E-3 |
| WB | metallurgical base width | m | 9.0E-5 |

^{1.} See .MODEL (model definition) on page 57 statement.

Analog Devices

IGBT equations

In the following equations:

```
\begin{split} &\mathbf{I}_{mos} = \text{MOSFET channel current} \\ &\mathbf{I}_{T} = \text{anode current} \\ &\mathbf{I}_{css} = \text{steady-state (bipolar) collector current} \\ &\mathbf{I}_{bss} = \text{Steady-state base current} \\ &\mathbf{I}_{mult} = \text{avalanche multiplication current} \\ &\mathbf{R}_{b} = \text{conductivity modulated base resistance} \\ &b = \text{ambipolar mobility ratio} \\ &\mathbf{D}_{p} = \text{diffusion coefficient for holes} \\ &\mathbf{W} = \text{quasi-neutral base width} \\ &\mathbf{Q}_{eb} = \text{instantaneous excess carrier base charge} \\ &\mathbf{Q}_{b} = \text{background mobile carrier charge} \\ &\mathbf{n}_{i} = \text{intrinsic carrier concentration} \\ &\mathbf{M} = \text{avalanche multiplication factor} \\ &\mathbf{I}_{gen} = \text{(bipolar)collector-base thermally generated current} \\ \end{split}
```

 ε_{si} = dielectric permittivity of silicon

 W_{bci} = base (bipolar) to collector depletion width

q = electron charge

Analog Devices

IGBT equations for DC current

MOSFET channel current

$$\mathsf{IMOS} = \begin{cases} & \mathsf{For}\, \mathsf{V}_{\mathsf{gs}} < \mathsf{VT} \\ \\ \frac{\mathsf{KF} \cdot \mathsf{KP} \cdot \left((V_{gs} - \mathsf{VT}) \cdot V_{ds} - \frac{\mathsf{KF} \cdot V_{ds}^{-2}}{2} \right)}{1 + \mathsf{THETA} \cdot (V_{gs} - \mathsf{VT})} \\ \\ \frac{\mathsf{KP} \cdot (V_{gs} - \mathsf{VT})^2}{2 \cdot (1 + \mathsf{THETA} \cdot (V_{gs} - \mathsf{VT}))} \end{cases} \qquad \mathsf{For}\, \mathsf{V}_{\mathsf{ds}} > \left(\mathsf{V}_{\mathsf{gs}} - \mathsf{VT} \right) / \mathsf{KF} \end{cases}$$

anode current: current through the resistor Rb

$$I_T = \frac{V_{Ce}}{R_b}$$

steady-state collector current

$$I_{css} = \begin{cases} 0 & \text{For } \forall_{\text{eb}} \leq 0 \\ \left(\frac{1}{1+b}\right) \cdot I_T + \left(\frac{b}{1+b}\right) \cdot \left(\frac{4 \cdot D_p}{W^2}\right) \cdot Q_{eb} & \text{For } \forall_{\text{eb}} > 0 \end{cases}$$

steady-state base current

$$I_{\text{bss}} = \begin{cases} 0 & \text{For } V_{\text{eb}} \leq 0 \\ \frac{Q_{eb}}{\text{TAU}} + \left(\frac{Q_{eb}^{2}}{Q_{B}}\right) \cdot \left(\frac{4 \cdot \text{NB}^{2}}{n_{i}^{2}}\right) \cdot (\text{JSNE} \cdot \text{AREA}) & \text{For } V_{\text{eb}} > 0 \end{cases}$$

Analog Devices

avalanche multiplication current

$$I_{mult} = (M-1) \cdot (I_{mos} + I_{css}) + M \cdot I_{gen}$$

IGBT equations for capacitance

gate source

$$C_{gs} = CGS$$

$$Q_{gs} = \mathbf{cgs} \cdot V_{gs}$$

drain source

$$C_{ds} = \frac{(\text{AREA-AGD}) \cdot \varepsilon_{si}}{W_{dsj}}$$

$$Q_{ds} = q \cdot (\texttt{AREA-AGD}) \cdot \texttt{NB} \cdot W_{dsj}$$

where:

$$W_{dsj} = \sqrt{\frac{2 \cdot \varepsilon_{si} \cdot (V_{ds} + 0.6)}{q \cdot \text{NB}}}$$

gate drain

For
$$V_{ds} < V_{gs} - \text{VTD}$$

$$C_{da} = COXD$$

$$Q_{dg} = \mathbf{COXD} \cdot V_{dg}$$

For
$$V_{ds} \ge V_{gs} - VTD$$

$$C_{dg} = \frac{C_{dgj} \cdot \cos \mathbf{D}}{C_{dgj} + \cos \mathbf{D}}$$

$$Q_{dg} = \frac{q \cdot \text{NB} \cdot \boldsymbol{\varepsilon}_{si} \cdot \text{AGD}^2}{\text{COXD}} \Big(\frac{\text{COXD} \cdot \boldsymbol{W}_{dgj}}{\boldsymbol{\varepsilon}_{si} \cdot \text{AGD}} - \log \Big(1 + \frac{\text{COXD} \cdot \boldsymbol{W}_{dgj}}{\boldsymbol{\varepsilon}_{si} \cdot \text{AGD}} \Big) \Big) - \text{COXD} \cdot \text{VTD}$$

where:

Analog Devices

$$\begin{split} C_{dgj} &= \frac{\mathbf{AGD} \cdot \boldsymbol{\varepsilon}_{si}}{W_{dgj}} \\ W_{dgj} &= \sqrt{\frac{2 \cdot \boldsymbol{\varepsilon}_{si} \cdot (V_{dg} + \mathbf{VTD})}{q \cdot \mathbf{NB}}} \end{split}$$

Ccer

$$C_{cer} = \frac{Q_{eb} \cdot C_{bcj}}{3 \cdot Q_{B}} \qquad \text{and} \qquad C_{bcj} = \frac{\varepsilon_{si} \cdot \text{AREA}}{W_{bcj}}$$

Cmult

$$C_{mult} = (M-1) \cdot C_{cer}$$

$$Q_{mult} = (M-1) \cdot Q_{cer}$$

emitter base

$$C_{eb} = \frac{dQ_{eb}}{dV_{eb}}$$

References

For more information on the IGBT model, refer to:

- [1] G.T. Oziemkiewicz, "Implementation and Development of the NIST IGBT Model in a SPICE-based Commercial Circuit Simulator," Engineer's Thesis, University of Florida, December 1995.
- [2] A.R.Hefner, Jr., "INSTANT IGBT Network Simulation and Transient Analysis Tool," National Institute of Standards and Technology Special Publication SP 400-88, June 1992.
- [3] A.R.Hefner, Jr., "An Investigation of the Drive Circuit Requirements for the Power Insulated Gate Bipolar Transistor (IGBT)," <u>IEEE Transactions on Power Electronics</u>, Vol. 6, No. 2, April 1991, pp. 208-219.
- [4] A.R.Hefner, Jr., "Modeling Buffer Layer IGBTs for Circuit Simulation," <u>IEEE Transactions on Power Electronics</u>, Vol. 10, No. 2, March 1995, pp. 111-123

Analog Devices

Battery Model

General .X awbflooded_cell PARAMS VOC=<value> AH=<value> SOC=<value>

SOC=<value>.....

.X awbvalve regulated cell PARAMS VOC=<value> AH=<value>

SOC=<value>

Examples .X awbflooded_cell PARAMS VOC=5 AH=15 SOC=0.8

Arguments and options

Analog Devices

awbflooded_cell

PSpice model for modelling the flooded cell batteries. In the flooded cells batteries since the gases created during charging are vented to the atmosphere, distilled water must be added occasionally to bring the electrolyte back to its required level.

Example: 12-V automobile battery.

awbvalve_regulated_cell

PSpice model for modelling the valve regulated batteries.

VOC

Indicates the open circuit voltage. This is the voltage across the two terminals of the battery when the battery is not connected to a circuit.

AΗ

It is the ampere hour of the battery. This is the amount of time for which a battery operates without having to recharge it. For example, if a battery is marked *300Ah* then it is assumed that the battery can supply 20A current for 15 hours or 10A current for 30 hrs.

Note: An ampere hour (Ah) indicates the amount of energy charge in a battery that will allow one ampere of current to flow for one hour.

SOC

Indicates the state of charge in a a battery. For a completely charged battery, SOC is 100% and for a fully discharged battery, SOC is 0%.

Digital devices

| Behavioral Primitives on page 418 | Multi-bit A/D and D/A converter on page 414 |
|--|---|
| Bidirectional transfer gates on page 381 | Programmable logic array on page 399 |
| Delay line on page 398 | Pullup and pulldown on page 397 |
| Digital input (N device) on page 455 | Random access read-write memory on page 409 |
| Digital output (O Device) on page 460 | Read only memory on page 405 |
| File stimulus on page 446 | Standard gates on page 375 |
| Flip-flops and latches on page 385 | Stimulus generator on page 439 |
| Input/output model on page 452 | Tristate gates on page 379 |

Digital devices

Digital device summary

| Device class | Туре | Description |
|--------------|------|--|
| primitives | U | low-level digital devices (e.g., gates and flip-flops) |
| stimuli | U | digital stimulus generators |
| | | file-based stimulus |
| interface | Ν | digital input device |
| | 0 | digital output device |

Primitives are primarily used in subcircuits to model complete devices.

Stimulus devices are used in the circuit to provide input for other digital devices during the simulation.

Interface devices are mainly used inside subcircuits that model analog/digital and digital/analog interfaces.

Note: The digital devices are part of the digital simulation feature of PSpice A/D. For more information on digital simulation and creating models, refer to your *PSpice User Guide*.

Digital devices

Digital primitive summary

Digital primitives are low-level devices whose main use is modeling off-the-shelf parts, often in combination with each other.

Digital primitives should not be confused with the subcircuits in the libraries that use them. For instance, the 74LS00 subcircuit in 741s.1ib uses a NAND digital primitive to model the 74LS00 part, but it also includes timing and interface information that makes the model adapted for use in a circuit simulation. For more information, refer to your *PSpice User Guide*.

Digital devices

This section provides a reference for each of the digital primitives supported by the simulator, to help you create digital parts that are not in the model library.

| Primitive class | Туре | Description |
|----------------------------|-------|--------------------------|
| Standard gates on page 375 | BUF | buffer |
| | INV | inverter |
| | AND | AND gate |
| | NAND | NAND gate |
| | OR | OR gate |
| | NOR | NOR gate |
| | XOR | exclusive OR gate |
| | NXOR | exclusive NOR gate |
| | BUFA | buffer array |
| | INVA | inverter array |
| | ANDA | AND gate array |
| | NANDA | NAND gate array |
| | ORA | OR gate array |
| | NORA | NOR gate array |
| | XORA | exclusive OR gate array |
| | NXORA | exclusive NOR gate array |
| | AO | AND-OR compound gate |
| | OA | OR-AND compound gate |
| | AOI | AND-NOR compound gate |
| | OAI | OR-NAND compound gate |

PSpice A/D Reference Guide Digital devices

| Primitive class | Туре | Description |
|---------------------------------|---------|---------------------------------|
| Tristate gates on page 379 | BUF3 | buffer |
| | INV3 | inverter |
| | AND3 | AND gate |
| | NAND3 | NAND gate |
| | OR3 | OR gate |
| | NOR3 | NOR gate |
| | XOR3 | exclusive OR gate |
| | NXOR3 | exclusive NOR gate |
| | BUF3A | buffer array |
| | INV3A | inverter array |
| | AND3A | AND gate array |
| | NAND3A | NAND gate array |
| | OR3A | OR gate array |
| | NOR3A | NOR gate array |
| | XOR3A | exclusive OR gate array |
| | NXOR3A | exclusive NOR gate array |
| Bidirectional transfer gates on | NBTG | N-channel transfer gate |
| page 381 | PBTG | P-channel transfer gate |
| Flip-flops and latches on | JKFF | J-K, negative-edge triggered |
| page 385 | DFF | D-type, positive-edge triggered |
| | SRFF | S-R gated latch |
| | DLTCH | D gated latch |
| Pullup and pulldown on | PULLUP | pullup resistor array |
| page 397 | PULLDN | pulldown resistor array |
| <u>Delay line</u> on page 398 | DLYLINE | delay line |
| | | |

Digital devices

| Primitive class | Туре | Description | | |
|---|-------------------|--|--|--|
| Programmable logic array on | PLAND | AND array | | |
| page 399 | PLOR | OR array | | |
| | PLXOR | exclusive OR array | | |
| | PLNAND | NAND array | | |
| | PLNOR | NOR array | | |
| | PLNXOR | exclusive NOR array | | |
| | PLANDC | AND array, true and complement | | |
| | PLORC | OR array, true and complement | | |
| | PLXORC | exclusive OR array, true and | | |
| | PLNANDC | complement | | |
| | PLNORC PLNXORC | NAND array, true and complement | | |
| | | NOR array, true and complement | | |
| | | exclusive NOR array, true and complement | | |
| Read only memory on page 405 | ROM | read-only memory | | |
| Random access read-write memory on page 409 | RAM | random access read-write memory | | |
| Multi-bit A/D and D/A converter | ADC | multi-bit A/D converter | | |
| on page 414 | DAC | multi-bit D/A converter | | |
| Behavioral Primitives on | LOGICEXP | logic expression | | |
| page 418 | PINDLY | pin-to-pin delay | | |
| | CONSTRAINT | constraint checking | | |

The format for specifying a digital primitive follows the general format described in the next section. Primitive-specific formats are also described which includes parameters and nodes that are specific to the primitive type.

Also listed is the specific timing model format for each primitive, along with the appropriate timing model parameters.

Digital devices

For example, the 74393 part provided in the model library is defined as a subcircuit composed of U devices as shown below.

```
.subckt 74393
                   A CLR QA QB QC QD
                   optional: DPWR=$G DPWR DGND=$G DGND
                    params: MNTYMXDLY=0 IO LEVEL=0
UINV inv DPWR DGND
                    CLR
                           CLRBAR
                    DO GATE IO STD IO LEVEL={IO_LEVEL}
U1 jkff(1) DPWR DG\overline{N}D
                    $D HI CLRBAR A $D HI $D HI
                                                         QA BUF $D NC
                    D \overline{3}93 1 IO STD MNTY\overline{M}XDLY=\overline{\{MNTYMXDLY\}}=
                    IO LEVEL={IO LEVEL}
U2 jkff(1) DPWR DG\overline{N}D
                    $D HI CLRBAR QA BUF $D HI $D HI
                                                                QB BUF $D NC
                    D \overline{3}93 2 IO STD \overline{M}NTYMXDLY = \{MNTY\overline{M}XDLY\}
U3 jkff(1) DPWR D\overline{G}ND
                    $D HI CLRBAR QB BUF
                                              $D HI $D HI
                                                                 QC BUF $D NC
                    D \overline{3}93 2 IO_STD \overline{M}NTYMXDLY = \{MNTY\overline{M}XDLY\}
U4 jkff(1) DPWR DGND
                    $D HI CLRBAR QC BUF
                                               $D HI $D HI
                                                                 QD BUF $D NC
                    D \overline{3}93 3 IO STD \overline{M}NTYMXDLY = \{MNTYMXDLY\}
UBUFF bufa(4) DPW\overline{R} DG\overline{N}D
                    QA BUF QB BUF QC BUF QD BUF
                                                        QA QB QC QD
                    D 393 4 IO STD MNTYMXDLY={MNTYMXDLY}IO LEVEL={IO LEVEL}
.ends
```

When adding digital parts to a part library, you can create corresponding digital device models by connecting U devices in a subcircuit definition similar to the one shown above. We recommend that these be saved in a custom model file. The model files can then be configured into the model library or specified for use in a given design.

Digital devices

General digital primitive format

The format of digital primitives is similar to that of analog devices. One difference is that most digital primitives use two models instead of one. One of the models is the timing model, which specifies propagation delays and timing constraints, such as setup and hold times. The other model is the I/O model, which specifies information specific to the device's input/output characteristics. The reason for having two models is that, while timing information is specific to a device, the input/output characteristics apply to a whole device family. Thus, many devices in the same family reference the same I/O model, but each device has its own timing model. If wanted, the timing models can be selected among primitives of the same class.

The general digital primitive format is shown below. Each statement can span one or more lines by using the <u>+ (line continuation)</u> on page 135 character in the first column position. Comments can be added to each line by using the <u>: (in-line comment)</u> on page 134. For specific information on each primitive type, see the sections that follow.

See <u>Input/output model</u> on page 452 for a list of the UIO model parameters.

Timing model format

```
.MODEL <model name> <model type> ( <model parameters>* )

Examples

U1 NAND(2) $G_DPWR $G_DGND 1 2 10 D0_GATE IO_DFT

U2 JKFF(1) $G_DPWR $G_DGND 3 5 200 3 3 10 2 D_293ASTD IO_STD

U3 INV $G_DPWR $G_DGND IN OUT D_INV IO_INV MNTYMXDLY=3

I0 LEVEL=2
```

Arguments and options

Digital devices

<primitive type> [(<parameter value>*)]

The type of digital device, such as NAND, JKFF, or INV. It is followed by zero or more parameters specific to the primitive type, such as number of inputs. The number and meaning of the parameters depends on the primitive type. See the sections that follow for a complete description of each primitive type and its parameters.

<digital power node> <digital ground node>

These nodes are used by the interface subcircuits which connect analog nodes to digital nodes or vice versa. Refer to your *PSpice User Guide* for more information.

<node>*

One or more input and output nodes. The number of nodes depends on the primitive type and its parameters. Analog devices, digital devices, or both can be connected to a node. If a node has both analog and digital connections, then the simulator automatically inserts an interface subcircuit to translate between logic levels and voltages. Refer to your *PSpice User Guide* for more information.

Digital devices

<timing model name>

The name of a timing model that describes the device's timing characteristics, such as propagation delay and setup and hold times. Each timing parameter has a minimum, typical, or maximum value which can be selected using the optional MNTYMXDLY device parameter (described below) or the DIGMNTYMX option (see OPTIONS (analysis options) on page 71). The type of the timing model and its parameters are specific to each primitive type and are discussed in the following sections. (Note that the PULLUP, PULLDN, and PINDLY primitives do not have timing models.)

<I/O model name>

The name of an I/O model, which describes the device's loading and driving characteristics. I/O models also contain the names of up to four DtoA and AtoD interface subcircuits, which are automatically called by the simulator to handle interface nodes. Refer to your *PSpice User Guide* for a more detailed description of I/O models.

<model type>

Is specific to the primitive type. See the specific primitive for the correct < mode1 type> and associated < mode1 parameters>. General timing model issues are discussed in the next section.

Digital devices

MNTYMXDLY

An optional device parameter that selects either the minimum, typical, or maximum delay values from the device's timing model. A fourth option operates the primitive in Digital Worst-Case (min/max) mode. If not specified, MNTYMXDLY defaults to 0. Valid values are:

```
0 = Current value of .OPTIONS DIGMNTYMX (default=2)
1 = Minimum
2 = Typical
3 = Maximum
4 = Worst-case (min/max) timing

IO LEVEL
```

An optional device parameter that selects one of the four AtoD or DtoA interface subcircuits from the device's I/O model. The simulator calls the selected subcircuit automatically in the event a node connecting to the primitive also connects to an analog device. If not specified, IO LEVEL defaults to 0. Valid values are:

```
0 = the current value of .OPTIONS DIGIOLVL (default=1)
1 = AtoD1/DtoA1
2 = AtoD2/DtoA2
3 = AtoD3/DtoA3
4 = AtoD4/DtoA4
```

Refer to your *PSpice User Guide* for more information.

Digital devices

Timing models

With the exception of the PULLUP, PULLDN, and PINDLY devices, all digital primitives have a timing model that provides timing parameters to the simulator. Within a timing model, there can be one or more types of parameters

- propagation delays (TP)
- setup times (TSU)
- hold times (TH)
- pulse widths (TW)
- switching times (TSW)

Each parameter is further divided into three values: minimum (MN), typical (TY), and maximum (MX). For example, the typical low-to-high propagation delay on a gate is specified as TPLHTY. The minimum data-to-clock setup time on a flip-flop is specified as TSUDCLKMN.

One or more parameters can be missing from the timing model definition. Data books do not always provide all three (minimum, typical, and maximum) timing specifications. The way the simulator handles missing parameters depends on the type of parameter.

Treatment of unspecified propagation delays

Note: This discussion applies only to propagation delay parameters (TP). All other timing parameters, such as setup/hold times and pulse widths, are handled differently and are described in <u>Treatment of unspecified timing constraints</u> on page 373.

Often, only the typical and maximum delays are specified in data books. If, in this case, the simulator were to assume that the unspecified minimum delay just defaults to zero, the logic in certain circuits could break down.

For this reason, the simulator provides two configurable options, DIGMNTYSCALE and DIGTYMXSCALE (set using the <u>.OPTIONS</u> (analysis options) on page 71 command), which are used to extrapolate unspecified propagation delays in the timing models.

DIGMNTYSCALE

ThIS option computes the minimum delay when a typical delay is known, using the formula

```
TPxxMN = DIGMNTYSCALE · TPxxTY
```

DIGMNTYSCALE has a default value of 0.4, or 40% of the typical delay. Its value must be between 0.0 and 1.0.

Digital devices

DIGTYMXSCALE

This option computes the maximum delay from a typical delay, using the formula

```
TPxxMX = DIGTYMXSCALE · TPxxTY
```

DIGTYMXSCALE has a default value of 1.6. Its value must be greater than 1.0.

When a typical delay is unspecified, its value is derived from the minimum and/or maximum delays, in one of the following ways. If both the minimum and maximum delays are known, the typical delay is the average of these two values. If only the minimum delay is known, the typical delay is derived using the value of the <code>DIGMNTYSCALE</code> option. Likewise, if only the maximum delay is specified, the typical delay is derived using <code>DIGTYMXSCALE</code>. Obviously, if no values are specified, all three delays have a default value of zero.

Treatment of unspecified timing constraints

The remaining timing constraint parameters are handled differently from the propagation delays. Often, data books state pulse widths, setup times, and hold times as a minimum value. These parameters do not lend themselves to the extrapolation method used for propagation delays.

Instead, when one or more timing constraints are omitted, the simulator uses the following steps to fill in the missing values:

- If the minimum value is omitted, the default value is zero.
- If the maximum value is omitted, it takes on the typical value if one was specified, otherwise it takes on the minimum value.
- If the typical value is omitted, it is computed as the average of the minimum and maximum values.

Digital devices

Gates

Logic gates come in two types: standard and tristate. Standard gates always have their outputs enabled, whereas tristate gates have an enable control. When the enable control is 0, the output's strength is Z and its level is X.

Logic gates also come in two forms: simple gates and gate arrays. Simple gates have one or more inputs and only one output. Gate arrays contain one or more simple gates in one component. Gate arrays allow one to work directly using parts that have several gates in one package.

The usual Boolean equations apply to these gates having the addition of the X level. The rule for X is: if an input is X, and if changing that input between one and zero would cause the output to change, then the output is also X. In other words, X is only propagated to the output when necessary. For example: 1 AND X = X; 0 AND X = 0; 0 OR X = X; 1 OR X = 1.

Digital devices

Standard gates

Device format

```
U<name> <gate type> (<parameter value>*)
    + <digital power node> <digital ground node>
    + <input node>* <output node>*
    + <timing model name> <I/O model name>
    + [MNTYMXDLY=<delay select value>]
    + [IO LEVEL=<interface subckt select value>]
```

The standard gate types and their parameters are listed in <u>Standard Gate Types</u> on page 377.

Timing model format

```
<timing model name> UGATE [model parameters]
```

Examples

```
U5 AND(2) $G_DPWR $G_DGND INO IN1 OUT two-input AND gate
+ T_AND2 IO_STD

U2 INV $G_DPWR $G_DGND 3 5; simple INVerter
+ T_INV IO_STD

U13 NANDA(2,4) $G_DPWR $G_DGND; four two-input NAND gates
+ INAO INA1 INBO INB1 INCO INC1
+ INDO IND1 OUTA OUTB OUTC OUTD
+ T_NANDA IO_STD

U9 AO(3,3) $G_DPWR $G_DGND; three-input AND-OR gate
+ INAO INA1 INA2 INBO INB1 INB2 INCO INC1 INC2
+ OUT T_AO IO_STD
+ MNTYMXDLY=1 IO_LEVEL=1

.MODEL T_AND2 UGATE; AND2 Timing Model
+ TPLHMN=15ns TPLHTY=20ns TPLHMX=25ns
+ TPHLMN=10ns TPHLTY=15ns TPHLMX=20ns
+)
```

Arguments and options

```
<no. of inputs><no. of gates>
```

The <no. of inputs> is the number of inputs per gate and <no. of gates> is the number of gates. in* and out* mean one or more nodes, whereas in and out refer to only one node.

In gate arrays the order of the nodes is: all inputs for the first gate, all inputs for the second gate, ..., output for the first gate, output for the second gate, ... In other words, all of the input nodes come first, then all of the output nodes. The total number of input nodes is < no. of inputs> < no. of gates>; the number of output nodes is < no. of gates>.

Digital devices

A compound gate is a set of <no. of gates> first-level gates which each have <no. of inputs> inputs. Their outputs are connected to a single second-level gate. For example, the AO component has <no. of gates> AND gates whose outputs go into one OR gate. The OR gate's output is the AO device's output. The order of the nodes is: all inputs for the first, first-level gate; all inputs for the second, first-level gate; ...; the output of the second-level gate. In other words, all of the input nodes followed by the one output node.

Digital devices

Standard gates

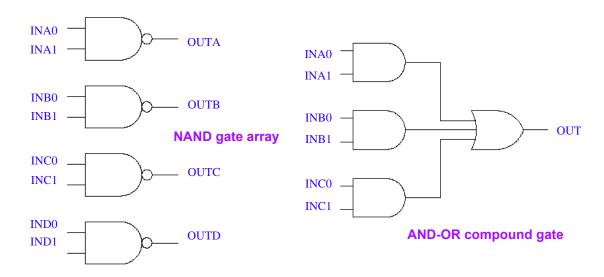


Table 3-1 Standard Gate Types

| Туре | Parameters | Nodes | Description |
|-------|---|-----------|-----------------------|
| AND | (<no. inputs="" of="">)</no.> | in*, out | AND gate |
| ANDA | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out* | AND gate array |
| AO | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out | AND-OR compound gate |
| AOI | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out | AND-NOR compound gate |
| BUF | not applicable | in, out | buffer |
| BUFA | (<no. gates="" of="">)</no.> | in*, out* | buffer array |
| INV | not applicable | in, out | inverter |
| INVA | (<no. gates="" of="">)</no.> | in*, out* | inverter array |
| NAND | (<no. inputs="" of="">)</no.> | in*, out | NAND gate |
| NANDA | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out* | NAND gate array |
| NOR | (<no. inputs="" of="">)</no.> | in*, out | NOR gate |

Digital devices

Table 3-1 Standard Gate Types

| Туре | Parameters | Nodes | Description |
|-------|---|------------------|--------------------------|
| NORA | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out* | NOR gate array |
| NXOR | not applicable | in1, in2, out | exclusive NOR gate |
| NXORA | (<no. gates="" of="">)</no.> | in*, out* | exclusive NOR gate array |
| OA | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out | OR-AND compound gate |
| OAI | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out | OR-NAND compound gate |
| OR | (<no. inputs="" of="">)</no.> | in*, out | OR gate |
| ORA | <pre>(<no. inputs="" of="">,<no. gates="" of="">)</no.></no.></pre> | in*, out* | OR gate array |
| XOR | not applicable | in1, in2, out | exclusive OR gate |
| XORA | (<no. gates="" of="">)</no.> | in*, out* | exclusive OR gate array |

Table 3-2 Standard gate timing model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-------------------------|-------|---------|
| TPLHMN | delay: low to high, min | sec | 0 |
| TPLHTY | delay: low to high, typ | sec | 0 |
| TPLHMX | delay: low to high, max | sec | 0 |
| TPHLMN | delay: high to low, min | sec | 0 |
| TPHLTY | delay: high to low, typ | sec | 0 |
| TPHLMX | delay: high to low, max | sec | 0 |

^{1.} See .MODEL (model definition) on page 57

Digital devices

Tristate gates

Device format

```
U<name> <tristate gate type> [( <parameter value>* )]
+ <digital power node> <digital ground node>
+ <input node>* <enable node> <output node>*
+ <timing model name> <I/O model name>
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
```

Timing model format

```
.MODEL <timing model name> UTGATE [model parameters]
```

Examples

Arguments and options

```
<no. of inputs>
        The number of inputs per gate.
<no. of gates>
        The number of gates in model.
```

Comments

In gate arrays the order of the nodes is: all inputs for the first gate, all inputs for the second gate, ..., enable, output for the first gate, output for the second gate, ... In other words, all of the input nodes come first, then the enable, then all of the output nodes. The total number of input nodes is <no. of inputs>·<no. of gates>+1; the number of output nodes is <no. of gates>. If a tristate gate is connected to a net that has at least one device input using an INLD I/O model, or a device output using an OUTLD I/O model where both parameters are greater than zero, then that net is simulated as a charge storage net.

Digital devices

Tristate gate types

| Туре | Parameters | Nodes ¹ | Description |
|--------|---|--------------------|----------------------|
| AND3 | (<no. inputs="" of="">)</no.> | in*, en, out | AND gate |
| AND3A | (<no. inputs="" of="">,<no. gates="" of="">)</no.></no.> | in*, en, out* | AND gate array |
| BUF3 | | in, en, out | Buffer |
| BUF3A | (<no. gates="" of="">)</no.> | in*, en, out* | Buffer array |
| INV3 | | in, en, out | Inverter |
| INV3A | (<no. gates="" of="">)</no.> | in*, en, out* | Inverter array |
| NAND3 | (<no. inputs="" of="">)</no.> | in*, en, out | NAND gate |
| NAND3A | (<no. inputs="" of="">,<no. gates="" of="">)</no.></no.> | in*, en, out* | NAND gate array |
| NOR3 | (<no. inputs="" of="">)</no.> | in*, en, out | NOR gate |
| NOR3A | (<no. inputs="" of="">,<no. gates="" of="">)</no.></no.> | in*, en, out* | NOR gate array |
| NXOR3 | | in1, in2, en, out | Exclusive NOR gate |
| NXOR3A | (<no. gates="" of="">)</no.> | in*, en, out* | Excl. NOR gate array |
| OR3 | (<no. inputs="" of="">)</no.> | in*, en, out | OR gate |
| OR3A | (<no. inputs="" of="">,<no. gates="" of="">)</no.></no.> | in*, en, out* | OR gate array |
| XOR3 | | in1, in2, en, out | Exclusive OR gate |
| XOR3A | (<no. gates="" of="">)</no.> | in*, en, out* | Excl. OR gate array |

^{1.} in* and out*—Mean one or more nodes present. in and out—Refer to only one node. en—Refers to the output enable node.

Tristate gate timing model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-------------------------|-------|---------|
| TPLHMN | Delay: low to high, min | sec | 0 |
| TPLHTY | Delay: low to high, typ | sec | 0 |
| TPLHMX | Delay: low to high, max | sec | 0 |
| TPHLMN | Delay: high to low, min | sec | 0 |

Digital devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|-------------------------|-------|---------|
| TPHLTY | Delay: high to low, typ | sec | 0 |
| TPHLMX | Delay: high to low, max | sec | 0 |
| TPHZMN | Delay: high to Z, min | sec | 0 |
| TPHZTY | Delay: high to Z, typ | sec | 0 |
| TPHZMX | Delay: high to Z, max | sec | 0 |
| TPLZMN | Delay: low to Z, min | sec | 0 |
| TPLZTY | Delay: low to Z, typ | sec | 0 |
| TPLZMX | Delay: low to Z, max | sec | 0 |
| TPZLMN | Delay: Z to low, min | sec | 0 |
| TPZLTY | Delay: Z to low, typ | sec | 0 |
| TPZLMX | Delay: Z to low, max | sec | 0 |
| TPZHMN | Delay: Z to high, min | sec | 0 |
| TPZHTY | Delay: Z to high, typ | sec | 0 |
| TPZHMX | Delay: Z to high, max | sec | 0 |

^{1.} See .MODEL statement.

Bidirectional transfer gates

The bidirectional transfer gate is a passive device that connects or disconnects two nodes. Bidirectional transfer gates have no parameters.

The state of the gate input controls whether the gate connects the two digital nets. The device type NBTG connects the nodes if the gate is one, and disconnects the nodes if the gate is zero. Device type PBTG connects the nodes if the gate is zero and disconnects the nodes if the gate is one.

The I/O Model DRVH and DRVL parameters are used as a ceiling on the strength of a one or zero, which is passed through a bidirectional transfer gate. If a bidirectional transfer gate is connected to a net which has at least one device input using an INLD I/O model parameter

Digital devices

greater than zero, or a device output using an OUTLD I/O model parameter greater than zero, then that net is simulated as a charge storage net.

```
Device
                  U<name> NBTG
                  + <digital power node> <digital ground node>
format
                  + <gate node> <channel node 1> <channel node 2>
                  + <timing model name> <I/O model name>
                  + [MNTYMXDLY = <delay select value>]
                  + [IO LEVEL = <interface subckt select value>]
                  U<name> PBTG
                  + <digital power node> <digital ground node>
                  + <gate node> <channel node 1> <channel node 2>
                  + <timing model name> <I/O model name>
                  + [MNTYMXDLY = <delay select value>]
                  + [IO LEVEL = <interface subckt select value>]
Examples
                  U4 NBTG $G DPWR $G DGND GATE SD1 SD2
                  + BTG1 IO BTG
                  .MODEL BT\overline{G}1 UBTG
Model form
              .MODEL <timing model name> UBTG
```

Special behavior when the NBTG or PBTG is connected to an analog device

If a channel node of one of these bidirectional transfer gates is connected to an analog device, then the bidirectional transfer gate is removed during simulation and is replaced with the digital-to-analog subcircuit specified by the bidirectional transfer gate's I/O model. Because the bidirectional transfer gate is passive and bidirectional, this digital-to-analog subcircuit must model the behavior of the whole bidirectional transfer gate, not just convert its digital levels to analog signals. Use this format to define the digital-to-analog subcircuit:

The contents of the subcircuit must model the behavior of the transfer gate in the analog domain, at least for the channel. If the subcircuit's gate node is connected to analog devices, then PSpice will simulate the gate node as an analog net. If this behavior is not desired (e.g., the gate will be connected to a clock signal, which will slow simulation if it is an analog signal), then the subcircuit should not have any analog devices connected to the gate node.

Note: The gate node has the same behavior if it is connected to an analog net as other digital device pins: the analog-to-digital subcircuit specified by the I/O model and IO_LEVEL is connected between the analog net and the gate pin of the device.

Digital devices

Examples

The first example is a subcircuit that models the switch with an analog gate connection. In some circuit topologies, this may cause large parts of a circuit to convert to analog if a single net is connected to an analog part. To avoid this, use the _D version of the digital-to-analog converter by setting IO_LEVEL to 3 or 4.

```
.model io nbtg uio (drvh=200 drvl=200 inld=10pf outld=15pf
        digpower="DIGIFPWR"TstoreMN=10us
        inR=10MEGdrvZ =5MEG
  AtoD1="AtoD HC"AtoD2="AtoD HC"
  AtoD3="AtoD HC"AtoD4="AtoD HC"
  DtoA1="DtoA_NBTG"DtoA2="DtoA NBTG"
   DtoA3="DtoA NBTG D"DtoA4="DtoA NBTG D"
.model io pbtg \overline{u}io (\overline{d}rvh=200 drvl=\overline{2}00 i\overline{n}ld=10pf outld=15pf
        digpower="DIGIFPWR"TstoreMN=10us
        inR=10MEGdrvZ =5MEG
 AtoD1="AtoD HC"AtoD2="AtoD HC"
  AtoD3="AtoD HC"AtoD4="AtoD HC"
  DtoA1="DtoA PBTG"DtoA2="DtoA PBTG"
  DtoA3="DtoA PBTG D"DtoA4="DtoA PBTG D"
.model io_nbtgs_uio (drvh=200 drvl=200
        digpower="DIGIFPWR"TstoreMN=10us
        inR=10MEGdrvZ =5MEG
  AtoD1="AtoD HC"AtoD2="AtoD HC"
  AtoD3="AtoD_HC"AtoD4="AtoD_HC"
  DtoA1="DtoA NBTG"DtoA2="DtoA NBTG"
 DtoA3="DtoA NBTG D"DtoA4="DtoA NBTG D"
.model io pbtqs uio (drvh=200 drvl=200
        digpower="DIGIFPWR"TstoreMN=10us
        inR=10MEGdrvZ =5MEG
  AtoD1="AtoD_HC"AtoD2="AtoD_HC"
   AtoD3="AtoD_HC"AtoD4="AtoD_HC"
   DtoA1="DtoA_PBTG"DtoA2="DtoA_PBTG"
DtoA3="DtoA_PBTG_D"DtoA4="DtoA_PBTG_D"
.model btg1
              ubtq
```

The next two examples are switch models with digital gate inputs. The digital-to-analog conversion of the gate inputs uses an I/O model ($_{\rm HC}$ in this example) that is defined here, not the I/O model of the device driving the gate.

Use these examples in cases where using an analog input would create too many analog switches. Do not use these when the gate is analog, since this would make an analog-to-digital-to-analog conversion, which may cause invalid simulation results. (This is because the analog gate is squared up before being converted to analog again and applied to the "gate" of the switch.)

```
.subckt DtoA_NBTG gate sd1 sd2 pwr gnd
+    params: DRVL=0 DRVH=0 INLD=0 OUTLD=0 VTH=.9 VSAT=1.2
S1 sd1 sd2 gate gnd nbtg_smod
C1 sd1 gnd {.1pf+outld}
C2 sd2 gnd {.1pf+outld}
C3 gate gnd {.1pf+inld}
.model nbtg_smod vswitch
+ (ron={(drvl+drvh)/2} roff=1meg von={VSAT} voff={VTH})
.ends
```

Digital devices

```
.subckt DtoA PBTG gate sd1 sd2 pwr gnd
+ params: DRVL=0 DRVH=0 INLD=0 OUTLD=0 VTH=-0.9 VSAT=-1.2
S1 sd1 sd2 gate pwr pbtg smod
C1 sd1 pwr {.1pf+outld}
C2 sd2 pwr {.1pf+outld}
C3 gate gnd {.1pf+inld}
.model pbtq smod vswitch
+ (ron={(drvl+drvh)/2} roff=1meg von={VSAT} voff={VTH})
.ends
.subckt DtoA NBTG D gate sd1 sd2 pwr gnd + params: DRVL=0 DRVH=0 INLD=0 OUTLD=0 VTH=.9 VSAT=1.2
X1 gate gate a pwr gnd DtoA HC
+ params: DRVL={DRVL} DRVH={DRVH} CAPACITANCE={INLD}
S1 sd1 sd2 gate a gnd nbtg smod
C1 sd1 gnd \{.1p\overline{f}+outld\}
C2 sd2 qnd {.1pf+outld}
.model nbtg smod vswitch
+ (ron={(drvl+drvh)/2} roff=1meg von={VSAT} voff={VTH})
.ends
.subckt DtoA PBTG D gate sd1 sd2 pwr gnd
   params: DRVL=0 DRVH=0 INLD=0 OUTLD=0 VTH=-.9 VSAT=-1.2
X1 gate gate a pwr gnd DtoA HC
+ params: DRVL={DRVL} DRVH={DRVH} CAPACITANCE={INLD}
S1 sd1 sd2 gate_a pwr pbtg_smod
C1 sd1 gnd \{.1p\overline{f}+outld\}
C2 sd2 gnd {.1pf+outld}
.model pbtg_smod vswitch
+ (ron={(drvl+drvh)/2} roff=1meg von={VSAT} voff={VTH})
.ends
```

Digital devices

Flip-flops and latches

The simulator supports both edge-triggered and gated flip-flops. Edge-triggered flip-flops change state when the clock changes: on the falling edge for JKFFs, on the rising edge for DFFs. Gated flip-flops are often referred to as latches. The state of gated flip-flops follows the input as long as the clock (gate) is high. The state is frozen when the clock (gate) falls. Multiple flip-flops can be specified in each device. This allows direct modeling of parts which contain more than one flip-flop in a package.

Initialization

By default, at the beginning of each simulation, all flip-flops and latches are initialized to the unknown state (that is, they output an X). Each device remains in the unknown state until explicitly set or cleared by an active-low pulse on either the preset or clear pins, or until a known state is clocked in.

You can override the X start-up state by setting <u>.OPTIONS</u> (analysis options) on page 71 DIGINITSTATE to either zero or one. If set to zero, all flip-flops and latches in the circuit are cleared. Likewise, if set to one, all such devices are preset. Any other values produce the default (X) start-up state. The DIGINITSTATE option is useful in situations where the initial state of the flip-flop is unimportant to the function of the circuit, such as a toggle flip-flop in a frequency divider.

It is important to note that if the initial state is set to zero or one, the device still outputs an X at the beginning of the simulation if the inputs would normally produce an X on the output. For example, if the initial state is set to one, but the clock is an X at time zero, Q and QBar both go to X when the simulation begins.

X-level handling

The truth-table for each type of flip-flop and latch is given in the sections that follow. However, how the flip-flops treat X levels on the inputs is not depicted in the truth tables because it can depend on the state of the device.

The rule is as follows: if an input is X, and if changing that input between one and zero would cause the output to change, then the output is set to X. In other words, X is only propagated to the output when necessary. For example: if Q = 0 and PresetBar = X, then $Q \to X$; but if Q = 1 and $Q \to X$; but if $Q \to X$ and $Q \to X$.

Digital devices

Timing violations

The flip-flop and latch primitives have model parameters which specify timing constraints such as setup/hold times and minimum pulse-widths. If these model parameter values are greater than zero, the simulator compares measured times on the inputs against the specified value. See <u>Standard gate timing model parameters</u> on page 378 and <u>Tristate gate timing model parameters</u> on page 380.

The simulator reports flip-flop timing violations as digital simulation warning messages in the .out file. These messages can also be viewed using the Windows version of Probe.

Edge-triggered flip-flops

The simulator supports four types of edge-triggered flip-flops:

- D-type flip-flop (DFF), which is positive-edge triggered
- J-K flip-flop (JKFF), which is negative-edge triggered
- Dual-edge D flip-flop (DFFDE), which is selectively positive and/or negative edge triggered

Digital devices

 Dual-edge J-K flip-flop (JKFFDE), which is selectively positive and/or negative edge triggered

```
Device format
```

```
U<name> DFF (<no. of flip-flops>)
+ <digital power node> <digital ground node>
+ + clearbar node> <clock node>
+ <d node 1> ... <d node n>
+ <q output 1> ... <q output n>
+ <qbar output 1> ... <qbar output n>
+ <timing model name> <1/0 model name>
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
U<name> JKFF (<no. of flip-flops>)
+ <digital power node> <digital ground node>
+ + clearbar node> <clockbar node>
+ <j node 1> ... <j node n>
+ <k node 1> ... <k node n>
+ <q output 1> ... <q output n>
+ <qbar output 1> ... <qbar output n>
+ <timing model name> <1/0 model name>
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
U<name> DFFDE(<no. of flip-flops>)
+ <digital power node> <digital ground node>
+ + clrbar node> <clock node>
+ <positive-edge enable node> <negative-edge enable
node>
+ <d node 1> ... <d node n>
+ <q output 1> ... <q output n>
+ <qbar output 1> ... <qbar output n>
+ <timing model name> <I/O model name>
+ [MNTYMXDLY = <delay select value>]
+ [IO LEVEL = <interface subckt select value>]
U<name> JKFFDE(<no. of flip-flops>)
+ <digital power node> <digital ground node>
+ + clrbar node> <clock node>
+ <positive-edge enable node> <negative-edge enable
node>
+ <j node 1> ... <j node n>
+ < k \text{ node } 1 > \dots < k \text{ node } n >
+ <q output 1> ... <q output n>
+ <qbar output 1> ... <qbar output n>
+ <timing model name> <I/O model name>
+ [MNTYMXDLY = <delay select value>]
+ [IO LEVEL = <interface subckt select value>]
```

Timing model format

.MODEL <timing model name> UEFF [model parameters]

Digital devices

Examples

U5 JKFF(1) \$G_DPWR \$G_DGND PREBAR CLRBAR CLKBAR

* one JK flip-flop

+ J K Q QBAR

+ T_JKFF IO_STD

U2 DFF(2) \$G_DPWR \$G_DGND PREBAR CLRBAR CLK

* two DFF flip-flops

+ D0 D1 Q0 Q1 QBAR0 QBAR1

+ T_DFF IO_STD

.MODEL T JKFF UEFF(...); JK Timing Model

Comments

Use $<\!no$. of flip-flops> to specify the number of flip-flops in the device. The three nodes, $<\!presetbar\ node>$, $<\!clearbar\ node>$, and $<\!clock\ (bar)\ node>$, are common to all flip-flops in the device.

The compositive-edge enable node> and <negativeedge enable node> are common to all flip-flops in the dualedge flip-flops.

Digital devices

Edge-triggered flip-flop timing model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|---|-------|---------|
| THDCLKMN | Hold: j/k/d after clk/clkb edge, min | sec | 0 |
| THDCLKTY | Hold: j/k/d after clk/clkb edge, typ | sec | 0 |
| THDCLKMX | Hold: j/k/d after clk/clkb edge, max | sec | 0 |
| TPCLKQLHMN | Delay: clk/clkb edge to q/qb low to hi, min | sec | 0 |
| TPCLKQLHTY | Delay: clk/clkb edge to q/qb low to hi, typ | sec | 0 |
| TPCLKQLHMX | Delay: clk/clkb edge to q/qb low to hi, max | sec | 0 |
| TPCLKQHLMN | Delay: clk/clkb edge to q/qb hi to low, min | sec | 0 |
| TPCLKQHLTY | Delay: clk/clkb edge to q/qb hi to low, typ | sec | 0 |
| TPCLKQHLMX | Delay: clk/clkb edge to q/qb hi to low, max | sec | 0 |
| TPPCQLHMN | Delay: preb/clrb to q/qb low to hi, min | sec | 0 |
| TPPCQLHTY | Delay: preb/clrb to q/qb low to hi, typ | sec | 0 |
| TPPCQLHMX | Delay: preb/clrb to q/qb low to hi, max | sec | 0 |
| TPPCQHLMN | Delay: preb/clrb to q/qb hi to low, min | sec | 0 |
| TPPCQHLTY | Delay: preb/clrb to q/qb hi to low, typ | sec | 0 |
| TPPCQHLMX | Delay: preb/clrb to q/qb hi to low, max | sec | 0 |
| TSUDCLKMN | Setup: j/k/d to clk/clkb edge, min | sec | 0 |
| TSUDCLKTY | Setup: j/k/d to clk/clkb edge, typ | sec | 0 |
| TSUDCLKMX | Setup: j/k/d to clk/clkb edge, max | sec | 0 |
| TSUPCCLKHMN | Setup: preb/clrb hi to clk/clkb edge, min | sec | 0 |
| TSUPCCLKHTY | Setup: preb/clrb hi to clk/clkb edge, typ | sec | 0 |

Digital devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|---------|
| TSUPCCLKHMX | TSUPCCLKHMX Setup: preb/clrb hi to clk/clkb edge, max | | 0 |
| TWPCLMN | Min preb/clrb width low, min | sec | 0 |
| TWPCLTY | Min preb/clrb width low, typ | sec | 0 |
| TWPCLMX | Min preb/clrb width low, max | sec | 0 |
| TWCLKLMN | Min clk/clkb width low, min | sec | 0 |
| TWCLKLTY | Min clk/clkb width low, typ | sec | 0 |
| TWCLKLMX | Min clk/clkb width low, max | sec | 0 |
| TWCLKHMN | Min clk/clkb width hi, min | sec | 0 |
| TWCLKHTY | Min clk/clkb width hi, typ | sec | 0 |
| TWCLKHMX | Min clk/clkb width hi, max | sec | 0 |
| TSUCECLKMN | Setup: clock enable to clk edge, min | sec | 0 |
| TSUCECLKTY | Setup: clock enable to clk edge, typ | sec | 0 |
| TSUCECLKMX | Setup: clock enable to clk edge, max | sec | 0 |
| THCECLKMN | Hold: clock enable after clk edge, min | sec | 0 |
| THCECLKTY | Hold: clock enable after clk edge, typ | sec | 0 |
| THCECLKMX | Hold: clock enable after clk edge, max | sec | 0 |

^{1.} See .MODEL (model definition) on page 57.

Table 3-3 Edge-triggered flip-flop truth tables DFF

| Inputs | | Outputs | | | |
|--------|-----|---------|-----|----------------|----|
| D | CLK | PRE | CLR | Q | Q |
| X | Х | 1 | 0 | 0 | 1 |
| x | X | 0 | 1 | 1 | 0 |
| x | X | 0 | 0 | 1 ¹ | 1* |
| x | 0 | 1 | 1 | Q′ | Q′ |
| x | 1 | 1 | 1 | Q' | Q' |

Digital devices

Table 3-3 Edge-triggered flip-flop truth tables DFF

| Inputs | | Outputs | | | |
|--------|------------|---------|-----|---|---|
| D | CLK | PRE | CLR | Q | Q |
| 0 | ↑ | 1 | 1 | 0 | 1 |
| 1 | \uparrow | 1 | 1 | 1 | 0 |

^{1.} Shows an unstable condition.

Table 3-4 Edge-triggered flip-flop truth tables JKFF

| Inputs | | Outputs | | | | |
|--------|---|--------------|-----|-----|----------------|----|
| J | K | CLK | PRE | CLR | Q | Θ |
| Х | Х | Х | 1 | 0 | 0 | 1 |
| X | X | Х | 0 | 1 | 1 | 0 |
| х | x | Х | 0 | 0 | 1 ¹ | 1* |
| Х | х | 0 | 1 | 1 | Q' | Q' |
| Х | X | 1 | 1 | 1 | Q′ | Q′ |
| 0 | 0 | Ø | 1 | 1 | Q' | Q′ |
| 0 | 1 | Ø | 1 | 1 | 0 | 1 |
| 1 | 0 | \downarrow | 1 | 1 | 1 | 0 |
| 1 | 1 | \downarrow | 1 | 1 | Q' | Q′ |

^{1.} Shows an unstable condition.

Digital devices

Edge-triggered flip-flop truth tables DFFDE and JKFFDE

Table 3-5 Dual-edge D flip-flop (DFFDE) truth table

| Inputs | | | | | | Outputs | • |
|--------|------------|------|------|-----|-----|---------|----|
| D | CLK | PENA | NENA | PRE | CLR | Q | Q |
| Χ | Χ | X | X | 1 | 0 | 0 | 1 |
| X | Χ | Χ | X | 0 | 1 | 1 | 0 |
| Χ | Χ | Χ | X | 0 | 0 | 1^{1} | 1* |
| Χ | 0 | X | X | 1 | 1 | Q' | Q' |
| Χ | 1 | Χ | X | 1 | 1 | Q' | Q' |
| Χ | Χ | 0 | 0 | 1 | 1 | Q' | Q' |
| 0 | \uparrow | 1 | X | 1 | 1 | 0 | 1 |
| 1 | ↑ | 1 | X | 1 | 1 | 1 | 0 |
| 0 | \ | Χ | 1 | 1 | 1 | 0 | 1 |
| 1 | → | Χ | 1 | 1 | 1 | 1 | 0 |

^{1.} Shows an unstable condition.

Table 3-6 Dual-edge J-K flip-flop (JKFFDE) truth table

| Inputs | | | | | | | Output | s |
|--------|---|--------------|------|------|-----|-----|-----------------|----------|
| J | K | CLK | PENA | NENA | PRE | CLR | Q | Q |
| Χ | Χ | Χ | X | X | 1 | 0 | 0 | 1 |
| Χ | X | Χ | X | X | 0 | 1 | 1 | 0 |
| Χ | X | Χ | X | X | 0 | 0 | 1^1 | 1* |
| Χ | Χ | 0 | X | X | 1 | 1 | Q' | Q' |
| Χ | Χ | 1 | X | X | 1 | 1 | Q' | Q' Q' |
| Χ | Χ | Χ | 0 | 0 | 1 | 1 | Q' | Q' |
| 0 | 0 | \uparrow | 1 | X | 1 | 1 | Q' | Q' |
| 0 | 1 | \uparrow | 1 | X | 1 | 1 | 0 | 1 |
| 1 | 0 | \uparrow | 1 | X | 1 | 1 | 1 | 0 |
| 1 | 1 | \uparrow | 1 | X | 1 | 1 | \overline{Q}' | Q' |
| 0 | 0 | \downarrow | X | 1 | 1 | 1 | Q' | Q' Q' |
| 0 | 1 | ↓ | X | 1 | 1 | 1 | 0 | 1 |
| 1 | 0 | ↓ ↓ | Χ | 1 | 1 | 1 | 1 | 0 |
| 1 | 1 | ↓ | Χ | 1 | 1 | 1 | \overline{Q}' | Q' |

^{1.} Shows an unstable condition.

Digital devices

Gated latch

The simulator supports two types of gated latches: the S-R flip-flop (SRFF) and the D-type latch (DLTCH).

```
Device
                 U<name> SRFF (<no. of flip-flops>)
                 + <digital power node> <digital ground node>
format
                 + + clearbar node> <gate node>
                 + < s \text{ node } 1 > \dots < s \text{ node } n >
                 + <r node 1> \dots <r node n>
                  + <q output 1> ... <q output n>
                  + <qbar output 1> ... <qbar output n>
                 + <timing model name> <1/0 model name>
                 + [MNTYMXDLY=<delay select value>]
                 + [IO LEVEL=<interface subckt select value>]
                 U<name> DLTCH (<no. of latches>)
                 + <digital power node> <digital ground node>
                  + + clearbar node> <gate node>
                  + <d node 1> ... <d node n>
                  + <q output 1> ... <q output n>
                  + <qbar output 1> ... <qbar output n>
                  + <timing model name> <1/0 model name>
                  + [MNTYMXDLY=<delay select value>]
                  + [IO LEVEL=<interface subckt select value>]
Model form
              .MODEL <timing model name> UGFF [model parameters]
Examples
                 U5 SRFF(4)$G DPWR $G DGND PRESET CLEAR GATE
                  * four S-R latches
                 + S0 S1 S2 S3 R0 R1 R2 R3
                  + Q0 Q1 Q2 Q3 QB0 QB1 QB2 QB3
                  + T SRFF IO STD
                 U2 DLTCH(8) $G DPWR $G DGND PRESET CLEAR GATE
                  * eight D latches
                 + D0 D1 D2 D3 D4 D5 D6 D7
                 + Q0 Q1 Q2 Q3 Q4 Q5 Q6 Q7
                 + QB0 QB1 QB2 QB3 QB4 QB5 QB6 QB7
                  + T DLTCH IO_STD
                  .MODEL T SRFF UGFF(<optional parameters>) ; SRFF Timing
                 Model
```

Comments

Use < no. of flip-flops> to specify the number of flip-flops in the device. The three nodes, $< presetbar\ node>$, $< clearbar\ node>$, and $< gate\ node>$, are common to all of the flip-flops in the device.

Digital devices

Gated latch timing model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|---------|
| THDGMN | Hold: s/r/d after gate edge, min | sec | 0 |
| THDGTY | Hold: s/r/d after gate edge, typ | sec | 0 |
| THDGMX | Hold: s/r/d after gate edge, max | sec | 0 |
| TPDQLHMN | Delay: s/r/d to q/qb low to hi, min | sec | 0 |
| TPDQLHTY | Delay: s/r/d to q/qb low to hi, typ | sec | 0 |
| TPDQLHMX | Delay: s/r/d to q/qb low to hi, max | sec | 0 |
| TPDQHLMN | Delay: s/r/d to q/qb hi to low, min | sec | 0 |
| TPDQHLTY | Delay: s/r/d to q/qb hi to low, typ | sec | 0 |
| TPDQHLMX | Delay: s/r/d to q/qb hi to low, max | sec | 0 |
| TPGQLHMN | Delay: gate to q/qb low to hi, min | sec | 0 |
| TPGQLHTY | Delay: gate to q/qb low to hi, typ | sec | 0 |
| TPGQLHMX | Delay: gate to q/qb low to hi, max | sec | 0 |
| TPGQHLMN | Delay: gate to q/qb hi to low, min | sec | 0 |
| TPGQHLTY | Delay: gate to q/qb hi to low, typ | sec | 0 |
| TPGQHLMX | Delay: gate to q/qb hi to low, max | sec | 0 |
| TPPCQLHMN | Delay: preb/clrb to q/qb low to hi, min | sec | 0 |
| TPPCQLHTY | Delay: preb/clrb to q/qb low to hi, typ | sec | 0 |
| TPPCQLHMX | Delay: preb/clrb to q/qb low to hi, max | sec | 0 |
| TPPCQHLMN | Delay: preb/clrb to q/qb hi to low, min | sec | 0 |
| TPPCQHLTY | Delay: preb/clrb to q/qb hi to low, typ | sec | 0 |
| TPPCQHLMX | Delay: preb/clrb to q/qb hi to low, max | sec | 0 |
| TSUDGMN | Setup: s/r/d to gate edge, min | sec | 0 |
| TSUDGTY | Setup: s/r/d to gate edge, typ | sec | 0 |
| TSUDGMX | Setup: s/r/d to gate edge, max | sec | 0 |
| TSUPCGHMN | Setup: preb/clrb hi to gate edge, min | sec | 0 |
| | | | |

Digital devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---------------------------------------|-------|---------|
| TSUPCGHTY | Setup: preb/clrb hi to gate edge, typ | sec | 0 |
| TSUPCGHMX | Setup: preb/clrb hi to gate edge, max | sec | 0 |
| TWPCLMN | Min preb/clrb width low, min | sec | 0 |
| TWPCLTY | Min preb/clrb width low, typ | sec | 0 |
| TWPCLMX | Min preb/clrb width low, max | sec | 0 |
| TWGHMN | Min gate width hi, min | sec | 0 |
| TWGHTY | Min gate width hi, typ | sec | 0 |
| TWGHMX | Min gate width hi, max | sec | 0 |

^{1.} See <u>.MODEL (model definition)</u> on page 57.

Gated latch truth tables

The function tables for the SRFF and DLTCH primitives are given below.

| Inputs | | | | | | |
|--------|---|------|-----|-----|----------------|---------------------------------------|
| S | R | GATE | PRE | CLR | Qn+1 | Q |
| X | X | X | 1 | 0 | 0 | 1 |
| Χ | X | X | 0 | 1 | 1 | 0 |
| Χ | X | X | 0 | 0 | 1^1 | 1^{1} |
| Χ | X | 0 | 1 | 1 | Qn | Qn |
| 0 | 0 | 1 | 1 | 1 | Qn | $\frac{\overline{Qn}}{\overline{Qn}}$ |
| 0 | 1 | 1 | 1 | 1 | 0 | 1 |
| 1 | 0 | 1 | 1 | 1 | 1 | 0 |
| 1 | 1 | 1 | 1 | 1 | 1 ¹ | 1 ¹ |

^{1.} Shows an unstable condition.

D-type latch (DLTCH) truth table

| Inputs | | | | Outputs | |
|--------|------|-----|-----|---------|---|
| D | GATE | PRE | CLR | Q | Q |
| X | Χ | 1 | 0 | 0 | 1 |

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| Inputs | | | | Outputs | |
|--------|------|-----|-----|---------|--------------------------|
| D | GATE | PRE | CLR | Q | Q |
| Χ | X | 0 | 1 | 1 | 0 |
| Χ | X | 0 | 0 | 1^1 | 1* |
| Χ | 0 | 1 | 1 | Q' | $\overline{\mathrm{Q}}'$ |
| 0 | 1 | 1 | 1 | 0 | 1 |
| 1 | 1 | 1 | 1 | 1 | 0 |

Shows an unstable condition.

Digital devices

Pullup and pulldown

The PULLUP and PULLDN primitives function as digital pullup/pulldown resistors. They have no inputs (other than the digital power and ground nodes). Their output is a one level (pullup) or a zero level (pulldown), having a strength determined by the I/O model.

```
Device format

U<name> <resistor type> (<number of resistors>)
+ <digital power node> <digital ground node>
+ <output node>*
+ <I/O model name>
+ [IO_LEVEL=<interface subckt select value>]

Examples

U5 PULLUP(4) $G_DPWR $G_DGND ; four pullup resistors
+ BUSO BUS1 BUS2 BUS3 R1K
U2 PULLDN(1) $G_DPWR $G_DGND ; one pulldown resistor
+ 15 R500
```

Arguments and options

```
<resistor type>
    One of the following:

PULLUP pullup resistor array
PULLDN pulldown resistor array
<number of resistors>
    Specifies the number of resistors in the array.
```

Comments

Notice that PULLUP and PULLDN do not have Timing Models, just I/O models.

Digital devices

Delay line

The output of a delay line follows the input after the delay specified in the Timing Model. Any width pulse can propagate through a delay line. This behavior is different from gates, which don't propagate a pulse when its width is less than the propagation delay.

The delay line device has no parameters, and only one input and one output node.

Device
format

U<name> DLYLINE

+ <digital power node> <digital ground node>
+ <input node> <output node>
+ <timing model name> <I/O model name>
+ [MNTYMXDLY=<delay select value>]
+ [IO_LEVEL=<interface subckt select value>]

Examples

U5 DLYLINE \$G_DPWR \$G_DGND IN OUT; delay line
+ DLY20NS IO_STD
.MODEL DLY20NS UDLY(; delay line Timing Model
+ DLYMN=20ns DLYTY=20ns DLYMX=20ns
+)

Timing model format

.MODEL <timing model name> UDLY [model parameters]

Delay line timing model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|----------------|-------|---------|
| DLYMN | Delay: min | sec | 0 |
| DLYTY | Delay: typical | sec | 0 |
| DLYMX | Delay: max | sec | 0 |

1. See .MODEL (model definition) on page 57.

Digital devices

Programmable logic array

The programmable logic array is made up of a variable number of inputs, which form columns, and a variable number of outputs, which form rows. Each output (row) is driven by one logic gate. The "program" for the device determines which of the inputs (columns) are connected to each gate. All of the gates in the array are the same type (e.g., AND, OR, NAND, and NOR). Commercially available ICs (PALs, GALs, PEELs, and such) can have buffers, registers, more than one array of gates, and so on, all on the same part. These would normally be combined in a library subcircuit to make the part easier to use.

There are two ways to provide the program data for Programmable Logic Arrays. The normal way is to give the name of a JEDEC format file which contains the program data. This file would normally be produced by a PLD design package, or by using MicroSim PLSyn, which translates logic design information into a program for a specific programmable logic part. The other way to program the logic array is by including the program data, in order, on the device line (using the DATA=... construct).

If one of the PAL or GAL devices are being used in the model library, you will not need to use the Programmable Logic Array primitive directly, nor any of the model information below, since the library contains all of the appropriate modeling information. Using a PLD from the library is just like using any other logic device from the library, except that the simulator needs to know the name of the JEDEC file which contains the program for that part. A TEXT parameter name JEDEC_FILE is used to specify the file name, as shown in the following example:

Digital devices

This example creates a 14H4 PAL which is programmed by the JEDEC file myprog.jed.

```
Device
format

U<name> <pld type> (<no. of inputs>, <no. of outputs>)
+ <digital power node> <digital ground node>
+ <input_node>* <output_node>*
+ <timing model name> <I/O model name>
+ [FILE=<(file name) text value>]
+ [DATA=<radix flag>$<program data>$]
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
```

Timing model format

.MODEL <timing model name> UPLD [model parameters]

```
Examples
                   UDECODE PLANDC(3, 8); 3 inputs, 8 outputs
                   + \$G DPWR \$G DGND ; digital power supply and ground + IN1 IN2 IN3 ; the inputs
                   + OUTO OUT1 OUT2 OUT3 OUT4 OUT5 OUT6 OUT7 ; the
                   outputs
                   + PLD MDL
                                        ; the timing model name
                   + IO \overline{S}TD
                                        ; the I/O model name
                                        ; the programming data
                   + DA\overline{T}A=B$
                   * IN1 IN2 IN3
                   * TF TF TF
                   + 01 01 01
                                        ; OUTO
                                        ; OUT1
                   + 01 01 10
                                        ; OUT2
                   + 01 10 01
                   + 01 10 10
                                        ; OUT3
                   + 10 01 01
                                        ; OUT4
                   + 10 01 10
                                        ; OUT5
                   + 10 10 01
+ 10 10 10 $
                                        ; OUT6
                                        ; OUT7
```

.MODEL PLD MDL UPLD(...) ; PLD timing model definition

Arguments and options

```
<pld><pld type>
```

One of the following:

| PLD type | Description |
|----------|--|
| PLAND | AND array |
| PLANDC | AND array using true and complement columns for each input |
| PLNAND | NAND array |

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| PLD type | Description |
|----------|--|
| PLNANDC | NAND array using true and complement columns for each input |
| PLNOR | NOR array |
| PLNORC | NOR array using true and complement columns for each input |
| PLNXOR | Exclusive NOR array |
| PLNXORC | Exclusive NOR array using true and complement columns for each input |
| PLOR | OR array |
| PLORC | OR array using true and complement columns for each input |
| PLXOR | Exclusive OR array |
| PLXORC | Exclusive OR array using true and complement columns for each input |

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Digital devices

<file name text value>

The name of a JEDEC format file which specifies the programming data for the array. The file name can be specified as a text constant (enclosed in double quotes ""), or as a text expression (enclosed in vertical bars "I"). If a FILE is specified, any programming data specified by a DATA section is ignored. The mapping of addresses in the JEDEC file to locations in the array is controlled by model parameters specified in the timing model.

<radix flag>

One of the following:

B - binary data follows

O - octal data follows (most significant bit has the lowest address)

X - hexadecimal data follows (most significant bit has lowest address)

cprogram data>

A string of data values used to program the logic array. The values start at address zero, which programs the array for the connection of the first input pin to the gate which drives the first output. A 0 (zero) specifies that the input is not connected to the gate, and a 1 specifies that the input is connected to the gate. (Initially, all inputs are not connected to any gates.) The next value programs the array for the connection of the complement of the first input to the gate which drives the first output (if this is a programmable gate having true and complement inputs) or, the second input connection to the gate which drives the first output. Each additional 1 or 0 programs the connection of the next input or its complement to the gate which drives the first output, until the connection of all inputs (and their complements) to that gate have been programmed. Data values after that, program the connection of inputs to the gate driving the second output, and so on.

The data values must be enclosed in dollar signs (\$), but can be separated by spaces or continuation lines.

Digital devices

Comments

The example defines a 3-to-8 line decoder. The inputs are IN1 (MSB), IN2, and IN3 (LSB). If the inputs are all low, OUT0 is true. If IN1 and IN2 are low and IN3 is high, then OUT1 is true, and so on. The programming data has been typed in as an array, so that it is easier to read. The comments above the columns identify the true and false (complement) inputs, and the comments at the end of the line identify the output pin which is controlled by that gate. (Note, the simulator does not process any of these comments—they just help make the programming data readable.)

Programmable logic array timing model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|---|----------|--------------------------------|
| COMPOFFSET | JEDEC file mapping: address of complement of first input and first gate program | | 1 |
| INSCALE | JEDEC file mapping: amount the | std | 1 |
| | JEDEC file address changes for each new input pin | true/cmp | 2 |
| OFFSET | JEDEC file mapping: address of first input and first gate program | | 0 |
| OUTSCALE | JEDEC file mapping: amount the | std | <no. inputs="" of=""></no.> |
| | JEDEC file address changes for each new output pin (gate) | true/cmp | 2* <no. inputs="" of=""></no.> |
| TPHLMN | delay: in to out, hi to low, min | sec | 0 |
| TPHLTY | delay: in to out, hi to low, typ | sec | 0 |
| TPHLMX | delay: in to out, hi to low, max | sec | 0 |
| TPLHMN | delay: in to out, low to hi, min | sec | 0 |
| TPLHTY | delay: in to out, low to hi, typ | sec | 0 |
| TPLHMX | delay: in to out, low to hi, max | sec | 0 |

See <u>.MODEL (model definition)</u> on page 57.

Digital devices

Read only memory

There are two ways to provide the program data for ROMs. The normal way is to provide the name of an Intel Hex Format file. This file is read before the simulation starts, and the ROM is programmed to contain the data in the file. The other way to program the ROM is to include the program data on the device line (with the DATA=... construct).

The example below defines a 4-bit by 4-bit to 8-bit multiplier ROM.

```
Device
format

U<name> ROM( <no. of address pins>, <no. of output pins> )
+ <digital power node> <digital ground node>
+ <enable_node> <address node msb> ... <address node lsb>
+ <output node msb> ... <output node lsb>
+ <timing model name> <I/O model name>
+ [FILE=<file name text value>]
+ [DATA=<radix flag>$<program data>$]
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
```

Timing model format

.MODEL <timing model name> UROM (<model parameters>*)

Digital devices

Examples

```
UMULTIPLY ROM(8, 8)
                                ; 8 address bits, 8 outputs
+ $G DPWR $G DGND; digital power supply and ground
+ ENABLE
                                ; enable node
+ AIN3 AIN2 AIN1 AIN0
                                ; the first 4 bits of address
+ BIN3 BIN2 BIN1 BIN0
                                ; the second 4 bits of address
+ OUT7 OUT6 OUT5 OUT4 OUT3 OUT2 OUT1 OUT0 ; the outputs
                                ; the Timing Model name
 ROM MDL
+ IO \overline{S}TD
                                ; the I/O MODEL name
                                ; the programming data
+ DATA=X$
  B input value:
    0
              2
                  3
                           5
                                6
                                     7
                                         8
                                              9
                                                       В
                                                            CDEF
                                                   Α
    00
         00
              00
                  00
                       00
                           00
                                00
                                     00
                                         00
                                              00
                                                  00
                                                       00
                                                            00000000
  A = 0
                       04
                           05
                                                            OCOD0E0F
    00
         01
              02
                  03
                                06
                                     07
                                         08
                                              09
                                                   0A
                                                       0В
  A = 1
    00
              04
                  06
                       08
                           0A
                                0C
                                     ΟE
                                         10
                                              12
                                                   14
                                                            181A1C1E
         02
                                                       16
  A = 2
    00
         03
              06
                  09
                       0C
                           0F
                                12
                                     15
                                         18
                                              1B
                                                   1E
                                                       21
                                                            24272A2D
  A = 3
;
    00
              08
                  0C
                       10
                                18
                                     1C
                                         20
                                              24
                                                   28
                                                       2C
                                                            3034383C
         04
                           14
 A = 4
    00
         05
              0A
                  0F
                       14
                           19
                                1E
                                     23
                                         28
                                              2D
                                                   32
                                                       37
                                                            3C41464B
  A = 5
    00
         06
              0C
                  12
                       18
                           1E
                                24
                                     2A
                                         30
                                              36
                                                   3C
                                                       42
                                                            484E545A
  A = 6
    00
                           23
                                2A
                                     31
                                         38
         07
              OΕ
                  15
                       1C
                                              3F
                                                   46
                                                       4 D
                                                            545B6269
    = 7
;
  Α
    00
         08
              10
                  18
                       20
                           28
                                30
                                     38
                                         40
                                              48
                                                   50
                                                       58
                                                            60687078
  A = 8
+
    00
         80
              12
                       24
                           2 D
                                36
                                         48
                                              51
                                                   5A
                                                            6C757E87
                  1B
                                     ЗF
                                                       63
  A = 9
    00
         0A
              14
                  1E
                       28
                           32
                                3C
                                     46
                                         50
                                              5A
                                                   64
                                                       6E
                                                            78828C96
;
  A = A
    00
         0B
              16
                  21
                       2C
                           37
                                42
                                     4 D
                                         58
                                              63
                                                   6E
                                                       79
                                                            848F9AA5
  A = B
    00
              18
                       30
                           3C
                                48
                                     54
                                         60
                                                   78
         0C
                  24
                                              6C
                                                       84
                                                            909CA8B4
 A = C
    00
         0 D
              1A
                  27
                       34
                           41
                                4E
                                     5B
                                         68
                                              75
                                                   82
                                                       8F
                                                            9CA9B6C3
 A = D
    00
         OΕ
                  2A
                       38
                                54
                                     62
                                         70
                                                   8C
                                                            A8B6C4D2
+
             1C
                           46
                                              7E
                                                       9A
 A = E
                                     69
                                         78
                                              87
    00 OF
             1E
                  2D
                       3C
                           4B
                                5A
                                                   96
                                                       Α5
                                                            B4C3D1
E1$ ; A = F
```

.MODEL ROM_MDL UROM(...); ROM Timing Model definition

Digital devices

Arguments and options

<file name text value>

The name of an Intel Hex format file which specifies the programming data for the ROM. The file name can be specified as a text constant (enclosed in double quotes ""), or as a text expression (enclosed in vertical bars "|"). If a FILE is specified, any programming data specified by a DATA section is ignored.

<radix flag>

One of the following:

- B binary data follows
- O octal data follows (most significant bit has lowest address)
- X hexadecimal data follows (most significant bit has lowest address)

ogram data>

The program data is a string of data values used to program the ROM. The values start at address zero, first output bit. The next bit specifies the next output bit, and so on until all of the output bits for that address have been specified. Then the output values for the next address are given, and so on.

The data values must be enclosed in dollar signs (\$ \$), but can be separated by spaces or continuation lines.

Read only memory timing model parameters

| Model parameters ¹ | Description | Units | Defau It |
|----------------------------------|--|-------|-------------|
| TPADHMN | delay: address to data, low to hi, min | sec | 0 |
| TPADHTY | delay: address to data, low to hi-Z, typ | sec | 0 |
| TPADHMX | delay: address to data, low to hi, max | sec | 0 |
| TPADLMN | delay: address to data, hi to low, min | sec | 0 |
| TPADLTY | delay: address to data, hi to low, typ | sec | 0 |

Digital devices

| Model parameters ¹ | Description | Units | Defau It |
|----------------------------------|---|-------|-------------|
| TPADLMX | delay: address to data, hi to low, max | sec | 0 |
| TPEDHMN | delay: enable to data, hi-Z to hi, min | sec | 0 |
| TPEDHTY | delay: enable to data, hi-Z to hi, typ | sec | 0 |
| TPEDHMX | delay: enable to data, hi-Z to hi, max | sec | 0 |
| TPEDLMN | Delay: enable to data, hi-Z to low, min | sec | 0 |
| TPEDLTY | delay: enable to data, hi-Z to low, typ | sec | 0 |
| TPEDLMX | delay: enable to data, hi-Z to low, max | sec | 0 |
| TPEDHZMN | delay: enable to data, hi to hi-Z, min | sec | 0 |
| TPEDHZTY | delay: enable to data, hi to hi-Z, typ | sec | 0 |
| TPEDHZMX | delay: enable to data, hi to hi-Z, max | sec | 0 |
| TPEDLZMN | delay: enable to data, low to hi-Z, min | sec | 0 |
| TPEDLZTY | delay: enable to data, low to hi-Z, typ | sec | 0 |
| TPEDLZMX | delay: enable to data, low to hi-Z, max | sec | 0 |

^{1.} See .MODEL (model definition) on page 57.

Digital devices

Random access read-write memory

The RAM is normally initialized using unknown data at all addresses. There are two ways to provide other initialization data for RAMs. The normal way is to give the name of an Intel Hex Format file. This file is read before the simulation starts, and the RAM is initialized to match the data in the file. The other way to initialize the RAM is to include the initialization data on the device line (using the DATA=... construct).

Device format

```
U<name> RAM(<no. of address bits>, <no. of output bits>)
+ <digital power node> <digital ground node>
+ <read enable node> <write enable node>
+ <address msb node>...<address lsb node>
+ <write-data msb node>...<write-data lsb node>
+ <read-data msb node>...<read-data lsb node>
+ <timing model name> <I/O model name>
+ [MNTYMXDLY=<delay select value>]
+ [IO LEVEL=<interface subckt select value>]
+ [FILE=<file name text value>]
+ [DATA=<radix flag>$<initialization data>$]
```

Timing model format

.MODEL <timing model name> URAM (<model parameters>*)

Arguments and options

Digital devices

<file name text value>

The name of an Intel Hex format file which specifies the initialization data for the RAM. The file name can be specified as a text constant (enclosed in double quotes ""), or as a text expression (enclosed in vertical bars II). If a FILE is specified, any initialization data specified by a DATA section is ignored.

<radix flag>

One of the following:

B - binary data follows

O - octal data follows (most significant bit has lowest address)

X - hexadecimal data follows (most significant bit has lowest address)

<initialization data>

A string of data values used to initialize the RAM. The values start at address zero, first output bit. The next bit specifies the next output bit, and so on until all of the output bits for that address have been specified. Then the output values for the next address are given, and so on.

The data values must be enclosed in dollar signs (\$ \$), but can be separated by spaces or continuation lines.

The initialization of a RAM using the DATA=... construct is the same as the programming of a ROM. See <u>Read only memory</u> on page 405 on the ROM primitive for an example.

Digital devices

Comments

The RAM has separate read and write sections, using separate data and enable pins, and shared address pins. To write to the RAM, the address and write data signals must be stable for the appropriate setup times, then write enable is raised. It must stay high for at least the minimum time, then fall. Address and data must remain stable while write enable is high, and for the hold time after it falls. Write enable must remain low for at least the minimum time before changing.

To read from the RAM, raise read enable, and the outputs change from Z (high impedance) to the appropriate value after a delay. The address can change while read enable is high, and if it does, the new data is available at the outputs after the delay.

Nothing prevents both the read and write enable from being true at the same time, although most real devices would not allow this. The new value from the write is sent to the read data outputs on the falling edge of write enable.

Random access memory timing model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|---------|
| TPADHMN | delay: address to read data, low to hi, min | sec | 0 |
| TPADHTY | delay: address to read data, low to hi, typ | sec | 0 |
| TPADHMX | delay: address to read data, low to hi, max | sec | 0 |
| TPADLMN | delay: address to read data, hi to low, min | sec | 0 |
| TPADLTY | delay: address to read data, hi to low, typ | sec | 0 |
| TPADLMX | delay: address to read data, hi to low, max | sec | 0 |
| TPERDHMN | delay: read enable to read data, hi-Z to hi, min | sec | 0 |
| TPERDHTY | delay: read enable to read data, hi-Z to hi, typ | sec | 0 |
| TPERDHMX | delay: read enable to read data, hi-Z to hi, max | sec | 0 |
| TPERDLMN | delay: read enable to read data, hi-Z to low, min | sec | 0 |
| TPERDLTY | delay: read enable to read data, hi-Z to low, typ | sec | 0 |
| TPERDLMX | delay: read enable to read data, hi-Z to low, max | sec | 0 |

PSpice A/D Reference Guide Digital devices

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-------|---------|
| TPERDHZM N | delay: read enable to read data, hi to hi-Z, min | sec | 0 |
| TPERDHZTY | delay: read enable to read data, hi to hi-Z, typ | sec | 0 |
| TPERDHZM X | delay: read enable to read data, hi to hi-Z, max | sec | 0 |
| THAEWTY | min hold time:write enable fall to address change, typ | sec | 0 |
| THAEWMX | min hold time:write enable fall to address change, max | sec | 0 |
| THDEWMN | min hold time:write enable fall to data change, min | sec | 0 |
| THDEWTY | min hold time:write enable fall to data change, typ | sec | 0 |
| THDEWMX | min hold time:write enable fall to data change, max | sec | 0 |
| THAEWMN | min hold time:write enable fall to address change, min | sec | 0 |
| TPERDLZM N | delay: read enable to read data, low to hi-Z, min | sec | 0 |
| TPERDLZTY | delay: read enable to read data, low to hi-Z, typ | sec | 0 |
| TPERDLZM X | delay: read enable to read data, low to hi-Z, max | sec | 0 |
| TSUDEWMN | min setup time: data to write enable rise, min | sec | 0 |
| TSUDEWTY | min setup time: data to write enable rise, typ | sec | 0 |
| TSUDEWMX | min setup time: data to write enable rise, max | sec | 0 |
| TSUAEWMN | min setup time: address to write enable rise, min | sec | 0 |
| TSUAEWTY | min setup time: address to write enable rise, typ | sec | 0 |
| TSUAEWMX | min setup time: address to write enable rise, max | sec | 0 |
| TWEWHMN | min width: enable write hi, min | sec | 0 |
| TWEWHTY | min width: enable write hi, typ | sec | 0 |
| TWEWHMX | min width: enable write hi, max | sec | 0 |
| TWEWLMN | min width: enable write low, min | sec | 0 |
| TWEWLTY | min width: enable write low, typ | sec | 0 |

Digital devices

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|----------------------------------|-------|---------|
| TWEWLMX | min width: enable write low, max | sec | 0 |

^{1.} See .MODEL (model definition) on page 57.

Digital devices

Multi-bit A/D and D/A converter

The simulator provides two primitives to model analog-to-digital converters and digital-to-analog converters: the ADC and the DAC. These two primitives simplify the modeling of these complex mixed-signal devices.

Multi-bit analog-to-digital converter

| Device format | <pre>U<name> ADC(<number bits="" of="">) + <digital node="" power=""> <digital ground="" node=""> + <in node=""> <ref node=""> <gnd node=""> <convert node=""></convert></gnd></ref></in></digital></digital></number></name></pre> |
|------------------|--|
| | <pre>+ <status node=""> <over-range node=""> + <output msb="" node=""> <output lsb="" node=""> + <timing model="" name=""> <i model="" name="" o=""> + [MNTYMXDLY=<delay select="" value="">] + [IO_LEVEL=<interface select="" subckt="" value="">]</interface></delay></i></timing></output></output></over-range></status></pre> |

Timing model format

```
.MODEL <timing model name> UADC [model parameters]
```

Examples

```
U5 ADC(4) $G_DPWR $G_DGND; 4-bit ADC
+ Sig Ref 0 Conv Stat OvrRng Out3 Out2 Out1 Out0
+ ADCModel IO_STD
```

.MODEL ADCModel UADC(...); Timing Model

Multi-bit A/D converter timing model parameters

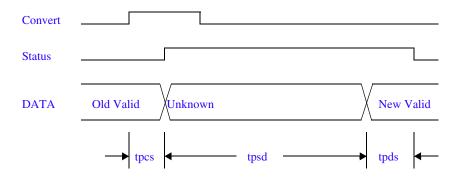
| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|---------|
| TPCSMN | propagation delay: rising edge of convert to rising edge of status, min | sec | 0 |
| TPCSTY | propagation delay: rising edge of convert to rising edge of status, typ | sec | 0 |
| TPCSMX | propagation delay: rising edge of convert to rising edge of status, max | sec | 0 |
| TPDSMN | propagation delay: data valid to falling edge of status, min | sec | 0 |
| TPDSTY | propagation delay: data valid to falling edge of status, typ | sec | 0 |
| TPDSMX | propagation delay: data valid to falling edge of status, max | sec | 0 |

Digital devices

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|---|-------|---------|
| TPSDMN | propagation delay: rising edge of status to data valid, min | sec | 0 |
| TPSDTY | propagation delay: rising edge of status to data valid, typ | sec | 0 |
| TPSDMX | propagation delay: rising edge of status to data valid, max | sec | 0 |

See <u>.MODEL (model definition)</u> on page 57.

ADC primitive device timing



DATA refers to both the data and over-range signals. The Convert pulse can be any width, including zero. If the propagation delay between the rising edge of the Convert signal and the Status signal (tpsd) is zero, the data and over-range do not go to unknown but directly to the new value. There is a resistive load from <ref node> to <gnd node>, and from <in node> to <gnd node>, of 1/GMIN.

The voltage at <in node> and <ref node> with respect to <gnd node> is sampled starting at the rising edge of the Convert signal, and ending when the Status signal becomes high. This gives a sample aperture time of tpcs plus any rising time for Convert. If, during the sample aperture, the output calculated having the minimum <ref node> voltage and maximum <in node> voltage is different from the output calculated having the maximum <ref node> voltage and minimum <in node> voltage, the appropriate output bits are set to the unknown state and a warning message is printed in the output file.

The output is the binary value of the nearest integer to

$$\frac{V(in, gnd)}{V(ref, gnd)} \cdot 2^{nbits}$$

Digital devices

If this value is greater than 2^{nbits}-1, then all data bits are 1, and over-range is 1. If this value is less than zero, then all data bits are zero, and over-range is 1.

Multi-bit digital-to-analog converter

| Device | <pre>U<name> DAC(<number bits="" of="">)</number></name></pre> |
|--------|---|
| format | <pre>+ <digital node="" power=""> <digital ground="" node=""> + <out node=""> <ref node=""> <qnd node=""></qnd></ref></out></digital></digital></pre> |
| | + <input msb="" node=""/> <input lsb="" node=""/> |
| | <pre>+ <timing model="" name=""> <i model="" name="" o=""></i></timing></pre> |
| | <pre>+ [MNTYMXDLY=<delay select="" value="">]</delay></pre> |
| | + [IO LEVEL= <interface select="" subckt="" value="">]</interface> |

Timing model format

.MODEL <timing model name> UDAC [model parameters]

U7 DAC(4) \$G DPWR \$G DGND ; 4-bit DAC + Sig Ref 0 $\overline{\text{In}}$ 3 $\overline{\text{In}}$ 2 $\overline{\text{In}}$ 1 $\overline{\text{In}}$ 0 **Examples**

+ DACModel IO STD

.MODEL DACModel UDAC(...); Timing model

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-------|---------|
| TSWMN | Switching time: change in data to analog out stable, min | sec | 10ns |
| TSWTY | Switching time: change in data to analog out stable, typ | sec | 10ns |
| TSWMX | Switching time: change in data to analog out stable, max | sec | 10ns |

^{1.} See .MODEL (model definition) on page 57.

Digital devices

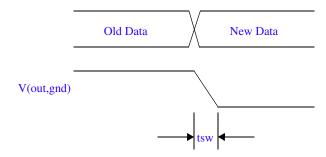
DAC primitive device timing

The DAC is a zero impedance voltage source from <out node> to <gnd node>. The voltage is

$$V(ref, gnd) \cdot \frac{(binary\ value\ of\ inputs)}{\gamma^{nbits}}$$

There is a resistance of 1/GMIN between <ref node> and <gnd node>.

If any inputs are unknown (X), the output voltage is halfway between the output voltage if all the X bits were 1 and the output voltage if all the X bits were 0. When an input bit changes, the output voltage changes linearly to the new value during the switching time.



Digital devices

Behavioral Primitives

The simulator offers three primitives to aid in the modeling of complex digital devices: the Logic Expression, Pin-to-Pin Delay, and Constraint Checker primitives. These devices are distinct from other primitives in that they allow data-sheet descriptions to be specified more directly, allowing a one-to-one correspondence using the function diagrams and timing specifications.

The Logic Expression primitive, LOGICEXP, uses free-format logic expressions to describe the functional behavior device.

The Pin-To-Pin Delay primitive, PINDLY, describes propagation delays using sets of rules based on the activity on the device inputs.

The Constraint Checker primitive, CONSTRAINT allows a listing of timing rules such as setup/hold times, and minimum pulse widths. When a violation occurs, the simulator issues a message indicating the time of the violation and its cause.

Logic expression

The LOGICEXP primitive allows combinational logic to be expressed in an equation-like style, using standard logic operators, node names, and temporary variables.

Device format

```
U<name> LOGICEXP ( <no. of inputs>, <no. of outputs> )
+ <digital power node> <digital ground node>
+ <input node 1> ... <input node n>
+ <output node 1> ... <output node n>
+ <timing model name>
+ <I/O model name>
+ [IO_LEVEL = <value>]
+ [MNTYMXDLY = <value>]
+ LOGIC:
+ <logic assignment>*
```

Timing model format

```
.MODEL <timing model name> UGATE [model parameters]
```

Arguments and options

LOGIC:

Marks the beginning of a sequence of one or more <logic assignments>. A <logic assignment> can have one of the two following forms:

```
<output node> = { <logic expression > }
<temporary value> = { <logic expression> }
```

Digital devices

<output node>

One of the output node names as it appears in the interface list. Assignments to an <code><output node></code> causes the result of the <code><logic expression></code> to be scheduled on that output pin. Each <code><output node></code> must have exactly one assignment.

<temporary value>

Any target of an assignment which is not specified as one of the nodes attached to the device defines a temporary variable. Once assigned, <temporary values> can be used inside subsequent logic expressions>. They are provided to reduce the complexity and improve the readability of the model. The rules for node names apply to <temporary value> names.

<logic expression>

A C-like, infix-notation expression that returns one of the five digital logic levels. Like all other expressions, <1ogic expressions> must be surrounded by curly braces { }. They can span one or more lines using the + continuation character in the first column position.

The logic operators are listed below from highest-to-lowest precedence.

Logic Expression Operators

~ unary not

& and

^ exclusive or

l or

The allowed operands are:

- <input nodes>
- Previously assigned <temporary values>
- Previously assigned <output nodes>
- <logic constants>: 0, 1, X, R, F

Digital devices

As in other expressions, parentheses () can be used to group subexpressions. Note that these logic operators can also be used in Probe trace definitions.

Comments

The LOGICEXP primitive uses the same timing model as the standard gate primitives, UGATE.

See "Standard gate timing model parameters" on page 378 for the list of UGATE model parameters.

Simulation behavior

When a LOGICEXP primitive is evaluated during a transient analysis, the assignment statements using in it are evaluated in the order they were specified in the netlist. The logic expressions are evaluated using no delay. When the result is assigned to an output node, it is scheduled on that output pin using the appropriate delay specified in the timing model.

Internal feedback loops are not allowed in expressions. That is, an expression cannot reference a value which has yet to be defined. However, external feedback is allowed if the output node also appears on the list of input nodes.

This example models the functionality of the 74181 Arithmetic/Logic Unit. The logic for the entire part is contained in just one primitive. Timing would be handled by the PINDLY and CONSTRAINT primitives. Refer to any major device manufacturer's data book for a detailed description of the operation of the 74181.

```
U74181 LOGICEXP (14, 8) DPWR DGND
+ AOBAR A1BAR A2BAR A3BAR B0BAR B1BAR B2BAR B3BAR S0 S1 S2 S3 M CN
+ LF0BAR LF1BAR LF2BAR LF3BAR LAEQUALB LPBAR LGBAR LCN+4
+ D0 GATE IO STD
+ LOGIC:
* Intermediate terms:
+ 131 = { \sim ((B3BAR \& S3 \& A3BAR) | (A3BAR \& S2 \& \sim B3BAR)) }
+ I32 = { \sim ((\sim B3BAR \& S1) | (S0 \& B3BAR) | A3BAR) }
+ 121 = { \sim ((B2BAR \& S3 \& A2BAR) | (A2BAR \& S2 \& \sim B2BAR)) }
+ I22 = { \sim ((\sim B2BAR \& S1) | (S0 \& B2BAR) | A2BAR ) }
+ I11 = { \sim ((B1BAR \& S3 \& A1BAR) | (A1BAR \& S2 \& \sim B1BAR)) }
+ I12 = { \sim ((\sim B1BAR \& S1) | (S0 \& B1BAR) | A1BAR) }
+ 101 = { \sim ((B0BAR \& S3 \& A0BAR) | (A0BAR \& S2 \& \sim B0BAR)) }
+ I02 = { \sim ((\sim B0BAR \& S1) | (S0 \& B0BAR) | A0BAR ) }
+ MBAR = { \sim M }
+ P = { I31 & I21 & I11 & I01 }
```

Digital devices

Pin-to-pin delay

The pin-to-pin (PINDLY) primitive is a general mechanism that allows the modeling of complex device timing. It can be thought of as a set of delay-lines (paths) and rules describing how to associate specific amounts of delay using each path.

A PINDLY primitive is used in the output path of a device model, typically at the output pins of a subcircuit definition. A single PINDLY primitive can model the timing and output characteristics of an entire part, including tristate behavior.

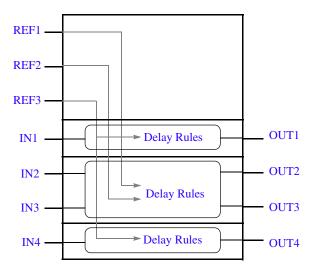
PINDLY primitives are expressed and evaluated in a manner similar to the LOGICEXP primitive, except in this case a delay expression is assigned to each output. Whenever an output path undergoes a transition, its delay expression is evaluated to determine the propagation delay which is to be applied to that change.

A delay expression can contain one or more rules that determine which activity on the part's inputs is responsible for the output change, for example, "is the output changing because the clock changed or the data changed?" This allows device models to be derived directly from data sheets, which typically specify propagation delays based on which input is changing. The PINDLY primitive uses its reference inputs to determine the logic state and recent transitions on nodes which are not in the output path.

Pin-to-pin delay modeling is much simpler compared to earlier methods, in which input-tooutput delays had to be distributed among the low-level primitives used to model the device. The latter method can require a great deal of trial and error because manufacturer's data sheets do not provide a one-to-one association between the logic diagram and the timing specifications.

Digital devices

PINDLY primitives can also contain constraints such as setup/hold, width, and frequency specifications, like those supported by the CONSTRAINT primitive. When used in the PINDLY primitive, these constraints allow the simulator to propagate hazard conditions and report violations in subsequent logic.



Device format

```
U<name> PINDLY ( <no. of paths>, <no. of enables>, <no. of
refs> )
+ <digital-power-node> <digital-ground-node>
+ <input node 1> ... <input node n>
+ [<enable node 1> ... <enable node n>]
+ [<reference node 1> ... <reference node n>]
+ <output node 1> ... <output node n>
+ <I/O model name>
+ [MNTYMXDLY = <delay select value>]
 [IO LEVEL = <interface subckt select value>]
 [BOOLEAN:
      <boolean assignment>* ]
 PINDLY:
      <delay assignment>*
  [TRISTATE:
     ENABLE LO | HI <enable node>
      <delay assignment>* 1
 [SETUP HOLD: <setup-hold-specification> ]
 [WIDTH: <width-specification> ]
+ [FREQ: <frequency-specification> ]
+ [GENERAL: <general-specification> ]
```

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Examples

```
U1 PINDLY(4,0,3) $G_DPWR $G_DGND
+ IN1 IN2 IN3 IN4
+ REF1 REF2 REF3
+ OUT1 OUT2 OUT3 OUT4
+ IO_STD DO_GATE
+ PINDLY:
+ ...
```

Arguments and options

<no. of paths>

Specifies the number of input-to-output paths represented by the device; the number of inputs must be equal to the number of outputs. A path is defined as an input-to-output association, having the appropriate delay rules started according to the described conditions.

<no. of enables>

Specifies the number of tristate enable nodes used by the primitive. Enable nodes are used in TRISTATE sections. <no. of enables> can be zero.

<no. of refs>

Specifies the number of reference nodes used by the primitive. Reference nodes are used within delay expressions to get state information about signals which are not in the input-to-output paths. <no. of refs> can be zero.

Comments

The example depicts the relationship and purpose of the different pins on the PINDLY primitive.

The PINDLY primitive can be viewed as four buffers, IN1 to OUT1 through IN4 to OUT4, and three reference nodes which are used by the output delay rules. The figure shows how the reference nodes can be used in one or more set of delay rules. In this case, REF1 and REF2 are used by the delay rules for OUT2, and REF3 is used by the delay rules for OUT1 and OUT4. The figure also shows that OUT2 and OUT3 can share the same delay rules. The remainder of the format description describes how to create delay rules.

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BOOLEAN:

Marks the beginning of a section of one or more <boolean assignments>, which define temporary variables that can be used in subsequent <delay expressions>. BOOLEAN sections can appear in any order within the PINDLY primitive. A <boolean assignment> has the following form:

```
<boolean variable> = { <boolean-expression> }
```

<boolean variable> can be any name which follows the node name rules.

<boolean expression> is a C-like, infix-notation expression which returns the boolean value TRUE or FALSE. Like all other expressions, <boolean expressions> must be surrounded by curly braces {...}. They can span one or more lines by using the + continuation character in the first column position. The boolean operators are listed below from highest-to-lowest precedence:

```
~ unary not
== equality
!= inequality
& and
^ exclusive or
| or
```

All boolean operators take the following boolean values as operands:

- Previously assigned <boolean variables>
- Reference functions (defined below)
- Transition functions (defined below)
- <boolean constants>: TRUE, FALSE

In addition, the == and != operators take logic values, such as <input nodes> and <logic constants>. This allows for a check of the values on nodes; for example, CLEAR == 1 returns TRUE if the current level on the node CLEAR is a logic one and FALSE otherwise.

Reference functions

Reference functions are used to detect changes (transitions) on <reference nodes> or <input nodes>. All reference functions return boolean values, and therefore can be used within any <boolean expression>. Following is the list of available reference functions and their arguments:

```
CHANGED <node>, <delta time> )
CHANGED_LH <node>, <delta time> )
CHANGED_HL <node>, <delta time> )
```

Digital devices

The CHANGED function returns TRUE if the specified < node> has undergone any state transition within the past < delta time>, prior to the current simulation time; otherwise it returns FALSE.

Similarly, CHANGED_LH returns TRUE if < node> has specifically undergone a low-to-high transition within the past < delta time>; FALSE otherwise. Note that CHANGED_LH only looks at the most recent (or current) transition. It cannot, for example, determine if $0\rightarrow 1$ occurred two transitions ago.

Finally, CHANGED_HL is similar to CHANGED_LH, but checks for high-to-low transitions.

If a <delta time> is specified zero, the reference functions return TRUE if the node has changed at the current simulation time. This allows all of the functionality of a device to be modeled in zero delay so that the total delay through the device can be described using the delay expressions.

Transition functions

Transition functions are used to determine the state change occurring on the changing output, that is, the *<output node>* for which the *<delay expression>* is being evaluated. Like reference functions, transition functions return boolean values. However, they differ from reference functions in that transition functions take no arguments, since they implicitly refer to the changing output at the current time. The transition functions are of the general form:

where p is the previous state value and n is the new state value. State values are taken from the set { L H Z \$ }. Where appropriate, the \$ can be used to signify don't care, e.g., a TRN_H\$ matches a transition from H to ANY state. Rising states automatically map to High, and Falling states automatically map to Low.

As a term in any boolean expression, for example, TRN_LH takes on a TRUE value if the changing output is propagating a change from zero to one.

Following is the complete set of transition functions.

```
TRN_LH TRN_LZ TRN_L$ TRN_HL TRN_HZ TRN_H$ TRN_ZL TRN_ZH TRN_Z$ TRN_$L TRN _$H TRN_$Z
```

Note: The TRN_pZ and TRN_Zn functions return true only if it is used within a TRISTATE section, described below. Although open-collector outputs also transition to a high-impedance Z (instead of H), most data books describe propagation times on open-collector outputs as TPLH or TPHL. Therefore, open-collector output devices should use TRN_LH and TRN_HL, and tristate output devices should use TRN_LZ, TRN_HZ, TRN_ZL, and TRN_ZH.

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PINDLY: marks the beginning of a section of one or more <delay assignments>, which are used to associate propagation delays using the PINDLY primitive's outputs. <delay assignments> are of the form:

```
<output node>* = { <delay expression> }
```

<output node> is one of the output node names as it appears in the interface list. Each
<output node> must have exactly one assignment. Several outputs can share the same
delay rules by listing them (separated by spaces or commas) on the left-hand side of the
<delay expression>.

The simplest <delay expression> is a single <delay value>, defined as:

```
DELAY(<min>, <typ>, <max>)
```

where <min>, <typ>, and <max> are floating point constants or expressions (involving parameters), expressed in seconds. To specify unknown values, use -1. For example, DELAY(20ns,-1,35ns) specifies a minimum time of 20ns, a default (program-computed) value for typical, and a maximum of 35ns. See <u>Treatment of unspecified propagation delays</u> on page 372 for more information on default delays.

The delay assignment below specifies the propagation delays through output Y to be: min=2ns, typ=5ns, and max=9ns.

```
+ PINDLY:
+ Y = { DELAY(2ns, 5ns, 9ns) }
```

To define more complex, rule-based *<delay expressions>*, use the CASE function, which has the form:

The arguments to the CASE function are pairs of <boolean expressions> and <delay expressions>, followed by a final default <delay expression>. <boolean expressions> (described above) can contain <boolean values>, reference functions, and transition functions.

When the CASE function is evaluated, each < boolean expression > is evaluated in order of appearance until one produces a TRUE result. When this occurs, the < delay

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expression> is paired with the result of the CASE function, and the evaluation of the CASE is ended. If none of the

case is ended. If none of the

case is ended. If none of the

case is expressions> return a TRUE result, the value of the final <delay expression> is used. Because it is possible for all

case is expressions> to evaluate FALSE, the default delay value must be supplied. Note that each argument to the CASE function must be separated by commas.

```
+ BOOLEAN:
+ CLOCK = { CHANGED_LH( CLK, 0 ) }
+ PINDLY:
+ QA QB QC QD = {
+ CASE (
+ CLOCK & TRN_LH, DELAY(-1,13ns,24ns),
+ CLOCK & TRN_HL, DELAY(-1,18ns,27ns),
+ CHANGED_HL( CLRBAR,0), DELAY(-1,20ns,28ns),
+ DELAY(-1,20ns,28ns) ; Default
+ )
+ }
```

This example describes the delays through a four-bit counter. It shows how rules can be defined to precisely isolate the cause of the output change. In this example, the boolean variable CLOCK is being defined. It is TRUE whenever the reference input CLK changes from low-to-high at the current simulation time. This is only true if the device functionality is modeled in zero delay.

The four outputs QA through QD all share the same delay expression. The CASE is used to specify different delays when the device is counting or clearing. The first two rules define delays when the device is counting (CLK changing low-to-high); the first when the output (QA through QD) is going from low-to-high, the second from high-to-low.

The third rule simply uses the CHANGED_HL function directly to determine whether CLRBAR is changing, and in this case the specification applies to any change (low-to-high or high-to-low) on the output. The default delay applies to all other output transitions which are not covered by the first three rules.

TRISTATE: marks the beginning of a sequence of one or more <delay assignments>. The TRISTATE section differs from the PINDLY section in that the outputs are controlled by the specified enable node.

Immediately following the TRISTATE keyword, an enable node must be specified using its polarity and the ENABLE keyword:

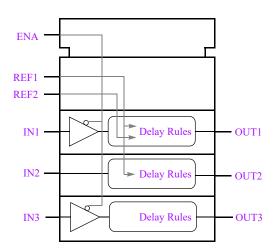
```
ENABLE HI <enable node>; Specifies active HI enable ENABLE LO <enable node>; Specifies active LO enable
```

The specified <enable node> applies to all <output node> assignments in the current section.

Note: Note that < delay expressions> within a TRISTATE section can contain the transition functions pertaining to the Z state, for example TRN_ZL and TRN_HZ.

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The following example demonstrates how an enable node can be used to control more than one output. It also shows that some device outputs can use the standard output (PINDLY) while others use the tristate output. (Delay values have been omitted.)



```
U1 PINDLY(3,1,2) $G DPWR $G DGND
+ IN1 IN2 IN3
+ ENA
+ REF1 REF2
+ OUT1 OUT2 OUT3
+ IO MODEL
  TRĪSTATE:
    ENABLE LO = ENA
    OUT1 = {
        CASE (
            CHANGED (REF1, 0) & TRN LH, DELAY (...),
            CHANGED (REF2, 0),
                                       DELAY(...),
            TRN ZL,
                                       DELAY(...),
    OUT3 = {
        CASE (
            TRN LZ, DELAY(...),
            TRN HZ, DELAY (...),
```

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- **1.** Each CONSTRAINT clause operates independently of all others within a device.
- **2.** By default, for violations involving <input node>, the message tag propagates to the <output node> having positional correspondence.
- **3.** By default, for violations involving *<reference node>*, the message tag propagates to ALL *<output node>*s.
- **4.** The default behavior can be overridden by use of one of the following statements, which can appear anywhere within any constraint clause proper:

```
AFFECTS (#OUTPUTS) = <output node> { ... }
AFFECTS ALL
```

5. AFFECTS_NONE is always the default for the GENERAL constraint.

SETUP-HOLD: Marks the beginning of a constraint specification.

WIDTH: These constructs have the same syntax as those used in the CONSTRAINT primitive (see General

notes on page 436).

GENERAL:

When a PINDLY primitive is used, the constraint specifications allow the simulator to report timing violations and track the effects of the violations in downstream logic. This allows persistent hazards to be reported. This differs from the CONSTRAINT primitive, which only reports timing violations.

PINDLY primitive simulation behavior

A PINDLY primitive is evaluated whenever any of its <input nodes> or <enable nodes> change. The <input node> is positionally associated using its corresponding <output node>. The BOOLEAN statements up to the output assignment are evaluated first, then the appropriate PINDLY or TRISTATE <delay expression> which has been assigned to the changing <output node> is evaluated. The changing input's state is then applied to the output, using its delay value.

Digital devices

The following PINDLY primitive models the timing behavior of a 74LS160A counter. This example is derived directly from the device model in the model library.

```
ULS160ADLY PINDLY(5,0,4) DPWR DGND
+ RCO QA QB QC QD ; Inputs
+ CLK LOADBAR ENT CLRBAR; Reference nodes
+ RCO O QA O QB O QC O QD O; Outputs
 IO LS MNTYMXDLY={MNTYMXDLY} IO LEVEL={IO LEVEL}
+ BOOLEAN:
  CLOCK = { CHANGED LH(CLK, 0) }
   CNTENT = \{ CHANGED(ENT, 0) \}
+ PINDLY:
   QA O QB O QC O QD O = {
       CASE (
          CLOCK & TRN LH, DELAY(-1,13NS,24NS),
          CLOCK & TRN_HL, DELAY(-1,18NS,27NS), CHANGED_HL(CLRBAR,0), DELAY(-1,20NS,28NS),
          DELAY(-\overline{1}, 20NS, 28NS); Default
        }
   RCO = {
      CASE (
         CNTENT, DELAY(-1,9NS,14NS),
         CLOCK & TRN_LH, DELAY(-1,18NS,35NS),
CLOCK & TRN_HL, DELAY(-1,18NS,35NS),
         DELAY(-1,20\overline{N}S,35NS); Default
       }
```

Constraint checker

The CONSTRAINT primitive provides a general constraint checking mechanism to the digital device modeler. It performs setup and hold time checks, pulse width checks, frequency checks, and includes a general mechanism to allow user-defined conditions to be reported.

The CONSTRAINT primitive only reports timing violations. It does not affect propagated or stored logic state or propagation delays.

Timing specifications are usually given at the device (i.e., package pin) level. Thus, the inputs to the constraint description typically are those of the subcircuit description of the device, after any necessary buffering. CONSTRAINT devices can be used in conjunction with any

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combination of digital primitives, including gates, logic expressions, and pin-to-pin delay primitives.

Device format

Arguments and Options

BOOLEAN

marks the beginning of a section containing one or more <boolean assignments>, of the form:

```
<boolean variable> = { <boolean expression> }
```

BOOLEAN sections can appear in any order within the CONSTRAINT primitive.

The syntax of the <boolean expression> is the same
as that defined in the PINDLY primitive reference, having the
exception that transition functions have no meaning within
the CONSTRAINT primitive.

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SETUP_HOLD:

Marks the beginning of a setup/hold constraint specification, which has the following format:

```
+ SETUP_HOLD:
+ CLOCK <assertion edge> = <input node>
+ DATA ( <no. of data inputs> ) = <input node j> ...
<input node k>
+ [ SETUPTIME = <time value> ]
+ [ HOLDTIME = <time value> ]
+ [ RELEASETIME = <time value> ]
+ [ WHEN {<boolean expression>} ]
+ [ MESSAGE = "<additional message text>" ]
+ [ ERRORLIMIT = <value> ]
+ [ AFFECTS ALL | AFFECTS NONE |
+ AFFECTS (#OUTPUTS) = <output-node-list> ]
```

Note: One or more sections can be specified in any order. Note that AFFECTS clauses are only allowed in PINDLY primitives.

CLOCK defines the node to be used as the reference for setup/hold/release specification. <assertion edge> is one of LH or HL, and specifies which edge of the CLOCK node the setup/hold time is measured against. The CLOCK node must be specified.

DATA defines one or more nodes to be the nodes whose setup/ hold time is being measured. At least one DATA node must be specified.

SETUPTIME defines the minimum time that all DATA nodes must be stable prior to the <code><assertion edge></code> of the clock. The <code><time value></code> must be a nonnegative constant or expression, expressed in seconds. Some devices have different setup time requirements which depend on whether the data is a low or a high at the time of the clock change. In this case, one or both of the following can be used:

```
SETUPTIME_LO = <time value>
SETUPTIME HI = <time value>
```

instead of SETUPTIME, which defines both low- and high-level specifications. If one or both SETUPTIME_xx specifications is zero, the simulator does not perform a setup check for that data level.

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HOLDTIME defines the minimum time that all DATA nodes must be stable after the <code><assertion</code> <code>edge></code> of the clock. The <code><time</code> <code>value></code> must be a nonnegative constant or expression, expressed in seconds. Some devices have different hold time requirements which depend on whether the data is a low or a high at the time of the clock change. In this case, one or both of the following can be used:

```
HOLDTIME_LO = <time value>
HOLDTIME_HI = <time value>
```

instead of HOLDTIME, which defines both low- and high-level specifications. If one or both HOLDTIME_xx specifications is zero, the simulator does not perform a hold check for that data level.

RELEASETIME specifications cause the simulator to perform a special-purpose setup check. In a data sheet, release time (also called recovery time) specifications refer to the minimum time a signal (such as CLEAR) can go inactive before the active CLOCK edge. In other words, release times refer to the position of a specific data edge in relation to the clock edge. For this reason, one or both of the following can be used:

```
RELEASETIME_LH = <time value>
RELEASETIME_HL = <time value>
```

instead of RELEASETIME, which defines both LH- and HL-edge specifications. The <time value> must be a nonnegative constant or expression, expressed in seconds.

The difference between the release-time checker and the setup-time checker is that simultaneous CLOCK/DATA changes are never allowed in the release-time check. That is, a nonzero hold time is assumed, even though the HOLDTIME is not specified. This feature allows the data sheet values to be specified for release-times directly in a model. For this reason, release times are usually given alone, and not in conjunction with SETUPTIME or HOLDTIME specifications.

Simulation behavior: CLOCK

The sequence of setup/hold/release checks begins when the CLOCK node undergoes the specified LH or HL transition. At that time, the WHEN expression is evaluated. If the result is TRUE, all checks using nonzero specifications are performed for during this clock cycle. If the result is FALSE, then no setup, hold, or release checks are performed. The WHEN expression is used in device models to block the reporting of violations when the device is not listening to the DATA inputs, such as during a clearing function.

Digital devices

The simulator performs setup-time checks when the CLOCK node undergoes an <assertion edge>. If the HOLDTIME specification is zero, simultaneous CLOCK/DATA transitions are allowed, however the previous value of DATA is still checked for setup-time. If the HOLDTIME is not zero, simultaneous CLOCK/DATA transitions are reported as a HOLDTIME violation.

The simulator performs hold-time checks on any DATA node that changes after the <assertion edge> on the CLOCK node. If the SETUPTIME is zero, simultaneous CLOCK/DATA changes are allowed, and the next transition on DATA which occurs before the non-asserting clock edge is checked for a hold-time violation.

The simulator performs release-time checks when the CLOCK node undergoes an <assertion edge>. Simultaneous CLOCK/DATA transitions are not allowed, and is flagged as a violation.

If either the CLOCK or DATA node is unknown (X) at the time of a check, no violation is reported for that node. This reduces the number of unnecessary warning messages: an X being clocked into a device is usually a symptom of another problem which has already been reported.

The sequence ends when the CLOCK node undergoes the other (non-asserting) edge. At this time, any violations which occurred during that clock cycle are reported. (This makes it possible for violations to appear out of time-order in the .out file.)

WIDTH: Marks the beginning of a minimum pulse-width constraint specification, which has the following format:

```
+ WIDTH:
+ NODE = <input node>
+ [ MIN_HI = <time value> ]
+ [ MIN_LO = <time value> ]
+ [ WHEN {<boolean expression>} ]
+ [ MESSAGE = "<additional message text>" ]
+ [ ERRORLIMIT = <value> ]
+ [ AFFECTS_ALL | AFFECTS_NONE |
+ AFFECTS (#OUTPUTS) = <output-node-list> ]
```

Note: One or more sections can be specified in any order. Note that AFFECTS clauses are only allowed in the PINDLY primitive.

NODE defines the input node whose pulse width is to be checked.

MIN_HI specifies the minimum time that the <input node> can remain at a high (1) logic level. The <time value> must be a nonnegative constant or expression, expressed in seconds. If not specified, MIN_HI defaults to 0, meaning that any width HI pulse is allowed.

MIN_LO likewise specifies the minimum time that the <input node> can remain at a low (0) logic level. The <time value> must be a nonnegative constant or expression, expressed

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in seconds. If not specified, MIN_LO defaults to 0, meaning that any width LO pulse is allowed.

At least one instance of MIN_HI or MIN_LO must appear within a WIDTH specification.

FREQ: marks the beginning of a frequency constraint specification, which has the following format:

```
+ FREQ:
+ NODE = <input node>
+ [ MINFREQ = <frequency value> ]
+ [ MAXFREQ = <frequency value>]
+ [ WHEN { <boolean expression> }]
+ [ MESSAGE "<additional message text>" ]
+ [ ERRORLIMIT = <value> ]
+ [ AFFECTS ALL | AFFECTS NONE |
+ AFFECTS (#OUTPUTS) = <output-node-list> ]
```

Note: One or more sections can be specified in any order. Note that AFFECTS clauses are only allowed in the PINDLY primitive.

NODE defines the input node whose frequency is to be checked.

MINFREQ specifies the minimum frequency allowed on <input node>. The <frequency value> must be a nonnegative floating point constant or expression, expressed in hertz.

MAXFREQ specifies the maximum frequency allowed on <input node>. The <frequency value> must be a nonnegative floating point constant or expression, expressed in hertz.

At least one of MINFREQ or MAXFREQ must be specified within a FREQ specification.

Simulation Behavior: FREQ

When performing a MINFREQ check, the simulator reports a violation whenever the duration of a period on the <input node> is greater than 1/<frequency value>. Likewise, when performing a MAXFREQ check, it reports a violation whenever any period is less than 1/<frequency value>. To avoid large numbers of violations, the simulator does not report subsequent violations until after a valid cycle occurs.

Note that the use of maximum FREQ specifications provides a slightly different functionality from that achieved by use of minimum pulse-width checks: in the FREQ specification case, the duty-cycle characteristic of the signal is not measured or constrained in any way, whereas the pulse-width check effectively defines the allowable duty-cycle.

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Some clocked state-storage device specifications include information about maximum clock frequency, but omit duty-cycle information.

GENERAL: Marks the beginning of a general condition test. GENERAL constraints have the following form:

```
+ GENERAL:
+ WHEN { <boolean expression> }
+ MESSAGE = "<message text>"
+ [ ERRORLIMIT = <value> ]
+ [ AFFECTS_ALL | AFFECTS_NONE |
+ AFFECTS (#OUTPUTS) = <output-node-list> ]
```

Note: One or more sections can be specified in any order. Note that AFFECTS clauses are only allowed in the PINDLY primitive. The default for the GENERAL constraint is AFFECTS_NONE.

WHEN is used to define a boolean expression, which can describe arbitrary signal relationships that represent the error or condition of interest.

MESSAGE defines the message to be reported by the simulation whenever the WHEN expression evaluates TRUE. The < message text > must be a text constant (enclosed by double quotes "") or a text expression.

Note: The $<boolean\ expression>$ is evaluated whenever the CONSTRAINT primitive is evaluated, that is, whenever any of its inputs undergo a transition. If the result is TRUE, the simulator produces a header containing the time of the occurrence, followed by the $<message\ text>$.

General notes

Any or all of the constraint specifications (SETUP_HOLD, WIDTH, FREQ, GENERAL) can appear, in any order, within a CONSTRAINT primitive. Further, more than one constraints of the same type can appear (such as two WIDTH specifications). Each of the constraint specifications is evaluated whenever any inputs to the CONSTRAINT primitive instance change.

All constraint specifications can optionally include a WHEN statement, which is interpreted as "only perform the check when result of $<boolean\ expression> == TRUE$." The WHEN statement is required in the GENERAL constraint.

Each constraint type (SETUP_HOLD, WIDTH, FREQ, and GENERAL) has an associated built-in message. In addition, each instance can include a MESSAGE specification, which takes a text constant (enclosed in double quotes "") or text expression. The <additional message text> is appended to the end of the internally-generated, type-specific message which is output whenever a violation occurs. The MESSAGE clause is required for the GENERAL constraint device.

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All of the constraint specifications can accept an optional ERRORLIMIT specification. The <value> must be a nonnegative constant or expression. The default <value> is obtained from the value of the DIGERRDEFAULT (set using the .OPTIONS command), which defaults to 20. A value of zero is interpreted as infinity, i.e., no limit. When more than <value> violations of the associated constraint have occurred, no further message output is generated for that constraint checker; other checkers within the CONSTRAINT primitive that have not exceeded their own ERRORLIMITs continue to operate.

During simulation, if the total number of digital violations reported exceeds the value given by DIGERRLIMIT (set using the <u>.OPTIONS (analysis options)</u> on page 71 command), then the simulation is halted. DIGERRLIMIT defaults to infinity.

This CONSTRAINT primitive example below was derived from the 74LS160A device in the model library. It demonstrates how all of the timing checks can be performed by a single primitive.

```
ULS160ACON CONSTRAINT (10) DPWR DGND
+ CLK ENP ENT CLRBAR LOADBAR A B C D EN
+ IO LS
+ FREQ:
  NODE = CLK
  MAXFREQ = 25MEG
+ WIDTH:
  NODE = CLK
  MIN LO = 25NS
  MIN^-HI = 25NS
+ WIDTH:
   NODE = CLRBAR
   MIN LO = 20NS
+ SETUP HOLD:
  DAT\overline{A}(1) = LOADBAR
  CLOCK LH = CLK
  SETUPTIME = 20NS
  HOLDTIME = 3NS
  WHEN = { CLRBAR!='0 }
+ SETUP HOLD:
  DAT\overline{A}(2) = ENP ENT
   CLOCK LH = CLK
   SETUPTIME = 20NS
  HOLDTIME = 3NS
  WHEN = { CLRBAR!='0 & (LOADBAR!='0 ^ CHANGED(LOADBAR,0))
     & CHANGED (EN, 20NS) }
+ SETUP HOLD:
  DAT\overline{A}(4) = A B C D
   CLOCK LH = CLK
    SETUPTIME = 20NS
   HOLDTIME = 3NS
   WHEN = { CLRBAR!='0 & (LOADBAR!='1 ^ CHANGED(LOADBAR,0)) }
+ SETUP HOLD:
 DAT\overline{A}(1) = CLRBAR
  CLOCK LH = CLK
 RELEASETIME LH = 25NS
```

Digital devices

Stimulus devices

Stimulus devices apply digital waveforms to a node. Their purpose is to provide the input to a digital circuit or a digital portion of a mixed circuit. They play the same role in the digital simulator that the independent voltage and current sources (V and I devices) do in the analog simulator.

There are two types of stimulus devices: the stimulus generator (STIM), which uses a simple command to generate a wide variety of waveforms; and the file stimulus (FSTIM), which obtains the waveforms from an external file.

Unlike digital primitives, stimulus devices do not have a Timing Model. This is similar to the analog V and I devices: the timing characteristics are described by the device itself, not in a separate model.

Digital devices

Stimulus generator

Arguments and options

<width>

Specifies the number of signals (nodes) output by the stimulus generator.

```
<format array>
```

Specifies the format of < value> s used in defining the stimulus. < format array> is a sequence of digits which specifies the number of signals (nodes) that the corresponding digit in a < value> represents. Each digit of < value> is assumed to be in base 2 < m> where < m> is the corresponding digit in < format array>. Each < value> must have the same number of digits as < format array>. The sum of the digits in < format array> must be < width>, and each digit must be either a 1, 3, or 4 (that is, binary, octal, or hexadecimal).

```
<digital power node> <digital ground node>
These nodes are used by the interface devices which connect analog nodes to digital nodes or vice versa. Refer to your PSpice User Guide for more information.
```

```
<node>*
```

One or more node names which are output by the stimulus generator. The number of nodes specified must be the same as < width>.

```
<I/O model name>
```

The name of an I/O model, which describes the driving characteristics of the stimulus generator. I/O models also contain the names of up to four DtoA interface subcircuits, which are automatically called by the simulator to handle interface nodes. In most cases, the I/O model named IO_STM can be used from the "dig_io.lib" library file. Refer to your *PSpice User Guide* for a more detailed description of I/O models.

Digital devices

STIMULUS

An optional parameter for referencing a stimulus definition.

IO_LEVELAn optional device parameter which selects one of the four DtoA interface subcircuits from the I/O model. The simulator calls the selected subcircuit automatically in the event a <node> connects to an analog device. If not specified, IO_LEVEL defaults to 0. Valid values are:

```
0 = the current value of .OPTIONS DIGIOLVL (default=1)
```

- 1 = DtoA1
- 2 = DtoA2
- 3 = DtoA3
- 4 = DtoA4

Refer to your *PSpice User Guide* for more information.

TIMESTEP

Number of seconds per clock cycle, or step. Transition times that are specified in clock cycles (using the C suffix) are multiplied by this amount to determine the actual time of the transition. (See <time> below.) If TIMESTEP is not specified, the default is zero seconds. TIMESTEP has no effect on <time> values which are specified in seconds (using the S suffix).

```
<command>*
```

A description of the stimuli to be generated, using one or more of the following.

```
<time> <value>
LABEL=<label name>
<time> GOTO <label name> <n> TIMES
<time> GOTO <label name> UNTIL GT <value>
<time> GOTO <label name> UNTIL GE <value>
<time> GOTO <label name> UNTIL LT <value>
<time> GOTO <label name> UNTIL LT <value>
<time> GOTO <label name> UNTIL LE <value>
<time> INCR BY <value>
<time> DECR BY <value>
REPEAT FOREVER
REPEAT <n> TIMES
ENDREPEAT
FILE=<file name>
```

<time>

Specifies the time for the new <value>, GOTO, or INCR/DECR command to occur.

Digital devices

Time units

Time values can be stated in seconds or in clock cycles (see TIMESTEP above). To specify a time value in clock cycles, use the C suffix. Otherwise, the units default to seconds.

Absolute/relative times

Times can be absolute, such as 45ns or 10c, or relative to the previous time. To specify a relative time, prefix the time using a "+" such as +5ns or +2c.

<value> is the value for each node (0, 1, R, F, X, or Z). <value> is interpreted using the
<format array>.

<label name> is the name used in GOTO statements. GOTO <label name> jumps to
the next non-label statement after the <LABEL = <label name>> statement.

<n> is the number of times to repeat a GOTO loop. Use a -1 to specify forever.

Keep the following in mind when using the stimulus command:

Transitions using absolute times within a GOTO loop are converted to relative times based on the time of the previous command and the current step size.

- GOTO < label name > must specify a label that has been defined in a previous LABEL = < label name > statement.
- Times must be in strictly ascending order, except that the transition after a GOTO can be at the same time as the GOTO.

A simpler syntax for constructing counted loops in digital stimulus is to use the REPEAT/ENDREPEAT construct. Specify the count value, for example:

```
REPEAT 3 TIMES
+ 5ns 0
+ 5ns 1
ENDREPEAT
```

For an infinite loop, use REPEAT FOREVER (equivalent to REPEAT -1 TIMES). All times within REPEAT loops are interpreted as relative to the start of the loop.

Transition (i.e., time-value pairs) information can be placed in a FILE and accessed one or more times from the STIM device by using the FILE= statement. The syntax for the file contents is identical to what can appear directly in the body of the STIM device <command> section.

Stimulus generator examples

One

The first example creates a simple reset signal, which could be used to set or clear a flip-flop at the beginning of a simulation. The node, named Reset, is set to a level zero at time zero nanoseconds, and to a Z (high impedance) at 20 ns.

This is useful when the Reset node is being driven by another device which does not reset the flip-flop at time zero. By using the library I/O model named IO_STM, the stimulus generator drives with a high strength, and thus overpowers the other output. By outputting a Z for the duration of the simulation, the stimulus generator cannot affect the node.

Two

The second example is a simple example of a clock stimulus which pulses every 5 nanoseconds. It has one output node, OUT1, and the format is represented in binary notation. This example specifies the time as relative to the previous step. IO_STM is an I/O model for stimulus devices and is available in the ${\tt dig_io.lib}$ library file which comes with the digital simulation feature.

```
UEx2 STIM( 1, 1 ) $G_DPWR $G_DGND Out1 IO_STM + 0s 0; At time=0 initialize Out1; to zero. + REPEAT FOREVER; repeats loop indefinitely + +5ns 1 ; 5ns later Out1 is set to 1 + +5ns 0 ; 5ns later Out1 is set to 0 + ENDREPEAT
```

Digital devices

Three

The third example illustrates the use of the timestep; a cycle is equal to one nanosecond:

```
UEx3 STIM( 2, 11 ) $G DPWR $G DGND 1 2
+ IO STM TIMESTEP=1ns
+ 0c 00
                         ;At time=0ns, both nodes are set to 0.
+ REPEAT 4 TIMES
                         ;What's in the loop is repeated
                         ;4 times
+ +1c 01
                         ;1ns later node 1 is set to 0
                         ; and node 2 is set to 1.
+ + 2c 11
                         ;2ns later both nodes set to 1.
+ ENDREPEAT
                                                      10ns
                         4ns
               2ns
                                              8ns
                                    6ns
                              Time
```

Four

The fourth example has four output nodes. The values of the nodes at each transition are in hexadecimal notation. This is because the <format array> is set to 4, meaning <value> is one digit representing the value of four nodes. Both the absolute and relative timing methods are used, but, at the start of execution, the simulation converts all absolute values to relative values based on the time of the command and the current step size. The timestep is equal to one nanosecond, setting the cycle to one nanosecond:

```
UEx4 STIM(4,4) $G DPWR $G DGND IN1 IN2 IN3 IN4
+ IO STM TIMESTEP=1ns
+ 0s^{-}0
                     ; At time=0 seconds, all nodes are set to 0.
+ LABEL=STARTLOOP
+ 10C 1
                     ; At time=10NS, IN1, IN2, & IN3 are set to 0 and IN4
                     ; is set to 1.
  +5NS 0
                     ; 5NS later, all nodes are set to 0.
   20NS A
                     ; At time=20NS, nodes IN1 & IN3 are set to 1 and
                     ;nodes IN2 &
                     ; IN4 are to 0.
+ +5NS 0
                     ; 5NS later, all nodes are set to 0.
+ 30C GOTO STARTLOOP 1 TIMES ; At time=30NS, execute the
                     ; first statement of the loop without
                     ; a further delay. "1 TIMES" causes the logic to loop
                      ; 1 time, actually executing the loop twice.
                      ; After the logic falls through the loop
+ +10C 1
                     ; the second
                     ; time and then waiting 10 additional cycles
                       (or 10 nanoseconds),
                 ; IN1, IN2, & IN3 are set to 0 and IN4 is set to 1.
```

Example four produces the following transitions. Note how all of the time values are calculated relative to the previous step:

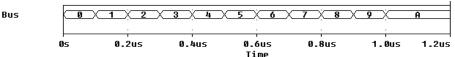
Digital devices

```
TIME
              VALUE
    0.00E+00 = 0000
    1.00E-08 = 0001
                               ; STARTLOOP
    1.50E-08 = 0000
    2.00E-08 = 1010
                               ; 1010 in hex=A
    2.50E-08 = 0000
    3.00E-08 = 0001
                               ; The GOTO STARTLOOP 1 TIMES causes the
                               ; first statement
                               ; after the STARTLOOP label to be executed
                               ; immediately.
    3.50E-08 = 0000
    4.00E-08 = 1010
    4.50E-08 = 0000
                               ; At time 5.00E-08 we checked the
                               ; GOTO STARTLOOP
                               ; 1 TIMES statement, but did not execute it
                               ; since it was already completed one time.
    6.00E-08 = 0001
                               ;At 10C=1ns * 10=10ns later we
                               ; execute the
                               ; last statement.
In
IN1
               X 1 X 0 X A
T N2
I N4
                      20ns
                                      40ns
                                                      6 Ons
                                                           70ns
                                  Time
```

Five

The fifth example illustrates the use of the INCR BY command used to increment the value of the 16 bit bus:

```
UEx5 STIM ( 16, 4444 ) $G DPWR $G DGND 
+ 16 15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 
+ IO_STM TIMESTEP = 10ns 
+ 0s 0000 ; At time=0 seconds, all nodes are set to 0. 
+ LABEL=STARTLOOP 
+ 10c INCR BY 0001 ; At 100ns, increment bus by 1. 
+ 20c GOTO STARTLOOP UNTIL GE 000A; If the bus value 
; is less 
; than 10, branch back to STARTLOOP and 
; execute the line following the 
; label without a further delay.
```

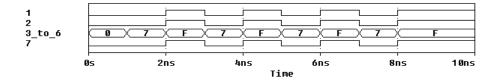


Digital devices

Six

The sixth example has seven output nodes: 1, 2, 3, 4, 5, 6, and 7. The <format array> specifies the notation (1=binary, 3=octal, or 4=hex) used to define the output of those seven nodes. The first two output signals are defined in binary, the next four are in hexadecimal, and the last one is in binary.

In this example, at time equal to one nanosecond, the value of 0070 creates the bit pattern 0001110 on the output nodes. The first two zeros correspond to outputs one and two, the 0111 (7 in hex) corresponds to output signals 3 through 6, and the last zero is the value of output signal 7.



Digital devices

File stimulus

The file stimulus device, FSTIM, allows the digital stimuli to be obtained from a file. This is often useful if the number of stimuli is very large, or if the inputs to one simulation come from the output of another simulation (or even from another simulator). To make the discussion of the FSTIM device more meaningful, the stimulus file format is discussed first.

Stimulus file format

The stimulus file has a simple format which allows outputs from other simulators, or the simulation output file, to be used with little modification. The file consists of two sections: the header, which contains a list of signal names, and the transitions, which is one or more lines containing the transition time and columns of values. The header and transitions must be separated by at least one blank line. Below is a simple example of the stimulus file format.

```
* Header, containing signal names (standard comments are
* allowed)
Clock, Reset, In1, In2; four signal names

* Beginning of the transitions - note the blank line
0 0000 ; values are in binary
10ns 1100
20ns 0101
30ns 1110
40ns 0111
```

Header format

```
[TIMESCALE=<value>]
<signame 1>...<signame n>...
OCT(<signame bit 3> ... <signame lsb>) ...
HEX(<signame bit 4> ... <signame lsb>) ...
```

The header consists of the list of signal names and an optional TIMESCALE value. The signal names can be separated by commas, spaces, or tabs. The list can span several lines, but must **not** include the + continuation character. The signal names listed correspond to the columns of values in the order that they are listed. Up to 255 signals can be listed in the header, however a maximum of 300 characters are allowed per line.

The OCT and HEX radix functions allows three or four signals to be grouped, respectively, into a single octal or hexadecimal digit in the columns of values. Note that exactly three signals must be included inside the parentheses in the OCT function, and that exactly four signals must be included in the HEX function. Signal names listed without the radix functions default to binary values.

The following example shows the use of the HEX radix function.

```
Clock Reset In1 In2
HEX(Addr7 Addr6 Addr5 Addr4) HEX(Addr3 Addr2 Addr1 Addr0)
```

Digital devices

```
ReadWrite

0 0000 00 0 ; spaces can be used to group values
10n 1100 4E 0
20n 0101 4E 1
30n 1110 4E 1
40n 0111 FF 0
```

In this example, there are four binary signals, followed by two occurrences of the HEX radix function, followed by a single binary signal. In the list of transitions following the header, there are seven values which correspond, in order, to the list of signals.

The optional TIMESCALE assignment is used to scale the time values in the transitions. The TIMESCALE assignment must be on a separate line. If unspecified, TIMESCALE defaults to 1.0. See <time> below for more information on the use of TIMESCALE.

Transition format

<time> <value>*

Following the first blank line after the header, the simulator looks for one or more lines containing transitions. Transitions consist of a time value, followed by one or more values corresponding to the signal names in the header. The <tine> and list of <values> must be separated by at least one space or tab.

<time>

Transition times are always stated in seconds. Times can be absolute, such as 45ns, 1.2e-8, or 10; or relative to the previous time. To specify relative time, prefix the time using a +, such as +5ns or +1e-9.

Time values are always scaled by the value of TIMESCALE. This is useful if the time values in the file are expressed as whole numbers, but the actual units are, for example, 10ns. An example showing the use of TIMESCALE is given below.

<value>*

Each value corresponds to a single binary signal (the default) or the entire group of signals inside the OCT or HEX radix functions. The number of values listed must equal the total number of binary signals and radix functions which are specified in the header. Valid

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<values> are:

| | Binary | ОСТ | HEX |
|---------------|--------|-----|-----|
| Logic/Numeric | 0,1 | 0-7 | 0-F |
| Unknown | Χ | Χ | Χ |
| Hi-impedance | Z | Z | Z |
| Rising | R | R | |
| Falling | F | F | |
| | | | |

When the <value> in a HEX or OCT column is a number, the simulator converts the number to binary and assigns the appropriate logic value of each bit (either zero or one) to the signals inside the radix function. The bits are assigned msb to lsb. When the <value> is X, Z, R, or F, all signals in the radix function take on that value. Note that there can be no falling value in a HEX column because F is used as a numeric value.

The following example shows the use of TIMESCALE and relative <time> values.

```
TIMESCALE=10ns ; must appear on separate line Clock, Reset, In1, In2
HEX(Addr7 Addr6 Addr5 Addr4) HEX(Addr3 Addr2 Addr1 Addr0)
ReadWrite

0 0000 00 0
1 110R 4E 0 ; transition occurs at 10ns
2 0101 4E 1 ; transition occurs at 50ns
7 011F C3 0 ; transition occurs at 70ns
8 11X0 C3 1
```

File stimulus device

The file stimulus device, FSTIM, is used to access one or more signals inside a stimulus file. More than one FSTIM device can access the same file. An FSTIM device can even refer to

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the same signal as another FSTIM device. Any number of stimulus files can be used during a simulation.

```
Device
                  U<name> FSTIM(<# outputs>)
                  + <digital power node> <digital ground node>
format
                  + <node>*
                  + <I/O model name>
                  + FILE=<stimulus file name>
                  + [IO LEVEL=<interface subckt select value>]
                  + [SIGNAMES=<stimulus file signal name>*]
Examples
                  U1 FSTIM(1) $G DPWR $G DGND
                   + IN1 IO STM FILE=DIG1.STM
                  U2 FSTIM(4) $G DPWR $G DGND
                   + ADDR3 ADDR2 ADDR1 ADDR0
                  + IO STM
                   + FI\overline{L}E = DIG 2.STM
                   + SIGNAMES = AD3 AD2 AD1 AD0
                  U3 FSTIM(4) $G DPWR $G DGND
                   + CLK PRE J K
                   + IO STM
                   + FI\overline{L}E = FLIPFLOP.STM
                   + SIGNAMES = CLOCK PRESET
```

Arguments and options

```
<# outputs>
```

Specifies the number of nodes driven by this device.

```
<digital power node> <digital ground node>
```

These nodes are used by the interface devices which connect analog nodes to digital nodes or vice versa. Refer to your *PSpice User Guide* for more information.

```
<node>*
```

One or more node names which are output by the file stimulus. The number of nodes specified must be the same as <# outputs>.

```
<I/O model name>
```

The name of an I/O model, which describes the driving characteristics of the stimulus device. I/O models also contain the names of up to four DtoA interface subcircuits, which are automatically called by the simulator to handle interface nodes. In most cases, the I/O model named IO_STM can be used from the library dig_io.lib. Refer to your *PSpice User Guide* for a more detailed description of I/O models.

Digital devices

FILE

The name of the stimulus file to be accessed by this device. The <stimulus file name> can be specified as a quoted string or as a text expression; see .TEXT (text parameter) on page 118. Note that the FILE device parameter is not optional.

IO LEVEL

An optional device parameter which selects one of the four AtoD or DtoA interface subcircuits from the device's I/O model. The simulator calls the selected subcircuit automatically in the event a node connecting to the primitive also connects to an analog device. If not specified, IO LEVEL defaults to 0. Valid values are:

- 0 = the current value of .OPTIONS DIGIOLVL (default=1)
 1 = AtoD1/DtoA1
 2 = AtoD2/DtoA2
 3 = AtoD3/DtoA3
 4 = AtoD4/DtoA4
- Refer to your *PSpice User Guide* for more information.

SIGNAMES

Used to specify the names of the signals inside the stimulus file which are to be referenced by the FSTIM device. The signal names correspond, in order, to the $<\!nodes>$ connected to the device. If any or all SIGNAMES are unspecified, The simulator looks in the stimulus file for the names of the $<\!nodes>$ given. Because the number of signal names can vary, the SIGNAMES parameter must be specified last. SIGNAMES can be a list of names or text expressions (see .TEXT), or a mixture of the two.

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Comments

The first example references a file named dig1.stm. This file must have a signal named IN1.

The second example references dig2.stm. This file would have to have signals named AD3 through AD0. These are mapped, in order, to the nodes ADDR3 through ADDR0, which are driven by this device.

In the third example, the FSTIM device references the file flipflop.stm.

The contents of flipflop.stm are shown below:

```
J K PRESET CLEAR CLOCK
0 0 0 010
10ns 0 0 111
.
```

In this example, the first two nodes, CLK and PRE, reference the signals named CLOCK and PRESET in the stimulus file. The last two nodes, J and K, directly reference the signals named J and K in the file, and therefore do not need to be listed in SIGNAMES. Note that the order of the SIGNAMES on the FSTIM device does not need to match the order of the names listed in the header of the stimulus file. It is not required that every signal in the file be referenced by an FSTIM device. In the example above, the signal named CLEAR is not referenced. One, several, or all signals in a stimulus file can be referenced by one or more FSTIM devices.

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Input/output model

Each digital device in the circuit must reference an I/O model. The I/O model describes the device's loading and driving characteristics. It also contains the names of up to four AtoD and DtoA subcircuits that the simulator calls to handle interface nodes.

I/O models are common to device families. For example, of the digital devices in the model library, there are only four I/O Models for the entire 74LS family: IO_LS, for standard inputs and outputs; IO_LS_OC, for standard inputs and open-collector outputs; IO_LS_ST, for schmitt trigger inputs and standard outputs; and IO_LS_OC_ST, for schmitt trigger inputs and open-collector outputs. This is in contrast to timing models, which are unique to each device in the library.

Model form

.MODEL <1/0 model name> UIO [model parameters]

| Model Parameter | Description | Units | Default |
|--------------------|---|-------|-------------|
| AtoD1 | Name of level 1 AtoD interface subcircuit | | AtoDDefault |
| AtoD2 | Name of level 2 AtoD interface subcircuit | | AtoDDefault |
| AtoD3 | Name of level 3 AtoD interface subcircuit | | AtoDDefault |
| AtoD4 | Name of level 4 AtoD interface subcircuit | | AtoDDefault |
| DIGPOWER | Name of power supply subcircuit | | DIGIFPWR |
| DRVH | Output high level resistance | ohm | 50 |
| DRVL | Output low level resistance | ohm | 50 |
| DRVZ | Output Z-state leakage resistance | ohm | 250 Kohm |
| DtoA1 | Name of level 1 DtoA interface subcircuit | | DtoADefault |
| DtoA2 | Name of level 2 DtoA interface subcircuit | | DtoADefault |
| DtoA3 | Name of level 3 DtoA interface subcircuit | | DtoADefault |
| DtoA4 | Name of level 4 DtoA interface subcircuit | | DtoADefault |
| INLD | Input load capacitance | farad | 0 |
| INR | Input leakage resistance | ohm | 30 Kohm |

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| Model | Description | Unite | Default |
|-----------|--|--------|---------------------------------|
| Parameter | Description | Ullits | Delault |
| OUTLD | Output load capacitance | farad | 0 |
| TPWRT | Pulse width rejection threshold | sec | same as propagation delay |
| TSTOREMN | Minimum storage time for net to be simulated as a charge | sec | 1.0 msec |
| TSWHL1 | Switching time high to low for DtoA1 | sec | 0 |
| TSWHL2 | Switching time high to low for DtoA2 | sec | 0 |
| TSWHL3 | Switching time high to low for DtoA3 | sec | 0 |
| TSWHL4 | Switching time high to low for DtoA4 | sec | 0 |
| TSWLH1 | Switching time low to high for DtoA1 | sec | 0 |
| TSWLH2 | Switching time low to high for DtoA2 | sec | 0 |
| TSWLH3 | Switching time low to high for DtoA3 | sec | 0 |
| TSWLH4 | Switching time low to high for DtoA4 | sec | 0 |

INLD and OUTLD are used in the calculation of loading capacitance, which factors into the propagation delay. Refer to your *PSpice User Guide* for more information.

DRVH and DRVL are used to determine the strength of the output. Refer to your *PSpice User Guide* for more information.

DRVZ, INR, and TSTOREMN are used to determine which nets should be simulated as charge storage nets.

AtoD1 through AtoD4 and DtoA1 through DtoA4 are used to hold the names of interface subcircuits. Note that INLD and AtoD1 through AtoD4 do not apply to stimulus generators because they have no input nodes. Refer to your *PSpice User Guide* for more information.

The switching times (TSWLHn and TSWHLn) are subtracted from a device's propagation delay on the outputs which connect to interface nodes. This compensates for the time it takes the DtoA device to change its output voltage from its current level to that of the switching threshold. By subtracting the switching time from the propagation delay, the analog signal reaches the switching threshold at the correct time (that is, at the exact time of the digital transition). The values for these model parameters should be obtained by measuring the time it takes the analog output of the DtoA (using a nominal analog load attached) to change to

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the switching threshold after its digital input changes. If the switching time is larger than the propagation delay for an output, no warning is issued, and a delay of zero is used. Note that the switching time parameters are not used when the output drives a digital node.

DIGPOWER specifies the name of the power supply subcircuit the simulator calls for when an AtoD or DtoA interface is created. The default value is DIGIFPWR, which is the power supply subcircuit used by the TTL and CMOS device libraries.

For more information on how to change the default power supplies, refer to your *PSpice User Guide*.

Digital devices

Digital/analog interface devices

The simulator provides two devices for converting digital logic levels to analog voltages or vice versa. These devices are at the heart of the interface subcircuits found in dig_io.lib. These devices also provide the Digital Files interface for interfacing using external logic simulators.

Digital input (N device)

The digital input device is used to translate logic levels (typically 1s, 0s, Xs, Zs, Rs, and Fs) into representative voltage levels using series resistances. These voltages and resistances model the output stage of a logic device (like a 74LS04) and hence form a digital input to the analog circuit. The logic level information can come from two places: the digital simulator or a file. (The file can be created by hand, or can be an output file from an external logic simulator.)

The general form for a digital input device, and some of the model parameters, are different for devices driven from a file and for those driven by the digital simulation feature. The digital simulation inserts digital input devices automatically when a digital device's output is connected to an analog component. The automatic insertion of digital input devices is discussed in your *PSpice User Guide*. Examples of the devices that are inserted can be found in the dig_io.lib library file.

Digital devices

| General form | for digital simulation | |
|--------------|---|--|
| | <pre>N<name> <interface node=""> <low level="" node=""> <high level="" node=""> + <model name=""> + DGTLNET = <digital name="" net=""> + <digital i="" model="" name="" o=""> + [IS = initial state] for digital files</digital></digital></model></high></low></interface></name></pre> | |
| | <pre>N<name> <interface node=""> <low level="" node=""> <high level="" node=""> + <model name=""> + [SIGNAME = <digital name="" signal="">] + [IS = initial state]</digital></model></high></low></interface></name></pre> | |
| Examples | N1 ANALOG DIGITAL_GND DIGITAL_PWR DIN74 + DGTLNET=DIGITAL_NODE IO_STD NRESET 7 15 16 FROM_TTL N12 18 0 100 FROM_CMOS SIGNAME=VCO_GATE IS=0 | |
| Model form | .MODEL <model name=""> DINPUT [model parameters]</model> | |

Table 3-7 Digital input model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-------|---------|
| CHI | capacitance to high level node | farad | 0 |
| CLO | capacitance to low level node | farad | 0 |
| FORMAT | digital input file format (digital files only) | | 1 |
| SONAME | state 0 character abbreviation | | |
| S0TSW | state 0 switching time | sec | |
| S0RLO | state 0 resistance to low level node | ohm | |
| S0RHI | state 0 resistance to high level node | ohm | |
| S1NAME | state 1 character abbreviation | | |
| S1TSW | state 1 switching time | sec | |
| S1RLO | state 1 resistance to low level node | ohm | |
| S1RHI | state 1 resistance to high level node | ohm | |
| S2NAME | state 2 character abbreviation | | |

Digital devices

Table 3-7 Digital input model parameters

| Model parameters ¹ | Description | Units | Default |
|-------------------------------|---|-------|---------|
| S2TSW | state 2 switching time | sec | |
| S2RLO | state 2 resistance to low level node | ohm | |
| S2RHI | state 2 resistance to high level node | ohm | |
| | | | |
| | | | |
| | | | |
| S19NAME | state 19 character abbreviation | | |
| S19TSW | state 19 switching time | sec | |
| S19RLO | state 19 resistance to low level node | ohm | |
| S19RHI | state 19 resistance to high level node | ohm | |
| TIMESTEP | digital input file step-size (digital files only) | sec | 1E-9 |
| | , | | |

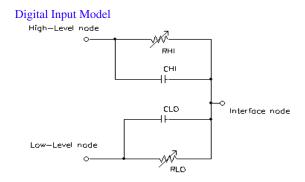
^{1.} See .MODEL (model definition) on page 57.

Note: For more information on using the digital input device to simulate mixed analog/digital systems refer to your *PSpice User Guide*.

As shown below, the digital input device is modeled as a time varying resistor from <low level node> to <interface node>, and another time varying resistor from <high level node> to <interface node>. Each of these resistors has an optional fixed value capacitor in parallel: CLO and CHI. When the state of the digital signal changes, the values of the resistors change (exponentially) from their present values to the values specified for the new state over the switching time specified by the new state. Normally the low and high level nodes would be attached to voltage sources which would correspond to

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the highest and lowest logic levels. (Using two resistors and two voltage levels, any voltage between the two levels can be created at any impedance.



For a digital simulation driven digital input, the parameters

```
DGTLNET = <digital net name> <digital I/O model name>
```

must be specified. Refer to your *PSpice User Guide* for more information on digital I/O models. The digital net must not be connected to any analog devices, otherwise the automatic analog/digital interface process disconnects the digital input device from the digital net.

Digital simulation can send states named 0, 1, X, R, F, and Z to a digital input device. The simulation stops if the digital simulation sends a state which is not modeled (does not have SnNAME, SnTSW, SnRLO, and SnRHI specified) to a digital input device.

The initial state of a digital simulation driven digital input is controlled by the bias point solution of the analog/digital system. It is sometimes necessary to override this solution (for example, an oscillator which contains both analog and digital parts). The optional parameter

```
IS = <initial state name>
```

can be used to do this. The digital input remains in the initial state until the digital simulation value changes from its TIME=0 value.

The model parameters FILE, FORMAT, and TIMESTEP are not used by digital simulation driven digital input devices, and only the FILE parameter is used for VIEWsim A/D driven digital inputs. For file driven digital inputs the FILE parameter defines the name of the file to be read, and the FORMAT parameter defines the format of the data in that file. The TIMESTEP parameter defines the conversion between the digital simulation's integer timing tick numbers and the simulation's floating-point time values:

```
tick number · TIMESTEP = seconds
```

Note: Tick number must be an integer.

Digital devices

For a file driven or VIEWsim A/D driven digital input, the DGTLNET parameter must not be specified, but the optional parameter

```
SIGNAME = <digital signal name>
```

is used to specify the name of the digital signal in the file (or the digital net name in VIEWsim A/D). If no SIGNAME is given, then the portion of the device name after the leading N identifies the name of the digital signal.

The parameter

```
IS=<initial state name>
```

can be used as described above to override the initial (TIME=0) values from the file.

The file name DGTLPSPC is used with VIEWsim A/D to tell the simulator to get digital state values from the VIEWsim A/D interface, rather than a file.

Any number of digital input models can be specified, and both file driven and digital simulation driven digital inputs can be used in the same circuit. Different digital input models can reference the same file, or different files. If the models reference the same file, the file must be specified in the same way, or unpredictable results occur. For example, if the default drive is C:, then one model should not have FILE=C:TEST.DAT if another has FILE=TEST.DAT.

For diagnostic purposes, the state of the digital input can be viewed in Probe by specifying B(Nxxx). The value of B(Nxxx) is 0.0 if the current state is S0NAME, 1.0 if the current state is S1NAME, and so on through 19.0. B(Nxxx) cannot be specified on a .PRINT, .PLOT, or .PROBE line. (For digital simulation, the digital window of Probe provides a better way to look at the state of the digital net connected to the digital input.)

Digital devices

Digital output (O Device)

The digital output device is used to translate analog voltages into digital logic levels (typically 1, 0, X, R, or F). The conversion of a voltage into a logic level, models the input stage of a logic device (like a 74LS04) and hence forms a digital output from the analog circuit. The logic level information can go to two places: the digital simulation, or a file. (The file can simply be inspected manually, or can be used as a stimulus file for an external logic simulator.)

Table 3-8 Digital output model parameters

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-------|---------|
| CHGONLY | 0: write each timestep, 1: write upon change | | 0 |
| CLOAD | output capacitor | farad | 0 |
| FORMAT | digital input file format (digital files only) | | 1 |
| RLOAD | output resistor | ohm | 1/GMIN |
| SONAME | state 0 character abbreviation | | |
| S0VLO | state 0 low level voltage | volt | |
| S0VHI | state 0 high level voltage volt | | |
| S1NAME | state 1 character abbreviation | | |
| S1VLO | state 1 low level voltage | volt | |
| S1VHI | state 1 high level voltage | volt | |
| S2NAME | state 2 character abbreviation | | |

Digital devices

Table 3-8 Digital output model parameters, continued

| Model parameters ¹ | Description | Units | Default |
|----------------------------------|--|-------|---------|
| S2VLO | state 2 low level voltage | volt | |
| S2VHI | state 2 high level voltage | volt | |
| S19NAME | state 19 character abbreviation | | |
| S19VLO | state 19 low level voltage | volt | |
| S19VHI | state 19 high level voltage | volt | |
| SXNAME | state applied when the interface node voltage falls outside all ranges | | "?" |
| TIMESTEP | digital input file step-size | sec | 1E-9 |
| TIMESCALE | scale factor for timestep (digital files only) | | 1 |

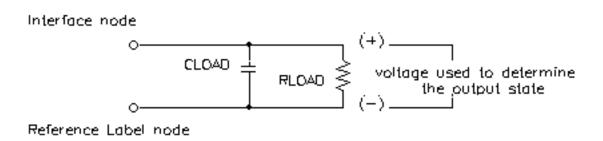
See <u>.MODEL (model definition)</u> on page 57.

The general form for a digital output device, and some of the model parameters, are different for devices that drive a file (or VIEWsim A/D) and those that drive the digital simulation feature. The digital simulation inserts digital output devices automatically when a digital device's input is connected to an analog component. The automatic insertion of digital output devices is discussed in your *PSpice User Guide*, and examples of the devices which are inserted can be found in the <code>dig_io.lib</code> library file.

Note: For more information on using the digital output device to simulate mixed analog/digital systems, refer to your *PSpice User Guide*.

As shown in <u>Figure 3-1</u> on page 462, the digital output device is modeled as a resistor and capacitor, of the values specified in the model statement, connected between <interface node> and <reference node>. At times which are integer multiples of TIMESTEP, the state of the device node is determined and written to the specified file.

Figure 3-1 Digital output model



The process of converting the input node voltage to a logic state begins by first obtaining the difference in voltage between the <interface node> and the <reference node>. The DOUTPUT model defines a voltage range, form SxVLO to SxVHI, for each state. If the input voltage is within the range defined for the current state, no state change occurs. Otherwise, the simulator searches forward through the model, starting at the current state, to find the next state whose voltage range contains the input voltage. This state then becomes the new state. When the end of the list (S19) is reached, the simulator wraps around to S0 and continues.

If the entire model has been searched and no valid voltage range has been found, the simulator generates a simulation warning message. Further if the O device is interfacing at the digital simulator, and the SXNAME parameter has not been specified in the model, the simulator uses the state whose voltage range is closed to the input voltage. Otherwise it uses SXNAME as the new state.

This circular state searching mechanism allows hysteresis to be modeled directly. The following model statement models the input thresholds of a 7400 series TTL Schmitt-trigger input. Notice that the 0.8 volt overlap between the 0 state voltage range and the 1 state voltage range.

```
.model D074 STd output (
+ s0name="0" s0vlo=1.5s0vhi=1.7
+ s1name="1" s1vlo=0.9s1vhi-7.0
+ )
```

Starting from the 0 state, a positive-going voltage must cross 1.7 volts to get out of the 0 state's voltage range. The next state which contains that voltage is 1. Once there, a negative-going voltage must go below 0.9 volts to leave the 1 state's range. Since no further states are defined, the simulator wraps around back to state 0, which contains the new voltage

For a digital output driving digital simulation, the parameters

```
DGTLNET = <digital net name> <digital I/O model name>
```

Digital devices

must be specified. Refer to your *PSpice User Guide* for more information on digital I/O models. The digital net must not be connected to any analog devices, otherwise the automatic analog/digital interface process disconnects the digital output device from the analog net.

For interfacing using digital simulation, the state names must be 0, 1, X, R, F, or Z (Z is usually not used however, since high impedance is not a voltage level). Other state names cause the simulator to stop if they occur; this includes the state? that occurs if the voltage is outside all the ranges specified.

The model parameters TIMESCALE, FILE, CHGONLY, and FORMAT are not used for digital outputs which drive digital simulation, but the TIMESTEP is used. The TIMESTEP value controls how accurately the analog simulator tries to determine the exact time at which the node voltage crosses a threshold.

To be sure that the transition time is accurately determined, the analog simulator has to evaluate the analog circuit at intervals no larger than TIMESTEP when a transition is about to occur. The default value for TIMESTEP is 1ns, or 1/DIGFREQ (a .OPTIONS (analysis options) on page 71 option) if it is larger. In many circuits, this is a much greater timing resolution than is required, and some analog simulation time can be saved by increasing the TIMESTEP value.

For digital outputs which write files, or drive VIEWsim A/D, the parameter

```
SIGNAME = <digital signal name>
```

can be used to specify the name written to the file of the digital signal (or for VIEWsim A/D, the name of the VIEWsim net). If SIGNAME is not specified, then the portion of the device name after the leading O identifies the name of the digital signal.

For digital outputs which write files, the FILE parameter defines the name of the file to be written, and the FORMAT parameter defines the format of the data written to that file.

The file name PSPCDGTL is used with VIEWsim A/D to tell the simulator to send the digital state values to the VIEWsim A/D interface, rather than a file. For VIEWsim A/D, the parameters FORMAT and CHGONLY are ignored.

The state of each device is written to the output file at times which are integer multiples of TIMESTEP. The time that is written is the integer:

```
time = TIMESCALE · TIME / TIMESTEP
```

TIMESCALE defaults to 1, but if digital simulation is using a very small timestep compared to the analog simulation timestep, it can speed up the simulation to increase the value of both TIMESTEP and TIMESCALE. This is because the simulator must take timesteps no greater than the digital TIMESTEP size when a digital output is about to change, in order to accurately determine the exact time that the state changes. The value of TIMESTEP should therefore

Digital devices

be the time resolution required at the analog-digital interface. The value of TIMESCALE is then used to adjust the output time to be in the same units as digital simulation uses.

For example, if a digital simulation using a timestep of 100 ps is being run, but the circuit has a clock rate of 1us, setting TIMESTEP to 0.1us should provide enough resolution. Setting TIMESCALE to 1000 scales the output time to be in 100 ps units.

If CHGONLY = 1, only those timesteps in which a digital output state changes are written to the file.

Any number of digital output models can be specified, and both file writing and digital simulation driving digital outputs can be used in the same circuit. Different digital output models can reference the same file, or different files. If the models reference the same file, the file must be specified in the same way, or unpredictable results occur. For example, if the default drive is C:, then one model should not have FILE=C:TEST.DAT if another has FILE=TEST.DAT.

For diagnostic purposes, the state of the digital output can be viewed in Probe by specifying B(Oxxx). The value of B(Oxxx) is 0.0 if the current state is S0NAME, 1.0 if the current state is S1NAME, and so on through 19.0. B(Oxxx) cannot be specified on a .PRINT, .PLOT, or .PROBE line. (For digital simulation, the digital window of Probe provides a better way to look at the state of the digital net connected to the digital output.)

Digital model libraries

| File | Contents |
|--------------|---|
| 7400.LIB | 7400-series TTL |
| 74AC.LIB | Advanced CMOS |
| 74ACT.LIB | TTL-compatible, Advanced CMOS |
| 74AS.LIB | Advanced Schottky TTL |
| 74F.LIB | FAST |
| 74H.LIB | High-Speed TTL |
| 74HCT.LIB | TTL-compatible, High-Speed CMOS |
| 74HC.LIB | High-Speed CMOS |
| 74L.LIB | Low-Power TTL |
| 74LS.LIB | Low-Power Schottky TTL |
| 74S.LIB | Schottky TTL |
| CD4000.LIB | CD4000 devices |
| DIG_ECL.LIB | 10 K and 100K ECL devices |
| DIG_GAL.LIB | GAL devices |
| DIG_IO.LIB | I/O models, AtoD and DtoA interface subcircuits, digital power supply subcircuits |
| DIG_MISC.LIB | pull-up/down resistors, delay line |
| DIG_PAL.LIB | PAL devices |
| DIG_PRIM.LIB | Digital primitives |
| NOM.LIB | master library: which references NOM_DIG.LIB, which references each of the above libraries. |

^{1.} Depending upon the platform being worked on, NOM.LIB references the appropriate list of libraries. For "digital only" platforms, NOM.LIB references NOM_DIG.LIB.

Digital devices

Digital PSpice Libraries

PSpice ships a set of models containing various devices such as 7400-series TTL and 4000-series CMOS. The simulation model libraries are installed at:

<installation_directory>\tools\pspice\library

The corresponding Capture symbol libraries for the simulation models are installed at: <installation_directory>\tools\capture\library\pspice

Name of these libraries indicates the name of the device family that they belong to.

For example:

The C:\Cadence\SPB_17.4\tools\capture\library\pspice\cd4000.olb library contains CMOS 4000 series parts.

If power supply nodes on CD4000 devices are not specified in the circuit, they can use the default power supply nodes G_CD4000_VDD and G_CD4000_VSS , which default to 5 volts. A new power supply can be created, and new power supply nodes can be specified to the devices in the circuit. Refer to your *PSpice User Guide* for more information on specifying your own power supplies. Output drives and input thresholds are correctly modeled for power supplies between 3 and 18 volts. Currently, propagation delays do not vary using supply voltages. For correct propagation delays at supply voltages other than 5 volts, the timing models in cd4000.1ib have to be modified.

Digital devices

Programmable array logic devices

Using a PLD from the library is just like using any other logic device from the library, except that the simulator has to be told the name of the JEDEC file which contains the program for the part. A TEXT parameter name JEDEC_FILE is used to specify the file name, as shown in the following example:

```
X1 IN1 IN2 IN3 IN4 IN5 IN6 IN7 IN8 IN9 IN10 IN11 IN12 + IN13 IN14 + OUT1 OUT2 OUT3 OUT4 + PAL14H4 + TEXT: JEDEC FILE = "myprog.jed"
```

This example creates a 14H4 PAL which is programmed by the JEDEC file myprog.jed.

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Behavioral Simulation Functions

General functions

ZERO() on page 470 ONE(expression) on page 470

CEIL(arg) on page 470 FLOOR(arg) on page 471

INTQ(arg) on page 471 RNDR() on page 475

RNDC() on page 475 RND() on page 475

DelayT(arg, arg, arg)

DelayT1(arg, arg)

Simulation variables

DELTA() on page 472 STATE() on page 473

TIME() on page 472

Simulation functions

BREAK() on page 474

System Variables

System Variables on page 477

ZERO()

Purpose Evaluates the function, and returns the value 0.

General form ZERO (expression)

Arguments expression

This can be any arithmetic expression. The expression is

evaluated, its value ignored and the output is 0.

Examples E1 1 0 value = {ZERO(sin({PI}/2))}

Comments In the example above the voltage V(1) will always be 0.

ONE(expression)

Purpose Evaluates the function, and returns the value 1.

General form ONE (expression)

Arguments expression

This can be any arithmetic expression. The expression is

evaluated, its value ignored and the output is 1.

Examples EE15 12 0 VALUE={ if (V(14)>0.7, ONE(PI), ZERO(PI)) }

Comments In the example above, if V(14) is greater than 7, the V(12) is 1 volts,

else it is 0 volts.

CEIL(arg)

Purpose Returns an integer value equal to or greater than the value of the

argument passed to the CEIL function.

General form CEIL (arg)

Arguments arg

The argument passed to the CEIL function, can be a numeric value or an expression that evaluates to a numeric value.

Behavioral Simulation Functions

Examples

G3 3 0 value = {CEIL(PI)}

E1 1 0 value = {CEIL(5)}

E1 1 0 value = $\{CEIL(5.4)\}$

Comments If arg is an integer, the return value is equal to the argument value. If

arg is a non-integer value, the return value is the nearest integer

greater than the argument value.

In the first example, the value of the charge source will be 4. Similarly, the value of V(1) in the second and third examples would be 5 and 6.

respectively.

FLOOR(arg)

Purpose Returns an integer value.

General form FLOOR (arg)

Arguments arg

The argument passed to the FLOOR function, can be a numeric

value or an expression that evaluates to a numeric value.

Examples E2 2 0 value = {FLOOR(PI)}

G3 3 0 value = $\{FLOOR(5)\}$

FLOOR(PI/2) = 1

Comments If arg is an integer, the return value is equal to the argument value. If

arg is a non-integer value, the return value is the nearest integer

smaller than the argument value.

In the first example, V(2) will be 3. Similarly, in the second example

the value of the charge source will be set to 5.

INTQ(arg)

Purpose Returns 1 if the argument is an integer, else returns 0

General form INTQ (arg)

Behavioral Simulation Functions

Arguments arg

The argument passed to integer function, INTQ, can be a numeric value or an expression that evaluates to a numeric

value.

Comments If arg is an integer, the return value is one. If arg is a non-integer

value, the return value is zero.

DELTA()

Purpose Returns the value of last three time steps taken by the simulator

General form DELTA(n)

Arguments n

Valid values are 0, 1, 2, and 3.

The argument ${\bf n}$ can also be an expression that evaluates to an integer value. If the evaluated value is greater than three, an

error is generated.

Examples Exy 11 0 VALUE= {delta(1)}

Comments If the value of n is 0, the result is same using the simulation variable

Delta.

At time t=n.

 $delta(1) = t_n - t_{n-1}$

TIME()

Purpose

Returns the time point value for last three simulation time-points.

General form

time(n)

where n = 0, 1, 2, 3

Behavioral Simulation Functions

Arguments

n

Valid values are 0, 1, 2, and 3.

The argument ${\bf n}$ can also be an expression that evaluates to an integer value. If the evaluated value is greater than three, an error is generated.

Examples

```
Exy 2 0 VALUE= {time(0)}
Exy 11 0 VALUE= {2*time(1)}
```

Comments

For n=0, the function returns the current simulation time-point. This is same value that you get value by adding the simulation variable DELTA to the last simulation time-point.

If the value of n is 0, the result is same using the simulation variable Time.

In the first example, voltage V(2) will be same as the current time. The value of V(2) at different time is shown below.

```
t=0, V(2) =0
t=1, V(2) =1
t=0.73, V(2) =0.73
```

STATE()

Purpose

Returns the history of the behavioral source up to last three states.

General form

STATE (n, source)

Arguments

n

Valid values are 0, 1, 2, and 3.

The argument n can also be an expression that evaluates to an integer value. If the evaluated valued is greater than three, an error is generated. And if the state were not mentioned, then the current state would be assumed.

```
<source>
```

A valid voltage, current, flux, or charge source

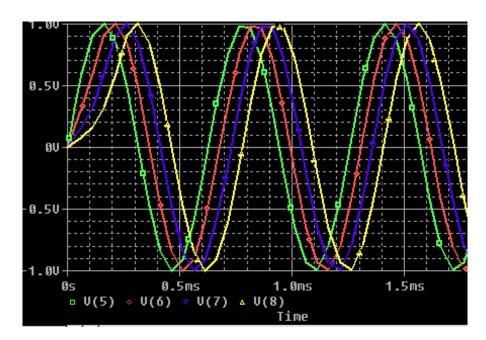
Behavioral Simulation Functions

Examples

```
Esin 5 0 value={sin(1e4*time)}
Estate1 6 0 value={state(1,V(5))}
Estate2 7 0 value={state(2,V(5))}
Estate3 8 0 value={state(3,V(5))}
```

Comments

The output of the example statements is shown in the figure given below.



BREAK()

Purpose

Schedules a break point at the specified time.

General form

BREAK(time)

Example

Exy 12 0 V= {BREAK(TIME+1E-5)}

Comments

The scheduling would be deferred until the correct solution at current time point.

Use BREAK() to ensure that simulator calculates values at a specific time point, defined by the value of the argument passed to the BREAK().

In the example statement, simulator will calculate the output V at time t, where t=current_time + 10 millisecond.

RND()

Purpose Returns a new random value at every time point.

General form {RND}

Example E1 N3 0 VALUE={5*RND}

Comments

RNDR()

Purpose Returns a new Random value at the start of any new analysis.

General form {RNDR}

Example E2 N4 0 VALUE={5*RNDR}

Comments If RNDR function is used for DC Analysis and Transient Analysis, it

will generate different value for each new analysis.

RNDC()

Purpose Returns a new random value at the start of each new analysis that

involves step run, such as Monte Carlo Analysis and Temperature

Analysis.

General form {RNDC}

Example E3 N5 0 VALUE={5*RNDC}

Comments If RNDC function is used for the Temperature Analsyis, it will

generate a different value for Temperature Analsyis than for Monte

Carlo Analysis.

DelayT(arg, arg, arg)

Purpose

The delayt() function removes the complexity of traditionally used delay functions, such as TLINE and Laplace-based functions. It reduces the convergence issues that exists in using the traditional functions, and it processes faster computation on signals (voltage or current) compared to traditional ones.

General form

Example

Comments

In delayt function, delay value and max delay parameters are required.

Note: DelayT is recommended over DelayT1 because it is more optimized in terms of memory usage.

DelayT1(arg, arg)

Purpose

The delayt1() function removes the complexity of traditionally used delay functions, such as TLINE and Laplace-based functions. It reduces the convergence issues that exists in using the traditional functions, and it processes faster computation on signals (voltage or current) compared to traditional ones.

General form

Example

Behavioral Simulation Functions

Comments In delayt1 function, only the delay value parameter is required.

Note: DelayT is recommended over DelayT1 because it is more optimized in terms of memory usage.

System Variables

<u>Table 4-1</u> on page 477, lists the system variables supported by the PSpice engine. You can use these variables in expressions to be evaluated using PSpice engine. These variables cannot be used in the trace expressions in the Probe window.

Table 4-1 System variables

| This variable | Evaluates to this |
|---------------|--|
| TEMP | Temperature values resulting from a temperature, parametric temperature, or DC temperature sweep analysis. |
| | The default temperature, TNOM, is set in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. TNOM defaults to 27°C. |
| | Note: TEMP can only be used in expressions pertaining to analog behavioral modeling and the propagation delay of digital models. |
| | Note: If a passive or semiconductor device has an independent temperature assignment, then TEMP does not represent that device's temperature. |
| | To find out more about customizing temperatures for passive or semiconductor devices, .MODEL (model definition) on page 57. |
| TIME | Time values resulting from a transient analysis. If no transient analysis is run, this variable is undefined. |
| | Note: TIME can only be used in analog behavioral modeling expressions. |
| RELTOL | Relative tolerance of Voltage and current |
| | The value of this variable is as specified in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. |
| ABSTOL | Current tolerance |
| | Describes the best accuracy of currents in a simulation run. The value of this variable is specified in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. |

Behavioral Simulation Functions

Table 4-1 System variables, continued

| This variable | Evaluates to this |
|---------------|--|
| VNTOL | Voltage tolerance |
| | Describes the best accuracy of voltages in a simulation run. The value of this variable is specified in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. |
| CHGTOL | Charge tolerance |
| | Describes the best accuracy of charges. The value of this variable is specified in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. |
| GMIN | Indicates the minimum conductance used for any branch. The value of this variable is specified in the <i>Options</i> tab of the <i>Simulation Settings</i> dialog box. |

Important

System variables covered in this section are reserved keywords for PSpice. You can use these variables in your circuits file but can not redefine them as user-defined variables. For example, you can not redefine these parameters in .PARAM or : PARAMS statements. An exception to this are the keywords GMIN, PI, and TEMP. These three variables can be declared within a .SUBCKT statement, to have a user defined value. Redefining GMIN, PI, and TEMP outside a .SUBCKT statement is not supported.

5

Behavioral Simulation Models

This chapter provides an overview of the behavioral models available with PSpice A/D. Using the behavioral models covered in this chapter, you can easily model the behavior of a system on your schematic. Besides providing you with an easy-to-use graphical interface, some of the models, such as DC motors, and tachometers, can be used to simulate systems which have no implementation in electrical circuitry. The models covered in this chapter are shipped with function.lib (Function library on page 484) and spice_elem.lib (Spice_elem_library on page 526).

<u>Table 5-1</u> on page 479 lists the application-specific categories and the library elements that fall in that category. For example, behavioral models for electromechanical parts, such as tachometer and DC motor, are listed under the mechanical elements category. Similarly, models such as ABS, SUM, and INTEGRATOR, are listed under arithmetic functions.

<u>Table 5-2</u> on page 484 and <u>Table 5-9</u> on page 526 provide the alphabetical listing of the elements in the function.lib and spice_elem.lib, respectively.

Table 5-1 Model categories

| Category | Library element | Comments |
|------------------------------|-----------------------|---|
| Laplace Domain Sources | ■ <u>BEHAV_FREQ</u> | These are also referred to as H(s) |
| | ■ <u>VOLTAGE FREQ</u> | sources. You can use these behavioral sources to define voltage |
| | ■ CURRENT_FREQ | and current as an expression of s. The output is in the frequency domain. You can use these sources in either the time or frequency domain. |
| Arbitrary Voltage Sources | ■ BEHAV_GEN | These are also known as F(x) |
| | ■ <u>VOLTAGE_GEN</u> | sources. |
| | ■ CURRENT GEN | |

Table 5-1 Model categories, continued

| Category | Library element | Comments |
|------------------------|---|---|
| Mechanical Elements | ■ <u>DC Motor</u> | The behavioral models provided for |
| | ■ <u>Tachometer</u> | the mechanical elements use a mechanical-to-electrical analogy in |
| | ■ <u>Gearbox</u> | which current represents torque and |
| | ■ <u>Flywheel</u> | voltage represents angular velocity. They are calibrated so that one volt |
| | ■ Viscous Friction | corresponds to one radian per second of shaft velocity, and a |
| | ■ Coil Spring | current of one Ampere is equal to one Newton-meter of torque. |
| Laplace Domain | ■ GAIN2 | |
| Functions | ■ Real Pole (<u>REALPOLE2</u>) | |
| | ■ Real Zero (<u>REALZERO2</u>) | |
| | Complex Pole, Frequency and Damping (<u>COMPLEX_FZ</u>) | |
| | Complex Pole, Real and Imaginary(<u>COMPLEX_RI</u>) | |
| | First Order Transfer Function (FY1) | |
| | Second Order Transfer Function (FY2) | |
| | Third Order Transfer Function (FY3) | |
| | Fourth Order Transfer Function (FY4) | |
| Analog Switches | ■ <u>ASW</u> | |
| | ■ ASW1 | |

Table 5-1 Model categories, continued

| Category | Library element | Comments |
|-------------------|----------------------------------|---|
| Time Functions | ■ DELAY | |
| | ■ DELAY1 | |
| | ■ ONE_SHOT | |
| | ■ <u>VCO</u> | |
| Arithmetic | ■ ABS | The arithmetic function blocks let you |
| Functions | ■ SUM | perform basic mathematical operations, such as addition and |
| | ■ DIFFERENCE | multiplication, on signals. |
| | ■ Multiply(<u>MULTIPLIER2</u>) | |
| | ■ Divide (<u>DIVIDER2</u>) | |
| | ■ Square Root(<u>SQRT</u>) | |
| | ■ Exponential (<u>EXP</u>) | |
| | ■ Natural Log (<u>LNX</u>) | |
| | ■ Maximum value (MAX) | |
| | ■ Minimum Value (MIN) | |
| Counter Functions | ■ DIV BY 2 | These are digital trigger-edge |
| | ■ DIV_BY_3 | counters, that are used as frequency dividers. |
| | ■ DIV_BY_4 | Each counter has two inputs: a clock |
| | ■ <u>DIV BY 5</u> | input labeled with a > symbol, and a reset input labeled R . |

Table 5-1 Model categories, continued

| Category | Library element | Comments |
|-------------------|--|---|
| Time Domain | ■ TIME | |
| Functions | ■ Differentiator(<u>DXDT</u>) | |
| | ■ Integrator (INTEGRATOR2) | |
| | ■ Current Limiter (ILIM) | |
| | ■ Voltage Limiter (<u>VLIM</u>) | |
| | ■ Slew Rate Limiter (SLEW_LIMIT) | |
| Switch Models | ■ <u>CC SWITCH</u> | Switch models allow you to model |
| | ■ <u>VV_SWITCH</u> | switches in PSpice. |
| | | The two types of switches that are supported are current controlled switches (CC_SWITCH) and voltage controlled switches (VC_SWITCH). |
| Dependent sources | Current Controlled Currer Source (<u>CCCS</u>) | can be used to model constant, linear, |
| | Current Controlled Voltag Source (<u>CCVS</u>) | or nonlinear dependent current or voltage sources by expressing the current or voltage as a polynomial |
| | Voltage Controlled Currer Source (<u>VCCS</u>) | t function of the current. This function is expressed in terms of the current |
| | Voltage Controlled Voltag Source (<u>VCVS</u>) | through the controlling source or the voltage difference between the controlling nodes. |

Table 5-1 Model categories, continued

| Category | Lik | orary element | Coi | mments |
|--------------------|-----|-------------------|---|--|
| Controlled sources | | Single Controller | | ese are controlled voltage and |
| | | <u>CCS10</u> | | rent sources, where the output is verned by the controlling current or |
| | | <u>CVS10</u> | voltage source, currentsense and | age source, currentsense and |
| | | Double Controller | | agesense, respectively. Dending on the number of |
| | | <u>CCS23</u> | controllers influencing the output, PSpice support two types of controlled sources: | |
| | | <u>CVS23</u> | | |
| | | | | Single Controller |
| | | | | These are the dependent source where output current or voltage is controlled by only one controller. CVS10 is a controlled voltage source and CCS10 is a controlled current sources. |
| | | | | Double Controller |
| | | | | These are the dependent source, where the output is controlled by more than one controller. CVS23 is a controlled voltage source and CCS23 is a controlled current source. |

Function library

Table 5-2 Elements in the Function library

| Element | Purpose | Comments |
|--------------|---|---|
| ABS | Returns absolute value of input | Calculates absolute value of the argument x, which can either be a number or an expression. |
| 4.0147 | . ABS | 0 1011 |
| ASW | Is an analog switch | See <u>ASW</u> on page 491. |
| ASW1 | Analog Switch | See <u>ASW1</u> on page 492 and <u>ASW</u> on page 491. |
| BEHAV_FREQ | Frequency Domain Behavioral Voltage Source | See <u>BEHAV_FREQ</u> on page 493. |
| BEHAV_GEN | Arbitrary Behavioral Voltage Sources | See <u>BEHAV_GEN</u> on page 495. |
| CHARGE_GEN | Charge generator | See Charge source on page 186 |
| COILSPRING | coil spring | See Coil Spring on page 496. |
| COMPLEX_FZ | Complex Pole, frequency and damping | See <u>COMPLEX_FZ</u> on page 503. |
| COMPLEX_RI | Complex Pole, Real and Imaginary | See COMPLEX RI on page 506. |
| CURRENT_FREQ | frequency-defined current source for describing continuous systems | The output current is specified by the IOUT property. |
| | | For information on other properties, see <u>BEHAV_FREQ</u> on page 493. |

Table 5-2 Elements in the Function library, continued

| Element | Purpose | Comments |
|-------------|--|--|
| CURRENT_GEN | Arbitrary Current Sources U11 F(x) IOUT = ? | The output is an arbitrary current source specified by the IOUT property. The value of IOUT can be set to any valid expression. |
| | | For information on other properties, see <u>BEHAV_GEN</u> on page 495. |
| DCMOTOR | DC Motor | For detailed information on DC motors, see <u>DC Motor</u> on page 498. |
| DELAY | Delay buffer U1 DELAY = 1m DELAY DELAY | The value of the DELAY property specifies the delay time. For example, if you set the value of DELAY property to 1m, a delay of 1 millisecond will be introduced in the output. |
| | | Note: In circuits with digital feedback, it is recommended that some delay parameter must be included at some point in the signal path, by using DELAY or DELAY1. This is to avoid erroneous simulation results, caused due to zero propagation delay in functions without any delay parameters. |
| DELAY1 | Delay buffer with inverted output U8 DELAY = ? DELAY1 | The value of the DELAY property specifies the delay time. For example, if you the input waveform is a sine wave, and the value of the DELAY property is set to 1m, the output waveform will be an inverted sine wave (180 degree phase shift) with a delay of 1 millisecond. |
| DIFFERENCE2 | two input difference | Output is the difference between two inputs. |

Table 5-2 Elements in the Function library, continued

| Element | Purpose | Comments |
|----------|-----------------------------|--|
| DIV_BY_2 | Frequency divider | Divides the frequency by 2. |
| | U4 | For example, if the frequency of the input clock signal is 60 Hz the frequency of the output signal would be 30Hz. |
| DIV_BY_3 | Frequency divider | Divides the frequency by 3. |
| | U13 /3 -0 /3 -0 PR DIV_BY_3 | For example, if the frequency of the input clock signal is 60 Hz the frequency of the output signal would be 20Hz. |
| DIV_BY_4 | Frequency divider | Divides the frequency by 4. |
| | U15 /4 R DIV_BY_4 | For example, if the frequency of the input clock signal is 60 Hz the frequency of the output signal would be 15Hz. |
| DIV_BY_5 | Frequency divider | Divides the frequency by 5. |
| | U16 | For example, if the frequency of the input clock signal is 60 Hz the frequency of the output signal would be 12Hz. |

Table 5-2 Elements in the Function library, continued

| Element | Purpose | Comments |
|----------|--|---|
| DIVIDER2 | Divider Block X X Y DIVIDER2 | Use this function to perform the mathematical function divide on the two inputs. You are not require to pass any parameters to this component and the output is Input1 by Input2. |
| DXDT | Differentiator | See <u>DIFFERENTIATOR</u> on page 520. |
| EXP | Exponential Block Property of the control of the c | The output is calculated using the mathematical expression $\mathrm{e}^{(x)}$, where x is the input. |
| FLUX_GEN | Flux generator | See Flux Source on page 184. |
| FLYWHEEL | Flywheel | See <u>Flywheel</u> on page 508. |
| FY1 | First order transfer function | See <u>Transfer Functions</u> on page 521 |
| FY2 | Second order transfer function | See <u>Transfer Functions</u> on page 521 |
| FY3 | Third order transfer function | See <u>Transfer Functions</u> on page 521 |
| FY4 | Fourth order transfer function | See <u>Transfer Functions</u> on page 521 |
| GAIN2 | Defines gain | This is a laplace function. |
| | U17 GAIN = 1 □ k = □ | If the value of the GAIN property attached to the component is set to 0, an error message pops up indicating that it is a zero value component. |
| | GAIN2 | Similarly, if the value of GAIN property is not defined, then also PSpice throws a error message. |

Table 5-2 Elements in the Function library, continued

| Element | Purpose | Comments |
|-------------|-------------------------------|--|
| GEARBOX | Is used as a torque converter | See <u>Gearbox</u> on page 510. |
| ILIM | Current limiter | See <u>ILIM</u> on page 517 |
| IN | Input Comparator | See <u>IN</u> on page 511. |
| INTEGRATOR2 | Integrator | See INTEGRATOR on page 519. |
| LNX | Natural log | Returns the logarithmic value of the input. Output is equal to $\ln(x)$, where x is the input. |
| MAX | Maximum value block | Use this when you want the greater of the two input voltages as output. |
| | HYSTERESIS = 1N U6 MAX | To get correct results, the difference between two input voltages should be greater than the value of the HYSTERESIS property. By default, the value of switch over hysteresis is one millivolt. For critical applications, you can reduce this value, but a smaller hysteresis might cause convergence problems in the time domain. |
| MIN | Minimum value block | Use this when you want the lesser of the two input voltages as output. |
| | HYSTERESIS = 1N U7 MIN MIN | As in the case of MAX, the difference between two input voltages should be greater than the value of the HYSTERESIS property. By default, the value of switch over hysteresis is one millivolt. For critical applications, you can reduce this value, but a smaller hysteresis might cause convergence problems in the time domain. |

Table 5-2 Elements in the Function library, continued

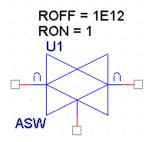
| Element | Purpose | Comments |
|-------------|---------------------------------------|---|
| MULTIPLIER2 | Multiplier block | Performs the mathematical task of multiplying the two inputs, and returns the product as the output. |
| | MULTIPLIER2 | |
| ONE_SHOT | Monostable multivibrator | See <u>ONE_SHOT</u> on page 513. |
| OUT | Output buffer | See <u>OUT</u> on page 512. |
| OUT1 | Output buffer with inverted output | OUT1 is similar to OUT, except that it performs a logic inversion. |
| | | See <u>OUT</u> on page 512. |
| REALPOLE2 | Models a single pole on the real axis | See <u>REALPOLE2</u> on page 523. |
| REALZERO2 | Models a singe zero on the real axis | See <u>REALZERO2</u> on page 524. |
| SLEW_LIMIT | Slew Rate Limiter | See <u>SLEW_LIMIT</u> on page 525. |
| SQRT | Returns square root of the input | Performs mathematical operation \sqrt{x} , where x is the input. Negative values of input are not supported and an error message will be generated if x<0. |
| SUM2 | Two Input Summer | Adds two inputs values and returns the sum |
| TACHO | tachometer | For details, see <u>Tachometer</u> on page 501. |
| TIME | time function | The output of the Time function is equal to <i>t</i> times the input. For the Time function to work properly, simulation time must be less than 1000 seconds. |

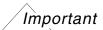
Table 5-2 Elements in the Function library, continued

| Element | Purpose | Comments |
|--------------|---|--|
| VCO | Macro Logic Voltage Controlled Oscillator | See <u>VCO</u> on page 515. |
| VISCOSITY | Use this component to simulate the viscous friction of a fluid. | The VISC property specifies the viscosity, which is the measure of the resistance of a fluid to deformation. It is measured in Newton-meter-seconds. |
| | VISC = 1 U7 UISCOSITY | |
| VLIM | Voltage limiter | See <u>VLIM</u> on page 518 |
| VOLTAGE_FREQ | Frequency Domain Voltage Source | It is a two-pin voltage source that defines the voltage in terms of an expression and a transfer function. |
| | | For information on the component properties, see <u>BEHAV_FREQ</u> on page 493. |
| VOLTAGE_GEN | Arbitrary Voltage | It is a two-pin arbitrary voltage source. |
| | Sources | For information on the component properties, see <u>BEHAV_GEN</u> on page 495. |

ASW

Analog switch **Purpose**





The symbol () denotes analog functionality. Terminals labeled with these symbols are the only terminals that can be connected to external circuitry.

Table 5-3 Analog Switch Properties

| Property | Meaning | Measured in |
|----------|--|---------------------------------|
| ROFF | Off resistance | ohms (Ω) |
| | Specifies the value of the resistor when the digital input is low. | Default value is 1e12 ohms. |
| RON | On resistance. | ohms (Ω) |
| | Defines the value of the resistor when the digital input is high | Default value is set to 1 ohms. |

Comment

If you use the ASW part to simulate the analog switch, the switch will

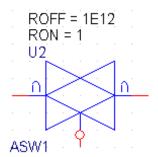
be ON if the input at pin B is set to 1.

The resistance of the switch, when ON is determined by the value of RON property. Similarly, the value of the ROFF property determines the resistance of the switch in the OFF state.

ASW1

Purpose

Analog switch



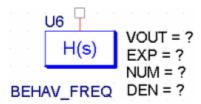
Comment

If you use the ASW1 part to simulate the analog switch, the switch will be ON if the digital input at pin B is set to 0.

The resistance of the switch, when ON is determined by the value of RON property. Similarly, the value of the ROFF property determines the resistance of the switch in the OFF state.

For more information, see <u>ASW</u> on page 491.

BEHAV_FREQ



Purpose Frequency domain behavioral source

Comment This function defines the output voltage in the frequency domain.

Using the BEHAV_FREQ function, you can define the output voltage

voltage an expression of s.

Conceptually, this device can be represented in two parts, a general source followed by a transfer function. The transfer function is defined in frequency domain terms.

$$H(s) = exp(As + B) \times \frac{NUM}{DEN}$$

Table 5-4 Behavioral Source Properties

| Property | Meaning |
|----------|--|
| VOUT | Expression |
| EXP | Delay and decay of the transfer function, exp(As+B). |
| NUM | Numerator of the transfer function as a polynomial of s |
| DEN | Denominator of the transfer function as a polynomial of s. |

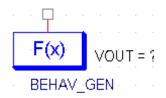
You can use these sources both in time and frequency domain.

Example

A transfer function with a gain of two and a single pole at 1 KHz can be implemented with the following expressions:

DEN = s + 2*pi*1e3

BEHAV_GEN



Description Frequency domain arbitrary behavioral voltage source

Comment This is a single pin arbitrary voltage source, where the output voltage

is defined as an expression.

Table 5-5 Arbitrary Voltage Source Properties

| Property | Meaning |
|------------|---|
| VOUT | Specifies the output voltage in form of a valid expression. |
| | The expression can have arithmetic operators, variables, and nested functions. |
| ERROR_COND | Specifies a condition, which when TRUE will stop the simulation process. |
| ERROR_MESG | Specifies the message statement displayed to a user when ERROR_COND is met. |
| | This message will be displayed only if an error condition has been specified. |
| WARN_COND | Specifies a condition, which when TRUE will throw the warning message. |
| WARN_MESG | Specifies the message statement displayed to a user in case of warning. |
| | The message statement will be displayed only if a warning condition has been specified. |
| | Note: The error and warning properties are optional. |

Behavioral Simulation Models

Coil Spring

A coil wound in a spiral shape that reacts against twisting motion.

General form X AWBCOILSPRING PARAMS: IC=<value> COILVAL=<value>

The symbol and properties for a coil spring are listed below.

Figure 5-1 Coil Spring

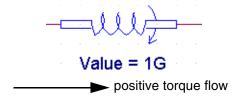


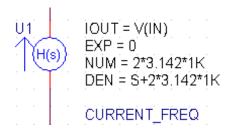
Table 5-6 Coil Spring Properties

| Property | Meaning | Measured in |
|-----------|--------------------------|---------------|
| IC | Current through the coil | Ampere (A) |
| COILVALUE | Spring constant | Newton-meters |
| | The default value is 1M | |

The IC property represents the initial current through the inductor during the bias point calculation. A positive initial torque can be measured as a current flowing from left to right.

Behavioral Simulation Models

CURRENT_FREQ



Purpose

Frequency-defined behavioral current source

Comment

This function defines the output current as a function of input voltage and an expression of s. You can use this source either in time or frequency domain.

$$I(out) = H(s) \times V(in)$$

The transfer function is defined in frequency domain terms.

$$H(s) = exp(As + B) \times \frac{NUM}{DEN}$$

For the explanation of properties attached to CURRENT_FREQ, see <u>Table 5-3</u> on page 491.

Example

A transfer function with a gain of 3 and a single pole at 1 KHz can be implemented with the following expressions:

```
IOUT = 3 * v(in)

EXP = 0

NUM = 2*pi*1e3

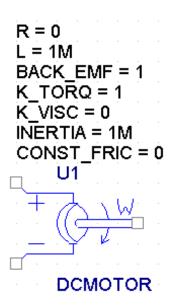
DEN = s + 2*pi*1e3
```

DC Motor

A DC motor is used to convert electrical energy to mechanical energy. It works on the principle that when electric current passes through a magnetic field, a torque is produced because of the magnetic force. This torque is used to run the DC motor.

General form

- X AWBDCMOTOR PARAMS: R=<value> L=<value> BACK_EMF=<value>
- + K TORQ=<value> K VISC=<value>
- + INERTIA=<value>
- + CONST FRIC=<value>



The electrical characteristics of the motor, synthetically winding, is modeled as a series RL circuit representing the armature inductance and resistance. Mechanical portion of motor is modelled as a parallel RC circuit. The electrical and mechanical portions are connected using controlled sources. Back EMF is also modeled and included in series with motor winding in such a manner that it opposes the input voltage. Voltage at pin C represents the Motor Torque.

<u>Table 5-7</u> on page 498 lists properties attached to a DC motor symbol.

Table 5-7 DC Motor Properties

| Property | Meaning | Measured in |
|----------|---------------------------|-----------------|
| R | Series winding resistance | ohms (Ω) |
| L | Series inductance | Henries |

Table 5-7 DC Motor Properties, continued

| Property | Meaning | Measured in |
|------------|-------------------------------------|---------------------------|
| BACK_EMF | Back electromagnetic field constant | volt-sec/rad |
| K_TORQ | Torque constant | N-m/amp |
| K_VISC | Viscous frictional coefficient | N-m-sec/rad |
| INERTIA | Rotor moment of inertia | N-m-sec ² /rad |
| CONST_FRIC | Constant friction torque | N-m |

Equations:

■ Motor Current:

 $V_{ip} - V_{backemf} = L_{di}/(dt) + R_i$

In this equation:

- ☐ Vbackemf = BACK_EMF X(Motor speed)
- □ Vip is Voltage applied to motor input terminals (A,B)
- □ L is winding inductance
- □ R is winding resistance

Torque:

Torque is modeled using the following equation.

Note: Solving the equation for voltage (Vt) gives the equivalent torque.

$$I = V_t/R_v + (C \cdot dV_t)/(dt)$$

In this equation:

- C represents inertia
- □ I represents torque
- extstyle ext
- □ Rv represents friction, which is 1/(K_VISC)

The back emf is a function of param {back_emf} and generated back EMF is a function of (velocity of motor) *{back_emf}.

| Generated torque | is function o | of angular velocity | (voltage drop) | across the | winding r | esistance |
|--------------------|---------------|---------------------|----------------|------------|-----------|-----------|
| (winding current). | The motor t | torque equation is: | · · | | | |

I=J dw/dt +W.B

In thsi equation:

- I represents torque
- $\ensuremath{\mathtt{J}}$ represents inertia
- $\ensuremath{\mathbb{W}}$ is angular velocity
- B is friction

Tachometer

General form

A tachometer is a device for indicating the angular (rotary) speed of a rotating shaft. It indicates the instantaneous values of speed in revolutions per minute (RPM). A tachometer converts mechanical energy into electrical energy.

+ CONST FRIC=<value>

X AWBTACHO PARAMS: R=<value> L=<value>
+ BACK_EMF=<value> K_TORQ=<value>
+ K_VISC=<value> INERTIA=<value>

```
R = 0
L = 1M
BACK_EMF = 1
K_TORQ = 1
K_VISC = 0
INERTIA = 1M
CONST_FRIC = 0
U4
```

TACHO

Table 5-8 on page 501 lists properties of a tachometer.

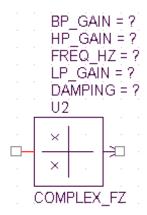
Table 5-8 Tachometer Properties

| Property | Meaning | Measured in |
|----------|------------------------------------|---------------------------|
| R | Series winding resistance | ohms (Ω) |
| L | Series inductance | Henries |
| BACK_EMF | Back electromagnetic field voltage | volt-sec/rad |
| K_TORQ | Torque constant | N-m/amp |
| K_VISC | Viscous frictional coefficient | N-m-sec/rad |
| INERTIA | Rotor moment of inertia | N-m-sec ² /rad |

Table 5-8 Tachometer Properties, continued

| Property | Meaning | Measured in |
|------------|--------------------------|-------------|
| CONST_FRIC | Constant friction torque | N-m |

COMPLEX_FZ



Purpose

Returns a second-order function.

The frequency and damping complex-pole function block is a generalpurpose, second-order block that can form linear combinations of lowpass, band-pass, and high-pass functions.

Arguments

 $FREQ_HZ$

Used to calculate the natural frequency, Omega (ω) using the equation, $\omega = 2\pi xFREQ_HZ$.

Omega is used to set the cutoff frequency for the high-pass and lowpass functions and the band center frequency for the bandpass function.

DAMPING

This is the damping factor Zeta (ζ). At values of ζ below 1, the poles or zeros separate from the x-axis and form complex pole or zero pairs, leading, respectively, to ringing or peaking in the frequency domain.

BP_GAIN

Specifies the gain for the band pass function.

 HP_GAIN

Specifies the gain for the high pass function.

 LP_GAIN

Specifies the gain for the low pass function.

Behavioral Simulation Models

Comments

The COMPLEX_FZ part uses Laplace function to generate a secondorder function. The combined transfer function used is:

$$\frac{As^2 + Bs + C}{\frac{s^2}{\omega^2} + \frac{2\zeta s}{\omega} + 1}$$

where

| Coefficient | Is specified by the parameter |
|---------------|-------------------------------|
| Α | HP_GAIN |
| В | BP_GAIN |
| С | LB_GAIN |
| ζ | DAMPING |
| $\omega/2\pi$ | FREQ_HZ |
| S | jω |

Setting A, B, or C to zero disables its associated function.

In practice it is recommended that you first set ω and ζ to the desired values. Then depending the function that you want to create, determine the value for A, B or C, one at a time.

Determining the Low-Pass Coefficient

To determine the low-pass coefficient, C (assuming that A = B = 0), you first decide what DC gain you want and then take the limit of the transfer function as s goes to zero The variable, s, is the zero-frequency or DC gain point. This equation simplifies to

C = the desired DC gain

Behavioral Simulation Models

Determining the High-Pass Coefficient

To determine the high-pass coefficient, A (assuming that B = C = 0), you must first decide what gain you want to have at a frequency high above the cutoff frequency and then take the limit of the transfer function as s goes to infinity, which is the high-frequency asymptote.

Solving this equation, you will notice that the square of infinity is involved in both the numerator and the denominator. This simplifies both terms and leads to cancellation of j-squared and infinity-squared. This calculation produces the following result

$$A\omega^2$$
 = the desired high-frequency gain

Therefore, A equals the desired gain divided by the square of ω . This implies that to maintain a constant gain, A must change as the natural frequency changes.

Determining the Bandpass Coefficient

To determine the band-pass coefficient, B (assuming that A = C = 0), you first decide what gain you want at the center of the pass band. Then, you take the limit of the transfer function as ω goes to ω .

Note: Remember that the natural frequency for a bandpass function is the center frequency.

With A and C at zero, the equation becomes

$$\frac{0j^2\omega^2 + Bj\omega + 0}{j^2\omega^2} + \frac{2\zeta j\omega}{\omega} + 1$$

In the denominator, the first term goes to -1 and the second term goes to $2\zeta j$.

Therefore, bandpass gain equals Biω/2jζ

Cancelling the js and solving for B, you get

$$B = \frac{2\zeta(\text{desired band-pass gain})}{\omega}$$

The value required for A depends on the natural frequency and the damping factor of the circuit. So, to maintain a constant gain when the natural frequency or ζ changes, the value of the coefficient B changes.

COMPLEX_RI

Description

Complex pole, real and imaginary



Purpose

Using the Real and Imaginary complex pole function block you define the complex poles based on real and imaginary parameters of a second order equation.

Arguments

 $REAL_HZ$

Real part of the complex pole.

 $IMAG_HZ$

This is the imaginary part of the complex pole.

BP_GAIN

Specifies the gain for the band pass function.

HP GAIN

Specifies the gain for the high pass function.

LP GAIN

Specifies the gain for the low pass function.

Behavioral Simulation Models

Comments

This is also a Laplace domain function, similar to the frequency and damping complex pole function block, <u>COMPLEX_FZ</u> on page 503

Using complex-pole, real and imaginary function block, you calculate complex poles based on real and imaginary parameters of the following second order equation.

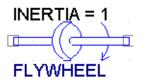
$$\frac{\omega(\mathsf{A}\mathsf{s}^* + \mathsf{B}\mathsf{s} + \mathsf{C})}{(\mathsf{s} + 2\pi\mathsf{D} + 2j\pi\mathsf{E})(\mathsf{s} + 2\pi\mathsf{D} - 2j\pi\mathsf{E})}$$

where

A is specified by HP_GAIN B is specified by BP_GAIN, C is specified by LP_GAIN, D is specified by REAL_HZ, and E is specified by IMG HZ.

Flywheel

Use this component to simulate the flywheel effect in a PSpice simulation. A flywheel is a heavy rotating disk on a shaft and resists changes in the rotation speed.



General form

X AWBFLYWHEEL PARAMS: INERTIA=<value>

$$energy = \frac{1}{2}I\omega^2$$

For a flywheel torque is measured by the equation given below.

$$T = J \times \frac{d\omega}{dt}$$

where:

T torque

Specified by the current

J Moment of Inertia

Specified by INERTIA

 ω Angular velocity

specified by circuit voltage

/Important

The mechanical elements in the FUNCTION library are simulated in PSpice using a mechanical-to-electrical analogy. The mechanical properties such as torque and angular velocity are represented by current and voltage, respectively. They are

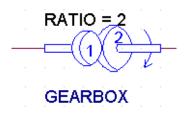
Behavioral Simulation Models

calibrated in a manner such that one volt corresponds to one radian per second of shaft velocity, and one Ampere current is equal to one Newton-meter of torque.

Behavioral Simulation Models

Gearbox

Use this component to simulate a mechanical gear box in PSpice. A gearbox is an assembly of gears that allows the rotational speed of an input shaft to be changed to a different speed.



The conversion is done using the equation given below.

$$TL = \left(\frac{N2}{N1}\right) \cdot TM$$

where

TL Torque at load shaft

N2/N1 gear ratio specified by the RATIO property

TM Torque at motor shaft

The value of the RATIO property can be obtained using one of the following ratios:

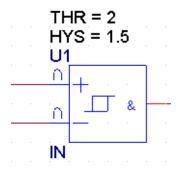
output diameter output number of teeth input diameter input number of teeth

Important

The mechanical elements in the FUNCTION library are simulated in PSpice using a mechanical-to-electrical analogy. The mechanical properties such as torque and angular velocity are represented by current and voltage, respectively. They are calibrated in a manner such that one volt corresponds to one radian per second of shaft velocity, and one Ampere current is equal to one Newton-meter of torque.

IN

This input comparator converts analog voltages to 0 and 1 volt levels that are compatible with the digital inputs of other functions.



General form

X AWBIN PARAMS: THR=<value> HYS=<value>

THR

Specifies threshold

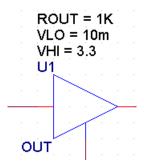
HYS

Specifies hysteresis value

Note: The properties for the IN function correspond to those for the voltage-controlled switch; the ON state in the voltage-controlled switch maps to 1 Volt at the output, and the OFF state maps to 0 Volts. The open and closed resistance values for the IN function are fixed at 1 Ohm and 1 MegOhm, respectively. In most cases you can connect an external reference voltage to one of the inputs, and leave the default properties unchanged.

OUT

OUT is an output buffer. It buffers the digital outputs of other functions so they can be connected to external (analog) circuitry.



General form

X AWBOUT1 PARAMS: ROUT=<value> VLO=<value> VHI=<value>

ROUT

Output impedance in ohms

VLO

Specifies the voltage level in volts, for the low output

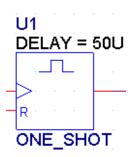
VHI

Specifies the voltage level in volts, for the high output

Note: The reference terminal, located at the bottom of the OUT or OUT1 symbol, must be connected to the reference voltage of the external circuitry. This is usually (but not necessarily) ground. To use OUT1 as a logic inverter, use the default property values and connect the reference terminal to ground.

ONE_SHOT

This is a monostable multivibrator.



General form

X AWBONE SHOT PARAMS: DELAY=<value>

DELAY

Specifies the maximum pulse width of the output waveform

A monostable multivibrator has two inputs: a clock input labeled >, and a reset input labeled R. The R input is used to initialize and reset the output. When the R input is high, the output is forced low. With R low, a positive-going edge at the clock input causes the output to step from low to high. The pulse is terminated by a high at the R input.

These relationships are summarized in the truth table shown below.

| Inputs | | Output |
|-----------|-----------|-----------|
| Clock (>) | Reset (R) | |
| X | 1 | 0 |
| | 0 | |
| | 0 | no change |

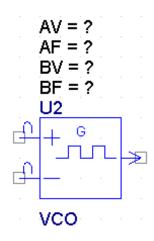
Behavioral Simulation Models



If the output terminal of the monostable multivibrator is loaded with a finite impedance, it malfunctions.

VCO

This is a *Square Wave* Voltage Controlled Oscillator that has a differential analog control voltage input that controls the frequency of the oscillator. The linear frequency transfer characteristic is determined by four parameters that are specified with the properties A Voltage (AV), A Frequency (AF), B Voltage (BV), and B Frequency (BF).



Parameters

Note: Positive and negative terminals are, respectively, represented as A and B.

AF

Specifies A frequency

ΑV

Specifies A voltage

BF

Specifies B frequency

BV

Specifies B Voltage



A frequency and B frequency must be greater than zero but not equal to 1. And A voltage must not equal B voltage.

The output frequency of the VCO is governed by the formula:

Behavioral Simulation Models

$$F_{OUT} = \frac{\left[\left\langle \boldsymbol{B}_{\boldsymbol{V}} \! \times \! \boldsymbol{A}_{\boldsymbol{F}} \right\rangle - \left(\boldsymbol{A}_{\boldsymbol{V}} \! \times \! \boldsymbol{B}_{\boldsymbol{F}} \right) \right] + \left[\left(\boldsymbol{B}_{\boldsymbol{F}} \! - \! \boldsymbol{A}_{\boldsymbol{F}} \right) \times V_{IN} \right]}{\left(\boldsymbol{B}_{\boldsymbol{V}} \! - \! \boldsymbol{A}_{\boldsymbol{V}} \right)}$$

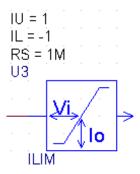
Where,

- lacksquare F_{OUT} : Output Frequency of the VCO
- V_{IN} : Input Voltage $[V_{IN1} V_{IN2}]$

Note: The Square Wave VCO malfunctions if its output terminal is loaded with a finite impedance.

ILIM

This current limiter limits the output current within the range specified by the user.



Parameters

ΙU

Specifies the upper limit of the output current. If the input current is more than the value of the ${\tt IU}$ parameter, the input current is clipped at this value.

IL

Specifies the lower limit of the output current. If the input current is less than ${\tt IL}$, the output current is maintained at ${\tt IL}$.

RS

Specifies device resistance

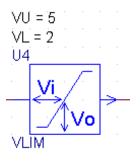
Note: The input current depends on the input voltage v_{in} , and the device resistance RS. The input current \mathbf{I}_{in} is calculated using the equation given below:

$$I_{in} = \frac{V_{in}}{RS}$$

Behavioral Simulation Models

VLIM

This is a voltage limiter that is used to maintain the output voltage within the range specified by the user.



Parameters

Specifies the upper limit of the output voltage. If the input voltage is more than the value of the $\lor U$ parameter, the output voltage is clipped at this value.

VL

VU

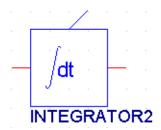
Specifies the lower limit of the output voltage. If the input voltage is less than VL, the output voltage is maintained at VL.

Behavioral Simulation Models

INTEGRATOR

The Integrator block models the transfer function k/s, but with a finite DC gain. For a gain of 1, the DC gain is 240 dB, but as the gain is changed, the DC gain varies. This can affect DC convergence if the gain is set too high.

Figure 5-2 Integrator Function

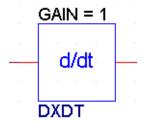


The integrator has an ideal buffered output on the right side of the symbol and a special initial condition (IC) pin on top. The GAIN property affects the unity gain frequency. For instance, to obtain a unity gain point of 1 Hz, enter a value of 6.28 ($\sim 2\pi$).

The rise time of the signal fed through an Integrator function must not be less than 0.1% of the total simulation time. If a DC voltage is applied to the input of the Integrator block and the output wire is not connected, you must assign initial conditions to the IC pin.

To set an initial condition, you can either use an IC part or a NODESET, by connecting it to the IC pin on the top of the symbol. Without the initial conditions, the output attempts to reach an infinite voltage.

DIFFERENTIATOR



Differentiator output is calculated using the equation given below.

$$output = GAIN \times \frac{d}{dt}input$$

Behavioral Simulation Models

Transfer Functions

A transfer function between an input variable, u(t), and an output variable, y(t), of a system is defined as the ratio of the Laplace transform of the output to the Laplace transform of the input:

$$U(s) = Laplace\{u(t)\}$$

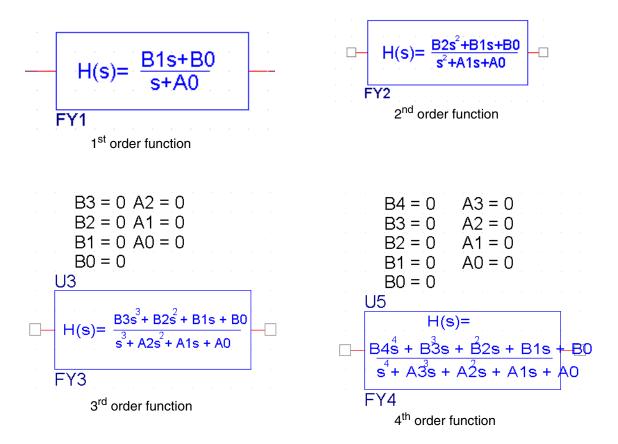
$$Y(s) = Laplace\{y(t)\}$$

$$H(s) = transfer function = \frac{Y(s)}{U(s)}$$

In these equations, *s* is the complex variable.

The four types of transfer functions supported in PSpice are FY1, FY2, FY3, and FY4, shown in <u>Figure 5-3</u> on page 521.

Figure 5-3 Transfer Functions



The following rules apply to transfer functions:

- Transfer functions are defined only for linear, time-invariant systems.
- The transfer function model assumes that all initial conditions are zero.
- Transfer functions are independent of input excitation.

The equations for the following fourth-order transfer function are

$$Y(s) = B4s^4 + B3s^3 + B2s^2 + B1s + B0$$

$$U(s) = s^4 + A3s^3 + A2s^2 + A1s + A0$$
where

| Y(s) | Output |
|--|--------------------------------|
| U(s) | Input |
| S | The complex frequency (s + jw) |
| B4, B3, B2, B1, B0, A3, A2, A1, and A0 | Constant coefficients |

REALPOLE2

The Real Pole function models a single pole on the real axis. The frequency response has constant gain from DC to about one decade below the pole frequency, by which point the gain rolls off to 3 dB below the DC gain. Above the pole, the frequency response rolls off at about 20 dB per decade.

Figure 5-4 Symbol and Properties for the Real Pole Function

GAIN=1 FREQ_HZ=? Transfer Function =
$$\frac{k}{1 + \frac{s}{\omega}}$$

 $f = \frac{\omega}{2\pi}$

The following are the properties for this function.

General form

X AWBREALPOLE2 PARAMS: FREQ HZ=<value> GAIN=<value>

FREQ_HZ

Specifies operating frequency in Hertz (Hz). This value cannot be negative.

GAIN

Specifies the linear gain factor. Fractional numbers provide attenuation, while negative numbers provide phase reversal with respect to a positive gain factor.

REALZERO2

The Real Zero function models a singe zero on the real axis. The frequency response has constant gain from DC to about one decade below the zero frequency, at which point the gain increases. Above zero, the frequency response increases at 20 dB per decade.

To avoid convergence problems in time domain analyses, use the Real Pole function block (with pole frequency equal to 1000 times the zero frequency) in series with the Real Zero function block.

Figure 5-5 Symbol and Properties for the Real Zero Function



$$f = \frac{\omega}{2\pi}$$

General form

X AWBREALPOLE2 PARAMS: FREQ HZ=<value> GAIN=<value>

FREQ_HZ

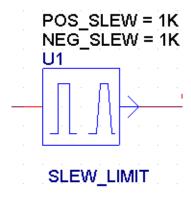
Specifies operating frequency in Hertz (Hz). For zero location, frequency can be negative. This is unlike the frequency value for a Real Pole.

GAIN

Specifies the linear gain. Fractional numbers provide attenuation, while negative numbers provide phase reversal with respect to a positive gain factor.

SLEW_LIMIT

Use this part to control the rise and fall value of the input waveforms.



General form

X AWBSLEW LIMIT PARAMS: POS SLEW=<value> NEG SLEW=<value>

POS_SLEW

Specifies the positive slew rate, which control the rise time of the input waveform. The rise time, t_r , is equal to the reciprocal of POS_SLEW.

NEG_SLEW

Specifies the negative slew rate, which control the fall time of the input waveform. The fall time, t_f , is equal to the reciprocal of NEG_SLEW.

$$t_r = \frac{1}{POSSLEW}$$
 and $t_f = \frac{1}{NEGSLEW}$

Spice_elem library

Table 5-9 Elements in the Spice_elem library

| Element | Purpose | Comments |
|--------------|--------------------------------------|--|
| CC_SWITCH | Current controlled switch | See <u>CC_SWITCH</u> on page 528. |
| CCCS | Current Controlled Current Source | See <u>CCCS</u> on page 540, and <u>Current-controlled Voltage Source</u> on page 182. |
| CCS10 | Controlled Current Source | This is a dependent current source. Output current can be controlled either by the voltagesense or by the currentsense. For more information see, CCS10 on page 533. |
| CCS23 | Controlled Current Source | This is also a dependent current source, where the output current is controlled both, by the voltagesense and by the currentsense. For more information see, <u>CCS23</u> on page 537. |
| CCVS | Current Controlled Voltage Source | See <u>CCCS</u> on page 540 and <u>Current-controlled Voltage Source</u> on page 182. |
| CURRENT | Independent Current source | The output current is determined by the value assigned to the VALUE property attached to the symbol. |
| CURRENTSENSE | Ammeter | See Currentsense on page 538. |
| CVS10 | Controlled Voltage Source | This is a dependent voltage source, where the output voltage is controlled either by the voltagesense or by the currentsense. For more information see, <u>CVS10</u> on page 530. |
| CVS23 | Controlled Voltage Source | This is also a dependent voltage source, where the output voltage is controlled by both, the voltagesense and the currentsense. For more information see, <u>CVS23</u> on page 536. |
| DC | DC transformer | See DC transformer on page 545. |
| DELAY_2_TERM | Delay Line | See <u>Delay lines</u> on page 544. |

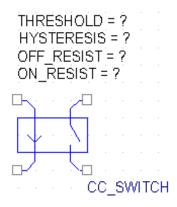
PSpice A/D Reference Guide Behavioral Simulation Models

Table 5-9 Elements in the Spice_elem library, continued

| Element | Purpose | Comments |
|--------------|--------------------------------------|-------------------------------------|
| DELAY_3_TERM | Delay Line | See <u>Delay lines</u> on page 544. |
| VC_CAP | Voltage Controlled Capacitor | |
| VC_CON | Voltage Controlled Conductor | |
| VC_IND | Voltage Controlled Inductor | |
| VC_RES | Voltage Controlled Resistor | |
| VC_SWITCH | Voltage Controlled Switch | See <u>CC_SWITCH</u> on page 528. |
| VCCS | Voltage Controlled Current Source | See <u>CCCS</u> on page 540. |
| VCVS | Voltage Controlled Voltage Source | See <u>CCCS</u> on page 540. |
| VOLTAGESENSE | Voltmeter | See Voltagesense on page 539. |

CC_SWITCH

Model for current controlled switches.



The properties passed as parameters to a switch model are shown in the table below.

Table 5-10 CC_SWITCH properties

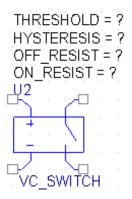
| Property | indicates |
|----------------|---|
| Threshold | Threshold current |
| Hysteresis | Hysteresis current |
| On resistance | Resistance when the switch on |
| Off resistance | Resistance when the switch off |
| | This is of the order of 10 ⁶ ohms. |
| Delay | time delay in seconds |

Use of switches can cause large discontinuities to occur in the circuit node voltages and branch currents. A rapid change such as that associated with a switch changing state can cause numerical round off or tolerance problems, leading to erroneous results or time step difficulties. You can improve the situation by taking the following actions:

- Set ideal switch impedances only high and low enough to be negligible with respect to other circuit elements. Using switch impedances that are close to "ideal" in all cases aggravates the discontinuity problem. When modeling real devices such as MOSFETs, adjust the on resistance to a realistic level, depending on the size of the device being modeled.
- Set a delay not equal to 0.

VV_SWITCH

Model for voltage controlled switches.



The properties passed as parameters to VC_SWITCH model are shown in the table below.

Table 5-11 VC_SWITCH Properties

| Property | indicates |
|----------------|--------------------------------|
| Threshold | Threshold voltage |
| Hysteresis | Hysteresis voltage |
| On resistance | Resistance when the switch on |
| Off resistance | Resistance when the switch off |
| Delay | time delay in seconds |

Behavioral Simulation Models

CVS10

This is a controlled voltage source. Here the output voltage is controlled either by a <u>Currentsense</u> or by a <u>Voltagesense</u>. To see how CVS10 is used with a currentsense, see <u>Figure 5-6</u> on page 531. To see how to use CVS10 with a voltage sense, see <u>Figure 5-7</u> on page 532.

Property

GAIN

Describes the voltage gain

VSOURCE

If the value of this parameter is set to TRUE, it indicates that the voltage source is being controlled by a voltagesense. If no value is assigned to this parameter, it indicates that the output voltage is controlled by a currentsense.

CONTROLLER

Specifies the name of the controller.

Figure 5-6 CVS10 used with CurrentSense

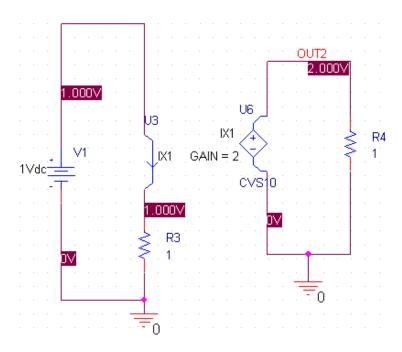


Table 5-12 Property values when CVS10 is controlled by a CurrentSense

| Property | Value assigned |
|------------|-------------------------------|
| VSOURCE | NULL |
| CONTROLLER | IX1(Name of the CurrentSense) |
| GAIN | 2 |

Figure 5-7 CVS10 used with a VoltageSense

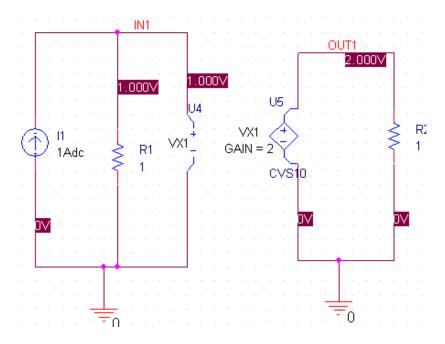


Table 5-13 Property values when CVS10 is controlled by a VoltageSense

| Property | Value assigned |
|------------|--------------------------------|
| VSOURCE | TRUE |
| CONTROLLER | VX1 (Name of the VoltageSense) |
| GAIN | 2 |

Behavioral Simulation Models

CCS10

This is a controlled current source. Here the output current is controlled either by a <u>Currentsense</u>, see <u>Figure 5-9</u> on page 535, or by a <u>Voltagesense</u>, <u>Figure 5-8</u> on page 534.

Property

VALUE<expression>

Indicates the gain of the current source, which is assigned using the GAIN property attached to the symbol.

VSOURCE

If the value of this parameter attached to the symbol, is set to TRUE, it indicates that the output current is being controlled by a voltagesense. If no value is assigned to this parameter, it indicates that the controller is a currentsense.

Figure 5-8 CCS10 used with a VoltageSense

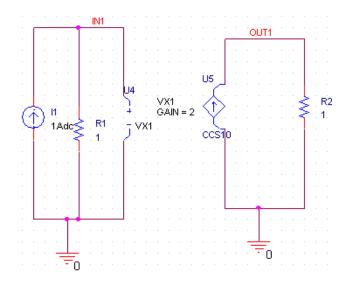


Table 5-14 Property values when CCS10 is controlled by a VoltageSense

| Property | Value assigned |
|------------|-------------------------------|
| VSOURCE | TRUE |
| CONTROLLER | VX1(Name of the VoltageSense) |
| GAIN | 2 |

Figure 5-9 CCS10 used with a CurrentSense

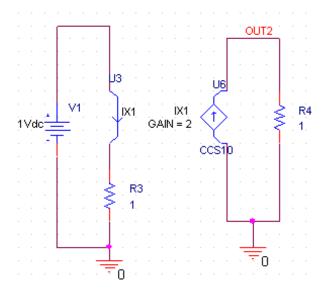
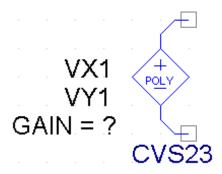


Table 5-15 Property values when CCS10 is controlled by a VoltageSense

| Property | Value assigned |
|------------|-------------------------------|
| VSOURCE | NULL |
| CONTROLLER | IX1(Name of the CurrentSense) |
| GAIN | 2 |

CVS23

This is a controlled voltage source, controlled by two voltagesenses or currentsenses.



Property

VALUE<expression>

Indicates the expression used to calculate the output current. The expression used is:

$$\begin{array}{l} \mathtt{GAIN} \ \star \\ + \ \mathtt{C_6} \cdot \mathtt{I_1}^3 \ + \ \mathtt{C_7} \cdot \mathtt{I_1}^2 \cdot \mathtt{I_2} \ + \ \mathtt{C_8} \cdot \mathtt{I_1} \cdot \mathtt{I_2}^2 \ + \mathtt{C_9} \cdot \mathtt{I_2}^3 \\ \end{array} \\ + \ \mathtt{C_8} \cdot \mathtt{I_1} \cdot \mathtt{I_2}^2 \ + \mathtt{C_9} \cdot \mathtt{I_2}^3 \end{array})$$

where

GAIN is the value of the GAIN property

C₀ is the value of the C0_VALUE property

C₁ is the value of the C1_VALUE property

C₂ is the value of the C2_VALUE property

and so on

VSOURCE

If the value VSOURCE is set to TRUE, it indicates that the output voltage is being controlled by a voltagesense. If no value is assigned to this parameter, it indicates that the controller is a currentsense.

XCONTROLLER

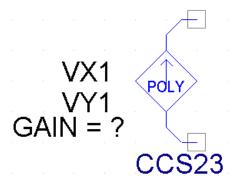
Specifies the name of the first controlling source.

YCONTROLLER

Specifies the name of the second controlling source.

CCS23

This controlled current source can be controlled either by two voltagesenses or by two currentsenses.

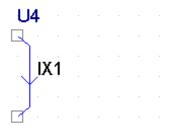


Note: For explanation of the parameters, see CVS23 on page 536.

Behavioral Simulation Models

Currentsense

This is a behavioral representation of an ammeter, which is an electrical device for measuring circuit current.



CURRENTSENSE

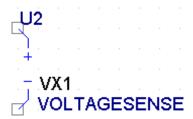
Ammeters are modeled using zero value voltage sources that can be inserted into the circuit for the purpose of measuring current.

Adding Currentsense has no effect on circuit operation because they represent short-circuit. These voltage sources need not be grounded.

Behavioral Simulation Models

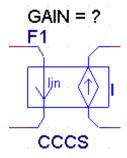
Voltagesense

This is a behavioral representation of a voltmeter, which is an electrical device for measuring voltage drop across two points in a circuit.



Adding voltagesense has no effect on circuit operation because they represent an open circuit.

CCCS



This is a Current Controlled Current Source.

Arguments

GAIN

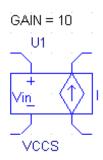
Used to calculate the output current. The output current is calculated using the equation listed below.

$$I_{out} = I_{in} \times GAIN$$

The input current \mathbb{I}_{in} is the current flowing through the input terminal of the device.

VCCS

This is the model for a voltage controlled current source.



Arguments

GAIN

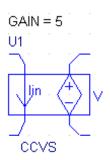
Used to calculate the output current. The output current is calculated using the equation listed below.

$$I_{out} = V_{in} \times GAIN$$

The input voltage \mathbb{V}_{in} is the voltage across the input terminal of the device.

CCVS

This is the behavioral model for a Current Controlled Voltage Source.



Arguments

GAIN

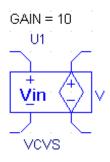
Used to calculate the output voltage. The output voltage is calculated using the equation listed below.

$$V_{out} = I_{in} \times GAIN$$

The input current \mathbb{I}_{in} is the current flowing through the input terminal of the device.

VCVS

This is the behavioral model for a Voltage Controlled Voltage Source.



Arguments

GAIN

Used to calculate the output voltage. The output voltage is calculated using the equation listed below.

$$V_{out} = V_{in} \times GAIN$$

The input voltage \mathbb{V}_{in} is the voltage across the input terminal of the device.

Delay lines

PSpice supports two types of delay lines. These are DELAY_2_TERM, which is two terminal device, and DELAY_3_TERM, which is a 3 terminal device.

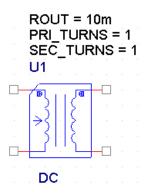
Table 5-16 Delay Line properties

| Property | |
|-------------|--|
| DELAY_TIME | introduces the specified delay in the output |
| IMPEDANCE | Z_0 |
| INSERT_LOSS | |
| Q | $Q = \frac{\omega L}{R}$ |

For a three terminal delay line, the third terminal is to be grounded.

DC transformer

This is the PSpice model used for state average analysis.



Arguments

 PRI_TURNS

Number of turns in the primary windings

 SEC_TURNS

Number of turns in the secondary windings

ROUT

Output resistance

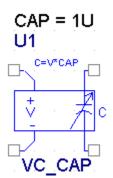
Comments

The output voltage is calculated as:

Vout = Vin*(SEC TURNS/PRI TURNS)

VC_CAP

This is a voltage controller capacitor. The capacitance is a function of the input voltage.



Parameters CAP

Capacitance factor

Comments The output capacitance is the product of input voltage and the value of the CAP property.

C = Vin*CAP

The output current is given by the equation:

 $Iout = Vout*(2*\pi*f*C)$

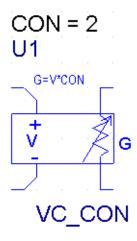
where

f = operating frequency

Vout is the voltage drop across VC_CAP

VC_CON

This is a voltage controller conductance. Electrical conductance is defined as the reciprocal of resistance.



Parameters

CON

Conductance factor

Comments

The output conductance, G, is the product of input voltage and the value of the CON property.

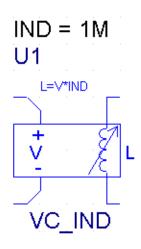
G= Vin*CON

The output current is given by the equation:

Iout = Vout*G

VC_IND

This is a voltage controlled inductor.



Parameter

IND

Inductance factor

Comments

The output inductance, L, is the product of input voltage and the value of the IND property.

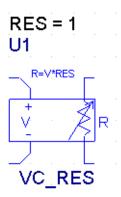
L= Vin*IND

The output current is given by the equation:

 $Iout = Vout/(2\pi fL)$

VC_RES

This is a voltage controlled resistor.



Parameter RES

Resistance factor

Comments The output resistance, R, is the product of input voltage and the value

of the RES property.

R= Vin*RS

The output current is given by the equation:

Iout = Vout/R

PSpice A/D Reference Guide Behavioral Simulation Models

Glossary

ABM analog behavioral modeling

AKO "A Kind Of" symbol. Symbols must either contain graphics

or refer to an AKO symbol. The AKO defines the symbol in terms of the graphics and pins of another part. Both must

exist in the same Symbol Library file.

alias An alias relates local schematic names for parts and

signals to netlist names (simulation devices and nodes). An alias is an exact electrical equivalent that can be used to reference a symbol. A command that sets up equivalences between pin names or net names and node names. As a command, it is the setup equivalences between node

names and pin names or net names.

annotation Annotation is a means by which parts are labeled when

they are placed, either automatically or manually.

annotation symbol An annotation symbol has no electrical significance, and is

used to clarify, point out, or define items on the schematic.

argument A value or an expression used with an operator or passed

to a subprogram (subroutine, procedure, or function).

attributes Attributes are special characteristics (a name and an

associated value) contained in a part instance or definition. For example, a MOSFET may contain specific length and width parameters which are represented as attributes on the symbol or part. Attributes may be changed through the

Property Editor and/or the Parts Editor.

A bus is a collection of homogeneously named signals.

call To transfer a program execution to some section of code

(usually a subroutine of some sort), while saving the necessary information to allow execution to resume at the

calling point when the call section has completed

execution.

Glossary

circuit A circuit is a configuration of electrically connected

components or devices.

comment A statement written into a program for documentation

purposes only and not for any functionality purposes.

compiler Translates between high-level computer language

understood by humans and machine language that is

understood by computers.

component A device or part employed in a circuit to obtain some

desired action. See package.

connector A connector is a physical device that is used for external

connections to a circuit board.

construct A computer program statement that produces a

predetermined effect.

CSHUNT The CSHUNT option adds shunt capacitors between all

nodes of the circuit and ground. Adding shunt capacitors helps in lowering the voltage fluctuations at different nodes. The shunt capacitors change the original circuit, therefore, the CSHUNT option should only be used when all other options to achieve convergence have failed. The default value is 1pF, but a lower value can be used to keep the

circuit close to its original state.

current source A current source can be an ideal current source (no limit on

the supply voltage) or a voltage source with a series

resistor.

defined function A computer instruction specifying the operation to be done

with predetermined limits.

declarative statement A computer source program instruction specifying the size,

format, and kind of data elements and variables in a

program for a complier.

device A simple or complex discrete electronic component.

Sometimes, a subsystem employed as a unit and,

therefore, thought of as a single component. See package.

DIBL drain-induced barrier lowering (MOSFET device)

dot command A type of formatting command typed into a document that

is preceded by a period (dot) to distinguish from other

syntax text.

Glossary

doping tail A changing amount of impurity in a semiconductor device.

It is observed as a change in the bulk resistance of the

semiconductor material.

ELSE An operation used in BASIC computer programing. It

specifies the operation to be performed if the conditions

given in the same program line didn't occur.

flicker noise A repeating low-frequency noise.

Fourier analysis A mathematical method of transforming a function in such

a way that the data of the function is retained but the representation of that data is changed. It is used to simplify

the reduction of the data.

FSTIM digital file stimulus device

gate A gate is a subset of a package, and corresponds to a part

instance. An electronic switch that follows a rule of Boolean

logic.

glitch An unwanted transient that recurs irregularly in the system.

global temperature Universally applied temperature (to all elements of a circuit)

global parameter Universally applied parameter (to all elements of a circuit)

hierarchical block A user defined rectangle placed on a schematic. It is used

to represent or hold the place for a collection of circuitry. A block is treated as a black box by the schematic editor. The schematic editor is aware of the connections going into and out of the block, but ignores the contents of the block until

the netlist is generated.

icon A small graphics image displayed on the screen to

represent an object that can be manipulated by the user.

IF An operation used in BASIC computer programing. It

specifies an IF-THEN operation to be performed when a condition has changed from what was expected in a

program line.

included file A smaller file that is read into a larger source-code file at a

specific spot and becomes part of a statement within the

larger source-code file.

instance The placement of a component one or more times on a

schematic.

Glossary

invoke To call or activate; used in reference to commands and

subroutines.

ionization knee A bend in the response curve where ionization starts.

IS temperature The temperature of the JFET and other transistor types

junction saturation current or the input leakage current

iteration A repeating series of arithmetic operations to arrive at a

solution.

Jiles-Atherton model A state equation model rather than an explicit function for

an inductor

junction A junction graphically indicates that wires, buses, and/or

pins are electrically connected.

keywordThe significant word in a syntax statement that directs the

process of the operation.

ls a word or symbol used to identify a file or other element

defined in a computer program.

LIBPATH A variable that specifies the directory that the model library

is in, and is first set in the PSpice.ini file.

link A branch instruction, or an address in such an instruction,

used to leave a subroutine to return to some point in the

main program.

Intercond to learn 1 The tolerance of a group of items taken as one unit.

Isb least significant bit

metafile A file that contains or defines other files.

mobility movement of electrons in semiconductor devices such as

MOSFETs

model library Consists of electrical model definitions for the parts used in

PSpice. Usually, the term model library refers to a simulation model library that has .lib extension.

mouse A common pointing device used in a windows environment.

The physical movement of the mouse will move the pointer

(cursor) on the screen.

msb most significant bit

msim.ini Legacy MicroSim configuration file that has the default

elements that are used to complete a simulation.

Glossary

nesting The embedding of one construct (such as a table in a

database; a data structure, a control structure) inside another—for example, a nested procedure is a procedure

declared within a procedure.

NETLIST The netlist provides the circuit definition and connectivity

information in simulation netlist format.

NODESET A nodeset symbol contains one or two pins, permitting you

to initialize a node voltage for simulation.

NOREUSE flagA piece of information that tells the simulator that the

automatic saving and restoring of bias point information between different temperatures, Monte Carlo runs, worst-

case runs, DC Sweep or parametric analyses is

suppressed. It is one of the options in the

.OPTIONS (analysis options) on page 71 command.

NOSUBCKT A variable that tells the simulator not to save the node

voltages and inductor currents for subcircuits.

NUMDGT An option that tells the simulator the number of digits that

will be printed for the analog values. It is one of the options in the <u>OPTIONS</u> (analysis options) on page 71 command.

object A variable comprising both routines and data that is treated

as a discrete entity, in object-oriented programing.

operator A symbol (mathematical, as an example) or other character

indicating an operation that acts on one or more elements.

OUTPUT ALL An option that asks for an output from the sensitivity runs,

after the nominal (first) run. The output from any run is governed by the <u>.PRINT (print)</u> on page 91, <u>.PLOT (plot)</u> on page 89, and <u>.PROBE (Probe)</u> on page 93 command in the file. If OUTPUT ALL is omitted, then only the nominal and worst-case runs produce output. OUTPUT ALL

ensures that all sensitivity information is saved for Probe.

package A package is an enclosure for an electronic device or

subsystem. A physical device consisting of one or more

gates.

page A page may contain both parts (represented by symbols),

port instances, connectors, and annotation symbols. A page may or may not have a title. Each schematic page

represents a single page of a circuit design.

Glossary

parameter A property used in model definition to define the electrical

behavior of the model.

part A part is an electrical component that is represented by a

schematic symbol. The term refers to the logical, rather

than the physical, component.

part definition See <u>symbol</u>.

part instance A part instance refers to an occurrence of a symbol in a

schematic.

pin Pins are contained in parts, ports, and offpage connectors.

Parts can contain multiple pins. Each part contains specific pin names associated with the part. Pins may connect to a

wire, a bus, or another pin.

pin current The current that flows into or out-of a defined pin.

POLY Specifies the number of dimensions of the polynomial.

port A port provides connectivity across schematic pages. A

port provides the anchor for a single pin. Ports are chosen from library files, placed, moved, and deleted in the same way as are parts. Ports may have multiple connections. Ports consist of three types: global, interface, and offpage.

run The execution of a computer routine or operation.

SCBE substrate current induced body effect (MOSFET device)

schematic A schematic consists of the following components: one or

more pages, a set of symbols representing local part

definitions or parts in a library file, and/or text.

setpoint A setpoint provides a graphical way of introducing

.IC (initial bias point condition) on page 49 or

.NODESET (set approximate node voltage for bias point) on page 66 commands for each instance of a symbol. These commands set one or more node voltages for the

bias point calculation.

SIMLIBPATH A variable that defines the environment that the simulator

is working in (path to the directory that the library is in).

simulation The use of a mathematical model to represent a physical

device or process.

skipbp (skip bias point)

Glossary

statement The smallest executable entity within a programming

language. In general, each line of a program is an individual statement and is considered an individual instruction. (Examples: command statements, option statements, control statements, assignment statements,

comment statements.)

Statz model A GaAsFET model

subcircuit model A model that is not built in PSpice. These models use the

.SUBCKT and .ENDS statements along with variable input parameters to define the structure and function of a part.

symbol A symbol consists of the graphical representation of a

logical or physical electronic part on the schematic page, and its definition. Symbols can be created either for a specific schematic or extracted from a library file, and may

contain schematic pages nested within them.

symbol library Contains symbols or graphical representation of off-the-

shelf PSpice parts that can directly be used in circuits being

developed.

syntax The grammar of a particular computer language, with rules

that govern the structure and content of the statement.

TEXTINT A function which returns a text string which is the integer

value closest to the value of the <value or expression>;

(<value or expression> is a floating-point value)

tick number The number generated from a regular recurring signal

emitted by a clocking circuit, or from the interrupt generated

by this signal.

TOM model a GaAsFET device

VARY BOTH The default option is VARY BOTH. When VARY BOTH is

used, sensitivity to parameters using both DEV and LOT

specifications is checked only with respect to LOT

variations. The parameter is then maximized or minimized using both DEV and LOT tolerances for the worst-case. All devices referencing the model have the same parameter

values for the worst-case simulation.

VARY DEV See VARY BOTH.

VARY LOT See VARY BOTH.

Glossary

VTO temperature The temperature of the JFET or MOSFET device when

there is zero-bias threshold (pinchoff) voltage.

window An area on the screen in a graphical computer interface

that contains instructional documentation or a message.

A

Appendix A: Battery Models

Battery Model

General .X n1 n2 awbflooded cell PARAMS VOC=<value> AH=<value>

form

.X n1 n2 awbvalve regulated cell PARAMS VOC=< value>

AH=<value> SOC=<\bar{value}>

Examples .X 7 5 awbflooded_cell PARAMS VOC=5 AH=15 SOC=0.8

Arguments and options

Appendix A: Battery Models

awbflooded_cell

PSpice model for modelling the flooded cell batteries. In the flooded cells batteries since the gases created during charging are vented to the atmosphere, distilled water must be added occasionally to bring the electrolyte back to its required level.

Example: 12-V automobile battery.

awbvalve_regulated_cell

PSpice model for modelling the valve regulated batteries.

n1, n2

Port numbers.

VOC

Indicates the open circuit voltage. This is the voltage across the two terminals of the battery when the battery is not connected to a circuit.

AΗ

It is the ampere hour of the ideal battery. This is the amount of time for which an ideal battery operates without having to recharge it. For example, if a battery is marked *300Ah* then it is assumed that the ideal battery can supply 20A current for 15 hours or 10A current for 30 hrs.

Note: An ampere hour (Ah) indicates the amount of energy charge in an ideal battery that will allow one ampere of current to flow for one hour.

SOC

Indicates the state of charge in a a battery. For a completely charged battery, SOC is 100% and for a fully discharged battery, SOC is 0%.

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